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# Cyclone Device Handbook, Volume 1



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formation and before placing orders for products or services.

ii Altera Corporation

I.S. EN ISO 9001

## **Contents**



Chapter Revision Dates	xi
About this Handbook	viii
About this Handbook	
How to Find Information	
How to Contact Altera	
Typographic Conventions	XIV
Section I. Cyclone FPGA Family Data Sheet	
Revision History	2–1
Chapter 1. Introduction	
Introduction	1–1
Features	
Document Revision History	
Chapter 2. Cyclone Architecture	
Functional Description	2_1
Logic Array Blocks	
LAB Interconnects	
LAB Control Signals	
Logic Elements	
LUT Chain and Register Chain	
addnsub Signal	
LE Operating Modes	
MultiTrack Interconnect	
Embedded Memory	
Memory Modes	
Parity Bit Support	
Shift Register Support	
Memory Configuration Sizes	
Byte Enables	
Control Signals and M4K Interface	
Independent Clock Mode	
Input/Output Clock Mode	
Read/Write Clock Mode	
Single-Port Mode	
Global Clock Network and Phase-Locked Loops	
Global Clock Network	

**Altera Corporation** 

Dual-Purpose Clock Pins	2–31
Combined Resources	2–31
PLLs	2–32
Clock Multiplication and Division	2–35
External Clock Inputs	2–36
External Clock Outputs	
Clock Feedback	
Phase Shifting	
Lock Detect Signal	
Programmable Duty Cycle	
Control Signals	
I/O Structure	
External RAM Interfacing	
DDR SDRAM and FCRAM	
Programmable Drive Strength	
Open-Drain Output	
Slew-Rate Control	
Bus Hold	
Programmable Pull-Up Resistor	
Advanced I/O Standard Support	
LVDS I/O Pins	
MultiVolt I/O Interface	
Power Sequencing and Hot Socketing	
Referenced Documents	2–56
	2–56
Referenced Documents	2–56
Referenced Documents	
Referenced Documents	
Referenced Documents Document Revision History  Chapter 3. Configuration and Testing IEEE Std. 1149.1 (JTAG) Boundary Scan Support SignalTap II Embedded Logic Analyzer	
Referenced Documents Document Revision History  Chapter 3. Configuration and Testing IEEE Std. 1149.1 (JTAG) Boundary Scan Support SignalTap II Embedded Logic Analyzer Configuration	
Referenced Documents Document Revision History  Chapter 3. Configuration and Testing IEEE Std. 1149.1 (JTAG) Boundary Scan Support SignalTap II Embedded Logic Analyzer Configuration Operating Modes	2–56 2–56 3–1 3–5 3–5 3–5 3–6
Referenced Documents Document Revision History  Chapter 3. Configuration and Testing IEEE Std. 1149.1 (JTAG) Boundary Scan Support SignalTap II Embedded Logic Analyzer Configuration Operating Modes Configuration Schemes	2–56 2–56 3–1 3–5 3–5 3–6 3–6
Referenced Documents Document Revision History  Chapter 3. Configuration and Testing IEEE Std. 1149.1 (JTAG) Boundary Scan Support SignalTap II Embedded Logic Analyzer Configuration Operating Modes Configuration Schemes Referenced Documents	2–56 2–56 3–1 3–5 3–5 3–5 3–6 3–6
Referenced Documents Document Revision History  Chapter 3. Configuration and Testing IEEE Std. 1149.1 (JTAG) Boundary Scan Support SignalTap II Embedded Logic Analyzer Configuration Operating Modes Configuration Schemes	2–56 2–56 3–1 3–5 3–5 3–5 3–6 3–6
Referenced Documents Document Revision History  Chapter 3. Configuration and Testing IEEE Std. 1149.1 (JTAG) Boundary Scan Support SignalTap II Embedded Logic Analyzer Configuration Operating Modes Configuration Schemes Referenced Documents Document Revision History	2–56 2–56 3–1 3–5 3–5 3–5 3–6 3–6
Referenced Documents Document Revision History  Chapter 3. Configuration and Testing IEEE Std. 1149.1 (JTAG) Boundary Scan Support SignalTap II Embedded Logic Analyzer Configuration Operating Modes Configuration Schemes Referenced Documents Document Revision History  Chapter 4. DC and Switching Characteristics	2–56 2–56 3–1 3–5 3–5 3–5 3–6 3–6 3–7
Referenced Documents Document Revision History  Chapter 3. Configuration and Testing IEEE Std. 1149.1 (JTAG) Boundary Scan Support SignalTap II Embedded Logic Analyzer Configuration Operating Modes Configuration Schemes Referenced Documents Document Revision History  Chapter 4. DC and Switching Characteristics Operating Conditions	2–56 2–56 3–1 3–5 3–5 3–5 3–6 3–6 3–7 4–1
Referenced Documents Document Revision History  Chapter 3. Configuration and Testing IEEE Std. 1149.1 (JTAG) Boundary Scan Support SignalTap II Embedded Logic Analyzer Configuration Operating Modes Configuration Schemes Referenced Documents Document Revision History  Chapter 4. DC and Switching Characteristics Operating Conditions Power Consumption	2–56 2–56 3–1 3–5 3–5 3–5 3–6 3–6 3–7 4–1 4–8
Referenced Documents Document Revision History  Chapter 3. Configuration and Testing IEEE Std. 1149.1 (JTAG) Boundary Scan Support SignalTap II Embedded Logic Analyzer Configuration Operating Modes Configuration Schemes Referenced Documents Document Revision History  Chapter 4. DC and Switching Characteristics Operating Conditions Power Consumption Timing Model	2–56 2–56 3–1 3–1 3–5 3–5 3–6 3–6 3–7 4–1 4–8 4–9
Referenced Documents Document Revision History  Chapter 3. Configuration and Testing IEEE Std. 1149.1 (JTAG) Boundary Scan Support SignalTap II Embedded Logic Analyzer Configuration Operating Modes Configuration Schemes Referenced Documents Document Revision History  Chapter 4. DC and Switching Characteristics Operating Conditions Power Consumption Timing Model Preliminary and Final Timing	2–56 2–56 3–1 3–1 3–5 3–5 3–6 3–6 3–7 4–1 4–8 4–9 4–9
Referenced Documents Document Revision History  Chapter 3. Configuration and Testing IEEE Std. 1149.1 (JTAG) Boundary Scan Support SignalTap II Embedded Logic Analyzer Configuration Operating Modes Configuration Schemes Referenced Documents Document Revision History  Chapter 4. DC and Switching Characteristics Operating Conditions Power Consumption Timing Model Preliminary and Final Timing Performance	2–56 2–56 3–1 3–1 3–5 3–5 3–6 3–6 3–7 3–7 4–1 4–9 4–9 4–10
Referenced Documents Document Revision History  Chapter 3. Configuration and Testing IEEE Std. 1149.1 (JTAG) Boundary Scan Support SignalTap II Embedded Logic Analyzer Configuration Operating Modes Configuration Schemes Referenced Documents Document Revision History  Chapter 4. DC and Switching Characteristics Operating Conditions Power Consumption Timing Model Preliminary and Final Timing Performance Internal Timing Parameters	2–56 2–56 3–1 3–1 3–5 3–5 3–6 3–6 3–7 3–7 4–1 4–1 4–9 4–10 4–10
Referenced Documents Document Revision History  Chapter 3. Configuration and Testing IEEE Std. 1149.1 (JTAG) Boundary Scan Support SignalTap II Embedded Logic Analyzer Configuration Operating Modes Configuration Schemes Referenced Documents Document Revision History  Chapter 4. DC and Switching Characteristics Operating Conditions Power Consumption Timing Model Preliminary and Final Timing Performance Internal Timing Parameters External Timing Parameters	2–56 2–56 3–1 3–1 3–5 3–5 3–6 3–6 3–7 3–7 4–1 4–1 4–9 4–10 4–11
Referenced Documents Document Revision History  Chapter 3. Configuration and Testing IEEE Std. 1149.1 (JTAG) Boundary Scan Support SignalTap II Embedded Logic Analyzer Configuration Operating Modes Configuration Schemes Referenced Documents Document Revision History  Chapter 4. DC and Switching Characteristics Operating Conditions Power Consumption Timing Model Preliminary and Final Timing Performance Internal Timing Parameters External I/O Delay Parameters External I/O Delay Parameters	2–56 2–56 3–1 3–1 3–5 3–5 3–6 3–6 3–7 3–7 4–1 4–1 4–9 4–10 4–11 4–15
Referenced Documents Document Revision History  Chapter 3. Configuration and Testing IEEE Std. 1149.1 (JTAG) Boundary Scan Support SignalTap II Embedded Logic Analyzer Configuration Operating Modes Configuration Schemes Referenced Documents Document Revision History  Chapter 4. DC and Switching Characteristics Operating Conditions Power Consumption Timing Model Preliminary and Final Timing Performance Internal Timing Parameters External I/O Delay Parameters External I/O Delay Parameters Maximum Input and Output Clock Rates	2–56 2–56 3–1 3–1 3–5 3–5 3–6 3–6 3–7 3–7 4–1 4–1 4–9 4–9 4–10 4–11 4–15 4–21
Referenced Documents Document Revision History  Chapter 3. Configuration and Testing IEEE Std. 1149.1 (JTAG) Boundary Scan Support SignalTap II Embedded Logic Analyzer Configuration Operating Modes Configuration Schemes Referenced Documents Document Revision History  Chapter 4. DC and Switching Characteristics Operating Conditions Power Consumption Timing Model Preliminary and Final Timing Performance Internal Timing Parameters External I/O Delay Parameters External I/O Delay Parameters	2–56 2–56 3–1 3–1 3–5 3–5 3–6 3–6 3–7 3–7 4–1 4–1 4–9 4–10 4–11 4–15 4–21 4–27

Document Revision History	4–31
Chapter 5. Reference and Ordering Information	
Software	
Device Pin-Outs	5–1
Ordering Information	5–1
Referenced Documents	5–2
Document Revision History	5–2
Section II. Clock Management	
Revision History	5–1
Chapter 6. Using PLLs in Cyclone Devices	
Introduction	
Hardware Overview	6–1
Software Overview	6–4
Pins and Clock Network Connections	6–6
Hardware Features	
Clock Multiplication and Division	6–8
Phase Shifting	
Programmable Duty Cycle	
External Clock Output	
Control Signals	
Clock Feedback Modes	
Normal Mode	6–14
Zero Delay Buffer Mode	
No Compensation	
Pins	
Board Layout	
VCCA and GNDA	
Jitter Considerations	
Specifications	
Software Support	
Quartus II altpll Megafunction	
altpll Input Ports	
altpll Output Ports	6–23
MegaWizard Customization	
MegaWizard Page Description	
Compilation Report	
Timing Analysis	
Simulation	
Global Clock Network	
Dedicated Clock Input Pins	
Dual-Purpose Clock I/O Pins	
Combined Courses	

Altera Corporation

Conclusion	
Referenced Documents	
Bocancia ne i Bioli i libioli y	0 11
Section III. Memory	
Revision History	7–1
Observe 7 On Obje Manage Involved and Hairy Ondon Manage Disable	
Chapter 7. On-Chip Memory Implementations Using Cyclone Memory Blocks	
Introduction	
M4K Memory Features	
Parity Bit Support	
Byte-Enable Support	
Power-up Conditions and Memory Initialization	
Using M4K Memory	
Implementing Single-Port Mode	
Implementing Simple Dual-Port Mode	7–6
Implementing True Dual-Port Mode	7–8
Implementing Shift-Register Mode	
Implementing ROM Mode	
Implementing FIFO Buffers	
Clock Modes	
Independent Clock Mode	
Input/Output Clock Mode	
Read/Write Clock Mode	
Single-Port Mode	
Synchronous and Pseudo-Asynchronous Modes	
Read-during-Write Operation at the Same Address	
Same-Port Read-during-Write Mode	
Mixed-Port Read-during-Write Mode	
Conclusion	
Referenced Documents	
Document Revision History	7–23
Section IV. I/O Standards	
Revision History	8_1
Revision History	0 1
Chapter 8. Using Selectable I/O Standards in Cyclone Devices	
Introduction	8–1
Supported I/O Standards	
3.3-V LVTTL (EIA/JEDEC Standard JESD8-B)	
3.3-V LVCMOS (EIA/JEDEC Standard JESD8-B)	
2.5-V LVTTL Normal and Wide Voltage Ranges (EIA/JEDEC Standard EIA/JESD8-5)	
2.5-V LVCMOS Normal and Wide Voltage Ranges (ELA/IEDEC Standard ELA/IESD8-	

vi Altera Corporation

1.8-V LVTTL Normal and Wide Voltage Ranges (EIA/JEDEC Standard EIA/JESD8-7)	
1.8-V LVCMOS Normal and Wide Voltage Ranges (EIA/JEDEC Standard EIA/JESD8-	-7) . 8–4
1.5-V LVCMOS Normal and Wide Voltage Ranges (EIA/JEDEC Standard JESD8-11)	
3.3-V (PCI Special Interest Group (SIG) PCI Local Bus Specification Revision 2.2)	
SSTL-3 Class I and II (EIA/JEDEC Standard JESD8-8)	
SSTL-2 Class I and II (EIA/JEDEC Standard JESD8-9A)	
LVDS (ANSI/TIA/EIA Standard ANSI/TIA/EIA-644)	
Differential SSTL-2 - EIA/JEDEC Standard JESD8-9A	
Cyclone I/O Banks	
Programmable Current Drive Strength	
Hot Socketing	
I/O Termination	
Voltage-Referenced I/O Standard Termination	
Differential I/O Standard Termination	
Pad Placement and DC Guidelines	
Differential Pad Placement Guidelines	
V <sub>REF</sub> Pad Placement Guidelines	
DC Guidelines	
Quartus II Software Support	
Settings	
Conclusion	
More Information	
References	
Referenced Documents	
Document Revision History	
Document Revision instory	0 25
Chapter 9. High-Speed Differential Signaling in Cyclone Devices	
Introduction	0 1
Cyclone High-Speed I/O Banks	
Cyclone High-Speed I/O Interface	
Clock Domains	
LVDS Receiver and Transmitter	
RSDS I/O Standard Support in Cyclone Devices	
Designing with RSDS	
RSDS Software Support	
High-Speed I/O Timing in Cyclone Devices	
LVDS Receiver and Transmitter Termination	
Implementing Cyclone LVDS and RSDS I/O Pins in the Quartus II Software	
Design Guidelines	
Differential Pad Placement Guidelines	
Board Design Considerations	
Conclusion	
Referenced Documents	
Document Revision History	
= = = =================================	/0

Altera Corporation vii

Section V. Design Considerations	
Revision History	10–1
Chapter 10. Implementing Double Data Rate I/O Signaling in Cyclone Devices	
Introduction	
Double Data Rate Input	
Double Data Rate Output	
Bidirectional Double Data Rate	
DDR Memory Support	
Conclusion	
Referenced Documents	
Document Revision History	10–5
Chapter 11. Using Cyclone Devices in Multiple-Voltage Systems	
Introduction	
I/O Standards	
MultiVolt I/O Operation	
5.0-V Device Compatibility	
Hot-Socketing	
Devices Can Be Driven before Power-Up	
I/O Pins Remain Tri-Stated during Power-Up	11–6
Signal Pins Do Not Drive the V <sub>CCIO</sub> or V <sub>CCINT</sub> Power Supplies	11–6
Power-Up Sequence	
Power-On Reset	
Conclusion	
Document Revision History	11–8
Chapter 12. Designing with 1.5-V Devices	
Introduction	
Power Sequencing and Hot Socketing	
Using MultiVolt I/O Pins	
Voltage Regulators	
Linear Voltage Regulators	
Switching Voltage Regulators	
Maximum Output Current	
Selecting Voltage Regulators	
Voltage Divider Network	
1.5-V Regulator Circuits	
1.5-V Regulator Application Examples	
Synchronous Switching Regulator Example	12–20
Board Layout	12–21
Split-Plane Method	12–23
Conclusion	
References	12–24
Referenced Documents	12–25
Document Revision History	12_25

viii Altera Corporation

Chamber 40 Cantinuving Cualana FDCAs	
Chapter 13. Configuring Cyclone FPGAs	
Introduction	
Device Configuration Overview	13–1
Data Compression	
Configuration Schemes	
Active Serial Configuration (Serial Configuration Devices)	
Passive Serial Configuration	
JTAG-Based Configuration	
Combining Configuration Schemes	
Active Serial and JTAG	
Device Configuration Pins	
Referenced Documents	13–50
Document Revision History	13–51
Chapter 14. Serial Configuration Devices (EPCS1, EPCS4, EPCS16, EPCS EPCS128) Data Sheet  Introduction	
Functional Description	
Accessing Memory in Serial Configuration Devices	
Active Serial FPGA Configuration	
Serial Configuration Device Memory Access	
Memory Array Organization	
Operation Codes	
Power and Operation	
Power Mode	
Power-On Reset	14–34
Error Detection	14–34
Timing Information	
Programming and Configuration File Support	
Operating Conditions	
Pin Information	
Package	
Ordering Code	
Referenced Documents	
Document Revision History	14–44
Section VII. Cyclone Device Package Information	
Revision History	

Altera Corporation ix

## Cyclone Device Handbook, Volume 1

Device and Package Cross Reference	15-1
Thermal Resistance	
Package Outlines	15–2
Document Revision History	

x Altera Corporation



## **Chapter Revision Dates**

The chapters in this book, *Cyclone Device Handbook, Volume 1*, were revised on the following dates. Where chapters or groups of chapters are available separately, part numbers are listed.

Chapter 1. Introduction

Revised: *May* 2008 Part number: *C51001-1.5* 

Chapter 2. Cyclone Architecture

Revised: *May* 2008 Part number: *C51002-1.6* 

Chapter 3. Configuration and Testing

Revised: *May* 2008 Part number: *C51003-1.4* 

Chapter 4. DC and Switching Characteristics

Revised: May 2008 Part number: C51004-1.7

Chapter 5. Reference and Ordering Information

Revised: *May* 2008 Part number: *C51005-1.4* 

Chapter 6. Using PLLs in Cyclone Devices

Revised: *May* 2008 Part number: *C51006-1.5* 

Chapter 7. On-Chip Memory Implementations Using Cyclone Memory Blocks

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Chapter 8. Using Selectable I/O Standards in Cyclone Devices

Revised: *May* 2008 Part number: *C51008-1.6* 

Chapter 9. High-Speed Differential Signaling in Cyclone Devices

Revised: May 2008 Part number: C51009-1.6

Altera Corporation xi

Chapter 10. Implementing Double Data Rate I/O Signaling in Cyclone Devices

Revised: May 2008 Part number: C51010-1.2

Chapter 11. Using Cyclone Devices in Multiple-Voltage Systems

Revised: *May* 2008 Part number: *C51011-1.2* 

Chapter 12. Designing with 1.5-V Devices

Revised: May 2008 Part number: C51012-1.4

Chapter 13. Configuring Cyclone FPGAs

Revised: May 2008 Part number: C51013-1.8

Chapter 14. Serial Configuration Devices (EPCS1, EPCS4, EPCS16, EPCS64, and EPCS128) Data

Sheet

Revised: May 2008 Part number: C51014-3.1

Chapter 15. Package Information for Cyclone Devices

Revised: May 2008 Part number: C52006-1.3

xii Altera Corporation



## **About this Handbook**

This handbook provides comprehensive information about the Altera® Cyclone® family of devices.

# How to Find Information

You can find more information in the following ways:

- The Adobe Acrobat Find feature, which searches the text of a PDF document. Click the binoculars toolbar icon to open the Find dialog box.
- Acrobat bookmarks, which serve as an additional table of contents in PDF documents.
- Thumbnail icons, which provide miniature previews of each page, provide a link to the pages.
- Numerous links, shown in green text, which allow you to jump to related information.

## How to Contact Altera

For the most up-to-date information about Altera products, refer to the following table.

Contact (1)	Contact Method Address		
Technical support	Website www.altera.com/support		
Technical training	Website	www.altera.com/training	
	Email	custrain@altera.com	
Product literature	Website	www.altera.com/literature	
Altera literature services	Email	literature@altera.com	
Non-technical support (General)	Email	nacomp@altera.com	
(Software Licensing)	Email	authorization@altera.com	

#### Note to table:

(1) You can also contact your local Altera sales office or sales representative.

Altera Corporation xiii

# Typographic Conventions

This document uses the typographic conventions shown below.

Visual Cue	Meaning		
Bold Type with Initial Capital Letters	Command names, dialog box titles, checkbox options, and dialog box options are shown in bold, initial capital letters. Example: <b>Save As</b> dialog box.		
bold type	External timing parameters, directory names, project names, disk drive names, filenames, filename extensions, and software utility names are shown in bold type. Examples: f <sub>MAX</sub> , \qdesigns directory, d: drive, chiptrip.gdf file.		
Italic Type with Initial Capital Letters	Document titles are shown in italic type with initial capital letters. Example: AN 75: High-Speed Board Design.		
Italic type	Internal timing parameters and variables are shown in italic type. Examples: $t_{PIA}$ , $n+1$ .		
	Variable names are enclosed in angle brackets (< >) and shown in italic type. Example: <file name="">, <pre><pre><pre><pre><pre><pre>pof</pre> file.</pre></pre></pre></pre></pre></file>		
Initial Capital Letters	Keyboard keys and menu names are shown with initial capital letters. Examples: Delete key, the Options menu.		
"Subheading Title"	References to sections within a document and titles of on-line help topics are shown in quotation marks. Example: "Typographic Conventions."		
Courier type	Signal and port names are shown in lowercase Courier type. Examples: data1, tdi, input. Active-low signals are denoted by suffix n, e.g., resetn.		
	Anything that must be typed exactly as it appears is shown in Courier type. For example: c:\qdesigns\tutorial\chiptrip.gdf. Also, sections of an actual file, such as a Report File, references to parts of files (e.g., the AHDL keyword SUBDESIGN), as well as logic function names (e.g., TRI) are shown in Courier.		
1., 2., 3., and a., b., c., etc.	Numbered steps are used in a list of items when the sequence of the items is important, such as the steps listed in a procedure.		
•••	Bullets are used in a list of items when the sequence of the items is not important.		
✓	The checkmark indicates a procedure that consists of one step only.		
	The hand points to information that requires special attention.		
4	The angled arrow indicates you should press the Enter key.		
	The feet direct you to more information on a particular topic.		

xiv Altera Corporation



# Section I. Cyclone FPGA Family Data Sheet

This section provides designers with the data sheet specifications for Cyclone® devices. The chapters contain feature definitions of the internal architecture, configuration and JTAG boundary-scan testing information, DC operating conditions, AC timing parameters, a reference to power consumption, and ordering information for Cyclone devices.

This section contains the following chapters:

- Chapter 1. Introduction
- Chapter 2. Cyclone Architecture
- Chapter 3. Configuration and Testing
- Chapter 4. DC and Switching Characteristics
- Chapter 5. Reference and Ordering Information

## **Revision History**

Refer to each chapter for its own specific revision history. For information on when each chapter was updated, refer to the Chapter Revision Dates section, which appears in the complete handbook.

Altera Corporation Section I–1

Section I–2 Altera Corporation

## 1. Introduction



C51001-1.5

### Introduction

The Cyclone® field programmable gate array family is based on a 1.5-V, 0.13-µm, all-layer copper SRAM process, with densities up to 20,060 logic elements (LEs) and up to 288 Kbits of RAM. With features like phase-locked loops (PLLs) for clocking and a dedicated double data rate (DDR) interface to meet DDR SDRAM and fast cycle RAM (FCRAM) memory requirements, Cyclone devices are a cost-effective solution for data-path applications. Cyclone devices support various I/O standards, including LVDS at data rates up to 640 megabits per second (Mbps), and 66- and 33-MHz, 64- and 32-bit peripheral component interconnect (PCI), for interfacing with and supporting ASSP and ASIC devices. Altera also offers new low-cost serial configuration devices to configure Cyclone devices.

### **Features**

The Cyclone device family offers the following features:

- 2,910 to 20,060 LEs, see Table 1–1
- Up to 294,912 RAM bits (36,864 bytes)
- Supports configuration through low-cost serial configuration device
- Support for LVTTL, LVCMOS, SSTL-2, and SSTL-3 I/O standards
- Support for 66- and 33-MHz, 64- and 32-bit PCI standard
- High-speed (640 Mbps) LVDS I/O support
- Low-speed (311 Mbps) LVDS I/O support
- 311-Mbps RSDS I/O support
- Up to two PLLs per device provide clock multiplication and phase shifting
- Up to eight global clock lines with six clock resources available per logic array block (LAB) row
- Support for external memory, including DDR SDRAM (133 MHz),
   FCRAM, and single data rate (SDR) SDRAM
- Support for multiple intellectual property (IP) cores, including Altera® MegaCore® functions and Altera Megafunctions Partners Program (AMPPSM) megafunctions.

Table 1–1. Cyclone Device Features (Part 1 of 2)					
Feature	EP1C3	EP1C4	EP1C6	EP1C12	EP1C20
LEs	2,910	4,000	5,980	12,060	20,060
M4K RAM blocks (128 × 36 bits)	13	17	20	52	64

Table 1–1. Cyclone Device Features (Part 2 of 2)					
Feature	EP1C3	EP1C4	EP1C6	EP1C12	EP1C20
Total RAM bits	59,904	78,336	92,160	239,616	294,912
PLLs	1	2	2	2	2
Maximum user I/O pins (1)	104	301	185	249	301

Note to Table 1–1:

(1) This parameter includes global clock pins.

Cyclone devices are available in quad flat pack (QFP) and space-saving FineLine® BGA packages (see Tables 1–2 through 1–3).

Table 1–2. Cyclone Package Options and I/O Pin Counts							
Device	100-Pin TQFP (1)	<b>144-Pin TQFP</b> (1), (2)	<b>240-Pin PQFP</b> (1)	256-Pin FineLine BGA	324-Pin FineLine BGA	400-Pin FineLine BGA	
EP1C3	65	104	_	_	_	_	
EP1C4	_	_	_	_	249	301	
EP1C6	_	98	185	185	_	_	
EP1C12	_	_	173	185	249	_	
EP1C20	_	_	_	_	233	301	

#### *Notes to Table 1–2:*

- (1) TQFP: thin quad flat pack. PQFP: plastic quad flat pack.
- (2) Cyclone devices support vertical migration within the same package (i.e., designers can migrate between the EP1C3 device in the 144-pin TQFP package and the EP1C6 device in the same package).

Vertical migration means you can migrate a design from one device to another that has the same dedicated pins, JTAG pins, and power pins, and are subsets or supersets for a given package across device densities. The largest density in any package has the highest number of power pins; you must use the layout for the largest planned density in a package to provide the necessary power pins for migration.

For I/O pin migration across densities, cross-reference the available I/O pins using the device pin-outs for all planned densities of a given package type to identify which I/O pins can be migrated. The Quartus® II software can automatically cross-reference and place all pins for you when given a device migration list. If one device has power or ground pins, but these same pins are user I/O on a different device that is in the migration path,the Quartus II software ensures the pins are not used as user I/O in the Quartus II software. Ensure that these pins are connected

to the appropriate plane on the board. The Quartus II software reserves I/O pins as power pins as necessary for layout with the larger densities in the same package having more power pins.

Table 1–3. Cyclone QFP and FineLine BGA Package Sizes							
Dimension	100-Pin TQFP	144-Pin TQFP	240-Pin PQFP	256-Pin FineLine BGA	324-Pin FineLine BGA	400-Pin FineLine BGA	
Pitch (mm)	0.5	0.5	0.5	1.0	1.0	1.0	
Area (mm²)	256	484	1,024	289	361	441	
$\begin{array}{c} \text{Length} \times \text{width} \\ \text{(mm} \times \text{mm)} \end{array}$	16×16	22×22	34.6×34.6	17×17	19×19	21×21	

## Document Revision History

Table 1--4 shows the revision history for this document.

Table 1–4. Document Revision History					
Date and Document Version	Changes Made	Summary of Changes			
May 2008 v1.5	Minor textual and style changes.	_			
January 2007 v1.4	Added document revision history.	_			
August 2005 v1.3	Minor updates.	_			
October 2003 v1.2	Added 64-bit PCI support information.	_			
September 2003 v1.1	<ul> <li>Updated LVDS data rates to 640 Mbps from 311 Mbps.</li> <li>Updated RSDS feature information.</li> </ul>	_			
May 2003 v1.0	Added document to Cyclone Device Handbook.	_			



## 2. Cyclone Architecture

C51002-1.6

# Functional Description

Cyclone<sup>®</sup> devices contain a two-dimensional row- and column-based architecture to implement custom logic. Column and row interconnects of varying speeds provide signal interconnects between LABs and embedded memory blocks.

The logic array consists of LABs, with 10 LEs in each LAB. An LE is a small unit of logic providing efficient implementation of user logic functions. LABs are grouped into rows and columns across the device. Cyclone devices range between 2,910 to 20,060 LEs.

M4K RAM blocks are true dual-port memory blocks with 4K bits of memory plus parity (4,608 bits). These blocks provide dedicated true dual-port, simple dual-port, or single-port memory up to 36-bits wide at up to 250 MHz. These blocks are grouped into columns across the device in between certain LABs. Cyclone devices offer between 60 to 288 Kbits of embedded RAM.

Each Cyclone device I/O pin is fed by an I/O element (IOE) located at the ends of LAB rows and columns around the periphery of the device. I/O pins support various single-ended and differential I/O standards, such as the 66- and 33-MHz, 64- and 32-bit PCI standard and the LVDS I/O standard at up to 640 Mbps. Each IOE contains a bidirectional I/O buffer and three registers for registering input, output, and output-enable signals. Dual-purpose DQS, DQ, and DM pins along with delay chains (used to phase-align DDR signals) provide interface support with external memory devices such as DDR SDRAM, and FCRAM devices at up to 133 MHz (266 Mbps).

Cyclone devices provide a global clock network and up to two PLLs. The global clock network consists of eight global clock lines that drive throughout the entire device. The global clock network can provide clocks for all resources within the device, such as IOEs, LEs, and memory blocks. The global clock lines can also be used for control signals. Cyclone PLLs provide general-purpose clocking with clock multiplication and phase shifting as well as external outputs for high-speed differential I/O support.

Figure 2–1 shows a diagram of the Cyclone EP1C12 device.

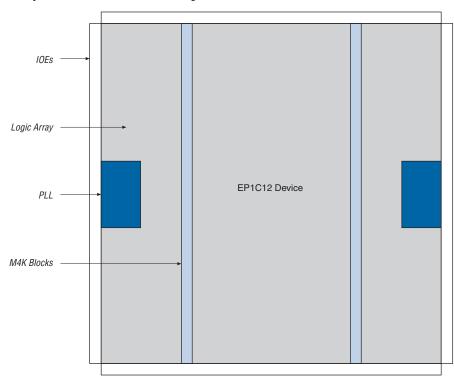


Figure 2-1. Cyclone EP1C12 Device Block Diagram

The number of M4K RAM blocks, PLLs, rows, and columns vary per device. Table 2–1 lists the resources available in each Cyclone device.

Table 2–1. Cyclone Device Resources							
Device	M4K	RAM	PLLs	LAB Columns	LAB Rows		
	Columns	Blocks					
EP1C3	1	13	1	24	13		
EP1C4	1	17	2	26	17		
EP1C6	1	20	2	32	20		
EP1C12	2	52	2	48	26		
EP1C20	2	64	2	64	32		

## Logic Array Blocks

Each LAB consists of 10 LEs, LE carry chains, LAB control signals, a local interconnect, look-up table (LUT) chain, and register chain connection lines. The local interconnect transfers signals between LEs in the same LAB. LUT chain connections transfer the output of one LE's LUT to the adjacent LE for fast sequential LUT connections within the same LAB. Register chain connections transfer the output of one LE's register to the adjacent LE's register within a LAB. The Quartus® II Compiler places associated logic within a LAB or adjacent LABs, allowing the use of local, LUT chain, and register chain connections for performance and area efficiency. Figure 2–2 details the Cyclone LAB.

Row Interconnect Column Interconnect Direct link interconnect from Direct link adjacent block interconnect from adjacent block Direct link Direct link interconnect to interconnect to adjacent block adjacent block LÄB Local Interconnect

Figure 2-2. Cyclone LAB Structure

#### LAB Interconnects

The LAB local interconnect can drive LEs within the same LAB. The LAB local interconnect is driven by column and row interconnects and LE outputs within the same LAB. Neighboring LABs, PLLs, and M4K RAM blocks from the left and right can also drive a LAB's local interconnect through the direct link connection. The direct link connection feature minimizes the use of row and column interconnects, providing higher

performance and flexibility. Each LE can drive 30 other LEs through fast local and direct link interconnects. Figure 2–3 shows the direct link connection.

Direct link interconnect from right LAB, M4K memory block, PLL, or IOE output

Direct link interconnect from right LAB, M4K memory block, PLL, or IOE output

Direct link interconnect from right LAB, M4K memory block, PLL, or IOE output

Direct link interconnect from right LAB, M4K memory block, PLL, or IOE output

Figure 2-3. Direct Link Connection

## **LAB Control Signals**

Each LAB contains dedicated logic for driving control signals to its LEs. The control signals include two clocks, two clock enables, two asynchronous clears, synchronous clear, asynchronous preset/load, synchronous load, and add/subtract control signals. This gives a maximum of 10 control signals at a time. Although synchronous load and clear signals are generally used when implementing counters, they can also be used with other functions.

Each LAB can use two clocks and two clock enable signals. Each LAB's clock and clock enable signals are linked. For example, any LE in a particular LAB using the labelk1 signal will also use labelkenal. If the LAB uses both the rising and falling edges of a clock, it also uses both LAB-wide clock signals. Deasserting the clock enable signal will turn off the LAB-wide clock.

Each LAB can use two asynchronous clear signals and an asynchronous load/preset signal. The asynchronous load acts as a preset when the asynchronous load data input is tied high.

With the LAB-wide addnsub control signal, a single LE can implement a one-bit adder and subtractor. This saves LE resources and improves performance for logic functions such as DSP correlators and signed multipliers that alternate between addition and subtraction depending on data.

The LAB row clocks [5..0] and LAB local interconnect generate the LAB-wide control signals. The MultiTrack<sup>TM</sup> interconnect's inherent low skew allows clock and control signal distribution in addition to data. Figure 2–4 shows the LAB control signal generation circuit.

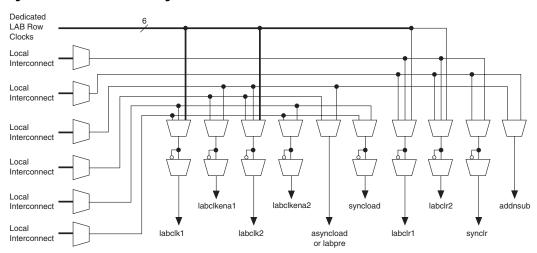
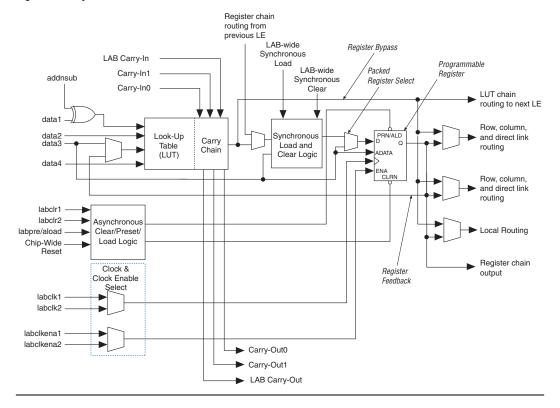


Figure 2-4. LAB-Wide Control Signals

## **Logic Elements**

The smallest unit of logic in the Cyclone architecture, the LE, is compact and provides advanced features with efficient logic utilization. Each LE contains a four-input LUT, which is a function generator that can implement any function of four variables. In addition, each LE contains a programmable register and carry chain with carry select capability. A single LE also supports dynamic single bit addition or subtraction mode selectable by a LAB-wide control signal. Each LE drives all types of interconnects: local, row, column, LUT chain, register chain, and direct link interconnects. See Figure 2–5.

Figure 2-5. Cyclone LE



Each LE's programmable register can be configured for D, T, JK, or SR operation. Each register has data, true asynchronous load data, clock, clock enable, clear, and asynchronous load/preset inputs. Global signals, general-purpose I/O pins, or any internal logic can drive the register's clock and clear control signals. Either general-purpose I/O pins or internal logic can drive the clock enable, preset, asynchronous load, and asynchronous data. The asynchronous load data input comes from the data3 input of the LE. For combinatorial functions, the LUT output bypasses the register and drives directly to the LE outputs.

Each LE has three outputs that drive the local, row, and column routing resources. The LUT or register output can drive these three outputs independently. Two LE outputs drive column or row and direct link routing connections and one drives local interconnect resources. This allows the LUT to drive one output while the register drives another output. This feature, called register packing, improves device utilization because the device can use the register and the LUT for unrelated

functions. Another special packing mode allows the register output to feed back into the LUT of the same LE so that the register is packed with its own fan-out LUT. This provides another mechanism for improved fitting. The LE can also drive out registered and unregistered versions of the LUT output.

### **LUT Chain and Register Chain**

In addition to the three general routing outputs, the LEs within a LAB have LUT chain and register chain outputs. LUT chain connections allow LUTs within the same LAB to cascade together for wide input functions. Register chain outputs allow registers within the same LAB to cascade together. The register chain output allows a LAB to use LUTs for a single combinatorial function and the registers to be used for an unrelated shift register implementation. These resources speed up connections between LABs while saving local interconnect resources. "MultiTrack Interconnect" on page 2–12 for more information on LUT chain and register chain connections.

### addnsub Signal

The LE's dynamic adder/subtractor feature saves logic resources by using one set of LEs to implement both an adder and a subtractor. This feature is controlled by the LAB-wide control signal addnsub. The addnsub signal sets the LAB to perform either A + B or A -B. The LUT computes addition; subtraction is computed by adding the two's complement of the intended subtractor. The LAB-wide signal converts to two's complement by inverting the B bits within the LAB and setting carry-in = 1 to add one to the least significant bit (LSB). The LSB of an adder/subtractor must be placed in the first LE of the LAB, where the LAB-wide addnsub signal automatically sets the carry-in to 1. The Quartus II Compiler automatically places and uses the adder/subtractor feature when using adder/subtractor parameterized functions.

## **LE Operating Modes**

The Cyclone LE can operate in one of the following modes:

- Normal mode
- Dynamic arithmetic mode

Each mode uses LE resources differently. In each mode, eight available inputs to the LE—the four data inputs from the LAB local interconnect, carry-in0 and carry-in1 from the previous LE, the LAB carry-in from the previous carry-chain LAB, and the register chain connection—are directed to different destinations to implement the desired logic function. LAB-wide signals provide clock, asynchronous clear, asynchronous

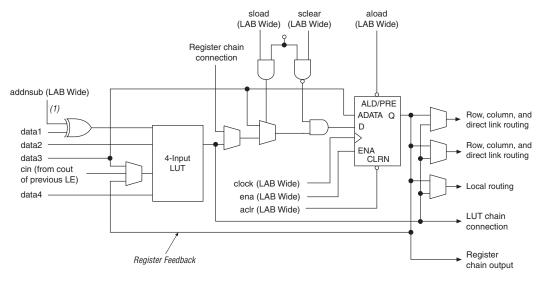
preset/load, synchronous clear, synchronous load, and clock enable control for the register. These LAB-wide signals are available in all LE modes. The addnsub control signal is allowed in arithmetic mode.

The Quartus II software, in conjunction with parameterized functions such as library of parameterized modules (LPM) functions, automatically chooses the appropriate mode for common functions such as counters, adders, subtractors, and arithmetic functions. If required, you can also create special-purpose functions that specify which LE operating mode to use for optimal performance.

#### Normal Mode

The normal mode is suitable for general logic applications and combinatorial functions. In normal mode, four data inputs from the LAB local interconnect are inputs to a four-input LUT (see Figure 2–6). The Quartus II Compiler automatically selects the carry-in or the data3 signal as one of the inputs to the LUT. Each LE can use LUT chain connections to drive its combinatorial output directly to the next LE in the LAB. Asynchronous load data for the register comes from the data3 input of the LE. LEs in normal mode support packed registers.

Figure 2-6. LE in Normal Mode



*Note to Figure 2–6:* 

This signal is only allowed in normal mode if the LE is at the end of an adder/subtractor chain.

#### Dynamic Arithmetic Mode

The dynamic arithmetic mode is ideal for implementing adders, counters, accumulators, wide parity functions, and comparators. An LE in dynamic arithmetic mode uses four 2-input LUTs configurable as a dynamic adder/subtractor. The first two 2-input LUTs compute two summations based on a possible carry-in of 1 or 0; the other two LUTs generate carry outputs for the two chains of the carry select circuitry. As shown in Figure 2–7, the LAB carry-in signal selects either the carry-in0 or carry-in1 chain. The selected chain's logic level in turn determines which parallel sum is generated as a combinatorial or registered output. For example, when implementing an adder, the sum output is the selection of two possible calculated sums:

```
data1 + data2 + carry-in0
or
data1 + data2 + carry-in1
```

The other two LUTs use the data1 and data2 signals to generate two possible carry-out signals—one for a carry of 1 and the other for a carry of 0. The carry-in0 signal acts as the carry select for the carry-out0 output and carry-in1 acts as the carry select for the carry-out1 output. LEs in arithmetic mode can drive out registered and unregistered versions of the LUT output.

The dynamic arithmetic mode also offers clock enable, counter enable, synchronous up/down control, synchronous clear, synchronous load, and dynamic adder/subtractor options. The LAB local interconnect data inputs generate the counter enable and synchronous up/down control signals. The synchronous clear and synchronous load options are LAB-wide signals that affect all registers in the LAB. The Quartus II software automatically places any registers that are not used by the counter into other LABs. The addnsub LAB-wide signal controls whether the LE acts as an adder or subtractor.

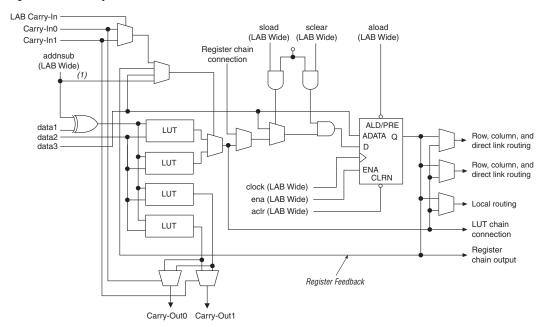


Figure 2-7. LE in Dynamic Arithmetic Mode

Note to Figure 2-7:

(1) The addnsub signal is tied to the carry input for the first LE of a carry chain only.

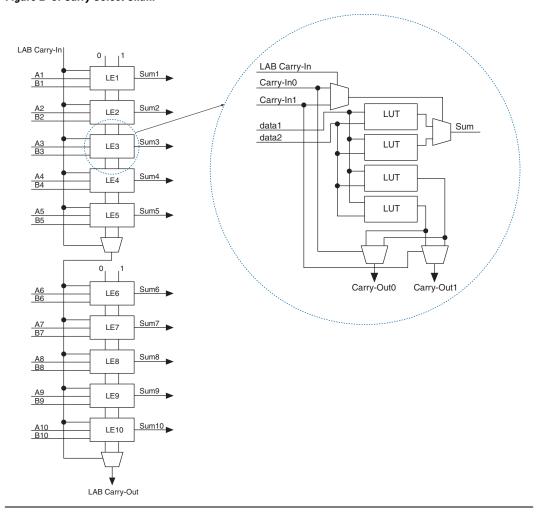
### Carry-Select Chain

The carry-select chain provides a very fast carry-select function between LEs in dynamic arithmetic mode. The carry-select chain uses the redundant carry calculation to increase the speed of carry functions. The LE is configured to calculate outputs for a possible carry-in of 0 and carry-in of 1 in parallel. The carry-in0 and carry-in1 signals from a lower-order bit feed forward into the higher-order bit via the parallel carry chain and feed into both the LUT and the next portion of the carry chain. Carry-select chains can begin in any LE within a LAB.

The speed advantage of the carry-select chain is in the parallel pre-computation of carry chains. Since the LAB carry-in selects the precomputed carry chain, not every LE is in the critical path. Only the propagation delays between LAB carry-in generation (LE 5 and LE 10) are now part of the critical path. This feature allows the Cyclone architecture to implement high-speed counters, adders, multipliers, parity functions, and comparators of arbitrary width.

Figure 2–8 shows the carry-select circuitry in a LAB for a 10-bit full adder. One portion of the LUT generates the sum of two bits using the input signals and the appropriate carry-in bit; the sum is routed to the output of the LE. The register can be bypassed for simple adders or used for accumulator functions. Another portion of the LUT generates carry-out bits. A LAB-wide carry-in bit selects which chain is used for the addition of given inputs. The carry-in signal for each chain, carry-in0 or carry-in1, selects the carry-out to carry forward to the carry-in signal of the next-higher-order bit. The final carry-out signal is routed to an LE, where it is fed to local, row, or column interconnects.

Figure 2-8. Carry Select Chain



The Quartus II Compiler automatically creates carry chain logic during design processing, or you can create it manually during design entry. Parameterized functions such as LPM functions automatically take advantage of carry chains for the appropriate functions.

The Quartus II Compiler creates carry chains longer than 10 LEs by linking LABs together automatically. For enhanced fitting, a long carry chain runs vertically allowing fast horizontal connections to M4K memory blocks. A carry chain can continue as far as a full column.

#### Clear and Preset Logic Control

LAB-wide signals control the logic for the register's clear and preset signals. The LE directly supports an asynchronous clear and preset function. The register preset is achieved through the asynchronous load of a logic high. The direct asynchronous preset does not require a NOT-gate push-back technique. Cyclone devices support simultaneous preset/ asynchronous load and clear signals. An asynchronous clear signal takes precedence if both signals are asserted simultaneously. Each LAB supports up to two clears and one preset signal.

In addition to the clear and preset ports, Cyclone devices provide a chip-wide reset pin (DEV\_CLRn) that resets all registers in the device. An option set before compilation in the Quartus II software controls this pin. This chip-wide reset overrides all other control signals.

## MultiTrack Interconnect

In the Cyclone architecture, connections between LEs, M4K memory blocks, and device I/O pins are provided by the MultiTrack interconnect structure with DirectDrive  $^{\rm TM}$  technology. The MultiTrack interconnect consists of continuous, performance-optimized routing lines of different speeds used for inter- and intra-design block connectivity. The Quartus II Compiler automatically places critical design paths on faster interconnects to improve design performance.

DirectDrive technology is a deterministic routing technology that ensures identical routing resource usage for any function regardless of placement within the device. The MultiTrack interconnect and DirectDrive technology simplify the integration stage of block-based designing by eliminating the re-optimization cycles that typically follow design changes and additions.

The MultiTrack interconnect consists of row and column interconnects that span fixed distances. A routing structure with fixed length resources for all devices allows predictable and repeatable performance when

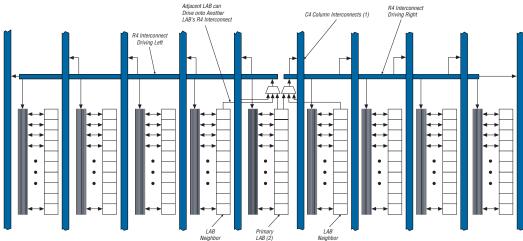
migrating through different device densities. Dedicated row interconnects route signals to and from LABs, PLLs, and M4K memory blocks within the same row. These row resources include:

- Direct link interconnects between LABs and adjacent blocks
- R4 interconnects traversing four blocks to the right or left

The direct link interconnect allows a LAB or M4K memory block to drive into the local interconnect of its left and right neighbors. Only one side of a PLL block interfaces with direct link and row interconnects. The direct link interconnect provides fast communication between adjacent LABs and/or blocks without using row interconnect resources.

The R4 interconnects span four LABs, or two LABs and one M4K RAM block. These resources are used for fast row connections in a four-LAB region. Every LAB has its own set of R4 interconnects to drive either left or right. Figure 2–9 shows R4 interconnect connections from a LAB. R4 interconnects can drive and be driven by M4K memory blocks, PLLs, and row IOEs. For LAB interfacing, a primary LAB or LAB neighbor can drive a given R4 interconnect. For R4 interconnects that drive to the right, the primary LAB and right neighbor can drive on to the interconnect. For R4 interconnects that drive to the left, the primary LAB and its left neighbor can drive on to the interconnect. R4 interconnects can drive other R4 interconnects to extend the range of LABs they can drive. R4 interconnects can also drive C4 interconnects for connections from one row to another.





#### Notes to Figure 2-9:

- C4 interconnects can drive R4 interconnects.
- (2) This pattern is repeated for every LAB in the LAB row.

The column interconnect operates similarly to the row interconnect. Each column of LABs is served by a dedicated column interconnect, which vertically routes signals to and from LABs, M4K memory blocks, and row and column IOEs. These column resources include:

- LUT chain interconnects within a LAB
- Register chain interconnects within a LAB
- C4 interconnects traversing a distance of four blocks in an up and down direction

Cyclone devices include an enhanced interconnect structure within LABs for routing LE output to LE input connections faster using LUT chain connections and register chain connections. The LUT chain connection allows the combinatorial output of an LE to directly drive the fast input of the LE right below it, bypassing the local interconnect. These resources can be used as a high-speed connection for wide fan-in functions from LE 1 to LE 10 in the same LAB. The register chain connection allows the register output of one LE to connect directly to the register input of the next LE in the LAB for fast shift registers. The Quartus II Compiler automatically takes advantage of these resources to improve utilization and performance. Figure 2–10 shows the LUT chain and register chain interconnects.

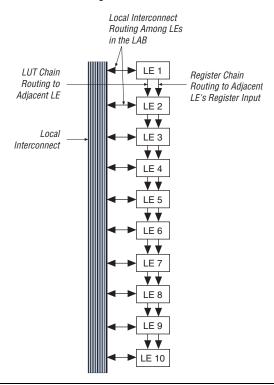


Figure 2–10. LUT Chain and Register Chain Interconnects

The C4 interconnects span four LABs or M4K blocks up or down from a source LAB. Every LAB has its own set of C4 interconnects to drive either up or down. Figure 2–11 shows the C4 interconnect connections from a LAB in a column. The C4 interconnects can drive and be driven by all types of architecture blocks, including PLLs, M4K memory blocks, and column and row IOEs. For LAB interconnection, a primary LAB or its LAB neighbor can drive a given C4 interconnect. C4 interconnects can drive each other to extend their range as well as drive row interconnects for column-to-column connections.

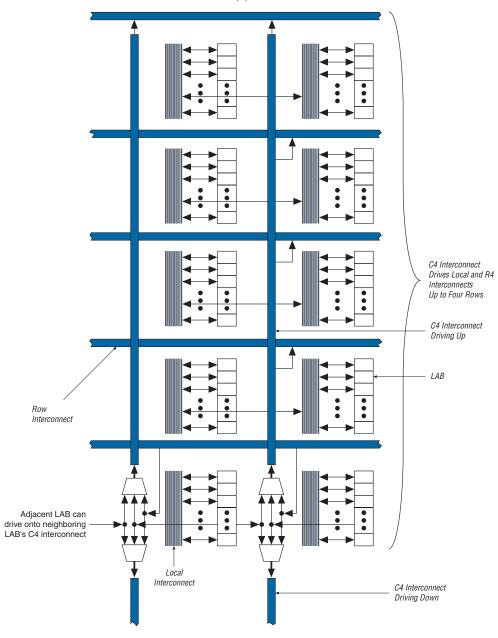


Figure 2–11. C4 Interconnect Connections Note (1)

Note to Figure 2–11:

(1) Each C4 interconnect can drive either up or down four rows.

All embedded blocks communicate with the logic array similar to LAB-to-LAB interfaces. Each block (i.e., M4K memory or PLL) connects to row and column interconnects and has local interconnect regions driven by row and column interconnects. These blocks also have direct link interconnects for fast connections to and from a neighboring LAB.

Table 2–2 shows the Cyclone device's routing scheme.

Table 2–2. Cyclone	Device I	evice Routing Scheme									
		Destination									
Source	LUT Chain	Register Chain	Local Interconnect	Direct Link Interconnect	R4 Interconnect	C4 Interconnect	31	M4K RAM Block	PLL	Column 10E	Row 10E
LUT Chain	_	_	_	_	_	_	<b>✓</b>	_	_	_	_
Register Chain	_	_	_	_	_	_	<b>✓</b>	_	_	_	_
Local Interconnect	_	_	_	_	_	_	<b>✓</b>	<b>✓</b>	<b>✓</b>	<b>✓</b>	<b>✓</b>
Direct Link Interconnect	_	_	<b>✓</b>	_	_	_	_	_	_	_	_
R4 Interconnect	_	_	<b>✓</b>	_	<b>✓</b>	<b>✓</b>	_	_	_	_	_
C4 Interconnect	_	_	<b>✓</b>	_	<b>✓</b>	<b>✓</b>	_	_	_	_	_
LE	<b>✓</b>	<b>✓</b>	<b>✓</b>	<b>✓</b>	<b>✓</b>	<b>✓</b>	_	_	_	_	_
M4K RAM Block	_	_	<b>✓</b>	<b>✓</b>	<b>✓</b>	<b>✓</b>	_	_	_	_	_
PLL	_	_	_	<b>✓</b>	<b>✓</b>	<b>✓</b>	_	_	_	_	_
Column IOE	_	_	_	_	_	<b>✓</b>	_	_	_	_	_
Row IOE	_	_	_	<b>✓</b>	<b>✓</b>	<b>✓</b>	_	_	_	_	_

# Embedded Memory

The Cyclone embedded memory consists of columns of M4K memory blocks. EP1C3 and EP1C6 devices have one column of M4K blocks, while EP1C12 and EP1C20 devices have two columns (refer to Table 1–1 on page 1–1 for total RAM bits per density). Each M4K block can implement various types of memory with or without parity, including true dual-port, simple dual-port, and single-port RAM, ROM, and FIFO buffers. The M4K blocks support the following features:

- 4,608 RAM bits
- 250 MHz performance
- True dual-port memory
- Simple dual-port memory
- Single-port memory
- Byte enable
- Parity bits
- Shift register
- FIFO buffer
- ROM
- Mixed clock mode

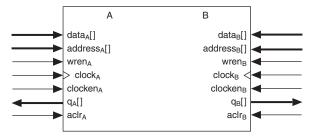


Violating the setup or hold time on the address registers could corrupt the memory contents. This applies to both read and write operations.

# **Memory Modes**

The M4K memory blocks include input registers that synchronize writes and output registers to pipeline designs and improve system performance. M4K blocks offer a true dual-port mode to support any combination of two-port operations: two reads, two writes, or one read and one write at two different clock frequencies. Figure 2–12 shows true dual-port memory.

Figure 2–12. True Dual-Port Memory Configuration



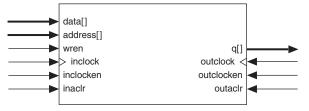
In addition to true dual-port memory, the M4K memory blocks support simple dual-port and single-port RAM. Simple dual-port memory supports a simultaneous read and write. Single-port memory supports non-simultaneous reads and writes. Figure 2–13 shows these different M4K RAM memory port configurations.

Figure 2–13. Simple Dual-Port and Single-Port Memory Configurations

#### Simple Dual-Port Memory



#### Single-Port Memory (1)



#### *Note to Figure 2–13:*

 Two single-port memory blocks can be implemented in a single M4K block as long as each of the two independent block sizes is equal to or less than half of the M4K block size.

The memory blocks also enable mixed-width data ports for reading and writing to the RAM ports in dual-port RAM configuration. For example, the memory block can be written in  $\times 1$  mode at port A and read out in  $\times 16$  mode from port B.

The Cyclone memory architecture can implement fully synchronous RAM by registering both the input and output signals to the M4K RAM block. All M4K memory block inputs are registered, providing synchronous write cycles. In synchronous operation, the memory block generates its own self-timed strobe write enable (wren) signal derived from a global clock. In contrast, a circuit using asynchronous RAM must generate the RAM wren signal while ensuring its data and address signals meet setup and hold time specifications relative to the wren

signal. The output registers can be bypassed. Pseudo-asynchronous reading is possible in the simple dual-port mode of M4K blocks by clocking the read enable and read address registers on the negative clock edge and bypassing the output registers.

When configured as RAM or ROM, you can use an initialization file to pre-load the memory contents.

Two single-port memory blocks can be implemented in a single M4K block as long as each of the two independent block sizes is equal to or less than half of the M4K block size.

The Quartus II software automatically implements larger memory by combining multiple M4K memory blocks. For example, two 256×16-bit RAM blocks can be combined to form a 256×32-bit RAM block. Memory performance does not degrade for memory blocks using the maximum number of words allowed. Logical memory blocks using less than the maximum number of words use physical blocks in parallel, eliminating any external control logic that would increase delays. To create a larger high-speed memory block, the Quartus II software automatically combines memory blocks with LE control logic.

## **Parity Bit Support**

The M4K blocks support a parity bit for each byte. The parity bit, along with internal LE logic, can implement parity checking for error detection to ensure data integrity. You can also use parity-size data words to store user-specified control bits. Byte enables are also available for data input masking during write operations.

# **Shift Register Support**

You can configure M4K memory blocks to implement shift registers for DSP applications such as pseudo-random number generators, multi-channel filtering, auto-correlation, and cross-correlation functions. These and other DSP applications require local data storage, traditionally implemented with standard flip-flops, which can quickly consume many logic cells and routing resources for large shift registers. A more efficient alternative is to use embedded memory as a shift register block, which saves logic cell and routing resources and provides a more efficient implementation with the dedicated circuitry.

The size of a  $w \times m \times n$  shift register is determined by the input data width (w), the length of the taps (m), and the number of taps (n). The size of a  $w \times m \times n$  shift register must be less than or equal to the maximum number of memory bits in the M4K block (4,608 bits). The total number of shift

register outputs (number of taps  $n \times \text{width } w$ ) must be less than the maximum data width of the M4K RAM block (×36). To create larger shift registers, multiple memory blocks are cascaded together.

Data is written into each address location at the falling edge of the clock and read from the address at the rising edge of the clock. The shift register mode logic automatically controls the positive and negative edge clocking to shift the data in one clock cycle. Figure 2–14 shows the M4K memory block in the shift register mode.

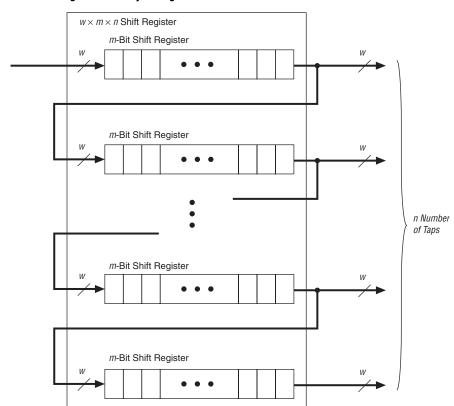


Figure 2-14. Shift Register Memory Configuration

# **Memory Configuration Sizes**

The memory address depths and output widths can be configured as  $4,096 \times 1, 2,048 \times 2, 1,024 \times 4,512 \times 8$  (or  $512 \times 9$  bits),  $256 \times 16$  (or  $256 \times 18$  bits), and  $128 \times 32$  (or  $128 \times 36$  bits). The  $128 \times 32$ - or 36-bit configuration

is not available in the true dual-port mode. Mixed-width configurations are also possible, allowing different read and write widths. Tables 2–3 and 2–4 summarize the possible M4K RAM block configurations.

Table 2–3. M4K RAM Block Configurations (Simple Dual-Port)									
Dood Dow		Write Port							
Read Port	4K × 1	2K × 2	1K × 4	512 × 8	256 × 16	128 × 32	512 × 9	256 × 18	128 × 36
4K × 1	<b>✓</b>	<b>✓</b>	<b>✓</b>	~	<b>✓</b>	<b>✓</b>	_	_	_
2K × 2	<b>✓</b>	<b>✓</b>	<b>✓</b>	<b>✓</b>	<b>✓</b>	<b>✓</b>	_	_	_
1K × 4	<b>✓</b>	<b>✓</b>	<b>✓</b>	~	<b>✓</b>	<b>✓</b>	_	_	_
512 × 8	<b>✓</b>	<b>✓</b>	<b>✓</b>	~	<b>✓</b>	<b>✓</b>	_	_	_
256 × 16	<b>✓</b>	<b>✓</b>	<b>✓</b>	~	<b>✓</b>	<b>✓</b>	_	_	_
128 × 32	<b>✓</b>	<b>✓</b>	<b>✓</b>	~	<b>✓</b>	<b>✓</b>	_	_	_
512 × 9	_	_	_	_	_	_	<b>✓</b>	~	<b>✓</b>
256 × 18	_	_	_	_	_	_	<b>✓</b>	<b>✓</b>	<b>✓</b>
128 × 36	_	_	_	_	_	_	<b>✓</b>	<b>✓</b>	<b>✓</b>

Table 2–4. M4K RAM Block Configurations (True Dual-Port)							
Dout A				Port B			
Port A	4K × 1	2K × 2	1K × 4	512 × 8	256 × 16	512 × 9	256 × 18
4K × 1	✓	<b>✓</b>	<b>✓</b>	<b>✓</b>	<b>✓</b>	_	_
2K × 2	✓	<b>✓</b>	<b>✓</b>	✓	<b>✓</b>	_	_
1K × 4	✓	<b>✓</b>	<b>✓</b>	✓	<b>✓</b>	_	_
512 × 8	✓	<b>✓</b>	<b>✓</b>	✓	<b>✓</b>	_	_
256 × 16	✓	<b>✓</b>	<b>✓</b>	✓	<b>✓</b>	_	_
512 × 9	_	_	_	_	_	<b>✓</b>	<b>✓</b>
256 × 18	_	_	_	_	_	<b>✓</b>	<b>✓</b>

When the M4K RAM block is configured as a shift register block, you can create a shift register up to 4,608 bits  $(w \times m \times n)$ .

## **Byte Enables**

M4K blocks support byte writes when the write port has a data width of 16, 18, 32, or 36 bits. The byte enables allow the input data to be masked so the device can write to specific bytes. The unwritten bytes retain the previous written value. Table 2–5 summarizes the byte selection.

Table 2–5. Byte Enable for M4K BlocksNotes (1), (2)						
byteena[30]	datain ×18	datain ×36				
[0] = 1	[80]	[80]				
[1] = 1	[179]	[179]				
[2] = 1	_	[2618]				
[3] = 1	_	[3527]				

Notes to Table 2-5:

- (1) Any combination of byte enables is possible.
- (2) Byte enables can be used in the same manner with 8-bit words, i.e., in ×16 and ×32 modes.

## **Control Signals and M4K Interface**

The M4K blocks allow for different clocks on their inputs and outputs. Either of the two clocks feeding the block can clock M4K block registers (renwe, address, byte enable, datain, and output registers). Only the output register can be bypassed. The six labclk signals or local interconnects can drive the control signals for the A and B ports of the M4K block. LEs can also control the clock\_a, clock\_b, renwe\_a, renwe\_b, clr\_a, clr\_b, clocken\_a, and clocken\_b signals, as shown in Figure 2–15.

The R4, C4, and direct link interconnects from adjacent LABs drive the M4K block local interconnect. The M4K blocks can communicate with LABs on either the left or right side through these row resources or with LAB columns on either the right or left with the column resources. Up to 10 direct link input connections to the M4K block are possible from the left adjacent LABs and another 10 possible from the right adjacent LAB. M4K block outputs can also connect to left and right LABs through 10 direct link interconnects each. Figure 2–16 shows the M4K block to logic array interface.

Figure 2-15. M4K RAM Block Control Signals

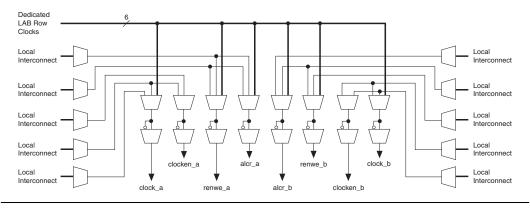
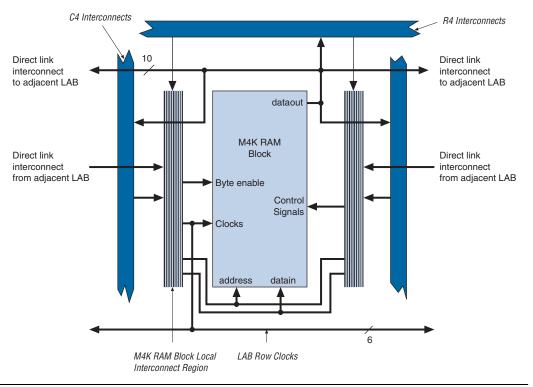


Figure 2-16. M4K RAM Block LAB Row Interface



# **Independent Clock Mode**

The M4K memory blocks implement independent clock mode for true dual-port memory. In this mode, a separate clock is available for each port (ports A and B). Clock A controls all registers on the port A side, while clock B controls all registers on the port B side. Each port, A and B, also supports independent clock enables and asynchronous clear signals for port A and B registers. Figure 2–17 shows an M4K memory block in independent clock mode.

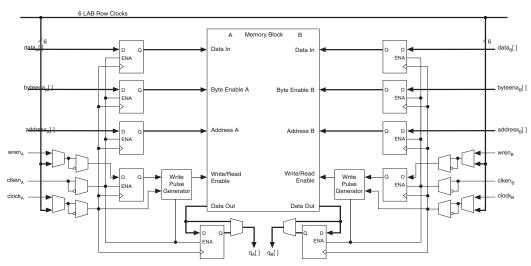


Figure 2–17. Independent Clock Mode Notes (1), (2)

Notes to Figure 2–17:

- (1) All registers shown have asynchronous clear ports.
- (2) Violating the setup or hold time on the address registers could corrupt the memory contents. This applies to both read and write operations.

# Input/Output Clock Mode

Input/output clock mode can be implemented for both the true and simple dual-port memory modes. On each of the two ports, A or B, one clock controls all registers for inputs into the memory block: data input, wren, and address. The other clock controls the block's data output registers. Each memory block port, A or B, also supports independent clock enables and asynchronous clear signals for input and output registers. Figures 2–18 and 2–19 show the memory block in input/output clock mode.

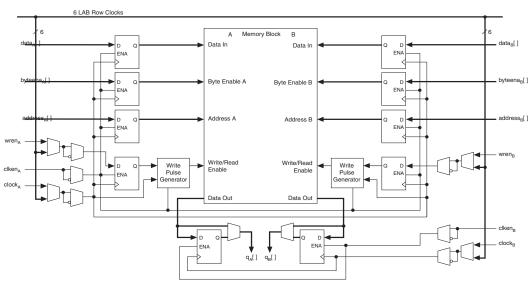


Figure 2–18. Input/Output Clock Mode in True Dual-Port Mode Notes (1), (2)

#### Notes to Figure 2–18:

- (1) All registers shown have asynchronous clear ports.
- (2) Violating the setup or hold time on the address registers could corrupt the memory contents. This applies to both read and write operations.

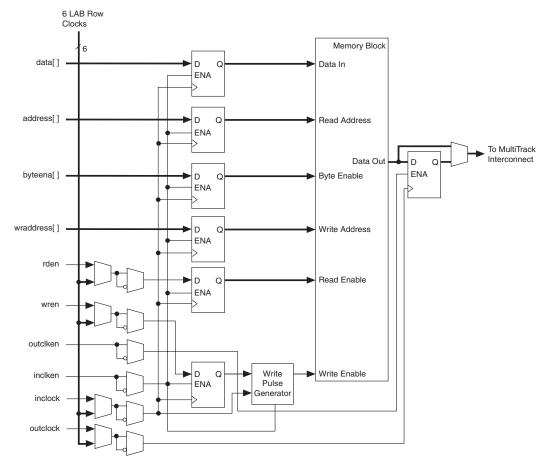


Figure 2–19. Input/Output Clock Mode in Simple Dual-Port Mode Notes (1), (2)

#### *Notes to Figure 2–19:*

- (1) All registers shown except the rden register have asynchronous clear ports.
- (2) Violating the setup or hold time on the address registers could corrupt the memory contents. This applies to both read and write operations.

### Read/Write Clock Mode

The M4K memory blocks implement read/write clock mode for simple dual-port memory. You can use up to two clocks in this mode. The write clock controls the block's data inputs, wraddress, and wren. The read clock controls the data output, rdaddress, and rden. The memory blocks support independent clock enables for each clock and asynchronous clear signals for the read- and write-side registers. Figure 2–20 shows a memory block in read/write clock mode.

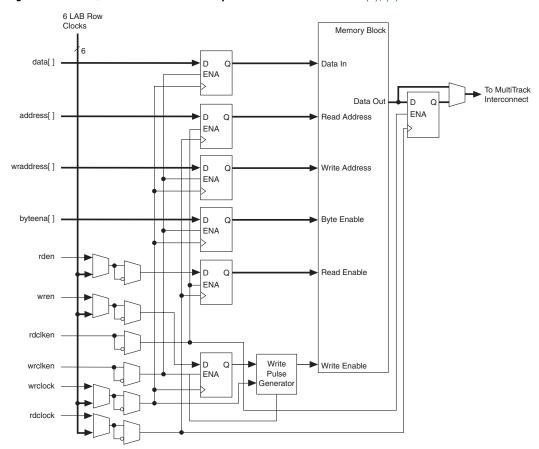


Figure 2–20. Read/Write Clock Mode in Simple Dual-Port Mode Notes (1), (2)

#### *Notes to Figure 2–20:*

- (1) All registers shown except the rden register have asynchronous clear ports.
- (2) Violating the setup or hold time on the address registers could corrupt the memory contents. This applies to both read and write operations.

## **Single-Port Mode**

The M4K memory blocks also support single-port mode, used when simultaneous reads and writes are not required. See Figure 2–21. A single M4K memory block can support up to two single-port mode RAM blocks if each RAM block is less than or equal to 2K bits in size.

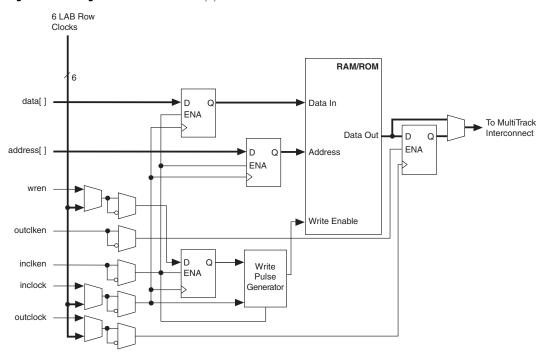


Figure 2–21. Single-Port Mode Note (1)

Note to Figure 2–21:

(1) Violating the setup or hold time on the address registers could corrupt the memory contents. This applies to both read and write operations.

# Global Clock Network and Phase-Locked Loops

Cyclone devices provide a global clock network and up to two PLLs for a complete clock management solution.

### **Global Clock Network**

There are four dedicated clock pins (CLK[3..0], two pins on the left side and two pins on the right side) that drive the global clock network, as shown in Figure 2–22. PLL outputs, logic array, and dual-purpose clock (DPCLK[7..0]) pins can also drive the global clock network.

The eight global clock lines in the global clock network drive throughout the entire device. The global clock network can provide clocks for all resources within the device—IOEs, LEs, and memory blocks. The global clock lines can also be used for control signals, such as clock enables and synchronous or asynchronous clears fed from the external pin, or DQS signals for DDR SDRAM or FCRAM interfaces. Internal logic can also drive the global clock network for internally generated global clocks and asynchronous clears, clock enables, or other control signals with large fanout. Figure 2–22 shows the various sources that drive the global clock network.

DPCLK2 DPCLK3 Cyclone Device Global Clock Network 8 DPCLK1 \_ □ DPCLK4 From logic From logic array array CLK0 [ □ CLK2 PLL2 PLL1 CLK1 (3) □ CLK3 (3) (2) 2 DPCLK0 [ □ DPCLK5 DPCLK7 DPCLK6

Figure 2–22. Global Clock Generation Note (1)

#### *Notes to Figure 2–22:*

- (1) The EP1C3 device in the 100-pin TQFP package has five DPCLK pins (DPCLK2, DPCLK3, DPCLK4, DPCLK6, and DPCLK7).
- (2) EP1C3 devices only contain one PLL (PLL 1).
- (3) The EP1C3 device in the 100-pin TQFP package does not have dedicated clock pins CLK1 and CLK3.

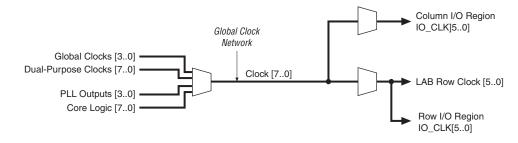
## **Dual-Purpose Clock Pins**

Each Cyclone device except the EP1C3 device has eight dual-purpose clock pins, DPCLK[7..0] (two on each I/O bank). EP1C3 devices have five DPCLK pins in the 100-pin TQFP package. These dual-purpose pins can connect to the global clock network (see Figure 2–22) for high-fanout control signals such as clocks, asynchronous clears, presets, and clock enables, or protocol control signals such as TRDY and IRDY for PCI, or DQS signals for external memory interfaces.

#### **Combined Resources**

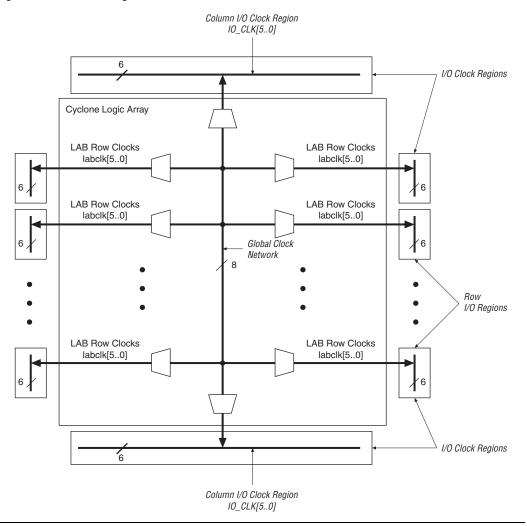
Each Cyclone device contains eight distinct dedicated clocking resources. The device uses multiplexers with these clocks to form six-bit buses to drive LAB row clocks, column IOE clocks, or row IOE clocks. See Figure 2–23. Another multiplexer at the LAB level selects two of the six LAB row clocks to feed the LE registers within the LAB.

Figure 2-23. Global Clock Network Multiplexers



IOE clocks have row and column block regions. Six of the eight global clock resources feed to these row and column regions. Figure 2–24 shows the I/O clock regions.

Figure 2-24. I/O Clock Regions



### **PLLs**

Cyclone PLLs provide general-purpose clocking with clock multiplication and phase shifting as well as outputs for differential I/O support. Cyclone devices contain two PLLs, except for the EP1C3 device, which contains one PLL.

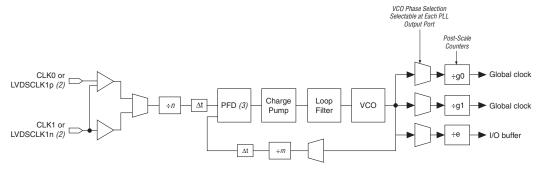
Table 2–6 shows the PLL features in Cyclone devices. Figure 2–25 shows a Cyclone PLL.

Table 2–6. Cyclone PLL Features					
Feature	PLL Support				
Clock multiplication and division	$m/(n \times \text{post-scale counter})$ (1)				
Phase shift	Down to 125-ps increments (2), (3)				
Programmable duty cycle	Yes				
Number of internal clock outputs	2				
Number of external clock outputs	One differential or one single-ended (4)				

#### Notes to Table 2-6:

- (1) The *m* counter ranges from 2 to 32. The *n* counter and the post-scale counters range from 1 to 32.
- (2) The smallest phase shift is determined by the voltage-controlled oscillator (VCO) period divided by 8.
- (3) For degree increments, Cyclone devices can shift all output frequencies in increments of 45°. Smaller degree increments are possible depending on the frequency and divide parameters.
- (4) The EP1C3 device in the 100-pin TQFP package does not support external clock output. The EP1C6 device in the 144-pin TQFP package does not support external clock output from PLL2.

Figure 2–25. Cyclone PLL Note (1)

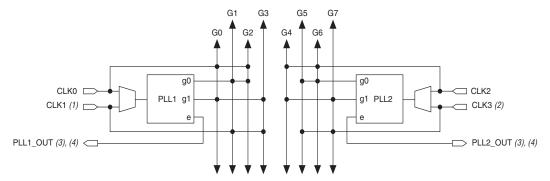


#### Notes to Figure 2–25:

- (1) The EP1C3 device in the 100-pin TQFP package does not support external outputs or LVDS inputs. The EP1C6 device in the 144-pin TQFP package does not support external output from PLL2.
- (2) LVDS input is supported via the secondary function of the dedicated clock pins. For PLL 1, the CLK0 pin's secondary function is LVDSCLK1p and the CLK1 pin's secondary function is LVDSCLK1n. For PLL 2, the CLK2 pin's secondary function is LVDSCLK2p and the CLK3 pin's secondary function is LVDSCLK2n.
- (3) PFD: phase frequency detector.

Figure 2–26 shows the PLL global clock connections.

Figure 2-26. Cyclone PLL Global Clock Connections



#### *Notes to Figure 2–26:*

- (1) PLL 1 supports one single-ended or LVDS input via pins CLK0 and CLK1.
- (2) PLL2 supports one single-ended or LVDS input via pins CLK2 and CLK3.
- (3) PLL1\_OUT and PLL2\_OUT support single-ended or LVDS output. If external output is not required, these pins are available as regular user I/O pins.
- (4) The EP1C3 device in the 100-pin TQFP package does not support external clock output. The EP1C6 device in the 144-pin TQFP package does not support external clock output from PLL2.

Table 2–7 shows the global clock network sources available in Cyclone devices.

Sou	rce	GCLKO	GCLK1	GCLK2	GCLK3	GCLK4	GCLK5	GCLK6	GCLK7
PLL Counter	PLL1 G0	_	<b>✓</b>	<b>✓</b>	_	_	_	_	_
Output	PLL1 G1	<b>✓</b>	_	_	<b>✓</b>	_	_	_	_
	PLL2 G0 (1)	_	_	_	_	_	<b>✓</b>	<b>✓</b>	_
	PLL2 G1 (1)	_	_	_	_	<b>✓</b>	_	_	<b>✓</b>
Dedicated	CLK0	<b>✓</b>	_	<b>✓</b>	_	_	_	_	_
Clock Input Pins	CLK1 (2)		<b>✓</b>	_	~	_	_	_	_
	CLK2		_	_	_	<b>✓</b>	_	<b>✓</b>	_
	CLK3 (2)	_	_	_	_	_	<b>✓</b>	_	<b>✓</b>

Table 2-7. Gl	Table 2–7. Global Clock Network Sources (Part 2 of 2)								
Sou	rce	GCLKO	GCLK1	GCLK2	GCLK3	GCLK4	GCLK5	GCLK6	GCLK7
Dual-Purpose	DPCLK0 (3)	_	_	_	<b>✓</b>	_	_	_	_
Clock Pins	DPCLK1 (3)	_	_	<b>✓</b>	_	_	_	_	_
	DPCLK2	~	_	_	_	_	_	_	_
	DPCLK3	_	_	_	_	<b>✓</b>	_	_	_
	DPCLK4	_	_	_	_	_		<b>✓</b>	_
	DPCLK5 (3)	_	_	_	_	_	_	_	<b>✓</b>
	DPCLK6	_	_	_	_	_	<b>✓</b>	_	_
	DPCLK7	_	<b>✓</b>	_	_	_	_	_	_

Notes to Table 2-7:

- (1) EP1C3 devices only have one PLL (PLL 1).
- (2) EP1C3 devices in the 100-pin TQFP package do not have dedicated clock pins CLK1 and CLK3.
- (3) EP1C3 devices in the 100-pin TQFP package do not have the DPCLK0, DPCLK1, or DPCLK5 pins.

## **Clock Multiplication and Division**

Cyclone PLLs provide clock synthesis for PLL output ports using  $m/(n \times post$  scale counter) scaling factors. The input clock is divided by a pre-scale divider, n, and is then multiplied by the m feedback factor. The control loop drives the VCO to match  $f_{\rm IN} \times (m/n)$ . Each output port has a unique post-scale counter to divide down the high-frequency VCO. For multiple PLL outputs with different frequencies, the VCO is set to the least-common multiple of the output frequencies that meets its frequency specifications. Then, the post-scale dividers scale down the output frequency for each output port. For example, if the output frequencies required from one PLL are 33 and 66 MHz, the VCO is set to 330 MHz (the least-common multiple in the VCO's range).

Each PLL has one pre-scale divider, n, that can range in value from 1 to 32. Each PLL also has one multiply divider, m, that can range in value from 2 to 32. Global clock outputs have two post scale G dividers for global clock outputs, and external clock outputs have an E divider for external clock output, both ranging from 1 to 32. The Quartus II software automatically chooses the appropriate scaling factors according to the input frequency, multiplication, and division values entered.

## **External Clock Inputs**

Each PLL supports single-ended or differential inputs for source-synchronous receivers or for general-purpose use. The dedicated clock pins (CLK[3..0]) feed the PLL inputs. These dual-purpose pins can also act as LVDS input pins. See Figure 2–25.

Table 2-8 shows the I/O standards supported by PLL input and output pins.

Table 2–8. PLL I/O Standards		
I/O Standard	CLK Input	EXTCLK Output
3.3-V LVTTL/LVCMOS	✓	✓
2.5-V LVTTL/LVCMOS	✓	✓
1.8-V LVTTL/LVCMOS	✓	✓
1.5-V LVCMOS	✓	✓
3.3-V PCI	✓	✓
LVDS	✓	✓
SSTL-2 class I	✓	✓
SSTL-2 class II	✓	✓
SSTL-3 class I	✓	✓
SSTL-3 class II	✓	✓
Differential SSTL-2	_	✓

For more information on LVDS I/O support, refer to "LVDS I/O Pins" on page 2–54.

# **External Clock Outputs**

Each PLL supports one differential or one single-ended output for source-synchronous transmitters or for general-purpose external clocks. If the PLL does not use these PLL\_OUT pins, the pins are available for use as general-purpose I/O pins. The PLL\_OUT pins support all I/O standards shown in Table 2–8.

The external clock outputs do not have their own  $V_{CC}$  and ground voltage supplies. Therefore, to minimize jitter, do not place switching I/O pins next to these output pins. The EP1C3 device in the 100-pin TQFP package

does not have dedicated clock output pins. The EP1C6 device in the 144-pin TQFP package only supports dedicated clock outputs from PLL 1.

#### Clock Feedback

Cyclone PLLs have three modes for multiplication and/or phase shifting:

- Zero delay buffer mode—The external clock output pin is phasealigned with the clock input pin for zero delay.
- Normal mode—If the design uses an internal PLL clock output, the normal mode compensates for the internal clock delay from the input clock pin to the IOE registers. The external clock output pin is phase shifted with respect to the clock input pin if connected in this mode. You defines which internal clock output from the PLL should be phase-aligned to compensate for internal clock delay.
- No compensation mode—In this mode, the PLL will not compensate for any clock networks.

## **Phase Shifting**

Cyclone PLLs have an advanced clock shift capability that enables programmable phase shifts. You can enter a phase shift (in degrees or time units) for each PLL clock output port or for all outputs together in one shift. You can perform phase shifting in time units with a resolution range of 125 to 250 ps. The finest resolution equals one eighth of the VCO period. The VCO period is a function of the frequency input and the multiplication and division factors. Each clock output counter can choose a different phase of the VCO period from up to eight taps. You can use this clock output counter along with an initial setting on the post-scale counter to achieve a phase-shift range for the entire period of the output clock. The phase tap feedback to the m counter can shift all outputs to a single phase. The Quartus II software automatically sets the phase taps and counter settings according to the phase shift entered.

# **Lock Detect Signal**

The lock output indicates that there is a stable clock output signal in phase with the reference clock. Without any additional circuitry, the lock signal may toggle as the PLL begins tracking the reference clock. Therefore, you may need to gate the lock signal for use as a system-control signal. For correct operation of the lock circuit below  $-20\,\mathrm{C}$ ,  $f_{\mathrm{IN/N}}$  > 200 MHz.

## **Programmable Duty Cycle**

The programmable duty cycle allows PLLs to generate clock outputs with a variable duty cycle. This feature is supported on each PLL post-scale counter (g0, g1, e). The duty cycle setting is achieved by a low- and high-time count setting for the post-scale dividers. The Quartus II software uses the frequency input and the required multiply or divide rate to determine the duty cycle choices.

# **Control Signals**

There are three control signals for clearing and enabling PLLs and their outputs. You can use these signals to control PLL resynchronization and the ability to gate PLL output clocks for low-power applications.

The pllenable signal enables and disables PLLs. When the pllenable signal is low, the clock output ports are driven by ground and all the PLLs go out of lock. When the pllenable signal goes high again, the PLLs relock and resynchronize to the input clocks. An input pin or LE output can drive the pllenable signal.

The areset signals are reset/resynchronization inputs for each PLL. Cyclone devices can drive these input signals from input pins or from LEs. When areset is driven high, the PLL counters will reset, clearing the PLL output and placing the PLL out of lock. When driven low again, the PLL will resynchronize to its input as it relocks.

The pfdena signals control the phase frequency detector (PFD) output with a programmable gate. If you disable the PFD, the VCO will operate at its last set value of control voltage and frequency with some drift, and the system will continue running when the PLL goes out of lock or the input clock disables. By maintaining the last locked frequency, the system has time to store its current settings before shutting down. You can either use their own control signal or gated locked status signals to trigger the pfdena signal.



For more information about Cyclone PLLs, refer to *Using PLLs in Cyclone Devices* chapter in the *Cyclone Device Handbook*.

# I/O Structure

IOEs support many features, including:

- Differential and single-ended I/O standards
- 3.3-V, 64- and 32-bit, 66- and 33-MHz PCI compliance
- Joint Test Action Group (JTAG) boundary-scan test (BST) support
- Output drive strength control
- Weak pull-up resistors during configuration
- Slew-rate control
- Tri-state buffers
- Bus-hold circuitry
- Programmable pull-up resistors in user mode
- Programmable input and output delays
- Open-drain outputs
- DQ and DQS I/O pins

Cyclone device IOEs contain a bidirectional I/O buffer and three registers for complete embedded bidirectional single data rate transfer. Figure 2–27 shows the Cyclone IOE structure. The IOE contains one input register, one output register, and one output enable register. You can use the input registers for fast setup times and output registers for fast clock-to-output times. Additionally, you can use the output enable (OE) register for fast clock-to-output enable timing. The Quartus II software automatically duplicates a single OE register that controls multiple output or bidirectional pins. IOEs can be used as input, output, or bidirectional pins.

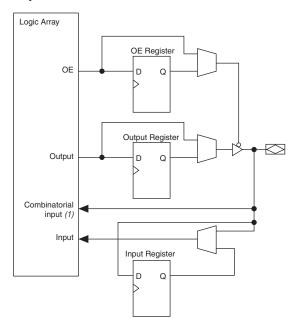


Figure 2-27. Cyclone IOE Structure

*Note to Figure 2–27:* 

 There are two paths available for combinatorial inputs to the logic array. Each path contains a unique programmable delay chain.

The IOEs are located in I/O blocks around the periphery of the Cyclone device. There are up to three IOEs per row I/O block and up to three IOEs per column I/O block (column I/O blocks span two columns). The row I/O blocks drive row, column, or direct link interconnects. The column I/O blocks drive column interconnects. Figure 2–28 shows how a row I/O block connects to the logic array. Figure 2–29 shows how a column I/O block connects to the logic array.

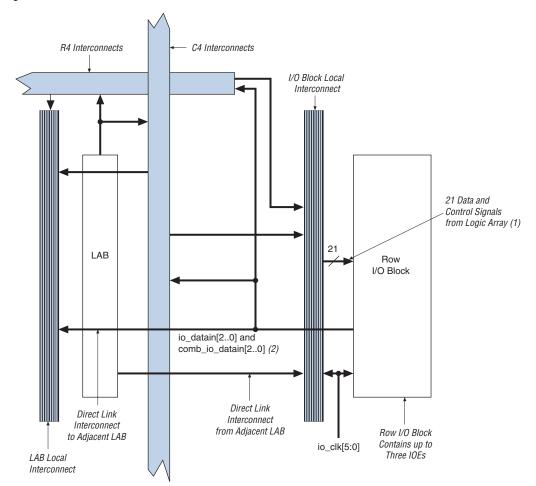


Figure 2-28. Row I/O Block Connection to the Interconnect

#### *Notes to Figure 2–28:*

- (1) The 21 data and control signals consist of three data out lines, io\_dataout[2..0], three output enables, io\_coe[2..0], three input clock enables, io\_cce\_in[2..0], three output clock enables, io\_cce\_out[2..0], three clocks, io\_cclk[2..0], three asynchronous clear signals, io\_caclr[2..0], and three synchronous clear signals, io\_csclr[2..0].
- (2) Each of the three IOEs in the row I/O block can have one io\_datain input (combinatorial or registered) and one comb\_io\_datain (combinatorial) input.

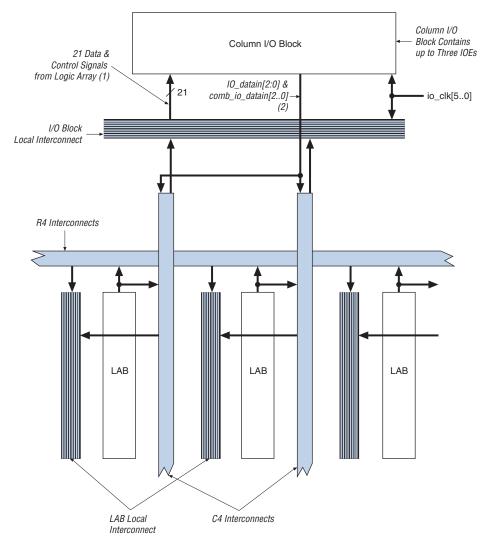


Figure 2-29. Column I/O Block Connection to the Interconnect

#### Notes to Figure 2-29:

- (1) The 21 data and control signals consist of three data out lines, io\_dataout[2..0], three output enables, io\_coe[2..0], three input clock enables, io\_cce\_in[2..0], three output clock enables, io\_cce\_out[2..0], three clocks, io\_cclk[2..0], three asynchronous clear signals, io\_caclr[2..0], and three synchronous clear signals, io csclr[2..0].
- (2) Each of the three IOEs in the column I/O block can have one io\_datain input (combinatorial or registered) and one comb io datain (combinatorial) input.

The pin's datain signals can drive the logic array. The logic array drives the control and data signals, providing a flexible routing resource. The row or column IOE clocks, io\_clk[5..0], provide a dedicated routing resource for low-skew, high-speed clocks. The global clock network generates the IOE clocks that feed the row or column I/O regions (see "Global Clock Network and Phase-Locked Loops" on page 2–29). Figure 2–30 illustrates the signal paths through the I/O block.

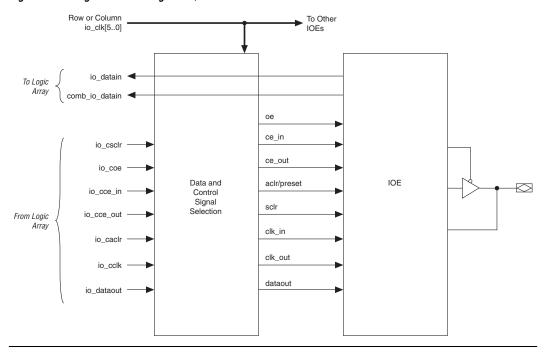


Figure 2-30. Signal Path through the I/O Block

Each IOE contains its own control signal selection for the following control signals: oe, ce\_in, ce\_out, aclr/preset, sclr/preset, clk\_in, and clk\_out. Figure 2–31 illustrates the control signal selection.

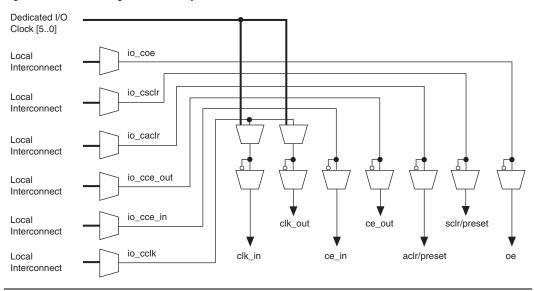


Figure 2-31. Control Signal Selection per IOE

In normal bidirectional operation, you can use the input register for input data requiring fast setup times. The input register can have its own clock input and clock enable separate from the OE and output registers. The output register can be used for data requiring fast clock-to-output performance. The OE register is available for fast clock-to-output enable timing. The OE and output register share the same clock source and the same clock enable source from the local interconnect in the associated LAB, dedicated I/O clocks, or the column and row interconnects. Figure 2–32 shows the IOE in bidirectional configuration.

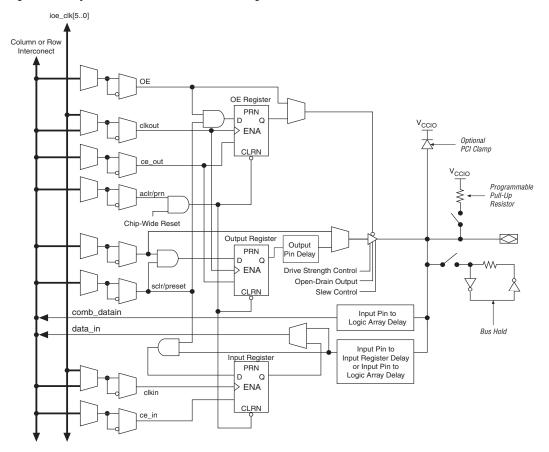


Figure 2-32. Cyclone IOE in Bidirectional I/O Configuration

The Cyclone device IOE includes programmable delays to ensure zero hold times, minimize setup times, or increase clock to output times.

A path in which a pin directly drives a register may require a programmable delay to ensure zero hold time, whereas a path in which a pin drives a register through combinatorial logic may not require the delay. Programmable delays decrease input-pin-to-logic-array and IOE input register delays. The Quartus II Compiler can program these delays

to automatically minimize setup time while providing a zero hold time. Programmable delays can increase the register-to-pin delays for output registers. Table 2–9 shows the programmable delays for Cyclone devices.

Table 2–9. Cyclone Programmable Delay Chain				
Programmable Delays	Quartus II Logic Option			
Input pin to logic array delay	Decrease input delay to internal cells			
Input pin to input register delay	Decrease input delay to input registers			
Output pin delay	Increase delay to output pin			

There are two paths in the IOE for a combinatorial input to reach the logic array. Each of the two paths can have a different delay. This allows you adjust delays from the pin to internal LE registers that reside in two different areas of the device. The designer sets the two combinatorial input delays by selecting different delays for two different paths under the **Decrease input delay to internal cells** logic option in the Quartus II software. When the input signal requires two different delays for the combinatorial input, the input register in the IOE is no longer available.

The IOE registers in Cyclone devices share the same source for clear or preset. The designer can program preset or clear for each individual IOE. The designer can also program the registers to power up high or low after configuration is complete. If programmed to power up low, an asynchronous clear can control the registers. If programmed to power up high, an asynchronous preset can control the registers. This feature prevents the inadvertent activation of another device's active-low input upon power up. If one register in an IOE uses a preset or clear signal then all registers in the IOE must use that same signal if they require preset or clear. Additionally a synchronous reset signal is available to the designer for the IOE registers.

# **External RAM Interfacing**

Cyclone devices support DDR SDRAM and FCRAM interfaces at up to 133 MHz through dedicated circuitry.

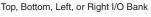
#### DDR SDRAM and FCRAM

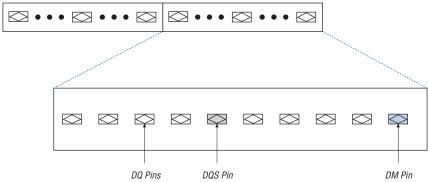
Cyclone devices have dedicated circuitry for interfacing with DDR SDRAM. All I/O banks support DDR SDRAM and FCRAM I/O pins. However, the configuration input pins in bank 1 must operate at 2.5 V because the SSTL-2  $\rm V_{CCIO}$  level is 2.5 V. Additionally, the configuration

output pins (nSTATUS and CONF\_DONE) and all the JTAG pins in I/O bank 3 must operate at 2.5 V because the  $V_{CCIO}$  level of SSTL-2 is 2.5 V. I/O banks 1, 2, 3, and 4 support DQS signals with DQ bus modes of  $\times$  8.

For ×8 mode, there are up to eight groups of programmable DQS and DQ pins, I/O banks 1, 2, 3, and 4 each have two groups in the 324-pin and 400-pin FineLine BGA packages. Each group consists of one DQS pin, a set of eight DQ pins, and one DM pin (see Figure 2–33). Each DQS pin drives the set of eight DQ pins within that group.

Figure 2–33. Cyclone Device DQ and DQS Groups in ×8 Mode Note (1)





*Note to Figure 2–33:* 

(1) Each DQ group consists of one DQS pin, eight DQ pins, and one DM pin.

Table 2–10 shows the number of DQ pin groups per device.

Table 2–10. DQ Pin Groups (Part 1 of 2)						
Device	Package	Number of × 8 DQ Pin Groups	Total DQ Pin Count			
EP1C3	100-pin TQFP (1)	3	24			
	144-pin TQFP	4	32			
EP1C4	324-pin FineLine BGA	8	64			
	400-pin FineLine BGA	8	64			

Table 2–10. DQ Pin Groups (Part 2 of 2)							
Device	Package	Number of × 8 DQ Pin Groups	Total DQ Pin Count				
EP1C6	144-pin TQFP	4	32				
	240-pin PQFP	4	32				
	256-pin FineLine BGA	4	32				
EP1C12	240-pin PQFP	4	32				
	256-pin FineLine BGA	4	32				
	324-pin FineLine BGA	8	64				
EP1C20	324-pin FineLine BGA	8	64				
	400-pin FineLine BGA	8	64				

Note to Table 2-10:

A programmable delay chain on each DQS pin allows for either a  $90^{\circ}$  phase shift (for DDR SDRAM), or a  $72^{\circ}$  phase shift (for FCRAM) which automatically center-aligns input DQS synchronization signals within the data window of their corresponding DQ data signals. The phase-shifted DQS signals drive the global clock network. This global DQS signal clocks DQ signals on internal LE registers.

These DQS delay elements combine with the PLL's clocking and phase shift ability to provide a complete hardware solution for interfacing to high-speed memory.

The clock phase shift allows the PLL to clock the DQ output enable and output paths. The designer should use the following guidelines to meet 133 MHz performance for DDR SDRAM and FCRAM interfaces:

- The DQS signal must be in the middle of the DQ group it clocks
- Resynchronize the incoming data to the logic array clock using successive LE registers or FIFO buffers
- LE registers must be placed in the LAB adjacent to the DQ I/O pin column it is fed by

Figure 2–34 illustrates DDR SDRAM and FCRAM interfacing from the I/O through the dedicated circuitry to the logic array.

EP1C3 devices in the 100-pin TQFP package do not have any DQ pin groups in I/O bank 1.

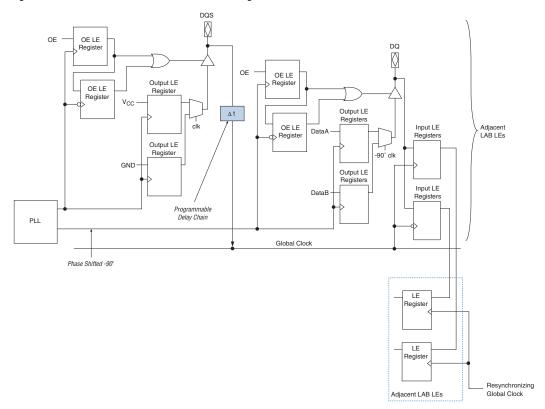


Figure 2-34. DDR SDRAM and FCRAM Interfacing

# **Programmable Drive Strength**

The output buffer for each Cyclone device I/O pin has a programmable drive strength control for certain I/O standards. The LVTTL and LVCMOS standards have several levels of drive strength that the designer can control. SSTL-3 class I and II, and SSTL-2 class I and II support a minimum setting, the lowest drive strength that guarantees the  $\rm I_{OH}/I_{OL}$ 

of the standard. Using minimum settings provides signal slew rate control to reduce system noise and signal overshoot. Table 2–11 shows the possible settings for the I/O standards with drive strength control.

Table 2–11. Programmable Drive Strength Note (1)				
I/O Standard	I <sub>OH</sub> /I <sub>OL</sub> Current Strength Setting (mA)			
LVTTL (3.3 V)	4			
	8			
	12			
	16			
	24(2)			
LVCMOS (3.3 V)	2			
	4			
	8			
	12(2)			
LVTTL (2.5 V)	2			
	8			
	12			
	16(2)			
LVTTL (1.8 V)	2			
	8			
	12(2)			
LVCMOS (1.5 V)	2			
	4			
	8(2)			

#### *Notes to Table 2–11:*

# **Open-Drain Output**

Cyclone devices provide an optional open-drain (equivalent to an open-collector) output for each I/O pin. This open-drain output enables the device to provide system-level control signals (e.g., interrupt and write-enable signals) that can be asserted by any of several devices.

SSTL-3 class I and II, SSTL-2 class I and II, and 3.3-V PCI I/O Standards do not support programmable drive strength.

<sup>(2)</sup> This is the default current strength setting in the Quartus II software.

#### Slew-Rate Control

The output buffer for each Cyclone device I/O pin has a programmable output slew-rate control that can be configured for low noise or high-speed performance. A faster slew rate provides high-speed transitions for high-performance systems. However, these fast transitions may introduce noise transients into the system. A slow slew rate reduces system noise, but adds a nominal delay to rising and falling edges. Each I/O pin has an individual slew-rate control, allowing the designer to specify the slew rate on a pin-by-pin basis. The slew-rate control affects both the rising and falling edges.

#### **Bus Hold**

Each Cyclone device I/O pin provides an optional bus-hold feature. The bus-hold circuitry can hold the signal on an I/O pin at its last-driven state. Since the bus-hold feature holds the last-driven state of the pin until the next input signal is present, an external pull-up or pull-down resistor is not necessary to hold a signal level when the bus is tri-stated.

The bus-hold circuitry also pulls undriven pins away from the input threshold voltage where noise can cause unintended high-frequency switching. The designer can select this feature individually for each I/O pin. The bus-hold output will drive no higher than  $V_{\text{CCIO}}$  to prevent overdriving signals. If the bus-hold feature is enabled, the device cannot use the programmable pull-up option. Disable the bus-hold feature when the I/O pin is configured for differential signals.

The bus-hold circuitry uses a resistor with a nominal resistance (RBH) of approximately 7 k $\Omega$  to pull the signal level to the last-driven state. Table 4–15 on page 4–6 gives the specific sustaining current for each  $V_{\text{CCIO}}$  voltage level driven through this resistor and overdrive current used to identify the next-driven input level.

The bus-hold circuitry is only active after configuration. When going into user mode, the bus-hold circuit captures the value on the pin present at the end of configuration.

# Programmable Pull-Up Resistor

Each Cyclone device I/O pin provides an optional programmable pull-up resistor during user mode. If the designer enables this feature for an I/O pin, the pull-up resistor (typically 25 k $\Omega$ ) holds the output to the V<sub>CCIO</sub> level of the output pin's bank. Dedicated clock pins do not have the optional programmable pull-up resistor.

### Advanced I/O Standard Support

Cyclone device IOEs support the following I/O standards:

- 3.3-V LVTTL/LVCMOS
- 2.5-V LVTTL/LVCMOS
- 1.8-V LVTTL/LVCMOS
- 1.5-V LVCMOS
- 3.3-V PCI
- LVDS
- RSDS
- SSTL-2 class I and II
- SSTL-3 class I and II
- Differential SSTL-2 class II (on output clocks only)

Table 2–12 describes the I/O standards supported by Cyclone devices.

Table 2–12. Cyclone I/O Standards						
I/O Standard	Туре	Input Reference Voltage (V <sub>REF</sub> ) (V)	Output Supply Voltage (V <sub>CCIO</sub> ) (V)	Board Termination Voltage (V <sub>TT</sub> ) (V)		
3.3-V LVTTL/LVCMOS	Single-ended	N/A	3.3	N/A		
2.5-V LVTTL/LVCMOS	Single-ended	N/A	2.5	N/A		
1.8-V LVTTL/LVCMOS	Single-ended	N/A	1.8	N/A		
1.5-V LVCMOS	Single-ended	N/A	1.5	N/A		
3.3-V PCI (1)	Single-ended	N/A	3.3	N/A		
LVDS (2)	Differential	N/A	2.5	N/A		
RSDS (2)	Differential	N/A	2.5	N/A		
SSTL-2 class I and II	Voltage-referenced	1.25	2.5	1.25		
SSTL-3 class I and II	Voltage-referenced	1.5	3.3	1.5		
Differential SSTL-2 (3)	Differential	1.25	2.5	1.25		

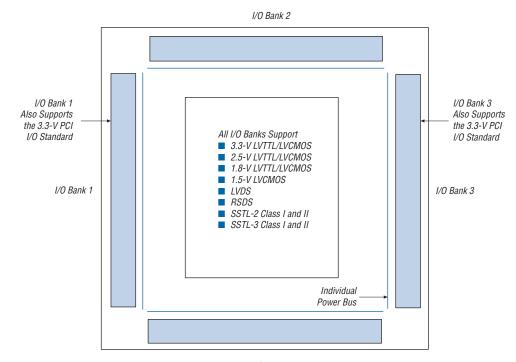
#### Notes to Table 2-12:

- (1) There is no megafunction support for EP1C3 devices for the PCI compiler. However, EP1C3 devices support PCI by using the LVTTL 16-mA I/O standard and drive strength assignments in the Quartus II software. The device requires an external diode for PCI compliance.
- (2) EP1C3 devices in the 100-pin TQFP package do not support the LVDS and RSDS I/O standards.
- (3) This I/O standard is only available on output clock pins (PLL\_OUT pins). EP1C3 devices in the 100-pin package do not support this I/O standard as it does not have PLL\_OUT pins.

Cyclone devices contain four I/O banks, as shown in Figure 2–35. I/O banks 1 and 3 support all the I/O standards listed in Table 2–12. I/O banks 2 and 4 support all the I/O standards listed in Table 2–12 except the 3.3-V PCI standard. I/O banks 2 and 4 contain dual-purpose DQS, DQ,

and DM pins to support a DDR SDRAM or FCRAM interface. I/O bank 1 can also support a DDR SDRAM or FCRAM interface, however, the configuration input pins in I/O bank 1 must operate at 2.5 V. I/O bank 3 can also support a DDR SDRAM or FCRAM interface, however, all the JTAG pins in I/O bank 3 must operate at 2.5 V.

**Figure 2–35. Cyclone I/O Banks** Notes (1), (2)



I/O Bank 4

#### *Notes to Figure 2–35:*

- (1) Figure 2–35 is a top view of the silicon die.
- (2) Figure 2–35 is a graphic representation only. Refer to the pin list and the Quartus II software for exact pin locations.

Each I/O bank has its own VCCIO pins. A single device can support 1.5-V, 1.8-V, 2.5-V, and 3.3-V interfaces; each individual bank can support a different standard with different I/O voltages. Each bank also has dual-purpose VREF pins to support any one of the voltage-referenced standards (e.g., SSTL-3) independently. If an I/O bank does not use voltage-referenced standards, the  $V_{\rm REF}$  pins are available as user I/O pins.

Each I/O bank can support multiple standards with the same  $V_{CCIO}$  for input and output pins. For example, when  $V_{CCIO}$  is 3.3-V, a bank can support LVTTL, LVCMOS, 3.3-V PCI, and SSTL-3 for inputs and outputs.

#### LVDS I/O Pins

A subset of pins in all four I/O banks supports LVDS interfacing. These dual-purpose LVDS pins require an external-resistor network at the transmitter channels in addition to 100- $\Omega$  termination resistors on receiver channels. These pins do not contain dedicated serialization or deserialization circuitry; therefore, internal logic performs serialization and deserialization functions.

Table 2–13 shows the total number of supported LVDS channels per device density.

Table 2–13. Cyclone Device LVDS Channels				
Device	Pin Count	Number of LVDS Channels		
EP1C3	100	(1)		
	144	34		
EP1C4	324	103		
	400	129		
EP1C6	144	29		
	240	72		
	256	72		
EP1C12	240	66		
	256	72		
	324	103		
EP1C20	324	95		
	400	129		

*Note to Table 2–13:* 

### MultiVolt I/O Interface

The Cyclone architecture supports the MultiVolt I/O interface feature, which allows Cyclone devices in all packages to interface with systems of different supply voltages. The devices have one set of  $V_{CC}$  pins for internal operation and input buffers ( $V_{CCINT}$ ), and four sets for I/O output drivers ( $V_{CCIO}$ ).

EP1C3 devices in the 100-pin TQFP package do not support the LVDS I/O standard.

The Cyclone  $V_{\rm CCINT}$  pins must always be connected to a 1.5-V power supply. If the  $V_{\rm CCINT}$  level is 1.5 V, then input pins are 1.5-V, 1.8-V, 2.5-V, and 3.3-V tolerant. The  $V_{\rm CCIO}$  pins can be connected to either a 1.5-V, 1.8-V, 2.5-V, or 3.3-V power supply, depending on the output requirements. The output levels are compatible with systems of the same voltage as the power supply (i.e., when  $V_{\rm CCIO}$  pins are connected to a 1.5-V power supply, the output levels are compatible with 1.5-V systems). When  $V_{\rm CCIO}$  pins are connected to a 3.3-V power supply, the output high is 3.3-V and is compatible with 3.3-V or 5.0-V systems. Table 2–14 summarizes Cyclone MultiVolt I/O support.

Table 2–14. Cyclone MultiVolt I/O Support Note (1)										
Input Signal Output Signal										
V <sub>CCIO</sub> (V)	1.5 V	1.8 V	2.5 V	3.3 V	5.0 V	1.5 V	1.8 V	2.5 V	3.3 V	5.0 V
1.5	<b>✓</b>	<b>✓</b>	<b>√</b> (2)	<b>√</b> (2)	_	<b>✓</b>	_	_	_	_
1.8	<b>✓</b>	<b>✓</b>	<b>√</b> (2)	<b>√</b> (2)	_	<b>√</b> (3)	<b>✓</b>	_	_	_
2.5	_	_	<b>✓</b>	<b>✓</b>	_	<b>√</b> (5)	<b>√</b> (5)	<b>✓</b>	_	_
3.3	_		<b>√</b> (4)	<b>✓</b>	<b>√</b> (6)	<b>√</b> (7)	<b>√</b> (7)	<b>√</b> (7)	<b>✓</b>	<b>√</b> (8)

#### Notes to Table 2-14:

- (1) The PCI clamping diode must be disabled to drive an input with voltages higher than V<sub>CCIO</sub>.
- (2) When V<sub>CCIO</sub> = 1.5-V or 1.8-V and a 2.5-V or 3.3-V input signal feeds an input pin, higher pin leakage current is expected. Turn on Allow voltage overdrive for LVTTL / LVCMOS input pins in the Assignments > Device > Device and Pin Options > Pin Placement tab when a device has this I/O combinations.
- (3) When  $V_{CCIO} = 1.8$ -V, a Cyclone device can drive a 1.5-V device with 1.8-V tolerant inputs.
- (4) When  $V_{CCIO}$  = 3.3-V and a 2.5-V input signal feeds an input pin, the  $V_{CCIO}$  supply current will be slightly larger than expected.
- (5) When  $V_{CCIO} = 2.5$ -V, a Cyclone device can drive a 1.5-V or 1.8-V device with 2.5-V tolerant inputs.
- (6) Cyclone devices can be 5.0-V tolerant with the use of an external resistor and the internal PCI clamp diode.
- (7) When V<sub>CCIO</sub> = 3.3-V, a Cyclone device can drive a 1.5-V, 1.8-V, or 2.5-V device with 3.3-V tolerant inputs.
- (8) When V<sub>CCIO</sub> = 3.3-V, a Cyclone device can drive a device with 5.0-V LVTTL inputs but not 5.0-V LVCMOS inputs.

# Power Sequencing and Hot Socketing

Because Cyclone devices can be used in a mixed-voltage environment, they have been designed specifically to tolerate any possible power-up sequence. Therefore, the  $V_{\text{CCIO}}$  and  $V_{\text{CCINT}}$  power supplies may be powered in any order.

Signals can be driven into Cyclone devices before and during power up without damaging the device. In addition, Cyclone devices do not drive out during power up. Once operating conditions are reached and the device is configured, Cyclone devices operate as specified by the user.

# Referenced Documents

This chapter references the following document:

■ Using PLLs in Cyclone Devices chapter in the Cyclone Device Handbook

# Document Revision History

Table 2–15 shows the revision history for this chapter.

Table 2–15. Document Revision History					
Date and Document Version	Changes Made	Summary of Changes			
May 2008 v1.6	Minor textual and style changes. Added "Referenced Documents" section.	_			
January 2007 v1.5	<ul> <li>Added document revision history.</li> <li>Updated Figures 2–17, 2–18, 2–19, 2–20, 2–21, and 2–32.</li> </ul>	_			
August 2005 v1.4	Minor updates.	_			
February 2005 v1.3	<ul> <li>Updated JTAG chain limits. Added test vector information.</li> <li>Corrected Figure 2-12.</li> <li>Added a note to Tables 2-17 through 2-21 regarding violating the setup or hold time.</li> </ul>	_			
October 2003 v1.2	<ul><li>Updated phase shift information.</li><li>Added 64-bit PCI support information.</li></ul>	_			
September 2003 v1.1	Updated LVDS data rates to 640 Mbps from 311 Mbps.	_			
May 2003 v1.0	Added document to Cyclone Device Handbook.	_			

# 3. Configuration and Testing

C51003-1.4

# IEEE Std. 1149.1 (JTAG) Boundary Scan Support

All Cyclone® devices provide JTAG BST circuitry that complies with the IEEE Std. 1149.1a-1990 specification. JTAG boundary-scan testing can be performed either before or after, but not during configuration. Cyclone devices can also use the JTAG port for configuration together with either the Quartus® II software or hardware using either Jam Files (.jam) or Jam Byte-Code Files (.jbc).

Cyclone devices support reconfiguring the I/O standard settings on the IOE through the JTAG BST chain. The JTAG chain can update the I/O standard for all input and output pins any time before or during user mode. Designers can use this ability for JTAG testing before configuration when some of the Cyclone pins drive or receive from other devices on the board using voltage-referenced standards. Since the Cyclone device might not be configured before JTAG testing, the I/O pins might not be configured for appropriate electrical standards for chip-to-chip communication. Programming those I/O standards via JTAG allows designers to fully test I/O connection to other devices.

The JTAG pins support 1.5-V/1.8-V or 2.5-V/3.3-V I/O standards. The TDO pin voltage is determined by the  $V_{\rm CCIO}$  of the bank where it resides. The bank  $V_{\rm CCIO}$  selects whether the JTAG inputs are 1.5-V, 1.8-V, 2.5-V, or 3.3-V compatible.

Cyclone devices also use the JTAG port to monitor the operation of the device with the SignalTap® II embedded logic analyzer. Cyclone devices support the JTAG instructions shown in Table 3–1.

Table 3–1. Cyclone JTAG Instructions (Part 1 of 2)					
JTAG Instruction	Instruction Code	Description			
SAMPLE/PRELOAD	00 0000 0101	Allows a snapshot of signals at the device pins to be captured and examined during normal device operation, and permits an initial data pattern to be output at the device pins. Also used by the SignalTap II embedded logic analyzer.			
EXTEST (1)	00 0000 0000	Allows the external circuitry and board-level interconnects to be tested by forcing a test pattern at the output pins and capturing test results at the input pins.			
BYPASS	11 1111 1111	Places the 1-bit bypass register between the TDI and TDO pins, which allows the BST data to pass synchronously through selected devices to adjacent devices during normal device operation.			

Table 3–1. Cyclone	Table 3–1. Cyclone JTAG Instructions (Part 2 of 2)				
JTAG Instruction	Instruction Code	Description			
USERCODE	00 0000 0111	Selects the 32-bit USERCODE register and places it between the TDI and TDO pins, allowing the USERCODE to be serially shifted out of TDO.			
IDCODE	00 0000 0110	Selects the IDCODE register and places it between TDI and TDO, allowing the IDCODE to be serially shifted out of TDO.			
HIGHZ (1)	00 0000 1011	Places the 1-bit bypass register between the TDI and TDO pins, which allows the BST data to pass synchronously through selected devices to adjacent devices during normal device operation, while tri-stating all of the I/O pins.			
CLAMP (1)	00 0000 1010	Places the 1-bit bypass register between the TDI and TDO pins, which allows the BST data to pass synchronously through selected devices to adjacent devices during normal device operation while holding I/O pins to a state defined by the data in the boundary-scan register.			
ICR instructions	_	Used when configuring a Cyclone device via the JTAG port with a MasterBlaster <sup>TM</sup> or ByteBlasterMV <sup>TM</sup> download cable, or when using a Jam File or Jam Byte-Code File via an embedded processor.			
PULSE_NCONFIG	00 0000 0001	Emulates pulsing the nCONFIG pin low to trigger reconfiguration even though the physical pin is unaffected.			
CONFIG_IO	00 0000 1101	Allows configuration of I/O standards through the JTAG chain for JTAG testing. Can be executed before, after, or during configuration. Stops configuration if executed during configuration. Once issued, the CONFIG_IO instruction will hold nSTATUS low to reset the configuration device. nSTATUS is held low until the device is reconfigured.			
SignalTap II instructions	_	Monitors internal device operation with the SignalTap II embedded logic analyzer.			

#### *Note to Table 3–1:*

In the Quartus II software, there is an Auto Usercode feature where you can choose to use the checksum value of a programming file as the JTAG user code. If selected, the checksum is automatically loaded to the USERCODE register. Choose Assignments > Device > Device and Pin Options > General. Turn on **Auto Usercode**.

<sup>(1)</sup> Bus hold and weak pull-up resistor features override the high-impedance state of HIGHZ, CLAMP, and EXTEST.

The Cyclone device instruction register length is 10 bits and the USERCODE register length is 32 bits. Tables 3–2 and 3–3 show the boundary-scan register length and device IDCODE information for Cyclone devices.

Table 3–2. Cyclone Boundary-Scan Register Length				
Device Boundary-Scan Register Lengt				
EP1C3	339			
EP1C4	930			
EP1C6	582			
EP1C12	774			
EP1C20	930			

Table 3–3. 32-Bit Cyclone Device IDCODE							
	IDCODE (32 bits) (1)						
Device	Version (4 Bits)  Part Number (16 Bits)  Manufacturer Identity (11 Bits)  LSB						
EP1C3	0000	0010 0000 1000 0001	000 0110 1110	1			
EP1C4	0000	0010 0000 1000 0101	000 0110 1110	1			
EP1C6	0000	0010 0000 1000 0010	000 0110 1110	1			
EP1C12	0000	0010 0000 1000 0011	000 0110 1110	1			
EP1C20	0000	0010 0000 1000 0100	000 0110 1110	1			

#### Notes to Table 3-3:

- (1) The most significant bit (MSB) is on the left.
- (2) The IDCODE's least significant bit (LSB) is always 1.

Figure 3-1. Cyclone JTAG Waveforms TMS TDI TCK t <sub>JPXZ</sub> t<sub>JPZX</sub> t<sub>JPCO</sub> TDO t<sub>JSH</sub> t<sub>JSSU</sub> Signal to Be Captured t<sub>JSCO</sub> t<sub>JSXZ</sub> t<sub>JSZX</sub> -Signal to Be Driven

Figure 3–1 shows the timing requirements for the JTAG signals.

Table 3–4 shows the JTAG timing parameters and values for Cyclone devices.

Table 3–4. Cyclone JTAG Timing Parameters and Values					
Symbol	Parameter	Min	Max	Unit	
$t_{JCP}$	TCK clock period	100	_	ns	
t <sub>JCH</sub>	TCK clock high time	50	_	ns	
t <sub>JCL</sub>	TCK clock low time	50	_	ns	
t <sub>JPSU</sub>	JTAG port setup time	20	_	ns	
t <sub>JPH</sub>	JTAG port hold time	45	_	ns	
t <sub>JPCO</sub>	JTAG port clock to output	_	25	ns	
$t_{JPZX}$	JTAG port high impedance to valid output	_	25	ns	
t <sub>JPXZ</sub>	JTAG port valid output to high impedance	_	25	ns	
t <sub>JSSU</sub>	Capture register setup time	20	_	ns	
t <sub>JSH</sub>	Capture register hold time	45	_	ns	
t <sub>JSCO</sub>	Update register clock to output	_	35	ns	
t <sub>JSZX</sub>	Update register high impedance to valid output	_	35	ns	
$t_{\text{JSXZ}}$	Update register valid output to high impedance	_	35	ns	



Cyclone devices must be within the first 8 devices in a JTAG chain. All of these devices have the same JTAG controller. If any of the Cyclone devices are in the 9th or after they will fail configuration. This does not affect the SignalTap® II logic analyzer.



For more information on JTAG, refer to the following documents:

- AN 39: IEEE Std. 1149.1 (JTAG) Boundary-Scan Testing in Altera Devices
- Jam Programming & Test Language Specification

# SignalTap II Embedded Logic Analyzer

Cyclone devices feature the SignalTap II embedded logic analyzer, which monitors design operation over a period of time through the IEEE Std. 1149.1 (JTAG) circuitry. A designer can analyze internal logic at speed without bringing internal signals to the I/O pins. This feature is particularly important for advanced packages, such as FineLine BGA packages, because it can be difficult to add a connection to a pin during the debugging process after a board is designed and manufactured.

# Configuration

The logic, circuitry, and interconnects in the Cyclone architecture are configured with CMOS SRAM elements. Altera FPGAs are reconfigurable and every device is tested with a high coverage production test program so the designer does not have to perform fault testing and can instead focus on simulation and design verification.

Cyclone devices are configured at system power-up with data stored in an Altera configuration device or provided by a system controller. The Cyclone device's optimized interface allows the device to act as controller in an active serial configuration scheme with the new low-cost serial configuration device. Cyclone devices can be configured in under 120 ms using serial data at 20 MHz. The serial configuration device can be programmed via the ByteBlaster II download cable, the Altera Programming Unit (APU), or third-party programmers.

In addition to the new low-cost serial configuration device, Altera offers in-system programmability (ISP)-capable configuration devices that can configure Cyclone devices via a serial data stream. The interface also enables microprocessors to treat Cyclone devices as memory and configure them by writing to a virtual memory location, making reconfiguration easy. After a Cyclone device has been configured, it can be reconfigured in-circuit by resetting the device and loading new data. Real-time changes can be made during system operation, enabling innovative reconfigurable computing applications.

### **Operating Modes**

The Cyclone architecture uses SRAM configuration elements that require configuration data to be loaded each time the circuit powers up. The process of physically loading the SRAM data into the device is called configuration. During initialization, which occurs immediately after configuration, the device resets registers, enables I/O pins, and begins to operate as a logic device. Together, the configuration and initialization processes are called command mode. Normal device operation is called user mode.

SRAM configuration elements allow Cyclone devices to be reconfigured in-circuit by loading new configuration data into the device. With real-time reconfiguration, the device is forced into command mode with a device pin. The configuration process loads different configuration data, reinitializes the device, and resumes user-mode operation. Designers can perform in-field upgrades by distributing new configuration files either within the system or remotely.

A built-in weak pull-up resistor pulls all user I/O pins to  $V_{\text{CCIO}}$  before and during device configuration.

The configuration pins support 1.5-V/1.8-V or 2.5-V/3.3-V I/O standards. The voltage level of the configuration output pins is determined by the  $V_{CCIO}$  of the bank where the pins reside. The bank  $V_{CCIO}$  selects whether the configuration inputs are 1.5-V, 1.8-V, 2.5-V, or 3.3-V compatible.

# **Configuration Schemes**

Designers can load the configuration data for a Cyclone device with one of three configuration schemes (see Table 3–5), chosen on the basis of the target application. Designers can use a configuration device, intelligent controller, or the JTAG port to configure a Cyclone device. A low-cost configuration device can automatically configure a Cyclone device at system power-up.

Multiple Cyclone devices can be configured in any of the three configuration schemes by connecting the configuration enable (nCE) and configuration enable output (nCEO) pins on each device.

Table 3–5. Data Sources for Configuration				
Configuration Scheme Data Source				
Active serial	Low-cost serial configuration device			
Passive serial (PS)	Enhanced or EPC2 configuration device, MasterBlaster or ByteBlasterMV download cable, or serial data source			
JTAG	MasterBlaster or ByteBlasterMV download cable or a microprocessor with a Jam or JBC file			

# Referenced Documents

This chapter references the following documents:

- AN 39: IEEE Std. 1149.1 (JTAG) Boundary-Scan Testing in Altera Devices
- Jam Programming & Test Language Specification

# Document Revision History

Table 3–6 shows the revision history for this chapter.

Table 3-6. Doc	Table 3–6. Document Revision History					
Date and Document Version	Changes Made	Summary of Changes				
May 2008 v1.4	Minor textual and style changes. Added "Referenced Documents" section.	_				
January 2007 v1.3	<ul><li>Added document revision history.</li><li>Updated handpara note below Table 3–4.</li></ul>	_				
August 2005 V1.2	Minor updates.	_				
February 2005 V1.1	Updated JTAG chain limits. Added information concerning test vectors.	_				
May 2003 v1.0	Added document to Cyclone Device Handbook.	_				



# 4. DC and Switching Characteristics

C51004-1.7

# Operating Conditions

Cyclone® devices are offered in both commercial, industrial, and extended temperature grades. However, industrial-grade and extended-temperature-grade devices may have limited speed-grade availability.

Tables 4–1 through 4–16 provide information on absolute maximum ratings, recommended operating conditions, DC operating conditions, and capacitance for Cyclone devices.

Table 4–1. Cyclone Device Absolute Maximum Ratings       Notes (1), (2)						
Symbol	Parameter	Conditions	Minimum	Maximum	Unit	
V <sub>CCINT</sub>	Supply voltage	With respect to ground (3)	-0.5	2.4	V	
V <sub>CCIO</sub>			-0.5	4.6	V	
V <sub>CCA</sub>	Supply voltage	With respect to ground (3)	-0.5	2.4	V	
Vı	DC input voltage		-0.5	4.6	V	
I <sub>OUT</sub>	DC output current, per pin		-25	25	mA	
T <sub>STG</sub>	Storage temperature	No bias	-65	150	°C	
T <sub>AMB</sub>	Ambient temperature	Under bias	-65	135	°C	
T <sub>J</sub>	Junction temperature	BGA packages under bias	_	135	°C	

Table 4–2. Cyclone Device Recommended Operating Conditions (Part 1 of 2)						
Symbol	Parameter	Conditions	Minimum	Maximum	Unit	
V <sub>CCINT</sub>	Supply voltage for internal logic and input buffers	(4)	1.425	1.575	V	
V <sub>CCIO</sub>	Supply voltage for output buffers, 3.3-V operation	(4)	3.00	3.60	V	
	Supply voltage for output buffers, 2.5-V operation	(4)	2.375	2.625	V	
	Supply voltage for output buffers, 1.8-V operation	(4)	1.71	1.89	V	
	Supply voltage for output buffers, 1.5-V operation	(4)	1.4	1.6	V	
V <sub>I</sub>	Input voltage	(3), (5)	-0.5	4.1	V	

Table 4-2. C	Table 4–2. Cyclone Device Recommended Operating Conditions (Part 2 of 2)						
Symbol	Parameter	Conditions	Minimum	Maximum	Unit		
Vo	Output voltage		0	V <sub>CCIO</sub>	V		
T <sub>J</sub>	Operating junction temperature	For commercial use	0	85	° C		
		For industrial use	-40	100	° C		
		For extended- temperature use	-40	125	° C		

Table 4-	3. Cyclone Device DC Operating	<b>Conditions</b> Note (6)				
Symbol	Parameter	Conditions	Minimum	Typical	Maximum	Unit
I	Input pin leakage current	$V_I = V_{CCIOmax}$ to 0 V (8)	-10	_	10	μΑ
l <sub>OZ</sub>	Tri-stated I/O pin leakage current	$V_O = V_{CCIOmax}$ to 0 V (8)	-10	_	10	μА
I <sub>CC0</sub>	V <sub>CC</sub> supply current (standby)	EP1C3	_	4	_	mA
	(All M4K blocks in power-down	EP1C4	_	6	_	mA
	mode) (7)	EP1C6	_	6	_	mA
		EP1C12	_	8	_	mA
		EP1C20	_	12	_	mA
R <sub>CONF</sub> (9)	Value of I/O pin pull-up resistor	$V_1 = 0 \text{ V}; V_{CCI0} = 3.3 \text{ V}$	15	25	50	kΩ
	before and during configuration	V <sub>I</sub> = 0 V; V <sub>CCI0</sub> = 2.5 V	20	45	70	kΩ
		V <sub>I</sub> = 0 V; V <sub>CCI0</sub> = 1.8 V	30	65	100	kΩ
		V <sub>I</sub> = 0 V; V <sub>CCI0</sub> = 1.5 V	50	100	150	kΩ
	Recommended value of I/O pin external pull-down resistor before and during configuration	_	_	1	2	kΩ

Table 4–4.	Table 4–4. LVTTL Specifications							
Symbol	Parameter	Conditions	Minimum	Maximum	Unit			
V <sub>CCIO</sub>	Output supply voltage	_	3.0	3.6	V			
V <sub>IH</sub>	High-level input voltage	_	1.7	4.1	V			
V <sub>IL</sub>	Low-level input voltage	_	-0.5	0.7	V			
V <sub>OH</sub>	High-level output voltage	$I_{OH} = -4 \text{ to } -24 \text{ mA } (11)$	2.4	_	V			
V <sub>OL</sub>	Low-level output voltage	I <sub>OL</sub> = 4 to 24 mA (11)	_	0.45	V			

Table 4–5.	Table 4–5. LVCMOS Specifications							
Symbol	Parameter	Conditions	Minimum	Maximum	Unit			
V <sub>CCIO</sub>	Output supply voltage	_	3.0	3.6	V			
V <sub>IH</sub>	High-level input voltage	_	1.7	4.1	V			
V <sub>IL</sub>	Low-level input voltage	_	-0.5	0.7	V			
V <sub>OH</sub>	High-level output voltage	$V_{CCIO} = 3.0,$ $I_{OH} = -0.1 \text{ mA}$	V <sub>CCIO</sub> - 0.2	_	٧			
V <sub>OL</sub>	Low-level output voltage	V <sub>CCIO</sub> = 3.0, I <sub>OL</sub> = 0.1 mA	_	0.2	V			

Table 4–6.	2.5-V I/O Specifications				
Symbol	Parameter	Conditions	Minimum	Maximum	Unit
V <sub>CCIO</sub>	Output supply voltage	_	2.375	2.625	V
V <sub>IH</sub>	High-level input voltage	_	1.7	4.1	V
V <sub>IL</sub>	Low-level input voltage	_	-0.5	0.7	V
V <sub>OH</sub>	High-level output voltage	I <sub>OH</sub> = -0.1 mA	2.1	_	V
		$I_{OH} = -1 \text{ mA}$	2.0	_	V
		$I_{OH} = -2 \text{ to } -16 \text{ mA } (11)$	1.7	_	V
V <sub>OL</sub>	Low-level output voltage	I <sub>OL</sub> = 0.1 mA	_	0.2	V
		I <sub>OH</sub> = 1 mA	_	0.4	V
		I <sub>OH</sub> = 2 to 16 mA (11)	1	0.7	V

Table 4–7. 1.8-V I/O Specifications						
Symbol	Parameter	Conditions	Minimum	Maximum	Unit	
V <sub>CCIO</sub>	Output supply voltage	_	1.65	1.95	٧	
V <sub>IH</sub>	High-level input voltage	_	0.65 × V <sub>CCIO</sub>	2.25 (12)	V	
V <sub>IL</sub>	Low-level input voltage	_	-0.3	0.35 × V <sub>CCIO</sub>	V	
V <sub>OH</sub>	High-level output voltage	$I_{OH} = -2 \text{ to } -8 \text{ mA } (11)$	V <sub>CCIO</sub> - 0.45	_	V	
V <sub>OL</sub>	Low-level output voltage	I <sub>OL</sub> = 2 to 8 mA (11)	_	0.45	V	

Table 4–8. 1.5-V I/O Specifications						
Symbol	Parameter	Conditions	Minimum	Maximum	Unit	
V <sub>CCIO</sub>	Output supply voltage	_	1.4	1.6	V	
V <sub>IH</sub>	High-level input voltage	_	0.65 × V <sub>CCIO</sub>	V <sub>CCIO</sub> + 0.3 (12)	V	
V <sub>IL</sub>	Low-level input voltage	_	-0.3	0.35 × V <sub>CCIO</sub>	V	
V <sub>OH</sub>	High-level output voltage	$I_{OH} = -2 \text{ mA } (11)$	0.75 × V <sub>CCIO</sub>	_	V	
V <sub>OL</sub>	Low-level output voltage	I <sub>OL</sub> = 2 mA (11)	_	0.25 × V <sub>CCIO</sub>	V	

Table 4–9.	Table 4–9. 2.5-V LVDS I/O SpecificationsNote (13)					
Symbol	Parameter	Conditions	Minimum	Typical	Maximum	Unit
V <sub>CCIO</sub>	I/O supply voltage	_	2.375	2.5	2.625	V
V <sub>OD</sub>	Differential output voltage	R <sub>L</sub> = 100 Ω	250	_	550	mV
ΔV <sub>OD</sub>	Change in V <sub>OD</sub> between high and low	R <sub>L</sub> = 100 Ω	_	_	50	mV
V <sub>OS</sub>	Output offset voltage	$R_L = 100 \Omega$	1.125	1.25	1.375	V
ΔV <sub>OS</sub>	Change in V <sub>OS</sub> between high and low	R <sub>L</sub> = 100 Ω	_	_	50	mV
V <sub>TH</sub>	Differential input threshold	V <sub>CM</sub> = 1.2 V	-100	_	100	mV
V <sub>IN</sub>	Receiver input voltage range	_	0.0	_	2.4	V
R <sub>L</sub>	Receiver differential input resistor	_	90	100	110	Ω

Table 4-10	Table 4–10. 3.3-V PCI Specifications (Part 1 of 2)					
Symbol	Parameter	Conditions	Minimum	Typical	Maximum	Unit
V <sub>CCIO</sub>	Output supply voltage	_	3.0	3.3	3.6	V
V <sub>IH</sub>	High-level input voltage	_	0.5 × V <sub>CCIO</sub>	_	V <sub>CCIO</sub> + 0.5	V
V <sub>IL</sub>	Low-level input voltage	_	-0.5	_	0.3 × V <sub>CCIO</sub>	V

Table 4-10	. 3.3-V PCI Specifications (	Part 2 of 2)				
Symbol	Parameter	Conditions	Minimum	Typical	Maximum	Unit
V <sub>OH</sub>	High-level output voltage	I <sub>OUT</sub> = -500 μA	$0.9 \times V_{CCIO}$	_	_	V
V <sub>OL</sub>	Low-level output voltage	I <sub>OUT</sub> = 1,500 μA	_		0.1 × V <sub>CCIO</sub>	V

Symbol	Parameter	Conditions	Minimum	Typical	Maximum	Unit
V <sub>CCIO</sub>	Output supply voltage	_	2.375	2.5	2.625	V
V <sub>TT</sub>	Termination voltage	_	V <sub>REF</sub> - 0.04	$V_{REF}$	V <sub>REF</sub> + 0.04	V
$V_{REF}$	Reference voltage	_	1.15	1.25	1.35	V
V <sub>IH</sub>	High-level input voltage	_	V <sub>REF</sub> + 0.18	_	3.0	V
V <sub>IL</sub>	Low-level input voltage	_	-0.3	_	V <sub>REF</sub> - 0.18	V
V <sub>OH</sub>	High-level output voltage	$I_{OH} = -8.1 \text{ mA}$ (11)	V <sub>TT</sub> + 0.57	_	_	V
V <sub>OL</sub>	Low-level output voltage	I <sub>OL</sub> = 8.1 mA (11)	_	_	V <sub>TT</sub> – 0.57	٧

Table 4–12. SSTL-2 Class II Specifications							
Symbol	Parameter	Conditions	Minimum	Typical	Maximum	Unit	
$V_{\text{CCIO}}$	Output supply voltage	_	2.3	2.5	2.7	٧	
V <sub>TT</sub>	Termination voltage	_	V <sub>REF</sub> - 0.04	V <sub>REF</sub>	V <sub>REF</sub> + 0.04	٧	
$V_{REF}$	Reference voltage	_	1.15	1.25	1.35	V	
V <sub>IH</sub>	High-level input voltage	_	V <sub>REF</sub> + 0.18	_	V <sub>CCIO</sub> + 0.3	V	
V <sub>IL</sub>	Low-level input voltage	_	-0.3	_	V <sub>REF</sub> - 0.18	V	
V <sub>OH</sub>	High-level output voltage	$I_{OH} = -16.4 \text{ mA}$ (11)	V <sub>TT</sub> + 0.76	_	_	V	
V <sub>OL</sub>	Low-level output voltage	I <sub>OL</sub> = 16.4 mA (11)	_	_	V <sub>TT</sub> – 0.76	V	

Table 4–13. SSTL-3 Class I Specifications (Part 1 of 2)						
Symbol	Parameter	Conditions	Minimum	Typical	Maximum	Unit
V <sub>CCIO</sub>	Output supply voltage	_	3.0	3.3	3.6	V
V <sub>TT</sub>	Termination voltage	_	V <sub>REF</sub> - 0.05	$V_{REF}$	V <sub>REF</sub> + 0.05	V

Table 4–13. SSTL-3 Class I Specifications (Part 2 of 2)							
Symbol	Parameter	Conditions	Minimum	Typical	Maximum	Unit	
$V_{REF}$	Reference voltage	_	1.3	1.5	1.7	V	
V <sub>IH</sub>	High-level input voltage	_	V <sub>REF</sub> + 0.2	_	V <sub>CCIO</sub> + 0.3	٧	
$V_{IL}$	Low-level input voltage	_	-0.3	_	V <sub>REF</sub> - 0.2	V	
V <sub>OH</sub>	High-level output voltage	$I_{OH} = -8 \text{ mA } (11)$	V <sub>TT</sub> + 0.6	_	_	V	
V <sub>OL</sub>	Low-level output voltage	I <sub>OL</sub> = 8 mA (11)	_	_	V <sub>TT</sub> - 0.6	V	

Table 4–14. SSTL-3 Class II Specifications								
Symbol	Parameter	Conditions	Minimum	Typical	Maximum	Unit		
V <sub>CCIO</sub>	Output supply voltage	_	3.0	3.3	3.6	V		
$V_{TT}$	Termination voltage	_	V <sub>REF</sub> - 0.05	$V_{REF}$	V <sub>REF</sub> + 0.05	V		
V <sub>REF</sub>	Reference voltage	_	1.3	1.5	1.7	V		
V <sub>IH</sub>	High-level input voltage	_	V <sub>REF</sub> + 0.2	_	V <sub>CCIO</sub> + 0.3	V		
V <sub>IL</sub>	Low-level input voltage	_	-0.3	_	V <sub>REF</sub> - 0.2	V		
V <sub>OH</sub>	High-level output voltage	I <sub>OH</sub> = -16 mA (11)	V <sub>TT</sub> + 0.8	_	_	V		
V <sub>OL</sub>	Low-level output voltage	I <sub>OL</sub> = 16 mA (11)	_	_	V <sub>TT</sub> – 0.8	V		

Table 4–15. Bus Hold Parameters											
			V <sub>CCIO</sub> Level								
Parameter	Conditions	1.5	5 V	1.8	B V	2.	5 V	3.3	3 V	Unit	
		Min	Max	Min	Max	Min	Max	Min	Max		
Low sustaining current	$V_{IN} > V_{IL}$ (maximum)	_	_	30	_	50	_	70	_	μΑ	
High sustaining current	V <sub>IN</sub> < V <sub>IH</sub> (minimum)	_	_	-30	_	-50	_	-70	_	μΑ	
Low overdrive current	0 V < V <sub>IN</sub> < V <sub>CCIO</sub>	_	_	_	200	_	300	_	500	μА	
High overdrive current	0 V < V <sub>IN</sub> < V <sub>CCIO</sub>	_	_	_	-200	_	-300	_	-500	μА	

Table 4–16. Cyclone Device Capacitance Note (14)							
Symbol	Parameter	Typical	Unit				
C <sub>IO</sub>	Input capacitance for user I/O pin 4.0 pF						
C <sub>LVDS</sub>	Input capacitance for dual-purpose LVDS/user I/O pin 4.7 pl						
C <sub>VREF</sub>	Input capacitance for dual-purpose V <sub>REF</sub> /user I/O pin. 12.0 pF						
C <sub>DPCLK</sub>	Input capacitance for dual-purpose DPCLK/user I/O pin. 4.4 pF						
C <sub>CLK</sub>	Input capacitance for CLK pin. 4.7 pF						

#### *Notes to Tables 4–1 through 4–16:*

- (1) Refer to the Operating Requirements for Altera Devices Data Sheet.
- (2) Conditions beyond those listed in Table 4–1 may cause permanent damage to a device. Additionally, device operation at the absolute maximum ratings for extended periods of time may have adverse affects on the device.
- (3) Minimum DC input is -0.5 V. During transitions, the inputs may undershoot to -2.0 V or overshoot to 4.6 V for input currents less than 100 mA and periods shorter than 20 ns.
- (4) Maximum  $V_{CC}$  rise time is 100 ms, and  $V_{CC}$  must rise monotonically.
- (5) All pins, including dedicated inputs, clock, I/O, and JTAG pins, may be driven before V<sub>CCINT</sub> and V<sub>CCIO</sub> are powered.
- (6) Typical values are for  $T_A = 25^{\circ}$  C,  $V_{CCINT} = 1.5$  V, and  $V_{CCIO} = 1.5$  V, 1.8 V, 2.5 V, and 3.3 V.
- (7)  $V_I = \text{ground}$ , no load, no toggling inputs.
- (8) This value is specified for normal device operation. The value may vary during power-up. This applies for all V<sub>CCIO</sub> settings (3.3, 2.5, 1.8, and 1.5 V).
- (9) R<sub>CONF</sub> is the measured value of internal pull-up resistance when the I/O pin is tied directly to GND. R<sub>CONF</sub> value will be lower if an external source drives the pin higher than V<sub>CCIO</sub>.
- (10) Pin pull-up resistance values will lower if an external source drives the pin higher than  $V_{\text{CCIO}}$ .
- (11) Drive strength is programmable according to values in Cyclone Architecture chapter in the Cyclone Device Handbook.
- (12) Overdrive is possible when a 1.5 V or 1.8 V and a 2.5 V or 3.3 V input signal feeds an input pin. Turn on "Allow voltage overdrive" for LVTTL/LVCMOS input pins in the Assignments > Device > Device and Pin Options > Pin Placement tab when a device has this I/O combination. However, higher leakage current is expected.
- (13) The Cyclone LVDS interface requires a resistor network outside of the transmitter channels.
- (14) Capacitance is sample-tested only. Capacitance is measured using time-domain reflections (TDR). Measurement accuracy is within ±0.5 pF.

# Power Consumption

Designers can use the Altera web Early Power Estimator to estimate the device power.

Cyclone devices require a certain amount of power-up current to successfully power up because of the nature of the leading-edge process on which they are fabricated. Table 4–17 shows the maximum power-up current required to power up a Cyclone device.

Table 4–17. Cyclone Maximum Power-Up Current ( $I_{CCINT}$ ) Requirements (In-Rush Current)						
Device	Commercial Specification	Industrial Specification	Unit			
EP1C3	150	180	mA			
EP1C4	150	180	mA			
EP1C6	175	210	mA			
EP1C12	300	360	mA			
EP1C20	500	600	mA			

#### *Notes to Table 4–17:*

- The Cyclone devices (except for the EP1C20 device) meet the power up specification for Mini PCI.
- (2) The lot codes 9G0082 to 9G2999, or 9G3109 and later comply to the specifications in Table 4–17 and meet the Mini PCI specification. Lot codes appear at the top of the device.
- (3) The lot codes 9H0004 to 9H29999, or 9H3014 and later comply to the specifications in this table and meet the Mini PCI specification. Lot codes appear at the top of the device.

Designers should select power supplies and regulators that can supply this amount of current when designing with Cyclone devices. This specification is for commercial operating conditions. Measurements were performed with an isolated Cyclone device on the board. Decoupling capacitors were not used in this measurement. To factor in the current for decoupling capacitors, sum up the current for each capacitor using the following equation:

$$I = C (dV/dt)$$

The exact amount of current that is consumed varies according to the process, temperature, and power ramp rate. If the power supply or regulator can supply more current than required, the Cyclone device may consume more current than the maximum current specified in Table 4–17. However, the device does not require any more current to successfully power up than what is listed in Table 4–17.

The duration of the  $I_{CCINT}$  power-up requirement depends on the  $V_{CCINT}$  voltage supply rise time. The power-up current consumption drops when the  $V_{CCINT}$  supply reaches approximately 0.75 V. For example, if the  $V_{CCINT}$  rise time has a linear rise of 15 ms, the current consumption spike drops by 7.5 ms.

Typically, the user-mode current during device operation is lower than the power-up current in Table 4–17. Altera recommends using the Cyclone Power Calculator, available on the Altera web site, to estimate the user-mode  $I_{\text{CCINT}}$  consumption and then select power supplies or regulators based on the higher value.

# **Timing Model**

The DirectDrive technology and MultiTrack interconnect ensure predictable performance, accurate simulation, and accurate timing analysis across all Cyclone device densities and speed grades. This section describes and specifies the performance, internal, external, and PLL timing specifications.

All specifications are representative of worst-case supply voltage and junction temperature conditions.

### **Preliminary and Final Timing**

Timing models can have either preliminary or final status. The Quartus<sup>®</sup> II software issues an informational message during the design compilation if the timing models are preliminary. Table 4–18 shows the status of the Cyclone device timing models.

Preliminary status means the timing model is subject to change. Initially, timing numbers are created using simulation results, process data, and other known parameters. These tests are used to make the preliminary numbers as close to the actual timing parameters as possible.

Final timing numbers are based on actual device operation and testing. These numbers reflect the actual performance of the device under worst-case voltage and junction temperature conditions.

Table 4–18. Cyclone Device Timing Model Status					
Device	Preliminary	Final			
EP1C3	_	✓			
EP1C4	_	✓			
EP1C6	_	✓			
EP1C12	_	✓			
EP1C20	_	✓			

#### **Performance**

The maximum internal logic array clock tree frequency is limited to the specifications shown in Table 4–19.

Table 4–19. Clock Tree Maximum Performance Specification											
Parameter	Definition	-6 Speed Grade		-7 Speed Grade			-8 Speed Grade			Unito	
Parameter	Deminion	Min	Тур	Max	Min	Тур	Max	Min	Тур	Max	Units
Clock tree f <sub>MAX</sub>	Maximum frequency that the clock tree can support for clocking registered logic		_	405	_	_	320		_	275	MHz

Table 4–20 shows the Cyclone device performance for some common designs. All performance values were obtained with the Quartus II software compilation of library of parameterized modules (LPM) functions or megafunctions. These performance values are based on EP1C6 devices in 144-pin TQFP packages.

Table 4–20. Cyclone Device Performance								
			R	esources U	sed	Performance		
Resource Used	Design Size and Function	Mode	LEs	M4K Memory Bits	M4K Memory Blocks	-6 Speed Grade (MHz)	-7 Speed Grade (MHz)	-8 Speed Grade (MHz)
LE	16-to-1 multiplexer	_	21	_	_	405.00	320.00	275.00
	32-to-1 multiplexer	_	44	_	_	317.36	284.98	260.15
	16-bit counter	_	16	_	_	405.00	320.00	275.00
	64-bit counter (1)	_	66	_	_	208.99	181.98	160.75

			R	esources U	sed	Performance		
Resource Used	Design Size and Function	Mode	LEs	M4K Memory Bits	M4K Memory Blocks	-6 Speed Grade (MHz)	-7 Speed Grade (MHz)	-8 Speed Grade (MHz)
M4K	RAM 128 × 36 bit	Single port	_	4,608	1	256.00	222.67	197.01
memory block	RAM 128 × 36 bit	Simple dual-port mode	_	4,608	1	255.95	222.67	196.97
	RAM 256 × 18 bit	True dual- port mode	_	4,608	1	255.95	222.67	196.97
	FIFO 128 × 36 bit	_	40	4,608	1	256.02	222.67	197.01
	Shift register 9 × 4 × 128	Shift register	11	4,536	1	255.95	222.67	196.97

Note to Table 4-20:

# **Internal Timing Parameters**

Internal timing parameters are specified on a speed grade basis independent of device density. Tables 4–21 through 4–24 describe the Cyclone device internal timing microparameters for LEs, IOEs, M4K memory structures, and MultiTrack interconnects.

Table 4–21. LE Internal Timing Microparameter Descriptions					
Symbol	Parameter				
t <sub>SU</sub>	LE register setup time before clock				
t <sub>H</sub>	LE register hold time after clock				
t <sub>CO</sub>	LE register clock-to-output delay				
t <sub>LUT</sub>	LE combinatorial LUT delay for data-in to data-out				
t <sub>CLR</sub>	Minimum clear pulse width				
t <sub>PRE</sub>	Minimum preset pulse width				
t <sub>CLKHL</sub>	Minimum clock high or low time				

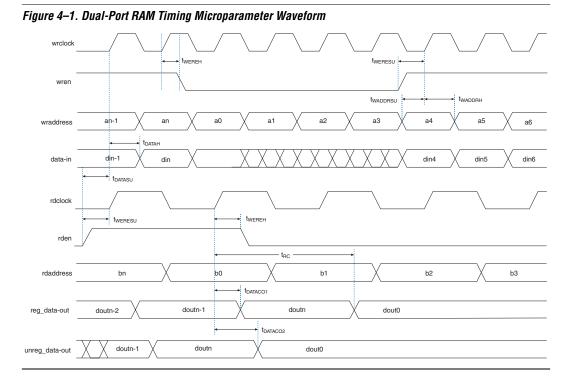
<sup>(1)</sup> The performance numbers for this function are from an EP1C6 device in a 240-pin PQFP package.

Table 4–22. IOE Internal Timing Microparameter Descriptions						
Symbol	Parameter					
t <sub>SU</sub>	IOE input and output register setup time before clock					
t <sub>H</sub>	IOE input and output register hold time after clock					
t <sub>CO</sub>	IOE input and output register clock-to-output delay					
t <sub>PIN2COMBOUT_R</sub>	Row input pin to IOE combinatorial output					
t <sub>PIN2COMBOUT_C</sub>	Column input pin to IOE combinatorial output					
t <sub>COMBIN2PIN_R</sub>	Row IOE data input to combinatorial output pin					
t <sub>COMBIN2PIN_C</sub>	Column IOE data input to combinatorial output pin					
t <sub>CLR</sub>	Minimum clear pulse width					
t <sub>PRE</sub>	Minimum preset pulse width					
t <sub>CLKHL</sub>	Minimum clock high or low time					

Table 4-23. M4	Table 4–23. M4K Block Internal Timing Microparameter Descriptions						
Symbol	Parameter						
t <sub>M4KRC</sub>	Synchronous read cycle time						
t <sub>M4KWC</sub>	Synchronous write cycle time						
t <sub>M4KWERESU</sub>	Write or read enable setup time before clock						
t <sub>M4KWEREH</sub>	Write or read enable hold time after clock						
t <sub>M4KBESU</sub>	Byte enable setup time before clock						
t <sub>M4KBEH</sub>	Byte enable hold time after clock						
t <sub>M4KDATAASU</sub>	A port data setup time before clock						
t <sub>M4KDATAAH</sub>	A port data hold time after clock						
t <sub>M4KADDRASU</sub>	A port address setup time before clock						
t <sub>M4KADDRAH</sub>	A port address hold time after clock						
t <sub>M4KDATABSU</sub>	B port data setup time before clock						
t <sub>M4KDATABH</sub>	B port data hold time after clock						
t <sub>M4KADDRBSU</sub>	B port address setup time before clock						
t <sub>M4KADDRBH</sub>	B port address hold time after clock						
t <sub>M4KDATACO1</sub>	Clock-to-output delay when using output registers						
t <sub>M4KDATACO2</sub>	Clock-to-output delay without output registers						
t <sub>M4KCLKHL</sub>	Minimum clock high or low time						
t <sub>M4KCLR</sub>	Minimum clear pulse width						

Table 4–24. Routing Delay Internal Timing Microparameter Descriptions							
Symbol Parameter							
t <sub>R4</sub>	Delay for an R4 line with average loading; covers a distance of four LAB columns						
t <sub>C4</sub>	Delay for an C4 line with average loading; covers a distance of four LAB rows						
t <sub>LOCAL</sub>	Local interconnect delay						

Figure 4–1 shows the memory waveforms for the M4K timing parameters shown in Table 4–23.



Internal timing parameters are specified on a speed grade basis independent of device density. Tables 4–25 through 4–28 show the internal timing microparameters for LEs, IOEs, TriMatrix memory structures, DSP blocks, and MultiTrack interconnects.

Table 4–25. LE Internal Timing Microparameters									
	-	-6		-7		-8			
Symbol	Min	Max	Min	Max	Min	Max	Unit		
t <sub>SU</sub>	29	_	33	_	37	_	ps		
t <sub>H</sub>	12	_	13	_	15	_	ps		
t <sub>CO</sub>	_	173	_	198	_	224	ps		
t <sub>LUT</sub>	_	454	_	522	_	590	ps		
t <sub>CLR</sub>	129	_	148	_	167	_	ps		
t <sub>PRE</sub>	129	_	148	_	167	_	ps		
t <sub>CLKHL</sub>	1,234	_	1,562	_	1,818	_	ps		

Table 4–26. IOE Internal Timing Microparameters									
Cumbal	-	6	_'	7	-8				
Symbol	Min	Max	Min	Max	Min	Max	Unit		
t <sub>SU</sub>	348	_	400	_	452	_	ps		
t <sub>H</sub>	0	_	0	_	0	_	ps		
t <sub>CO</sub>	_	511	_	587	_	664	ps		
t <sub>PIN2COMBOUT_R</sub>	_	1,130	_	1,299	_	1,469	ps		
t <sub>PIN2COMBOUT_C</sub>	_	1,135	_	1,305	_	1,475	ps		
t <sub>COMBIN2PIN_R</sub>	_	2,627	_	3,021	_	3,415	ps		
t <sub>COMBIN2PIN_C</sub>	_	2,615	_	3,007	_	3,399	ps		
t <sub>CLR</sub>	280	_	322	_	364	_	ps		
t <sub>PRE</sub>	280	_	322	_	364	_	ps		
t <sub>CLKHL</sub>	1,234	_	1,562	_	1,818	_	ps		

Table 4–27. M4K Block Internal Timing Microparameters									
Cumbal	-	-6		-7		-8			
Symbol	Min	Max	Min	Max	Min	Max	Unit		
t <sub>M4KRC</sub>	_	4,379		5,035		5,691	ps		
t <sub>M4KWC</sub>	_	2,910		3,346		3,783	ps		
t <sub>M4KWERESU</sub>	72	_	82	_	93	_	ps		
t <sub>M4KWEREH</sub>	43	_	49	_	55	_	ps		
t <sub>M4KBESU</sub>	72	_	82	_	93	_	ps		
t <sub>M4KBEH</sub>	43	_	49	_	55	_	ps		
t <sub>M4KDATAASU</sub>	72	_	82	_	93	_	ps		
t <sub>M4KDATAAH</sub>	43	_	49	_	55	_	ps		
t <sub>M4KADDRASU</sub>	72	_	82	_	93	_	ps		
t <sub>M4KADDRAH</sub>	43	_	49	_	55	_	ps		
t <sub>M4KDATABSU</sub>	72	_	82	_	93	_	ps		
t <sub>M4KDATABH</sub>	43	_	49	_	55	_	ps		
t <sub>M4KADDRBSU</sub>	72	_	82	_	93	_	ps		
t <sub>M4KADDRBH</sub>	43	_	49	_	55	_	ps		
t <sub>M4KDATACO1</sub>	_	621	_	714	_	807	ps		
t <sub>M4KDATACO2</sub>	_	4,351	_	5,003	_	5,656	ps		
t <sub>M4KCLKHL</sub>	1,234	_	1,562	_	1,818	_	ps		
t <sub>M4KCLR</sub>	286	_	328	_	371	_	ps		

Table 4–28. Routing Delay Internal Timing Microparameters									
Symbol	-	-6		-7		-8			
	Min	Max	Min	Max	Min	Max	Unit		
t <sub>R4</sub>	_	261	_	300	_	339	ps		
t <sub>C4</sub>	_	338	_	388	_	439	ps		
t <sub>LOCAL</sub>	_	244	_	281	_	318	ps		

# **External Timing Parameters**

External timing parameters are specified by device density and speed grade. Figure 4–2 shows the timing model for bidirectional IOE pin timing. All registers are within the IOE.

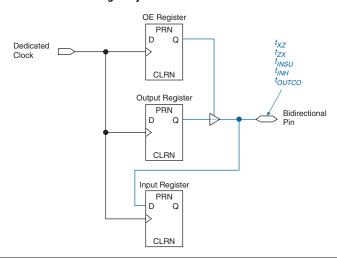


Figure 4-2. External Timing in Cyclone Devices

All external I/O timing parameters shown are for 3.3-V LVTTL I/O standard with the maximum current strength and fast slew rate. For external I/O timing using standards other than LVTTL or for different current strengths, use the I/O standard input and output delay adders in Tables 4–40 through 4–44.

Table 4–29 shows the external I/O timing parameters when using global clock networks.

Table 4–29. Cyclone Global Clock External I/O Timing Parameters         Notes (1), (2) (Part 1 of 2)								
Symbol	Parameter	Conditions						
t <sub>INSU</sub>	Setup time for input or bidirectional pin using IOE input register with global clock fed by CLK pin	_						
t <sub>INH</sub>	Hold time for input or bidirectional pin using IOE input register with global clock fed by CLK pin	_						
t <sub>оитсо</sub>	Clock-to-output delay output or bidirectional pin using IOE output register with global clock fed by CLK pin	C <sub>LOAD</sub> = 10 pF						
t <sub>INSUPLL</sub>	Setup time for input or bidirectional pin using IOE input register with global clock fed by Enhanced PLL with default phase setting	_						
t <sub>INHPLL</sub>	Hold time for input or bidirectional pin using IOE input register with global clock fed by enhanced PLL with default phase setting	_						

Table 4–29. C	yclone Global Clock External I/O Timing Parameters No	res (1), (2) <b>(Part 2 of 2)</b>
Symbol	Parameter	Conditions
toutcople	Clock-to-output delay output or bidirectional pin using IOE output register with global clock enhanced PLL with default phase setting	C <sub>LOAD</sub> = 10 pF

#### Notes to Table 4-29:

- (1) These timing parameters are sample-tested only.
- (2) These timing parameters are for IOE pins using a 3.3-V LVTTL, 24-mA setting. Designers should use the Quartus II software to verify the external timing for any pin.

Tables 4–30 through 4–31 show the external timing parameters on column and row pins for EP1C3 devices.

Table 4–30. EP1C3 Column Pin Global Clock External I/O Timing Parameters									
	-6 Spee	d Grade	-7 Spee	d Grade	-8 Spee				
Symbol	Min	Max	Min	Max	Min	Max	Unit		
t <sub>INSU</sub>	3.085	_	3.547	_	4.009	_	ns		
t <sub>INH</sub>	0.000	_	0.000	_	0.000	_	ns		
toutco	2.000	4.073	2.000	4.682	2.000	5.295	ns		
t <sub>INSUPLL</sub>	1.795	_	2.063	_	2.332	_	ns		
t <sub>INHPLL</sub>	0.000	_	0.000	_	0.000	_	ns		
toutcople	0.500	2.306	0.500	2.651	0.500	2.998	ns		

Table 4–31. EP1C3 Row Pin Global Clock External I/O Timing Parameters									
	-6 Speed Grade		-7 Spee	d Grade	-8 Spee	1124			
Symbol	Min	Max	Min	Max	Min	Max	Unit		
t <sub>INSU</sub>	3.157	_	3.630	_	4.103	_	ns		
t <sub>INH</sub>	0.000	_	0.000	_	0.000	_	ns		
t <sub>outco</sub>	2.000	3.984	2.000	4.580	2.000	5.180	ns		
t <sub>INSUPLL</sub>	1.867	_	2.146	_	2.426	_	ns		
t <sub>INHPLL</sub>	0.000	_	0.000	_	0.000	_	ns		
toutcople	0.500	2.217	0.500	2.549	0.500	2.883	ns		

Tables 4–32 through 4–33 show the external timing parameters on column and row pins for EP1C4 devices.

Table 4–32. EP1C4 Column Pin Global Clock External I/O Timing Parameters Note (1)

Oursh al	-6 Spee	d Grade	-7 Spee	d Grade	-8 Spee	II mit	
Symbol	Min	Max	Min	Max	Min	Max	Unit
t <sub>INSU</sub>	2.471	_	2.841	_	3.210	_	ns
t <sub>INH</sub>	0.000	_	0.000	_	0.000	_	ns
toutco	2.000	3.937	2.000	4.526	2.000	5.119	ns
t <sub>INSUPLL</sub>	1.471	_	1.690	_	1.910	_	ns
t <sub>INHPLL</sub>	0.000	_	0.000	_	0.000	_	ns
toutcople	0.500	2.080	0.500	2.392	0.500	2.705	ns

Table 4–33. EP1C4 Row Pin Global Clock External I/O Timing Parameters Note (1)

Cumbal	-6 Speed Grade		-7 Spee	-7 Speed Grade		d Grade	Hait
Symbol	Min	Max	Min	Max	Min	Max	Unit
t <sub>INSU</sub>	2.600	_	2.990	_	3.379	_	ns
t <sub>INH</sub>	0.000	_	0.000	_	0.000	_	ns
t <sub>outco</sub>	2.000	3.991	2.000	4.388	2.000	5.189	ns
t <sub>INSUPLL</sub>	1.300	_	1.494	_	1.689	_	ns
t <sub>INHPLL</sub>	0.000	_	0.000	_	0.000	_	ns
toutcople	0.500	2.234	0.500	2.569	0.500	2.905	ns

*Note to Tables 4–32 and 4–33:* 

<sup>(1)</sup> Contact Altera Applications for EP1C4 device timing parameters.

Tables 4–34 through 4–35 show the external timing parameters on column and row pins for EP1C6 devices.

Table 4-34	Table 4–34. EP1C6 Column Pin Global Clock External I/O Timing Parameters											
Cumbal	-6 Spee	d Grade	-7 Spee	d Grade	-8 Spee	Unit						
Symbol	Min	Max	Min	Max	Min	Max	UIIIL					
t <sub>INSU</sub>	2.691	_	3.094	_	3.496	_	ns					
t <sub>INH</sub>	0.000	_	0.000		0.000	_	ns					
toutco	2.000	3.917	2.000	4.503	2.000	5.093	ns					
t <sub>INSUPLL</sub>	1.513	_	1.739	_	1.964	_	ns					
t <sub>INHPLL</sub>	0.000	_	0.000	_	0.000	_	ns					
toutcople	0.500	2.038	0.500	2.343	0.500	2.651	ns					

Table 4–35. EP1C6 Row Pin Global Clock External I/O Timing Parameters											
Cumbal	-6 Spee	d Grade	-7 Spee	d Grade	-8 Spee	Unit					
Symbol	Min	Max	Min	Max	Min	Min Max					
t <sub>INSU</sub>	2.774	_	3.190	_	3.605	_	ns				
t <sub>INH</sub>	0.000	_	0.000	_	0.000	_	ns				
toutco	2.000	3.817	2.000	4.388	2.000	4.963	ns				
t <sub>INSUPLL</sub>	1.596	_	1.835	_	2.073	_	ns				
t <sub>INHPLL</sub>	0.000	_	0.000	_	0.000	_	ns				
toutcople	0.500	1.938	0.500	2.228	0.500	2.521	ns				

Tables 4–36 through 4–37 show the external timing parameters on column and row pins for EP1C12 devices.

Table 4–36. Parameters			n Global (	Clock Exte	rnal I/O Ti	ming					
Cumbal	-6 Speed Grade -7 Speed Grade -8 Speed Grade										
Symbol	Min	Max	Min	Max	Min	Max	Unit				
t <sub>INSU</sub>	2.510	_	2.885	_	3.259	_	ns				
t <sub>INH</sub>	0.000	_	0.000	_	0.000	_	ns				
tO <sub>UTCO</sub>	2.000	3.798	2.000	4.367	2.000	4.940	ns				
t <sub>INSUPLL</sub>	1.588		1.824	_	2.061	_	ns				

Table 4–36. EP1C12 Column Pin Global Clock External I/O Timing Parameters (Part 2 of 2)

Symbol	-6 Spee	d Grade	-7 Spee	-8 Spee	Unit		
Syllibol	Min	Max	Min	Max	Min Max		Oiiit
t <sub>INHPLL</sub>	0.000	_	0.000	_	0.000	_	ns
toutcople	0.500	1.663	0.500	1.913	0.500	2.164	ns

Table 4-37	Table 4–37. EP1C12 Row Pin Global Clock External I/O Timing Parameters											
Cumbal	-6 Spee	d Grade	-7 Spee	d Grade	-8 Spee	Unit						
Symbol	Min	Max	Min	Max	Min	Max	UIII					
t <sub>INSU</sub>	2.620	_	3.012	_	3.404	_	ns					
t <sub>INH</sub>	0.000	_	0.000	_	0.000	_	ns					
toutco	2.000	3.671	2.000	4.221	2.000	4.774	ns					
t <sub>INSUPLL</sub>	1.698	_	1.951	_	2.206	_	ns					
t <sub>INHPLL</sub>	0.000	_	0.000	_	0.000	_	ns					
toutcople	0.500	1.536	0.500	1.767	0.500	1.998	ns					

Tables 4-38 through 4-39 show the external timing parameters on column and row pins for EP1C20 devices.

Table 4–38 Parameters		Column P	in Global	Clock Exte	ernal I/O 1	iming	
Cumbal	-6 Spee	d Grade	-7 Spee	d Grade	-8 Spee	Heit	
Symbol	Min	Max	Min	Max	Min	Max	Unit
t <sub>INSU</sub>	2.417	_	2.779	_	3.140	_	ns
t <sub>INH</sub>	0.000	_	0.000	_	0.000	_	ns
toutco	2.000	3.724	2.000	4.282	2.000	4.843	ns
t <sub>INSUPLL</sub>	1.417	_	1.629	_	1.840	_	ns
t <sub>INHPLL</sub>	0.000	_	0.000	_	0.000	_	ns
toutcople	0.500	1.667	0.500	1.917	0.500	2.169	ns

Table 4-39	Table 4–39. EP1C20 Row Pin Global Clock External I/O Timing Parameters											
Cumbal	-6 Speed Grade		-7 Spee	-7 Speed Grade		-8 Speed Grade						
Symbol	Min	Max	Min	Max	Min	Max	Unit					
t <sub>INSU</sub>	2.417	_	2.779	_	3.140	_	ns					
t <sub>INH</sub>	0.000	_	0.000	_	0.000	_	ns					
toutco	2.000	3.724	2.000	4.282	2.000	4.843	ns					
t <sub>XZ</sub>	_	3.645	_	4.191	_	4.740	ns					
t <sub>ZX</sub>	_	3.645	_	4.191	_	4.740	ns					
t <sub>INSUPLL</sub>	1.417	_	1.629	_	1.840	_	ns					
t <sub>INHPLL</sub>	0.000	_	0.000	_	0.000	_	ns					
toutcople	0.500	1.667	0.500	1.917	0.500	2.169	ns					
t <sub>XZPLL</sub>	_	1.588	_	1.826	_	2.066	ns					
t <sub>ZXPLL</sub>	_	1.588	1	1.826	_	2.066	ns					

### **External I/O Delay Parameters**

External I/O delay timing parameters for I/O standard input and output adders and programmable input and output delays are specified by speed grade independent of device density.

Tables 4–40 through 4–45 show the adder delays associated with column and row I/O pins for all packages. If an I/O standard is selected other than LVTTL 4 mA with a fast slew rate, add the selected delay to the external  $t_{CO}$  and  $t_{SU}$  I/O parameters shown in Tables 4–25 through 4–28.

Table 4–40. Cyclone I/O S	tandard Col	umn Pin Inp	ut Delay Adı	ders (Part 1	of 2)		
I/O Standard	-6 Speed Grade		-7 Spee	d Grade	-8 Spee	Heit	
I/O Standard	Min	Max	Min	Max	Min	Max	Unit
LVCMOS	_	0	_	0	_	0	ps
3.3-V LVTTL	_	0	_	0	_	0	ps
2.5-V LVTTL	_	27	_	31	_	35	ps
1.8-V LVTTL	_	182	_	209	_	236	ps
1.5-V LVTTL	_	278	_	319	_	361	ps
SSTL-3 class I	_	-250	_	-288	_	-325	ps
SSTL-3 class II		-250		-288		-325	ps
SSTL-2 class I		-278		-320		-362	ps

Table 4–40. Cyclone I/O S	tandard Col	umn Pin Inp	ut Delay Ad	ders (Part 2	of 2)			
-6 Speed Grade -7 Speed Grade -8 Speed Grade								
I/O Standard	Min	Max	Min	Max	Min	Unit		
SSTL-2 class II		-278	_	-320	_	-362	ps	
LVDS		-261	_	-301	_	-340	ps	

Table 4–41. Cyclone I/O S	Table 4–41. Cyclone I/O Standard Row Pin Input Delay Adders									
I/O Standard	-6 Speed Grade		-7 Spee	ed Grade	-8 Spee	11-24				
I/O Standard	Min	Max	Min	Max	Min	Max	Unit			
LVCMOS	_	0	_	0	_	0	ps			
3.3-V LVTTL	_	0	_	0	_	0	ps			
2.5-V LVTTL	_	27	_	31	_	35	ps			
1.8-V LVTTL	_	182	_	209	_	236	ps			
1.5-V LVTTL	_	278	_	319	_	361	ps			
3.3-V PCI (1)	_	0	_	0	_	0	ps			
SSTL-3 class I	_	-250	_	-288	_	-325	ps			
SSTL-3 class II	_	-250	_	-288	_	-325	ps			
SSTL-2 class I	_	-278	_	-320	_	-362	ps			
SSTL-2 class II	_	-278	_	-320	_	-362	ps			
LVDS	_	-261	_	-301	_	-340	ps			

Standard		-6 Speed Grade		-7 Spe	ed Grade	-8 Spe	ed Grade	Unit
Stallt	iaru	Min	Max	Min	Max	Min	Min Max	
LVCMOS	2 mA	_	0	_	0	_	0	ps
	4 mA	_	-489	_	-563	_	-636	ps
	8 mA	_	-855	_	-984	_	-1,112	ps
	12 mA	_	-993	_	-1,142	_	-1,291	ps
3.3-V LVTTL	4 mA	_	0	_	0	_	0	ps
	8 mA	_	-347	_	-400	_	-452	ps
	12 mA	_	-858	_	-987	_	-1,116	ps
	16 mA	_	-819	_	-942	_	-1,065	ps
	24 mA	_	-993	_	-1,142	_	-1,291	ps

Table 4–42. Cyclone I/O Standard Output Delay Adders for Fast Slew Rate on Column Pins (Part 2 of 2)										
Standard		-6 Speed Grade		-7 Speed Grade		-8 Speed Grade		II.a.ii		
		Min	Max	Min	Max	Min	Max	Unit		
2.5-V LVTTL	2 mA	_	329	_	378	_	427	ps		
	8 mA	_	-661	_	-761	_	-860	ps		
	12 mA	_	-655	_	-754	_	-852	ps		
	16 mA	_	-795	_	-915	_	-1034	ps		
1.8-V LVTTL	2 mA	_	4	_	4	_	5	ps		
	8 mA	_	-208	_	-240	_	-271	ps		
	12 mA	_	-208	_	-240	_	-271	ps		
1.5-V LVTTL	2 mA	_	2,288	_	2,631	_	2,974	ps		
	4 mA	_	608	_	699	_	790	ps		
	8 mA	_	292	_	335	_	379	ps		
SSTL-3 class I		_	-410	_	-472	_	-533	ps		
SSTL-3 class II		_	-811	_	-933	_	-1,055	ps		
SSTL-2 class I		_	-485	_	-558	_	-631	ps		
SSTL-2 class II		_	-758	_	-872	_	-986	ps		
LVDS		_	-998	_	-1,148	_	-1,298	ps		

Table 4–43. Cyclone I/O Standard Output Delay Adders for Fast Slew Rate on Row Pins (Part 1 of 2)										
Standard		-6 Speed Grade		-7 Speed Grade		-8 Speed Grade		II:A		
		Min	Max	Min	Max	Min	Max	Unit		
LVCMOS	2 mA	_	0	_	0	_	0	ps		
	4 mA	_	-489	_	-563	_	-636	ps		
	8 mA	_	-855	_	-984	_	-1,112	ps		
	12 mA	_	-993	_	-1,142	_	-1,291	ps		
3.3-V LVTTL	4 mA	_	0	_	0	_	0	ps		
	8 mA	_	-347	_	-400	_	-452	ps		
	12 mA	_	-858	_	-987	_	-1,116	ps		
	16 mA	_	-819	_	-942	_	-1,065	ps		
	24 mA	_	-993	_	-1,142	_	-1,291	ps		
2.5-V LVTTL	2 mA	_	329	_	378	_	427	ps		
	8 mA	_	-661	_	-761	_	-860	ps		
	12 mA	_	-655	_	-754	_	-852	ps		
	16 mA	_	-795	_	-915	_	-1,034	ps		

Table 4-43. (	Cyclone I/O S	Standard Out	tput Delay A	dders for Fa	st Slew Rate	on Row Pi	ns (Part 2 o	f 2)
Standard		-6 Spee	ed Grade	-7 Speed Grade		-8 Speed Grade		11
Stanu	Statiuaru		Max	Min	Max	Min	Max	Unit
1.8-V LVTTL	2 mA	_	1,290	_	1,483	_	1,677	ps
	8 mA	_	4	_	4	_	5	ps
	12 mA	_	-208	_	-240	_	-271	ps
1.5-V LVTTL	2 mA	_	2,288	_	2,631	_	2,974	ps
	4 mA	_	608	_	699	_	790	ps
	8 mA	_	292	_	335	_	379	ps
3.3-V PCI (1)		_	-877	_	-1,009	_	-1,141	ps
SSTL-3 class I		_	-410	_	-472	_	-533	ps
SSTL-3 class I	I	_	-811	_	-933	_	-1,055	ps
SSTL-2 class I		_	-485	_	-558	_	-631	ps
SSTL-2 class I	I	_	-758	_	-872	_	-986	ps
LVDS		_	-998	_	-1,148	_	-1,298	ps

I/O Standard		-6 Speed Grade		-7 Speed Grade		-8 Speed Grade		II.a.ii
1/0 51a	nuaru	Min	Max	Min	Max	Min	Max	Unit
LVCMOS	2 mA	_	1,800	_	2,070	_	2,340	ps
	4 mA	_	1,311	_	1,507	_	1,704	ps
	8 mA	_	945	_	1,086	_	1,228	ps
	12 mA	_	807	_	928	_	1,049	ps
3.3-V LVTTL	4 mA	_	1,831	_	2,105	_	2,380	ps
	8 mA	_	1,484	_	1,705	_	1,928	ps
	12 mA	_	973	_	1,118	_	1,264	ps
	16 mA	_	1,012	_	1,163	_	1,315	ps
	24 mA	_	838	_	963	_	1,089	ps
2.5-V LVTTL	2 mA	_	2,747	_	3,158	_	3,570	ps
	8 mA	_	1,757	_	2,019	_	2,283	ps
	12 mA	_	1,763	_	2,026	_	2,291	ps
	16 mA	_	1,623	_	1,865	_	2,109	ps
1.8-V LVTTL	2 mA	_	5,506	_	6,331	_	7,157	ps
	8 mA	_	4,220	_	4,852	_	5,485	ps
	12 mA	_	4,008	_	4,608	_	5,209	ps

Table 4-44. 0	Table 4–44. Cyclone I/O Standard Output Delay Adders for Slow Slew Rate on Column Pins (Part 2 of 2)									
I/O Standard		-6 Speed Grade		-7 Speed Grade		-8 Speed Grade				
i/U Star	iuaru	Min	Max	Min	Max	Min	Max	Unit		
1.5-V LVTTL	2 mA	_	6,789	_	7,807	_	8,825	ps		
	4 mA	_	5,109	_	5,875	_	6,641	ps		
	8 mA	_	4,793	_	5,511	_	6,230	ps		
SSTL-3 class I		_	1,390	_	1,598	_	1,807	ps		
SSTL-3 class I	I	_	989	_	1,137	_	1,285	ps		
SSTL-2 class I		_	1,965	_	2,259	_	2,554	ps		
SSTL-2 class I	I	_	1,692	_	1,945		2,199	ps		
LVDS	·	_	802	_	922	_	1,042	ps		

Table 4-45.		1		i		1		1
I/O Sta	ndard	-6 Spee	ed Grade	-7 Speed Grade		-8 Speed Grade		Unit
1,001		Min	Max	Min	Max	Min	Max	J
LVCMOS	2 mA	_	1,800	_	2,070	_	2,340	ps
	4 mA	_	1,311	_	1,507	_	1,704	ps
	8 mA	_	945	_	1,086	_	1,228	ps
	12 mA	_	807	_	928	_	1,049	ps
3.3-V LVTTL	4 mA	_	1,831	_	2,105	_	2,380	ps
	8 mA	_	1,484	_	1,705	_	1,928	ps
	12 mA	_	973	_	1,118	_	1,264	ps
	16 mA	_	1,012	_	1,163	_	1,315	ps
	24 mA	_	838	_	963	_	1,089	ps
2.5-V LVTTL	2 mA	_	2,747	_	3,158	_	3,570	ps
	8 mA	_	1,757	_	2,019	_	2,283	ps
	12 mA	_	1,763	_	2,026	_	2,291	ps
	16 mA	_	1,623	_	1,865	_	2,109	ps
1.8-V LVTTL	2 mA	_	5,506	_	6,331	_	7,157	ps
	8 mA	_	4,220	_	4,852	_	5,485	ps
	12 mA	_	4,008	_	4,608	_	5,209	ps
1.5-V LVTTL	2 mA	_	6,789	_	7,807	_	8,825	ps
	4 mA	_	5,109	_	5,875	_	6,641	ps
	8 mA	_	4,793	_	5,511	_	6,230	ps
3.3-V PCI		_	923	_	1,061	_	1,199	ps

Table 4–45. Cyclone I/O Standard Output Delay Adders for Slow Slew Rate on Row Pins (Part 2 of 2)									
I/O Standard	-6 Spe	-6 Speed Grade		-7 Speed Grade		-8 Speed Grade			
	Min	Max	Min	Max	Min	Max	Unit		
SSTL-3 class I	_	1,390	_	1,598	_	1,807	ps		
SSTL-3 class II	_	989	_	1,137	_	1,285	ps		
SSTL-2 class I	_	1,965	_	2,259	_	2,554	ps		
SSTL-2 class II	_	1,692	_	1,945	_	2,199	ps		
LVDS	_	802	_	922	_	1,042	ps		

*Note to Tables 4–40 through 4–45:* 

Tables 4–46 through 4–47 show the adder delays for the IOE programmable delays. These delays are controlled with the Quartus II software options listed in the Parameter column.

Table 4–46. Cyclone 10	Table 4–46. Cyclone IOE Programmable Delays on Column Pins									
Parameter	Setting	-6 Speed Grade		-7 Speed Grade		-8 Speed Grade		11		
Parameter		Min	Max	Min	Max	Min	Max	Unit		
Decrease input delay to internal cells	Off	_	155	_	178	_	201	ps		
	Small	_	2,122	_	2,543	_	2,875	ps		
	Medium	_	2,639	_	3,034	_	3,430	ps		
	Large	_	3,057	_	3,515	_	3,974	ps		
	On	_	155	_	178	_	201	ps		
Decrease input delay to	Off	_	0	_	0	_	0	ps		
input register	On	_	3,057	_	3,515	_	3,974	ps		
Increase delay to output	Off	_	0	_	0	_	0	ps		
pin	On	_	552	_	634	_	717	ps		

<sup>(1)</sup> EP1C3 devices do not support the PCI I/O standard.

Table 4–47. Cyclone IOE Programmable Delays on Row Pins										
Davamatav	Setting	-6 Speed Grade		-7 Speed Grade		-8 Speed Grade		IIiA		
Parameter		Min	Max	Min	Max	Min	Max	Unit		
Decrease input delay to internal cells	Off	_	154	_	177	_	200	ps		
	Small	_	2,212	_	2,543	_	2,875	ps		
	Medium	_	2,639	_	3,034	_	3,430	ps		
	Large	_	3,057	_	3,515	_	3,974	ps		
	On	_	154	_	177	_	200	ps		
Decrease input delay to input	Off	_	0	_	0	_	0	ps		
register	On	_	3,057	_	3,515	_	3,974	ps		
Increase delay to output pin	Off	_	0	_	0	_	0	ps		
	On	_	556	_	639	_	722	ps		

Note to Table 4-47:

## **Maximum Input and Output Clock Rates**

Tables  $4\hbox{--}48$  and  $4\hbox{--}49$  show the maximum input clock rate for column and row pins in Cyclone devices.

Table 4–48. Cyclone Maximum Input Clock Rate for Column Pins								
I/O Standard	-6 Speed Grade	-7 Speed Grade	-8 Speed Grade	Unit				
LVTTL	464	428	387	MHz				
2.5 V	392	302	207	MHz				
1.8 V	387	311	252	MHz				
1.5 V	387	320	243	MHz				
LVCMOS	405	374	333	MHz				
SSTL-3 class I	405	356	293	MHz				
SSTL-3 class II	414	365	302	MHz				
SSTL-2 class I	464	428	396	MHz				
SSTL-2 class II	473	432	396	MHz				
LVDS	567	549	531	MHz				

<sup>(1)</sup> EPC1C3 devices do not support the PCI I/O standard.

Table 4–49. Cyclone Maximum Input Clock Rate for Row Pins								
I/O Standard	-6 Speed Grade	-7 Speed Grade	-8 Speed Grade	Unit				
LVTTL	464	428	387	MHz				
2.5 V	392	302	207	MHz				
1.8 V	387	311	252	MHz				
1.5 V	387	320	243	MHz				
LVCMOS	405	374	333	MHz				
SSTL-3 class I	405	356	293	MHz				
SSTL-3 class II	414	365	302	MHz				
SSTL-2 class I	464	428	396	MHz				
SSTL-2 class II	473	432	396	MHz				
3.3-V PCI (1)	464	428	387	MHz				
LVDS	567	549	531	MHz				

Note to Tables 4–48 through 4–49:

Tables 4–50 and 4–51 show the maximum output clock rate for column and row pins in Cyclone devices.

Table 4–50. Cyclone Max	Table 4–50. Cyclone Maximum Output Clock Rate for Column Pins								
I/O Standard	-6 Speed Grade	-7 Speed Grade	-8 Speed Grade	Unit					
LVTTL	304	304	304	MHz					
2.5 V	220	220	220	MHz					
1.8 V	213	213	213	MHz					
1.5 V	166	166	166	MHz					
LVCMOS	304	304	304	MHz					
SSTL-3 class I	100	100	100	MHz					
SSTL-3 class II	100	100	100	MHz					
SSTL-2 class I	134	134	134	MHz					
SSTL-2 class II	134	134	134	MHz					
LVDS	320	320	275	MHz					

Note to Table 4-50:

(1) EP1C3 devices do not support the PCI I/O standard.

<sup>(1)</sup> EP1C3 devices do not support the PCI I/O standard. These parameters are only available on row I/O pins.

Table 4–51. Cyclone Maximum Output Clock Rate for Row Pins								
I/O Standard	-6 Speed Grade	-7 Speed Grade	-8 Speed Grade	Unit				
LVTTL	296	285	273	MHz				
2.5 V	381	366	349	MHz				
1.8 V	286	277	267	MHz				
1.5 V	219	208	195	MHz				
LVCMOS	367	356	343	MHz				
SSTL-3 class I	169	166	162	MHz				
SSTL-3 class II	160	151	146	MHz				
SSTL-2 class I	160	151	142	MHz				
SSTL-2 class II	131	123	115	MHz				
3.3-V PCI (1)	66	66	66	MHz				
LVDS	320	303	275	MHz				

*Note to Tables 4–50 through 4–51:* 

## **PLL Timing**

Table 4–52 describes the Cyclone FPGA PLL specifications.

Table 4–52. Cyclone PLL Specifications (Part 1 of 2)								
Symbol	Parameter	Min	Max	Unit				
f <sub>IN</sub>	Input frequency (-6 speed grade)	15.625	464	MHz				
	Input frequency (-7 speed grade)	15.625	428	MHz				
	Input frequency (-8 speed grade)	15.625	387	MHz				
f <sub>IN</sub> DUTY	Input clock duty cycle	40.00	60	%				
t <sub>IN</sub> JITTER	Input clock period jitter	_	± 200	ps				
f <sub>OUT_EXT</sub> (external PLL clock output)	PLL output frequency (-6 speed grade)	15.625	320	MHz				
	PLL output frequency (-7 speed grade)	15.625	320	MHz				
	PLL output frequency (-8 speed grade)	15.625	275	MHz				

<sup>(1)</sup> EP1C3 devices do not support the PCI I/O standard. These parameters are only available on row I/O pins.

Table 4–52. Cyclone PLL Specifications (Part 2 of 2)							
Symbol	Parameter	Min	Max	Unit			
f <sub>OUT</sub> (to global clock)	PLL output frequency (-6 speed grade)	15.625	405	MHz			
	PLL output frequency (-7 speed grade)	15.625	320	MHz			
	PLL output frequency (-8 speed grade)	15.625	275	MHz			
t <sub>OUT</sub> DUTY	Duty cycle for external clock output (when set to 50%)	45.00	55	%			
t <sub>JITTER</sub> (1)	Period jitter for external clock output	_	±300 (2)	ps			
t <sub>LOCK</sub> (3)	Time required to lock from end of device configuration	10.00	100	μs			
f <sub>VCO</sub>	PLL internal VCO operating range	500.00	1,000	MHz			
-	Minimum areset time	10	_	ns			
N, G0, G1, E	Counter values	1	32	integer			

#### Notes to Table 4-52:

- (1) The t<sub>JITTER</sub> specification for the PLL[2..1]\_OUT pins are dependent on the I/O pins in its V<sub>CCIO</sub> bank, how many of them are switching outputs, how much they toggle, and whether or not they use programmable current strength or slow slew rate.
- (2)  $f_{OUT} \ge 100$  MHz. When the PLL external clock output frequency ( $f_{OUT}$ ) is smaller than 100 MHz, the jitter specification is 60 mUI.
- (3)  $f_{IN/N}$  must be greater than 200 MHz to ensure correct lock detect circuit operation below -20 C. Otherwise, the PLL operates with the specified parameters under the specified conditions.

## Referenced Document

This chapter references the following documents:

- Cyclone Architecture chapter in the Cyclone Device Handbook
- Operating Requirements for Altera Devices Data Sheet

## Document Revision History

Table 4–53 shows the revision history for this chapter.

Table 4–53. Document Revision History					
Date and Document Version	Changes Made	Summary of Changes			
May 2008 v1.7	Minor textual and style changes. Added "Referenced Document" section.	_			
January 2007 v1.6	<ul> <li>Added document revision history.</li> <li>Added new row for V<sub>CCA</sub> details in Table 4–1.</li> <li>Updated R<sub>CONF</sub> information in Table 4–3.</li> <li>Added new <i>Note</i> (12) on voltage overdrive information to Table 4–7 and Table 4–8.</li> <li>Updated <i>Note</i> (9) on R<sub>CONF</sub> information to Table 4–3.</li> <li>Updated information in "External I/O Delay Parameters" section.</li> <li>Updated speed grade information in Table 4–46 and Table 4–47.</li> <li>Updated LVDS information in Table 4–51.</li> </ul>	_			
August 2005 v1.5	Minor updates.	_			
February 2005 v1.4	<ul> <li>Updated information on Undershoot voltage. Updated Table 4-2.</li> <li>Updated Table 4-3.</li> <li>Updated the undershoot voltage from 0.5 V to 2.0 V in Note 3 of Table 4-16.</li> <li>Updated Table 4-17.</li> </ul>	_			
January 2004 v.1.3	<ul> <li>Added extended-temperature grade device information.</li> <li>Updated Table 4-2.</li> <li>Updated I<sub>CC0</sub> information in Table 4-3.</li> </ul>	_			
October 2003 v.1.2	<ul> <li>Added clock tree information in Table 4-19.</li> <li>Finalized timing information for EP1C3 and EP1C12 devices.         Updated timing information in Tables 4-25 through 4-26 and Tables 4-30 through 4-51.     </li> <li>Updated PLL specifications in Table 4-52.</li> </ul>	_			

July 2003 v1.1	Updated timing information. Timing finalized for EP1C6 and EP1C20 devices. Updated performance information. Added PLL Timing section.	_
May 2003 v1.0	Added document to Cyclone Device Handbook.	_



## 5. Reference and Ordering Information

C51005-1.4

## Software

Cyclone® devices are supported by the Altera® Quartus® II design software, which provides a comprehensive environment for system-on-a-programmable-chip (SOPC) design. The Quartus II software includes HDL and schematic design entry, compilation and logic synthesis, full simulation and advanced timing analysis, SignalTap® II logic analysis, and device configuration.



For more information about the Quartus II software features, refer to the *Quartus II Handbook*.

The Quartus II software supports the Windows 2000/NT/98, Sun Solaris, Linux Red Hat v7.1 and HP-UX operating systems. It also supports seamless integration with industry-leading EDA tools through the NativeLink® interface.

## **Device Pin-Outs**

Device pin-outs for Cyclone devices are available on the Altera website (www.altera.com) and in the *Cyclone Device Handbook*.

## Ordering Information

Figure 5–1 describes the ordering codes for Cyclone devices. For more information about a specific package, refer to the *Package Information for Cyclone Devices* chapter in the *Cyclone Device Handbook*.

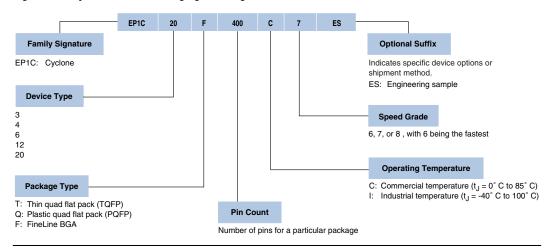


Figure 5-1. Cyclone Device Packaging Ordering Information

## Referenced Documents

This chapter references the following documents:

- Package Information for Cyclone Devices chapter in the Cyclone Device Handbook
- Quartus II Handbook

## Document Revision History

Table 5–1 shows the revision history for this chapter.

Table 5–1. Document Revision History					
Date and Document Version	Changes Made	Summary of Changes			
May 2008 v1.4	Minor textual and style changes. Added "Referenced Documents" section.	_			
January 2007 v1.3	Added document revision history.	_			
August 2005 v1.2	Minor updates.	_			

February 2005 v1.1	Updated Figure 5-1.	_
May 2003 v1.0	Added document to Cyclone Device Handbook.	_



# Section II. Clock Management

This section provides information on the Cyclone phase-lock loops (PLLs). The PLLs assist designers in managing clocks internally and also have the ability to drive off chip to control system-level clock networks. This chapter contains detailed information on the features, the interconnections to the logic array and off chip, and the specifications for Cyclone PLLs.

This section contains the following chapter:

Chapter 6. Using PLLs in Cyclone Devices

## **Revision History**

Refer to each chapter for its own specific revision history. For information on when each chapter was updated, refer to the Chapter Revision Dates section, which appears in the complete handbook.

Altera Corporation Section II–1

Section II-2 Altera Corporation



## 6. Using PLLs in Cyclone Devices

C51006-1.5

## Introduction

Cyclone® FPGAs offer phase locked loops (PLLs) and a global clock network for clock management solutions. Cyclone PLLs offer clock multiplication and division, phase shifting, programmable duty cycle, and external clock outputs, allowing system-level clock management and skew control. The Altera® Quartus® II software enables Cyclone PLLs and their features without using any external devices. This chapter explains how to design and enable Cyclone PLL features.

PLLs are commonly used to synchronize internal device clocks with an external clock, run internal clocks at higher frequencies than an external clock, minimize clock delay and clock skew, and reduce or adjust clock-to-out ( $t_{CO}$ ) and set-up ( $t_{SU}$ ) times.

#### **Hardware Overview**

Cyclone FPGAs contain up to two PLLs per device. Table 6–1 shows which PLLs are available for each Cyclone FPGA.

Table 6–1. Cyclone FPGA PLL Availability				
Device	PLL1 (1)	PLL2 (2)		
EP1C3	✓	_		
EP1C4	✓	✓		
EP1C6	✓	✓		
EP1C12	✓	✓		
EP1C20	✓	✓		

#### Notes to Table 6-1:

- (1) Located on the center left side of the device.
- (2) Located on the center right side of the device.

Table 6–2 provides an overview of available Cyclone PLL features.

Table 6–2. Cyclone PLL Features					
Feature	Description				
Clock multiplication and division	$M/(N \times post-scale counter)$ (1)				
Phase shift	Down to 125-ps increments (2), (3)				
Programmable duty cycle	<b>✓</b>				
Number of internal clock outputs	Two per PLL				
Number of external clock outputs (4)	One per PLL				
Locked port can feed logic array	✓				
PLL clock outputs can feed logic array	✓				

#### Notes to Table 6-2:

- (1) M, N, and post-scale counter values range from 1 to 32.
- (2) The smallest phase shift is determined by the Voltage Control Oscillator (VCO) period divided by 8.
- (3) For degree increments, Cyclone FPGAs can shift output frequencies in increments of at least 45°. Smaller degree increments are possible depending on the multiplication/division ratio needed on the PLL clock output.
- (4) The EP1C3 device in the 100-pin thin quad flat pack (TQFP) package does not have support for a PLL LVDS input or an external clock output. The EP1C6 PLL2 in the 144-pin TQFP package does not support an external clock output.

#### Cyclone PLL Blocks

The main goal of a PLL is to synchronize the phase and frequency of an internal/external clock to an input reference clock. There are a number of components that comprise a PLL to achieve this phase alignment.

Cyclone PLLs align the rising edge of the reference input clock to a feedback clock using a phase-frequency detector (PFD). The falling edges are determined by the duty cycle specifications. The PFD produces an up or down signal that determines whether the VCO needs to operate at a higher or lower frequency. The PFD output is applied to the charge pump and loop filter, which produces a control voltage for setting the frequency of the VCO. If the PFD produces an up signal, then the VCO frequency increases, while a down signal causes the VCO frequency to decrease.

The PFD outputs these up and down signals to a charge pump. If the charge pump receives an up signal, current is driven into the loop filter. Conversely, if it receives a down signal, current is drawn from the loop filter. The loop filter converts these up and down signals to a voltage that

is used to bias the VCO. The loop filter also removes glitches from the charge pump and prevents voltage over-shoot, which minimizes the jitter on the VCO.

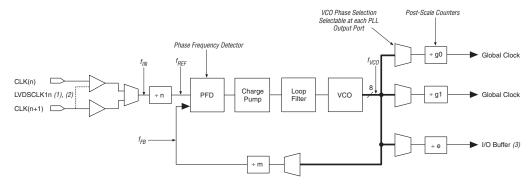
The voltage from the loop filter determines how fast the VCO operates. The VCO is implemented as a four-stage differential ring oscillator. A divide counter (M) is inserted in the feedback loop to increase the VCO frequency above the input reference frequency, making the VCO frequency ( $f_{\rm VCO}$ ) equal to M times the input reference clock ( $f_{\rm REF}$ ). The input reference clock ( $f_{\rm REF}$ ) to the PFD is equal to the input clock ( $f_{\rm IN}$ ) divided by the pre-scale counter (N). Therefore, the feedback clock ( $f_{\rm FB}$ ) that is applied to one input of the PFD is locked to the  $f_{\rm REF}$  that is applied to the other input of the PFD.

The VCO output can feed up to three post-scale counters (G0, G1, and E). These post-scale counters allow a number of harmonically-related frequencies to be produced within the PLL.

Additionally, the PLL has internal delay elements to compensate for routing on the global clock networks and I/O buffers of the external clock output pins. These internal delays are fixed and not accessible to the user.

Figure 6–1 shows a block diagram of the major components of a Cyclone PLL.

Figure 6-1. Cyclone PLL



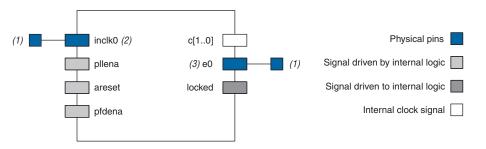
#### Notes to Figure 6–1:

- (1) The EP1C3 device in the 100-pin TQFP package does not have support for a PLL LVDS input.
- (2) If you are using the LVDS standard, then both CLK pins of that PLL are used. LVDS input is supported via the secondary function of the dedicated CLK pins. For PLL1, the CLK0 pin's secondary function is LVDSCLK1p and the CLK1 pin's secondary function is LVDSCLK1p. For PLL2, the CLK2 pin's secondary function is LVDSCLK2p and the CLK3 pin's secondary function is LVDSCLK2p.
- (3) The EP1C3 device in the 100-pin TQFP package, and the EP1C6 PLL2 in the 144-pin TQFP package do not support an external clock output.

#### **Software Overview**

Cyclone PLLs are enabled in the Quartus II software by using the altpl1 megafunction. Figure 6–2 shows the available ports (as they are named in the Quartus II altpl1 megafunction) of Cyclone PLLs and their sources and destinations. It is important to note that the c[1..0] and e0 clock output ports from altpl1 are driven by the post-scale counters G0, G1, and E (not necessarily in that order). The G0 and G1 counters feed the internal global clock network on the c0 and c1 PLL outputs, and the E counter feeds the PLL external clock output pin on the e0 PLL output.

Figure 6-2. Cyclone PLL Signals



#### *Notes to Figure 6–2:*

- (1) You can assign these signals to either a single-ended I/O standard or LVDS.
- (2) Inclk0 must be driven by the dedicated clock input pin(s).
- (3) e0 drives the dual-purpose PLL[2..1]\_OUT pins.

Tables 6–3 and 6–4 describe the Cyclone PLL input and output ports.

Table 6–3. PLL Input Signals						
Port	Description	Source	Destination			
inclk0	Clock input to PLL.	Dedicated clock input pin (1)	÷n counter			
pllena (2)	pllena is an active-high signal that acts as a combined enable and reset signal for the PLL. You can use It for enabling or disabling one or two PLLs. When this signal is driven low, the PLL clock output ports are driven to GND and the PLL loses lock. Once this signal is driven high again, the lock process begins and the PLL re-synchronizes to its input reference clock. You can drive the pllena port from internal logic or any general-purpose I/O pin.	Logic array (3)	PLL control signal			
areset	areset is an active-high signal that resets all PLL counters to their initial values. When this signal is driven high, the PLL resets its counters, clears the PLL outputs, and loses lock. Once this signal is driven low again, the lock process begins and the PLL resynchronizes to its input reference clock. You can drive the areset port from internal logic or any general-purpose I/O pin.	Logic array (3)	PLL control signal			
pfdena	pfdena is an active-high signal that enables or disables the up/down output signals from the PFD. When pfdena is driven low, the PFD is disabled, while the VCO continues to operate. The PLL clock outputs continue to toggle regardless of the input clock, but can experience some long-term drift. Because the output clock frequency does not change for some time, you can use the pfdena port as a shutdown or cleanup function when a reliable input clock is no longer available. You can drive the pfdena port from internal logic or any general-purpose I/O pin.	Logic array (3)	PFD			

#### Notes to Table 6–3:

- (1) The  ${\tt inclk0}$  port to the PLL must be driven by the dedicated clock input pin(s).
- (2) There is no dedicated pllena pin for all PLLs, allowing you to choose either one pllena pin for both PLLs or each PLL can have its own pllena pin.
- (3) Logic array source means that you can drive the port from internal logic or any general-purpose I/O pin.

Table 6–4. PLL Output Signals						
Port	Description	Source	Destination			
c[10]	PLL clock outputs driving the internal global clock network.	PLL post-scale counter G0 or G1	Global clock network (1)			
e0 <i>(2)</i>	PLL clock output driving the single-ended or LVDS external clock output pin(s).	PLL post-scale counter E	PLL[21]_OUT pin(s) (3)			
locked	Gives the status of the PLL lock. When the PLL is locked, this port drives logic high. When the PLL is out of lock, this port drives logic low. The locked port can pulse high and low during the PLL lock process.	PLL lock detect	Logic array (4)			

#### Notes to Table 6-4:

- (1) C[1..0] can also drive to any general-purpose I/O pin through the global clock network.
- (2) The EP1C3 device in the 100-pin TQFP package, and the EP1C6 PLL2 in the 144-pin TQFP package do not have support for the external clock output PLL[2..1] OUT.
- (3) The PLL[2..1]\_OUT pins are dual-purpose pins. If these pins are not required, they are available for use as general-purpose I/O pins.
- (4) Logic array destination means that you can drive the port to internal logic or any general-purpose I/O pin.

In the Quartus II software, you define which internal clock output from the PLL (c0 or c1) should be compensated. This PLL clock output is phase-aligned with respect to the PLL input clock. For example, if c0 is specified as the compensation clock in normal mode, the compensation is based on the c0 routing on the global clock network.

#### **Pins and Clock Network Connections**

You must drive Cyclone PLLs by the dedicated clock input pins CLK [3..0]. Inverted clocks and internally generated clocks cannot drive the PLL. Table 6–5 shows which dedicated clock pin drives which PLL input clock port.



A single clock input pin cannot drive both PLLs, but a single clock input pin can feed both registers in the logic array, as well as the PLL inclk port.

Table 6–5. PLL Input Clock Sources					
Clock Input Pins (1)	PLL1	PLL2 (2)			
CLK0	✓	_			
CLK1	<b>✓</b>	_			
CLK2	_	✓			
CLK3	_	✓			

Notes to Table 6-5:

- (1) If you are using the LVDS standard, then both CLK pins driving that PLL are used.
- (2) The EP1C3 device only supports PLL1.

The c[1..0] and e0 clock output ports from altpl1 are driven by the PLL post-scale counters G0, G1, and E (not necessarily in that order). The G0 and G1 counters feed the internal global clock network on the c0 and c1 PLL outputs, and the E counter feeds the PLL external clock output pin on the e0 PLL output. Table 6–6 shows which global clock network can be driven by which PLL post-scale counter output.

Table 6-0	Table 6–6. PLL Output Clock Destinations onto the Global Clock Network								
PLL	Counter Output	GCLKO	GCLK1	GCLK2	GCLK3	GCLK4	GCLK5	GCLK6	GCLK7
PLL 1	G0	_	<b>✓</b>	<b>✓</b>	_	_	_	_	_
	G1	<b>✓</b>	_	_	<b>✓</b>	_	_	_	_
PLL2	G0	_	_	_	_	_	<b>✓</b>	<b>✓</b>	_
	G1	1	_			<b>✓</b>	_	_	<b>✓</b>

Figure 6–3 summarizes Tables 6–5 and 6–6 by showing the PLL input and output clock connections.

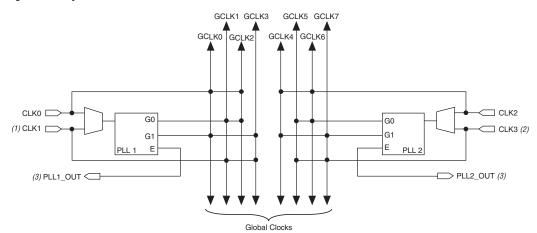


Figure 6-3. Cyclone PLL Clock Connections

#### *Notes to Figure 6–3:*

- (1) PLL1 supports one single-ended or LVDS input via the CLK0 and CLK1 pins.
- (2) PLL2 supports one single-ended or LVDS input via the CLK2 and CLK3 pins.
- (3) PLL1\_OUT and PLL2\_OUT support single-ended or LVDS outputs. If the external clock output is not required, these pins are available as general-purpose I/O pins.

You can invert the clock outputs of the PLL at the logic array block (LAB) and at the input/output element (IOE) level.

## Hardware Features

Cyclone PLLs have a number of advanced features available, including clock multiplication and division, phase shifting, programmable duty cycles, external clock outputs, and control signals.

## **Clock Multiplication and Division**

Cyclone PLLs provide clock synthesis for PLL output ports using  $M/(N \times \text{post-scale})$  scaling factors. There is one pre-scale divider (N) and one multiply counter (M) per PLL. N and post-scale counter values range from 1 to 32. The M counter ranges from 2 to 32. The input clock ( $f_{\text{IN}}$ ) is divided by a pre-scale counter (N) to produce the input reference clock ( $f_{\text{REF}}$ ) to the PFD.  $f_{\text{REF}}$  is then multiplied by the M feedback factor. The control loop drives the VCO frequency to match  $f_{\text{IN}} \times (M/N)$ . See the following equations:

$$\begin{split} f_{REF} &= f_{IN}/N \\ f_{VCO} &= f_{REF} \times M = f_{IN} \times (M/N) \end{split}$$

Each output port has a unique post-scale counter to divide down the high-frequency VCO. There are three post-scale counters (G0, G1, and E) that range from 1 to 32. See the following equations:

$$f_{C0} = f_{VCO}/G0 = f_{IN} \times (M/(N \times G0))$$
  
 $f_{C1} = f_{VCO}/G1 = f_{IN} \times (M/(N \times G1))$   
 $f_{E} = f_{VCO}/E = f_{IN} \times (M/(N \times E))$ 



c0 and c1 can use either post-scale counter, G0 or G1.

For multiple PLL outputs with different frequencies, the VCO is set to the least common multiple of the output frequencies that meets the VCO frequency specifications. Then, the post-scale counters scale down the output frequency for each PLL clock output port. For example, if clock output frequencies required from one PLL are 33 and 66 MHz, the VCO is set to 330 MHz (the least common multiple in the VCO's range).

### Phase Shifting

Cyclone PLLs have advanced clock shift capability to provide programmable phase shifting. You can enter the desired phase shift in the altpll MegaWizard® Plug-In Manager and the Quartus II software automatically sets and displays the closest phase shift achievable. You can enter the phase shift in degrees, or units of time, for each PLL clock output port. This feature is supported on all three PLL post-scale counters, G0, G1, and E and is supported for all available clock feedback modes.

Phase shifting is performed with respect to the PLL clock output that is compensated. For example, you have a 100 MHz input clock and request a  $\times 1$  multiplication with a +90° phase shift on c0 and a  $\times 1$  multiplication with a +45° phase shift on c1. If you choose to compensate for the c0 clock output, the PLL uses a zero phase-shifted c0 clock as a reference point to produce the +90° phase shift on c0. Since c0 is the compensated clock, it is phase-shifted +90° from the input clock. The c1 clock also uses the zero phase-shifted c0 reference to produce the +45° phase shift on c1.

For fine phase adjustment, each PLL clock output counter can choose a different phase of the VCO from up to eight phase taps. In addition, each clock output counter can use a unique initial count setting to achieve individual coarse phase shift selection, in steps of one VCO period. The Quartus II software can use this clock output counter, along with an initial setting on the post-scale counter, to achieve a phase shift range for the entire period of the output clock. You can phase shift the PLL clock output up to  $\pm 180^\circ$ . The Quartus II software automatically sets the phase taps and counter settings according to the phase shift requested.

The resolution of the fine phase adjustment is dependent on the input frequency and the multiplication/division factors (i.e., it is a function of the VCO period), with the finest step being equal to an eighth (  $\times$  0.125) of the VCO period. The minimum phase shift is  $1/(8 \times f_{VCO})$  or  $N/(8 \times M \times f_{IN})$ . In Cyclone FPGAs, the VCO ranges from 500 to 1,000 MHz. Therefore, phase shifting can be performed with a resolution range of  $1/(8 \times 1,000$  MHz) to  $1/(8 \times 500$  MHz), which is 125 to 250 ps in time units.

Because there are eight VCO phase taps, the maximum step size is  $45^{\circ}$ . Smaller steps are possible, depending on the multiplication and division ratio necessary on the output clock port. The equation to determine the precision of the phase shifting in degrees is  $45^{\circ}$  divided by the post-scale counter value. For example, if you have an input clock of 125 MHz with  $\times$  1, the post-scale counter G0 is 3. Therefore, the smallest phase shift step is  $(45^{\circ}/3=15^{\circ})$  and possible phase-shift values would be multiples of  $15^{\circ}$ .

This type of phase shift provides the highest precision since it is the least sensitive to process, voltage and temperature variation.

### Programmable Duty Cycle

The programmable duty cycle feature allows you to set the duty cycle of the PLL clock outputs. The duty cycle is the ratio of the clock output high/low time to the total clock cycle time, which is expressed as a percentage of high time. This feature is supported on all three PLL post-scale counters (G0, G1, and E).

The duty cycle is set by using a low- and high-time count setting for the post-scale counters. The Quartus II software uses the input frequency and target multiply/divide ratio to select the post-scale counter. The precision of the duty cycle is determined by the post-scale counter value chosen on a PLL clock output and is defined as 50% divided by the post-scale counter value. For example, if the post-scale counter value is 3, the allowed duty cycle precision would be 50% divided by 3 equaling 16.67%. Because the altpl1 megafunction does not accept non-integer values for the duty cycle values, the allowed duty cycles are 17, 33, 50, and 67%.

Due to hard limitations, you cannot achieve a duty cycle of 84% because you cannot achieve the closest value to 100% for a given counter value. However, you can achieve a duty cycle of 84% by choosing a 17% duty cycle and inverting the PLL clock output. For example, if the G0 counter is 10, increments of 5% are possible for duty cycle choices between 5 and 90%.

## **External Clock Output**

Each PLL supports one single-ended or LVDS external clock output for general-purpose external clocks, or for source-synchronous transmitters. The output of the E counter drives the PLL external clock output (e0), which can only feed to the PLL[2..1]\_OUT pins and not to internal logic. You can use PLL[2..1]\_OUT in all three clock feedback modes.



The EP1C3 device in the 100-pin package, and the EP1C6 PLL2 in the 144-pin package, do not have support for an external clock output.

The PLL [2..1] \_OUT pins are dual-purpose pins, meaning if the pins are not required by the PLL, they are available for use as general-purpose I/O pins. The I/O standards supported by the PLL [2..1] \_OUT pins are listed in Table 6–7.

Table 6–7. Supported I/O Standards for Cyclone PLL Pins					
I/O Standard	incik	PLL[21]_OUT (1)			
LVTTL	✓	✓			
LVCMOS	✓	✓			
2.5-V	✓	✓			
1.8-V	✓	✓			
1.5-V	✓	✓			
3.3-V PCI	✓	✓			
LVDS (2)	✓	✓			
SSTL-2 Class I	✓	✓			
SSTL-2 Class II	✓	✓			
SSTL-3 Class I	✓	✓			
SSTL-3 Class II	✓	✓			
Differential SSTL-2 Class II	_	✓			

Notes to Table 6-7:

- (1) The EP1C3 device in the 100-pin TQFP package and the EP1C6 PLL2 in the 144-pin TQFP package do not support an external clock output.
- (2) The EP1C3 device in the 100-pin TQFP package does not support an LVDS input.

Since the pllena and locked signal can be driven by or driven to general-purpose I/O pins, respectively, they support all Cyclone I/O standards.

The Cyclone external clock output pins (PLL[2..1]\_OUT) do not have a separate  $V_{CC}$  and GND bank internal to the device. The PLL[2..1]\_OUT pins share a  $V_{CCIO}$  bank with neighboring I/O pins. Only the I/O pins in the same bank have an effect on the PLL[2..1]\_OUT pins. Therefore, to minimize jitter on the PLL[2..1]\_OUT pins, I/O pins directly adjacent to these pins should be either inputs or they should not be used. For more information about board design guidelines, see "Jitter Considerations" on page 6–19.

### **Control Signals**

There are four available control signals, pllena, areset, pfdena, and locked, in Cyclone PLLs that provide added PLL management.

#### pllena

The PLL enable signal, pllena, enables or disables the PLL. You can either enable/disable a single PLL (by connecting pllena port independently) or multiple PLLs (by connecting pllena ports together). The pllena signal is an active-high signal. When pllena is low, the PLL clock output ports are driven to logic low and the PLL loses lock. All PLL counters, including gated lock counter return to default state. When pllena goes high again, the PLL relocks and resynchronizes to the input clock. Therefore, pllena is an active-high signal. In Cyclone FPGAs, you can feed the pllena port from internal logic or any general-purpose I/O pin because there is no dedicated pllena pin. This feature offers added flexibility, since each PLL can have its own pllena control circuitry, or both PLLs can share the same pllena circuitry. The pllena signal is optional, and when it is not enabled in the software, the port is internally tied to VCC.

#### areset

The PLL areset signal is the reset or resynchronization input for each PLL. The areset signal should be asserted every time the PLL loses lock to guarantee correct phase relationship between the PLL input and output clocks. Users should include the areset signal in designs where phase relationship between input and output clocks need to be maintained after a loss of lock condition. The areset signal is an active high signal and, when driven high, the PLL counters reset, clearing the PLL output and causing the PLL to lose lock. The clock outputs of the PLL are driven to ground as long as areset is active. When areset transitions low, the PLL will resynchronize to its input clock as the PLL relocks. If the target VCO frequency is below this nominal frequency, the PLL clock output frequency will start at a higher value than desired during the lock process. In this case, Altera recommends monitoring the gated locked signal to ensure the PLL is fully in lock before enabling the clock outputs

from the PLL. Cyclone FPGAs can drive this PLL input signal from LEs or any general-purpose I/O pin. The areset signal is optional. When it is not enabled in the Quartus II software, the port is internally tied to GND.

#### pfdena

The pfdena signal controls the PFD output in the PLL with a programmable gate. If you disable the PFD by driving areset low, the VCO operates at its last set control voltage and frequency value with some long-term drift to a lower frequency. The VCO frequency can drift up to +/- 5% over 25 us. Even though the PLL clock outputs continue to toggle regardless of the input clock, the PLL could lose lock. The system continues running when the PLL goes out of lock, or if the input clock is disabled. Because the last locked output frequency does not change for some time, you can use the pfdena port as a shutdown or cleanup function when a reliable input clock is no longer available. By maintaining this frequency, the system has time to store its current settings before shutting down. If the pfdena signal goes high again, the PLL relocks and resynchronizes to the input clock. Therefore, the pfdena pin is an active-high signal. You can drive the pfdena input signal by any general-purpose I/O pin, or from internal logic. This signal is optional, and when it is not enabled in the software, the port is internally tied to VCC.

#### locked

When the locked output is at a logic-high level, this level indicates a stable PLL clock output in phase with the PLL reference input clock. Without any additional circuitry, the locked port may toggle as the PLL begins tracking the reference clock. The locked port of the PLL can feed any general-purpose I/O pin and/or internal logic. This locked signal is optional, but is useful in monitoring the PLL lock process.

Whenever the PLL loses lock for any reason (be it excessive inclk jitter, power supply noise, etc.), the PLL must be reset with the areset signal to guarantee correct phase relationship between the PLL output clocks. If the phase relationship between the input clock versus output clock, and between different output clocks from the PLL is not important in your design, the PLL need not be reset.

## Clock Feedback Modes

Cyclone PLLs support three feedback modes: normal, zero delay buffer, and no compensation. Unlike other Altera device families, Cyclone PLLs do not have support for external feedback mode. All three supported

clock feedback modes allow for multiplication/division, phase shifting, and programmable duty cycle. The following sections give a brief description of each mode.



The phase relationship shown in Figure 6–4 through 6–6 are for the default phase shift setting of  $0^\circ$ . Changing the phase-shift setting will change the relationships.

#### **Normal Mode**

In normal mode, the PLL phase aligns the input reference clock with the clock signal at the ports of the registers in the logic array or the IOE to compensate for the internal global clock network delay. In the altpll MegaWizard Plug-In Manager, you can define which internal clock output from the PLL (c0 or c1) should be compensated.

If the external clock output (PLL [2..1]\_OUT) is used in this mode, there will be a phase shift with respect to the clock input pin. Similarly, if you use the internal PLL clock outputs to drive general-purpose I/O pins, there will be a phase shift with respect to the clock input pin.

Figure 6–4 shows an example waveform of the PLL clocks' phase relationship in normal mode.

PLL inclk

PLL clock at the register clock port

External PLL clock outputs (1)

Figure 6–4. Phase Relationship Between PLL Clocks in Normal Mode

Note to Figure 6-4:

(1) The external clock output can lead or lag the PLL clock signals.

## **Zero Delay Buffer Mode**

The clock signal on the PLL external clock output pin (PLL [2..1]\_OUT) is phase-aligned with the PLL input clock pin for zero delay. If you use the c[1..0] ports to drive internal clock ports, there will be a phase shift with respect to the input clock pin. Figure 6–5 shows an example waveform of the PLL clocks' phase relationship in zero delay buffer mode.

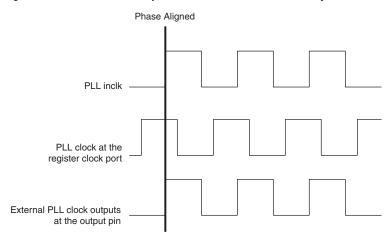


Figure 6-5. Phase Relationship Between PLL Clocks in Zero Delay Buffer Mode

## No Compensation

In this mode, the PLL does not compensate for any clock networks, which leads to better jitter performance because the clock feedback into the PFD does not pass through as much circuitry. Both the PLL internal and external clock outputs are phase shifted with respect to the PLL clock input. Figure 6–6 shows an example waveform of the PLL clocks' phase relationship in no compensation mode.

PLL inclk
PLL clock at the
Register clock port (1)

External PLL clock outputs

Figure 6–6. Phase Relationship Between PLL Clocks in No Compensation Mode

*Note to Figure 6–6:* 

(1) Internal clocks fed by the PLL are in phase alignment with each other.

## **Pins**

Table 6–8 describes the Cyclone PLL-related physical pins and their functionality.

Table 6–8. Cyclone PLL Pins (Part 1 of 2)	
Pin Name	Description
CLK0	Single-ended or LVDS p-pin that can drive the inclk0 port of PLL1.
CLK1 (1)	Single-ended or LVDS n-pin that can drive the inclk0 port of PLL1.
CLK2	Single-ended or LVDS p-pin that can drive the inclk0 port of PLL2.
CLK3 (1)	Single-ended or LVDS n-pin that can drive the inclk0 port of PLL2.
PLL1_OUTp (2) PLL1_OUTn (2)	Single-ended or LVDS pins driven by the $e0$ port from PLL1. If not used by the PLL, these are available as general-purpose I/O pins.
PLL2_OUTp (2) PLL2_OUTn (2)	Single-ended or LVDS pins driven by the $e0$ port from PLL2. If not used by the PLL, these are available as general-purpose I/O pins.
VCCA_PLL1 (3)	Analog power for PLL1. Even if the PLL is not used, you must connect this pin to 1.5 V.
GNDA_PLL1 (4)	Analog ground for PLL1. You can connect this pin to the GND plane on the board.
VCCA_PLL2 (3)	Analog power for PLL2. Even if the PLL is not used, you must connect this pin to 1.5 V.

Table 6–8. Cyclone PLL Pins (Part 2 of 2)	
Pin Name	Description
GNDA_PLL2 (4)	Analog ground for PLL2. You can connect this pin to the GND plane on the board.
GNDG_PLL1 (5)	Guard ring ground for PLL1. You can connect this pin to the GND plane on the board.
GNDG_PLL2 (5)	Guard ring ground for PLL2. You can connect this pin to the GND plane on the board.

#### Notes to Table 6-8:

- (1) The EP1C3 device in the 100-pin TQFP package does not have dedicated clock pins CLK1 and CLK3.
- (2) The EP1C3 device in the 100-pin TQFP package, and the EP1C6 PLL2 in the 144-pin TQFP package do not support an external clock output.
- (3) Refer to "Board Layout" on page 6–17 for filtering and other recommendations.
- (4) The EP1C3 device in the 100-pin TQFP package, and the EP1C6 PLL2 in the 144-pin TQFP package do not have a separate GNDA PLL pin. They are internally tied to GND.
- (5) The Guard ring power (VCCG PLL) is tied internally to  $V_{CCINT}$ .

## **Board Layout**

Cyclone PLLs contain analog components that are embedded in a digital device. These analog components have separate power and ground pins to provide immunity against noise generated by the digital components. These separate VCC and GND pins are used to isolate circuitry and improve noise resistance.

### V<sub>CCA</sub> and GNDA

Each PLL has separate VCC and GND pairs for their analog circuitry. The analog circuit power and ground pin for each PLL is called VCCA\_PLL# and GNDA\_PLL# (# represents the PLL number). Even if the PLL is not used, the  $V_{CCA}$  power must be connected to a 1.5-V supply. The power connected to  $V_{CCA}$  must be isolated from the power to the rest of the Cyclone FPGA, or any other digital device on the board. The following sections describe three different methods for isolating  $V_{CCA}$ .

## Separate V<sub>CCA</sub> Power Plane

The designer of a mixed-signal system would have already partitioned the system into analog and digital sections, each with its own power planes on the board. In this case, you can connect  $V_{\text{CCA}}$  to the analog 1.5-V power plane.

### Partitioned $V_{CCA}$ Island within $V_{CCINT}$ Plane

Most systems using Altera devices are fully digital, so there is not a separate analog power plane readily available on the board. Adding new planes to the board may be expensive. Therefore, you can create islands

for VCCA\_PLL. The dielectric boundary that creates the island is approximately 25 mils thick. Figure 6–7 shows a partitioned plane within  $V_{\rm CCINT}$  for  $V_{\rm CCA}$ .

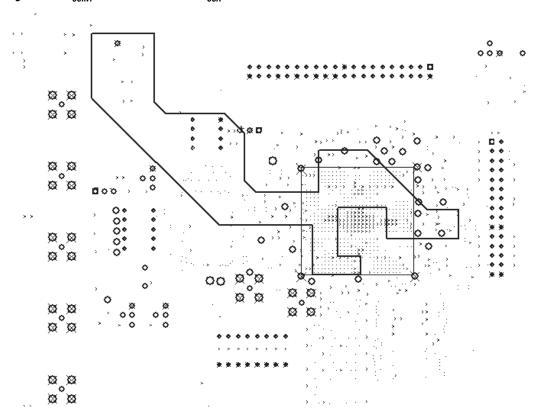


Figure 6–7.  $V_{CCINT}$  Plane Partitioned for  $V_{CCA}$  Island

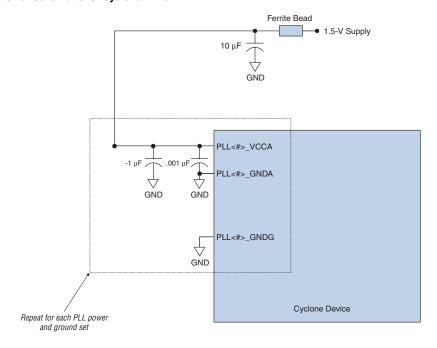
## Thick V<sub>CCA</sub> Traces

Due to board restraints, it may not be possible to partition a  $V_{\text{CCA}}$  island. Instead, run a thick trace from the power supply to each of the VCCA pins. The traces should be at least 20 mils thick.

In all cases, each VCCA pin must be filtered with a decoupling circuit shown in Figure 6–8. You must place a ferrite bead and a 10- $\mu$ F tantalum parallel capacitor where the power enters the board. Choose a ferrite bead that exhibits high impedance at frequencies of 50 MHz or higher. Each VCCA pin must be decoupled with a 0.1- $\mu$ F and a 0.001- $\mu$ F parallel

combination of ceramic capacitors located as close as possible to the Cyclone FPGA. You can connect the GNDA pins directly to the same GND plane as the digital GND of the device.

Figure 6-8. PLL Power Schematic for Cyclone PLLs





For more information about board design guidelines, refer to *AN 75: High-Speed Board Designs*.

#### **Jitter Considerations**

If the input clocks have any low-frequency jitter (below the PLL bandwidth), the PLL attempts to track it, which increases the jitter seen at the PLL clock output. To minimize this effect, avoid placing noisy signals in the same  $V_{\rm CCIO}$  bank as those that power the PLL clock input buffer. This is only important if the PLL input clock is assigned to 3.3-V or 2.5-V LVTTL or LVCMOS I/O standards. With these I/O standards,  $V_{\rm CCIO}$ 

powers the input clock buffer. Therefore, any noise on this  $V_{CCIO}$  supply can affect jitter performance. For all other I/O standards the input buffers are powered by  $V_{CCINT}$ .

Because Cyclone external clock output pins (PLL[2..1]\_OUT) do not have a separate  $V_{CC}$  and GND bank, you should avoid placing noisy output signals directly next to these pins. Therefore, Altera recommends that PLL[2..1]\_OUT neighboring I/O pins should be either inputs pins or not used at all. If noisy outputs are placed next to the PLL[2..1]\_OUT pins, they could inject noise through ground bounce or  $V_{CC}$  sag and mutual pin inductance, which would result in worse jitter performance on the PLL[2..1]\_OUT pins.

Additionally, you should take into consideration the number of simultaneously switching outputs within the same  $V_{\rm CCIO}$  bank as the  ${\tt PLL[2..1]\_OUT}$  pins. Altera recommends that you switch as few outputs simultaneously in the same direction as possible in these  $V_{\rm CCIO}$  banks. Also, if you have switching outputs in the same  $V_{\rm CCIO}$  bank as the  ${\tt PLL[2..1]\_OUT}$  pins, Altera recommends that you use the low current strength and/or slow slew rate options on those output pins as they will help to improve the jitter performance.

## **Specifications**

Refer to the *DC* and *Switching Characteristics* chapter of the *Cyclone Device Handbook* for Cyclone FPGA PLL specifications.

## Software Support

Support for Cyclone PLLs is available in the Quartus II software by using the altpll megafunction. The following section describes how the altpll megafunction enables the various Cyclone PLL features and options. This section includes the megafunction symbol, the input and output ports, a description of the MegaWizard Plug-In Manager options, and example MegaWizard screen shots.

## **Quartus II altpll Megafunction**

Figure 6–9 shows the altpll megafunction symbol in the Quartus II software.

pll1 inclk0 c0 inclk0 frequency: 100,000 MHz pllena с1 Operation Mode: Normal areset e0 Clk Ratio Ph (dg) Td (ns) DC (%) pfdena locked 1/1 0.00 0.00 50 е1 1/1 0.00 0.00 50 eθ 1/1 0.00 0.00 50 inst2

Figure 6-9. altpll Megafunction Symbol Targeted for Cyclone FPGAs



Refer to Quartus II Help for the altpll megafunction AHDL functional prototypes (applicable to Verilog HDL), VHDL component declaration, and parameter descriptions.

### altpll Input Ports

Table 6--9 shows the input ports of the <code>altpll</code> megafunction and describes their function.

Table 6–9. li	Table 6–9. Input Ports of the altpll Megafunction						
Port Name	Required	Description					
inclk0 (1)	Yes	The input clock port that drives the PLL.					
pllena (2)	No	pllena is an active-high signal, which acts as a combined enable and reset signal for the PLL. You can use it for enabling or disabling one or both PLLs. When this signal is driven low, the PLL clock output ports are driven to GND and the PLL loses lock. Once this signal is driven high again, the lock process begins and the PLL re-synchronizes to its input reference clock. The pllena port can be driven from internal logic or any general-purpose I/O pin.					
areset (2)	No	areset is an active-high signal, which resets all PLL counters to their initial values. When this signal is driven high, the PLL resets its counters, clears the PLL outputs, and loses lock. Once this signal is driven low again, the lock process begins and the PLL re-synchronizes to its input reference clock. You can drive the areset port from internal logic or any general-purpose I/O pin.					
pfdena (2)	No	pfdena is an active-high signal, which enables or disables the up/down output signals from the PFD. When pfdena is driven low, the PFD is disabled, while the VCO continues to operate. PLL clock outputs continue to toggle regardless of the input clock, but can experience some long-term drift. Because the output clock frequency does not change for some time, you can use the pfdena port as a shutdown or cleanup function when a reliable input clock is no longer available. You can drive the pfdena port from internal logic or any general-purpose I/O pin.					

### Notes to Table 6–9:

- (1) The inclk0 port to the PLL must be driven by the dedicated clock input pin(s).
- (2) See "Control Signals" on page 6–12 for further details.

### altpli Output Ports

Table 6–10 shows the output ports of the <code>altpll</code> megafunction and describes their function.

Table 6–10. Output Ports of the altpll Megafunction						
Port Name	Required	Description				
c[10] (1)	No	Clock output of the PLL that drives the internal global clock network.				
e0 (1)	No	Clock output that feeds the external clock output pins, PLL[21]_OUT.				
locked (2)	No	Gives the status of the PLL lock. When the PLL is locked, this port drives logic high. When the PLL is out of lock, this port drives logic low. The locked port can pulse high and low during the PLL lock process.				

### Notes to Table 6-10:

- (1) Either the internal or external clock output of the PLL must be selected.
- (2) See "Control Signals" on page 6–12 for further details.

### **MegaWizard Customization**

You can use the MegaWizard Plug-In Manager to set the altpll megafunction options for each PLL instance in your design.



If you instantiate the altpll megafunction without using the MegaWizard Plug-In Manager, search for "altpll" in the Quartus II Help for a list of the altpll parameters.

In the MegaWizard Plug-In Manager, select the altpl1 megafunction in the I/O directory from the **Available Megafunctions** dialog box (see Figure 6–10). The altclklock megafunction is also available from the Quartus II software for backward compatibility, but instantiates the new altpl1 megafunction when targeting Cyclone FPGAs.

MegaWizard Plug-In Manager [page 2a] X Which megafunction would you like to customize? Select a Available Megafunctions: megafunction from the list at left. 🖃 🖳 Installed Plug-Ins Which type of output file do you want to create? 🔎 Altera SOPC Builder 2.5 🖈 🔯 arithmetic AHDL 🔎 ARM-Based Excalibur C VHDL 🛨 📴 gates Verilog HDL Ė-**®** 1/0. 🔊 ALTCDR Browse... What name do you want for the output file? ALTCLKLOCK C:\DATA\Projects\Cyclone\PLL\_design\pll1 ALTDDIO BIDIR ALTDDIO\_IN ALTDDIO\_OUT ALTGXB Note: To compile a project successfully in the Quartus II. ALTLVDS software, your design files must be in the project directory or ALTPLL a user library that you specify in the User Libraries tab of ⊕ Storage General Settings command (Project menu). 庄 🌃 IP MegaStore Your current user library directories are: < Back Cancel Next>

Figure 6–10. altpll Megafunction Selection in the MegaWizard Plug-In Manager

The altpll MegaWizard Plug-In Manager has separate pages that apply to Cyclone PLLs. The MegaWizard will gray-out options that are unavailable in Cyclone PLLs. During compilation, theQuartus II Compiler verifies the altpll parameters selected against the available PLLs, and any PLL or input clock location assignments.

At the top right-hand corner of each page of the altpll MegaWizard Plug-In Manager, there is a **jump to page** drop-down list (see Figure 6–11). This drop-down list allows you to jump to any particular altpll MegaWizard page and set those options.

Jump to page for:

General/Modes

Scan/Lock

Bandwidth/SS

Clock switchover

Clock c0

Clock c1

Clock e0

Figure 6-11. Jump to Page Drop-Down List in the altpll MegaWizard Plug-In

### **MegaWizard Page Description**

This section describes the options available on the altpl1 MegaWizard pages. Each of the MegaWizard pages are shown. Tables 6–11 through 6–13 describe the features or settings on that page that apply to Cyclone PLLs. Use these tables, along with the hardware descriptions of the PLL features, to determine appropriate settings for your PLL instance.

You can use the **General/Modes** (Page 1) of the altpll MegaWizard Plug-In Manager for selecting the target device family, clock input frequency, general control signal selection, and clock feedback operation mode (see Figure 6–12 and Table 6–11).

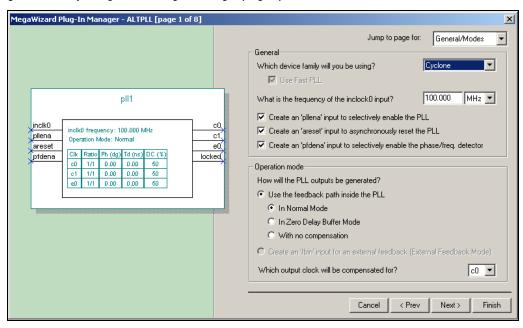


Figure 6-12. altpll MegaWizard Plug-In Manager (Page 1)

Function	Description				
Which device family will you be using?	This chapter explains all altpll options that apply when Cyclone is the target device family selected.				
What is the frequency of the inclock0 input	The frequency for the PLL input clock, inclock0.				
Create an pllena input to selectively enable the PLL	Creates a pllena port for this PLL instance. See Table 6–9 for pllena port description.				
Create an areset input to asynchronously reset the PLL	Creates a areset port for this PLL instance. See Table 6–9 for areset port description.				
Create an pfdena input to selectively enable the PFD	Creates a pfdena port for this PLL instance. See Table 6–9 for pfdena port description.				

Table 6–11. altpll MegaWizard Plug-In Options Page 1 (Part 2 of 2)					
Function	Description				
Use the feedback path inside the PLL	This option sets the OPERATION_MODE parameter to either normal, zero delay buffer, or no compensation mode. In normal mode, the PLL feedback path comes from a global clock network, which minimizes the clock delay to registers for that specific PLL clock output. You can specify which PLL output is compensated for by using the COMPENSATE_CLOCK parameter.  In zero delay buffer mode, the PLL feedback path is confined to the dedicated PLL external output pin. The clock signal driven off-chip on the PLL_OUT pin is phase aligned with the PLL clock input for a minimized delay between clock input and external clock output. If the PLL is also used to drive the internal clock network, a corresponding phase shift of that clock network results. In no compensation mode, the PLL feedback path is confined to the PLL loop; it does not come from the global clock network or an external source. There is no clock network compensation, but this mode minimizes jitter on clocks. This mode may lead to positive hold times on IOE registers; you can use manual phase shifting to compensate for positive hold times. For more information, see "Clock Feedback Modes" on page 6–13.				
Which output clock will be compensated?	Indicates which output port of the PLL is compensated. For normal mode, you can select c0 or c1.				

You can use **Scan/Lock** (Page 2) for selecting the locked output port (see Figure 6–13 and Table 6–12).

Figure 6–13. altpll MegaWizard Plug-In Manager (Page 2)

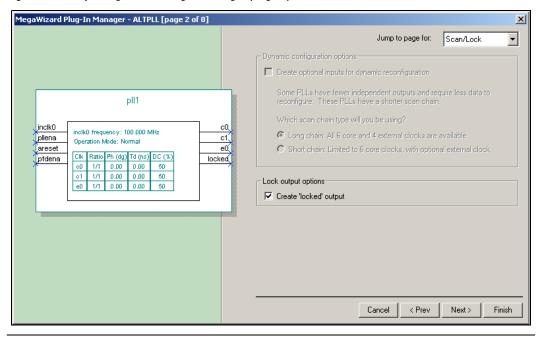


Table 6–12. altpll MegaWizard Plug-In Options Page 2					
Function Description					
Create "locked" output	Creates a locked output port to indicate PLL lock. See locked port description in Table 6–10.				

The options on the next two pages of the MegaWizard Plug-In Manager, (Pages 3 to 4, titled **Bandwidth/SS** and **Clock Switchover**) are not supported in Cyclone FPGAs.

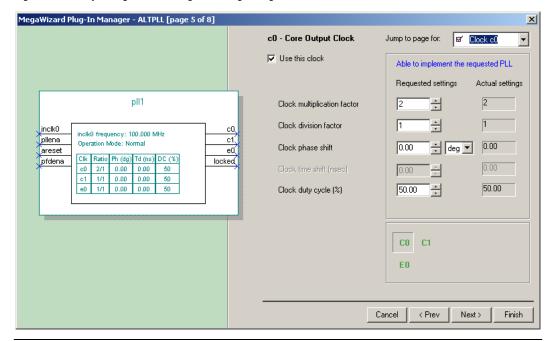


Figure 6-14. altpll MegaWizard Plug-In Manager Pages 5 of 8

The last 3 pages of the MegaWizard Plug-In Manager (Pages 5 to 7) allow you to set the multiplication/division factors, phase shift, and duty cycle for each PLL output port (see Figure 6–14 and Table 6–13).

Each page represents the settings for one PLL clock output port. Table 6–13 describes the options for Pages 5 to 8.

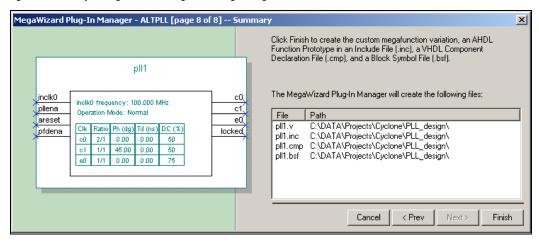
Table 6–13. altpll MegaWizard Plug-In Options Pages 5 of 8							
Function	Description						
Clock multiplication factor (ratio)	Specifies the clock multiplication for this PLL output. The multiplication factor cannot be greater than 32.						
Clock division factor (ratio)	Specifies the clock division for this PLL output.						
Clock phase shift (Ph)	Sets the programmable phase shift for the clock output with respect to the PLL clock output that is compensated. The equation to determine the precision of the phase shifting in degrees is (45° divided by the post-scale counter value). Therefore, the maximum step size is 45°, and smaller steps are possible, depending on the multiplication/division ratio necessary on the clock output port. For example, if you have an input clock of 125 MHz with ×1, the post-scale counter G0 is 3. Therefore, the smallest phase shift step is 15°, and additional phase shifting is in 15° increments.						
	The up/down buttons cycle through the possible phase shift settings with the default $M$ and post-scale dividers that the MegaWizard Pug-In Manager has chosen for your target frequency and multiplication/division ratio. It is possible to get other granularities of phase shifts if you manually enter a number into the phase shift field. For example, you can override the MegaWizard-chosen values and manually enter 7.5°. The MegaWizard Plug-In Manager verifies this is possible by using $M=6$ and $G0=6$ . The MegaWizard Plug-In Manager tries to achieve the closest phase shift possible. For example, if you enter 10°, the MegaWizard Plug-In Manager verifies that 9° is possible by using $M=5$ and $G0=5$ .						
	For more information, see "Phase Shifting" on page 6-9.						
Clock duty cycle (DC)	Specifies the clock duty cycle of the PLL clock output.  The equation to determine the precision of the duty cycle is (50% divided by the post-scale counter value). For example, if post-scale counter G0 is 3, the allowed duty cycles are 50% divided by 3, equaling 16.67%. Because the altpll megafunction does not accept non-integer values for the duty cycle values, the allowed duty cycles are 17, 33, 50, and 67%. Due to hard limitations, a duty cycle of 84% cannot be achieved because the closest value to 100% cannot be achieved for a given counter value. However, you can achieve a duty cycle of 84% by choosing a 17% duty cycle and inverting the PLL clock output. Use the up/down buttons to cycle through all possible settings.  For more information, see "Programmable Duty Cycle" on page 6–10.						

Page 8 is the summary page and tells you what files the MegaWizard Plug-In Manager will create (see Figure 6–15).



You can click **Finish** at anytime while in the MegaWizard Plug-In Manager to update the files.

Figure 6-15. altpll MegaWizard Plug-In Manager Page 8



### **Compilation Report**

During compilation, an information message displays whether the requested multiplication/division factors, and/or phase shift, and/or duty cycle were achieved. If you enter an invalid multiplication/division ratio, compilation fails, and the Quartus II software displays an error message. If you enter an invalid phase shift or duty cycle value, the compilation proceeds, and you will receive an information message displaying the best alternative values chosen by the Quartus II software.

The **Resource Section** of the compilation report provides two PLL reports: the **PLL Summary** and the **PLL Usage** reports. The **PLL Summary** provides information on each PLL's parameters (see Figure 6–16). The **PLL Summary** is column-based in the report file, where each column represents a different PLL instance. Table 6–14 lists and explains the parameters shown in the **PLL Summary** report. PLL properties not listed in Table 6–14 do not apply to Cyclone PLLs.

Figure 6–16. PLL Summary Report

PLL	PLL Summary								
	PLL Property	pll1:inst altpll:altpll_component pll							
1	PLL type	-							
2	Scan chain	None							
3	PLL mode	Normal							
4	Feedback source	-							
5	Compensate clock	clock0							
6	Switchover on loss of clock	-							
7	Switchover on gated lock	-							
8	Switchover counter	-							
9	Primary clock	-							
10	Input frequency 0	100.0 MHz							
11	Input frequency 1	-							
12	Nominal VCO frequency	400.0 MHz							
13	Freq min lock	74.99 MHz							
14	Freq max lock	200.0 MHz							
15	Hold conf done	Off							
16	M value	4							
17	N value	1							
18	M counter delay	-							
19	N counter delay	-							
20	M2 value	•							
21	N2 value	-							
22	SS counter	•							
23	Downspread	-							
24	Spread frequency	•							
25	Charge pump current	•							
26	Loop filter resistance	•							
27	Loop filter capacitance	-							
28	Freq zero	-							
29	Bandwidth	-							
30	Freq pole	-							
31	enable0 counter	-							
32	enable1 counter	-							
33	Real time reconfigurable	-							
34	Bit stream for reprogramming	-							

Table 6–14. PLL Summary in Compilation Report File (Part 1 of 2)					
PLL Property	Description				
PLL mode	Clock feedback mode				
Compensate clock	Indicates which PLL clock output (clock0, clock1, or extclock0) port is compensated				
Input frequency 0	Clock input frequency for inclk0				

Table 6–14. PLL Summary in Compilation Report File (Part 2 of 2)					
PLL Property Description					
Nominal VCO frequency	Shows the VCO frequency; $f_{VCO} = f_{IN} \times M/N$				
Freq min lock	Shows the minimum PLL input clock frequency for which the current combination of <i>M/N</i> still provides a valid VCO lock				
Freq max lock	Shows the maximum PLL input clock frequency for which the current combination of <i>M/N</i> still provides a valid VCO lock				
<i>M</i> value	M counter value				
N value	N counter value				

The **PLL Usage** report shows the breakdown information for each PLL clock output (see Figure 6–17). This report is categorized by PLL clock output ports, such that each row represents a different PLL clock output used in your design. Table 6–15 lists and explains the parameters shown in the **PLL Usage** report file in a row format. PLL parameters not listed in Table 6–15 do not apply to Cyclone PLLs.

Figure 6-17. PLL Usage Report

ľ	PLL Usage														
I	N	Name	Output Clock	Mult	Div	Output Frequency	Phase Shift	D	Duty Cycle	Counter	C	Counter Value	High / Low	Initial	VCO Tap
П	71	pll1:inst altpll:altpll_component[_clk0	clock0	2	1	200.0 MHz	0 (0 ps)	0	50/50	G1	-	2	1/1 Even	1	0
1	2	pll1:inst altpll:altpll_component[_clk1	clock1	1	1	100.0 MHz	45 (1250 ps)	0	50/50	G0	-	4	2/2 Even	1	4
П	3	pll1:inst[altpll:altpll_component[_extclk0	extclock0	1	1	100.0 MHz	0 (0 ps)	0	75/25	E0		4	3/1 Even	1	0

### **Timing Analysis**

Table 6–15 shows the usage in the compilation report file.

Table 6–15. PLL Usage in Compilation Report File (Part 1 of 2)					
PLL Parameter	Description				
Name	Indicates the PLL instance name and clock output reported.				
Output Clock	Indicates the PLL clock output (clock0, clock1, or extclock0) for which the parameter information in this row applies. This is the clock port specified in the MegaWizard Plug-In Manager (c0, c1, e0).				
Mult	Overall multiplication ratio.				
Div	Overall division ratio.				
Output Frequency	Output frequency for this output clock.				
Phase Shift	Achieved phase shift in degrees and units of time (can differ from user-entered value).				

Table 6–15. PLL Usage in Compilation Report File (Part 2 of 2)				
PLL Parameter Description				
Duty Cycle	Duty cycle for this clock output.			
Counter	Post-scale counter used for this clock output, which counter (G0, G1, E0) feeds the clock output.			
Counter Value	Value of post-scale counter.			
High/Low	High- and low-time counts that make up the counter value. The ratio of high- and low-counts is directly proportional to the duty cycle.			
Initial	Initial value for this post-scale counter (achieves the coarse granularity for phase shifting). Specifies the initial number of VCO cycles before starting the counter.			
VCO Tap	VCO tap ranges from 0 to 7 (achieves fine granularity for phase shift in units of 1/8 of the VCO period).			

The register-to-register timing for each PLL clock output that drives the logic array is reported with slack. The timing analysis section of the report file provides slack information in a clock requirement line for each PLL clock output.

You can derive  $f_{MAX}$  numbers from the slack reporting. The microparameters  $t_{CO}$ ,  $t_{SU}$ , and the path delay are given for a List Path command on the Actual Maximum P2P timing in the Slack Report window. You can add and invert these to find the  $f_{MAX}$  for that path. See the following equation:

During timing analysis for Cyclone designs using PLLs, the project clock settings override the PLL input clock frequency and duty cycle settings. It is important to note the following:

- A warning during compilation reports that the project clock settings override the PLL clock settings.
- The project clock setting overrides the PLL clock settings for timing-driven compilation. When you compile a design with timing-driven compilation turned on, you are overconstraining the design so that the fitter can give you a better f<sub>MAX</sub> performance. For example, if the PLL is set to output a 150 MHz clock, you can set a project clock setting for 170 MHz so that the fitter tries to achieve a design performance of 170 MHz.

- The Compiler checks the lock frequency range of the PLL. If the frequency specified in the project clock settings is outside the lock frequency range, the PLL clock settings will not be overridden.
- Overriding the PLL clock settings only changes the timing requirements; it does not change the overall multiplication/division and phase delay on each clock output of the PLL. The MegaWizard Plug-In Manager does not use the project clock settings to determine the altpll parameters.
- Performing a timing analysis without recompiling your design does not change the programming files. You must recompile your design to update the programming files.
- A Default Required f<sub>MAX</sub> setting does not override the PLL clock settings. Only individual clock settings will override the PLL clock settings.

This capability is useful when you have configured a Cyclone device and want to see if your timing requirements are met when you feed the PLL a different input clock than what is specified for the PLL parameters. Therefore, this feature allows you to overwrite the PLL input clock frequency settings for timing analysis, meaning you do not have to resynthesize or re-fit your design. The following procedure allows you to override the PLL input frequency setting and re-generate timing analysis.

- 1. Choose **Timing Settings** (Project menu).
- 2. Click on the **Clock Settings** tab.
- 3. Under Specify circuit frequency as, select Settings for individual clock signals.
- 4. Click New.
- 5. In the **New Clock Settings** dialog box, type a <name> for the new clock settings in the **Clock settings** box.
- 6. If you want to specify timing requirements for an absolute clock, follow these steps:
  - a. Under Relationship to other clock settings, select Independent of other clock settings.
  - b. In the **Required fMAX** box, type the required frequency  $(f_{MAX})$  of the clock signal and select a time unit from the list.

- In the **Duty Cycle** list, specify the required duty cycle for the clock.
- Cyclone PLLs accept input clocks with 40 to 60% duty cycle.
- d. If you want to include external delays to and from device pins in the  $f_{MAX}$  calculations, turn on **Include external delays to and from device pins in fMAX calculations**.
- e. Click OK.
- 7. Click **OK** to close the Timing Settings window.
- 8. Open the **Assignment Organizer** dialog box (Tools menu).
- 9. Click on the By Node tab.
- 10. Under *Mode*, select Edit specific entity & node settings for.
- 11. If necessary, copy a specific PLL input clock pin name to the **Name** box using the **Node Finder** dialog box.
- 12. Under **Assignment Categories**, click the + icon next to **Timing**.
- 13. Click on Click here to add a new assignment.
- 14. Under **Assignment**, select **Clock Settings** in the **Name** list, and select the <name> of the clock settings you created in step 5.
- 15. Under Stored in assignments for, select This instance only, This instance in all occurrences of its parent entity, or Other.
- 16. Click Add.
- 17. Click **OK** or **Apply**.
- 18. Select **Start Timing Analysis** (Processing Menu).

### **Simulation**

The altpl1 megafunction supports behavioral and timing simulation in both the Quartus II software and supported third-party simulation tools. You can simulate all digital aspects of the PLL, but none of the analog aspects. Simulation supports all control signals and clock outputs. Table 6–16 explains the simulation support for altpl1.

Table 6–16. altpll Simulation Support for Cyclone FPGAs							
Feature	Simulation Support						
pllena	The pllena signal is modeled. When this signal is driven low, the PLL loses lock and the PLL clock outputs are driven to logic low.						
areset	The areset signal is modeled. When this signal is driven high, the PLL loses lock and the PLL clock outputs are driven to logic low. Frequency over-shoot on the PLL clock outputs is not modeled.						
pfdena	The pfdena control signal is modeled. When this signal is driven low, the PLL's locked output is undefined and the PLL clock outputs continue to toggle at their last set frequency. The finite frequency long-term drift of the VCO is not modeled.						
locked	The locked signal is modeled for a high-bandwidth condition only. The PLL locks or relocks within 2 to 10 cycles during simulation, and does not necessarily reflect the real lock time.						
Frequency input change	If the input frequency of the PLL is changed in simulation, the model checks that $f_{\text{IN}} \times (\textit{M/N})$ is within the VCO frequency range and loses lock if outside the VCO operating range.						
Jitter	Jitter is not modeled in simulation.						

You can use the altpll behavioral model to simulate the Cyclone PLLs. The Cyclone behavioral model instantiation must follow the same guidelines and restrictions as the design entry. The altpll behavioral and timing models do not simulate jitter, lock time, or VCO drift.

The behavioral models for altpl1 reside in the \quartus\eda\sim\_lib directory. ALTERA\_MF.VHD contains the VHDL behavioral models and can be used for Cyclone designs that instantiate altpl1. ALTERA\_MF.v contains the Verilog HDL behavioral models. The behavioral model does not perform parameter error checking, and you must specify only valid values.



You must set the resolution of the simulator to units of pico seconds (ps) to simulate the model successfully. A larger resolution rounds off the calculations, providing incorrect results.

# Global Clock Network

Cyclone FPGAs have eight global clock networks. The four dedicated clock input pins (CLK[3..0]), eight dual-purpose clock pins (DPCLK[7..0]), and PLL clock outputs can drive the global clock networks. In addition, internal logic for internally-generated global clocks and asynchronous clears, clock enables, or other control signals with large fanout can drive the global clock networks.

The eight global clock lines that comprise the global clock network drive throughout the entire device. You can use the global clock network as clock sources for all device resources, including IOEs, logic elements (LEs), and memory blocks. You can also use global clock resources for control signals, such as clock enables and synchronous or asynchronous clears fed from external pins.

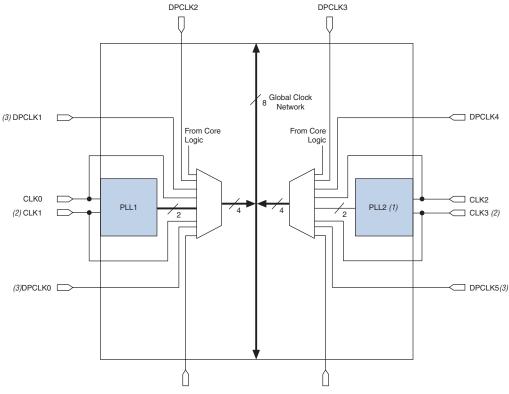


Figure 6–18 shows the global clock network resources.

Figure 6-18. Global Clock Generation

### Notes to Figure 6-18:

- (1) The EP1C3 device contains PLL1 only.
- The EP1C3 device in the 100-pin TQFP package does not have dedicated clock pins CLK1 and CLK3.

DPCLK7

The EP1C3 device in the 100-pin TQFP package has five  $\mathtt{DPCLKP}$  pins ( $\mathtt{DPCLK2}$ ,  $\mathtt{DPCLK3}$ ,  $\mathtt{DPCLK4}$ ,  $\mathtt{DPCLK4}$ , and DPCLK7). For more information, see ""Dual-Purpose Clock I/O Pins" on page 6-40.

DPCLK6

### **Dedicated Clock Input Pins**

Cyclone FPGAs have up to four dedicated clock input pins (CLK[3..0], two on the left and right side of the device. You can use the CLK[3..0] pins to drive the PLLs, or directly drive them onto the global clock network. Table 6–17 shows which clock pins drive which global clock network.

Table 6–17	Table 6–17. Dedicated Clock Input Pin Connections to Global Clock Network												
Clock Input Pin	GCLKO GCLK1 GCLK2 GCLK3 GCLK4 GCLK5 GCLK6 GCLK7												
CLK0	<b>✓</b>	_	<b>✓</b>	_	_	_	_	_					
CLK1 (1)	_	<b>✓</b>	_	<b>✓</b>	_	_	_	_					
CLK2	_	_	_	_	<b>✓</b>	_	<b>✓</b>	_					
CLK3 (1)		_		_		<b>✓</b>	_	<b>✓</b>					

Note to Table 6-17:

(1) The EP1C3 device in the 100-pin TQFP package does not have dedicated clock pins CLK1 and CLK3.

### **Dual-Purpose Clock I/O Pins**

Cyclone FPGAs can have up to eight dual-purpose clock pins,  $\label{eq:decompose} \begin{tabular}{l} $\operatorname{DPCLK}[7..0]$ (two on each side of the device). These dual-purpose pins can connect to the global clock network. You can use the <math display="block"> \begin{tabular}{l} $\operatorname{DPCLK}[7..0]$ pins for high fanout control signals, such as asynchronous clears, presets, clock enables, or protocol control signals (e.g., TRDY and IRDY for PCI, or DQS signals for external memory interfaces). These pins are also available as general-purpose I/O pins, meaning they can be inputs, outputs, or bidirectional pins. Table 6–18 shows which dual-purpose clock pins drive which global clock network in Cyclone FPGAs. \\ \end{tabular}$ 

Table 6–18.	Table 6–18. Dual-Purpose Clock I/O Connections to the Global Clock Network (Part 1 of 2)												
Dual- Purpose Clock Pin	GCLKO	GCLK1	GCLK2	GCLK3	GCLK4	GCLK5	GCLK6	GCLK7					
DPCLKO (1)	_	_	_	<b>✓</b>	_	_	_	_					
DPCLK1 (1)	_	_	✓	_	_	_	_	_					
DPCLK2	<b>✓</b>	_	_	_	_	_	_	_					
DPCLK3	_	_	_	_	<b>✓</b>	_	_	_					
DPCLK4	_	_	_	_	_	_	<b>✓</b>	_					

Table 6–18.	Table 6–18. Dual-Purpose Clock I/O Connections to the Global Clock Network (Part 2 of 2)												
Dual- Purpose Clock Pin	GCLKO	GCLK1	GCLK2	GCLK3	GCLK4	GCLK5	GCLK6	GCLK7					
DPCLK5 (1)	_	_	_	_	_	_	_	<b>✓</b>					
DPCLK6	_	_	_	_	_	<b>✓</b>	_	_					
DPCLK7	_	<b>✓</b>	_	_	_	_	_	_					

### Note to Table 6–18:

### **Combined Sources**

Table 6–19 shows which combined sources drive which global clock network.

Table 6–19	Table 6–19. Global Clock Network Sources (Part 1 of 2)												
S	ource	GCLKO	GCLK1	GCLK2	GCLK3	GCLK4	GCLK5	GCLK6	GCLK7				
	PLL1 G0	_	<b>✓</b>	<b>✓</b>	_	_	_	_	_				
PLL Counter	PLL1 G1	<b>✓</b>	_	_	<b>✓</b>	_	_	_	_				
Outputs	PLL2 G0 (1)	_	_	_	_	_	<b>✓</b>	<b>✓</b>	_				
•	PLL2 G1 (1)	_	_	_	_	<b>✓</b>	_	_	<b>✓</b>				
	CLK0	<b>✓</b>	_	<b>✓</b>	_	_	_	_	_				
Dedicated Clock	CLK1 (2)	_	<b>✓</b>	_	<b>✓</b>	_	_	_	_				
Input Pins	CLK2	_	_	_	_	<b>✓</b>	_	<b>✓</b>	_				
-	CLK3 (2)	_	_	_	_	_	<b>✓</b>	_	<b>✓</b>				

<sup>(1)</sup> The EP1C3 device in the 100-pin TQFP package does not have the DPCLK0, DPCLK1, or DPCLK5 pins.

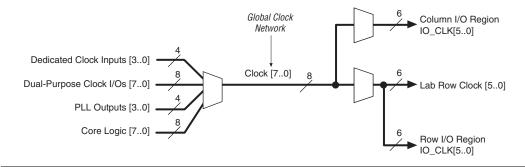
Table 6-19	Table 6–19. Global Clock Network Sources (Part 2 of 2)												
S	ource	GCLKO	GCLK1	GCLK2	GCLK3	GCLK4	GCLK5	GCLK6	GCLK7				
	DPCLK0	_	_	_	<b>✓</b>	_	_	_	_				
	DPCLK1 (3)	_	_	<b>✓</b>	_	_		_	_				
	DPCLK2	<b>✓</b>	_	_	_	_	_	_	_				
Dual-	DPCLK3	_	_	_	_	<b>✓</b>		_	_				
Purpose Clock Pins	DPCLK4	_	_	_	_	_		<b>✓</b>	_				
	DPCLK5		_	_	_	_	_	_	<b>✓</b>				
	DPCLK6	_	_	_	_	_	✓	_	_				
	DPCLK7	_	<b>✓</b>	_		_	1	_	_				

### *Notes to Table 6–19:*

- (1) The EP1C3 device only has PLL1.
- (2) The EP1C3 device in the 100-pin TQFP package does not have dedicated clock pins CLK1 and CLK3.
- (3) The EP1C3 device does not have DPCLK1.

In the Cyclone FPGA, there are eight distinct dedicated global clock networks. Multiplexers are used with these clocks to form six-bit buses to drive LAB row clocks, column IOE clocks, or row IOE clocks (see Figure 6–19). Another multiplexer is used at the LAB level to select two of the six row clocks to feed the LE registers within the LAB.

Figure 6-19. Global Clock Network Multiplexers



IOE clocks have horizontal (row) and vertical (column) block regions that are clocked by six I/O clock signals chosen from the eight global clock resources. Figure 6–20 shows the I/O clock regions.

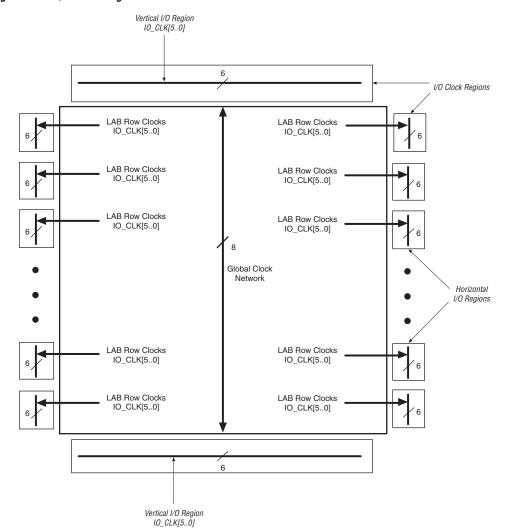


Figure 6-20. I/O Clock Regions

### **Conclusion**

Cyclone PLLs provide significant features such as  $M/(N \times \text{post-scale})$  multiplication/division, phase shift, and programmable duty cycle for your cost-sensitive clock synthesis applications. The reduction in clock delay, and the elimination of clock skew within the device, improves design speed. Cyclone PLL features simplify board design by running the internal logic of the device at a faster rate than the input clock frequency.

# Referenced Documents

This chapter references the following documents:

- AN 75: High-Speed Board Designs
- DC and Switching Characteristics chapter of the Cyclone Device Handbook

# Document Revision History

Table 6–20 shows the revision history for this chapter.

Table 6–20. Do	Table 6–20. Document Revision History							
Date and Document Version	Changes Made	Summary of Changes						
May 2008 v1.5	Minor textual and style changes. Added "Referenced Documents" section.	_						
January 2007 v1.4	<ul> <li>Added document revision history.</li> <li>Updated information about pllena signal in "Control Signals" section.</li> <li>Updated "Zero Delay Buffer Mode" section.</li> <li>Updated Figure 6–5.</li> </ul>	_						
August 2005 v1.3	Minor updates.	_						
October 2003 v1.2	Updated phase shift information.	_						
July 2003 v1.1	Updated input and output frequency specifications.	_						
May 2003 v1.0	Added document to Cyclone Device Handbook.	_						



# **Section III. Memory**

This section provides information on the M4K embedded memory blocks internal to Cyclone devices.

It contains the following:

 Chapter 7. On-Chip Memory Implementations Using Cyclone Memory Blocks

# **Revision History**

Refer to each chapter for its own specific revision history. For information on when each chapter was updated, refer to the Chapter Revision Dates section, which appears in the complete handbook.

Altera Corporation Part III-1

Part III-2 Altera Corporation



# 7. On-Chip Memory Implementations Using Cyclone Memory Blocks

C51007-1.4

### Introduction

Cyclone® devices feature embedded memory blocks that can be easily configured to support a wide range of system requirements. These M4K memory blocks present a very flexible and fast memory solution that you can use to provide excellent memory bandwidth and density for a host of cost-sensitive applications.

You can use M4K memory blocks in various memory modes, including single-port, simple dual-port, true dual-port (also known as bidirectional dual-port), shift-register, ROM, and first-in first-out (FIFO) mode. M4K memory blocks also include advanced features such as support for byte-enable operation, parity-bit-based error correction, and mixed-port widths. This chapter describes these modes and other characteristics of the M4K memory blocks.

# M4K Memory Features

Table 7–1 summarizes the features supported by the M4K memory block.

Table 7–1. Summary of M4K Memory Features (Part 1 of 2)						
Performance	250 MHz					
Total RAM bits (including parity bits)	4,608					
Configurations	4K × 1					
	2K × 2					
	1K × 4					
	512 × 8					
	512 × 9					
	256 × 16					
	256 × 18					
	128 × 32					
	128 × 36 <i>(1)</i>					
Parity bits	<b>✓</b>					
Byte enable	<b>✓</b>					
Single-port memory	✓					
Simple dual-port memory	✓					
True dual-port memory	✓					
Embedded shift register	✓					
ROM	✓					

Table 7–1. Summary of M4K Memory Features (Part 2 of 2)							
FIFO buffer	✓						
Simple dual-port mixed width support	✓						
True dual-port mixed width support	✓						
Memory initialization (.mif)	✓						
Mixed-clock mode	✓						
Power-up condition	Outputs cleared						
Register clears	Input and output registers (2)						
Same-port read-during-write	New data available at positive clock edge						
Mixed-port read-during-write	Outputs set to unknown or old data						

Notes to Table 7–1:

- The Altera® Quartus® II software will automatically cascade or concatenate multiple M4K memory blocks to provide deeper or wider memory functions.
- (2) Asserting the clear port of the rden and byte-enable registers drives the output of these registers high.

Table 7–2 shows the memory capacity for M4K memory blocks in each Cyclone device.

Table 7–2. M4K Memory Distribution in Cyclone Devices									
Device	Columns	Blocks	Total RAM Bits						
EP1C3	1	13	59,904						
EP1C4	1	17	78,336						
EP1C6	1	20	92,160						
EP1C12	2	52	239,616						
EP1C20	2	64	294,912						

### **Parity Bit Support**

M4K memory blocks support an optional parity bit for each data byte. Of the 4,608 bits of storage space available in an M4K block, 512 are available for use as parity-bit storage. The parity bit, along with logic implemented in logic elements (LEs), can facilitate parity-checking methods of error detection to ensure data integrity. You can also use parity-size data words to store user-specified control bits or as extra data bits to provide support for 9-bit, 18-bit, or 36-bit wide memories.

### **Byte-Enable Support**

Byte-enable signals can be used to mask the input data so that only specific bytes in memory are overwritten. The unwritten bytes retain the data value that was last written to them. The write-enable signal (wren) is used in conjunction with byte-enable signals (byteena) to control the M4K block's write operations. The default value for the byteena signal is high (enabled), in which case no bytes are masked and writing is controlled only by the wren signals.

Asserting the clear port of the byte-enable register drives the byte-enable signal to its default high level.

M4K blocks support byte write operations when the write port has a data width of 16, 18, 32, or 36 bits. Table 7–3 summarizes how byteena controls which bits are masked.

Table 7–3. Byte Enable for M4K Blocks Notes (1), (2)								
byteena	datain × 18	datain × 36						
[0] = 1	[80]	[80]						
[1] = 1	[179]	[179]						
[2] = 1	_	[2618]						
[3] = 1	_	[3527]						

Notes to Table 7-3:

- (1) Any combination of byte-enable signals is possible.
- (2) Byte enables can be used in the same manner with 8-bit words, i.e., in × 16 and × 32 modes.

Figure 7–1 shows how both the wren and the byteena signals control the write operations of the RAM.

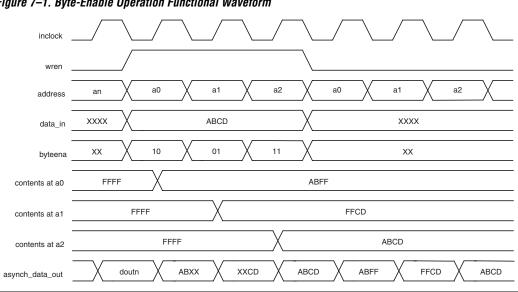


Figure 7–1. Byte-Enable Operation Functional Waveform

### **Power-up Conditions and Memory Initialization**

Upon power-up, M4K memory is in an idle state. The outputs always power-up to zero, regardless of whether the output registers are used or bypassed. Even if a memory initialization file is used to pre-load the contents of the RAM block, the outputs will still power-up cleared. For example, if address 0 is pre-initialized to FF, the M4K blocks power-up with the output at 00.

# Using M4K Memory

M4K memory blocks include input registers that synchronize write operations and output registers to pipeline designs and improve system performance. All M4K memory blocks are fully synchronous, meaning that all inputs are registered, but outputs can be either registered or combinatorial. M4K memory can emulate asynchronous memory.



Violating the setup or hold time on the address registers could corrupt the memory contents. This applies to both read and write operations.



For more information, refer to AN 210: Converting Memory from Asynchronous to Synchronous for Stratix and Stratix GX Designs.

M4K memory blocks can operate in various modes, including:

- Single-port
- Simple dual-port
- True dual-port (bidirectional dual-port)
- Shift-register
- ROM
- FIFO

### **Implementing Single-Port Mode**

Single-port mode supports non-simultaneous read and write operations. Figure 7–2 shows the single-port memory configuration for M4K blocks.

Figure 7–2. Single-Port Memory Note (1)



Note to Figure 7-2:

(1) Two single-port memory blocks can be implemented in a single M4K block.

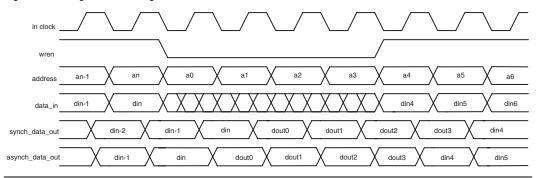
M4K memory blocks can also be divided in half and used for two independent single-port RAM blocks. The Quartus II software automatically uses this method of single-port memory packing when running low on memory resources. When deliberately assigning two single-port memories to one M4K block, first ensure that each of the two independent RAM blocks is equal to or less than half the size of the M4K block.

In the single-port RAM configuration, the outputs can only be in readduring-write mode, which means that during the write operation, data written to the RAM flows through to the RAM outputs. When the output registers are bypassed, the new data is available on the rising edge of the same clock cycle on which it was written.

For more information about read-during-write mode, see "Read-during-Write Operation at the Same Address" on page 7–20.

Figure 7–3 shows timing waveforms for read and write operations in single-port mode.

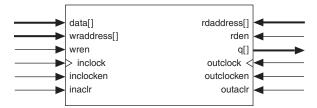
Figure 7-3. Single-Port Timing Waveforms



### **Implementing Simple Dual-Port Mode**

Simple dual-port memory supports simultaneous read and write operations. Figure 7–4 shows the simple dual-port memory configuration for M4K blocks.

Figure 7–4. Simple Dual-Port Memory Note (1)



Note to Figure 7-4:

 Simple dual-port RAM supports read/write clock mode in addition to the input/output clock mode shown.

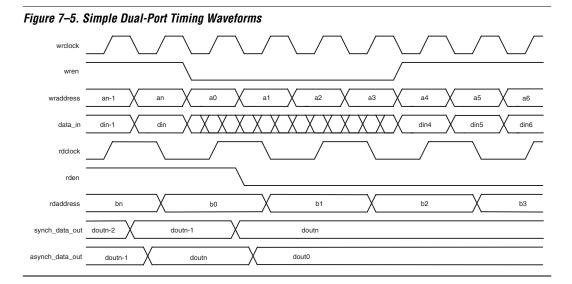
M4K memory supports mixed-width configurations, allowing different read and write port widths. This capability is useful for many applications, including implementing serializer-deserializers (SERDES) as well as interfacing with buses of differing widths. Table 7–4 shows the mixed-width configurations supported by the M4K blocks in Cyclone devices.

Read		Write Port											
Port	4K × 1	2K × 2	1K × 4	512 × 8	256 × 16	128 × 32	512 × 9	256 × 18	128 × 36				
4K × 1	<b>✓</b>	<b>✓</b>	<b>✓</b>	<b>✓</b>	<b>✓</b>	<b>✓</b>	_	_	_				
2K × 2	✓	<b>✓</b>	<b>✓</b>	<b>✓</b>	<b>✓</b>	<b>✓</b>	_	_	_				
1K × 4	✓	<b>✓</b>	<b>✓</b>	<b>✓</b>	<b>✓</b>	~	_	_	_				
512 × 8	✓	<b>✓</b>	<b>✓</b>	<b>✓</b>	<b>✓</b>	~	_	_	_				
256 × 16	✓	<b>✓</b>	<b>✓</b>	<b>✓</b>	<b>✓</b>	~	_	_	_				
128 × 32	✓	<b>✓</b>	<b>✓</b>	<b>✓</b>	<b>✓</b>	~	_	_	_				
512 × 9	_	_	_	_	_	_	<b>✓</b>	<b>✓</b>	<b>✓</b>				
256 × 18	_	_	_	_	_	_	<b>✓</b>	<b>✓</b>	<b>✓</b>				
128 × 36	_	_	_	_	_	_	<b>✓</b>	<b>✓</b>	<b>✓</b>				

In simple dual-port mode, M4K blocks have one write-enable and one read-enable signal. On the M4K block, asserting the clear port of the rden register drives rden high, which allows the read operation to occur. When the read-enable signal is deactivated, the current data is retained at the output ports. If the read-enable signal is activated during a write operation with the same address location selected, the simple dual-port RAM output is either unknown or can be set to output the old data stored at the memory address.

For more information, see "Read-during-Write Operation at the Same Address" on page 7–20.

Figure 7–5 shows timing waveforms for read and write operations in simple dual-port mode.

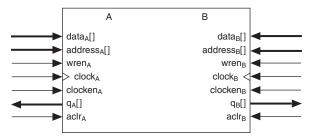


### **Implementing True Dual-Port Mode**

M4K blocks offer a true dual-port mode to support any combination of two-port operations: two read operations, two write operations, or one read operation and one write operation at two different clock frequencies. True dual-port memory can be used to increase memory bandwidth in numerous applications. An example system that benefits from the use of true dual-port memory is a system containing an Altera Nios® embedded processor and a direct memory access (DMA) controller. Such a system will experience bottlenecks if the processor and the DMA controller need simultaneous access to single-port memory. The ability of both the processor and the DMA controller to access the M4K memory simultaneously, avoiding the need for arbitration, can dramatically improve bandwidth in this type of system.

Figure 7–6 shows the true dual-port memory configuration for M4K blocks.

Figure 7–6. True Dual-Port Memory Note (1)



*Note to Figure 7–6:* 

(1) True dual-port memory supports input/output clock mode in addition to the independent clock mode shown.

The widest bit configuration of a single M4K block in true dual-port mode is  $256 \times 16$ -bit (or  $256 \times 18$ -bit with parity). The  $128 \times 32$ -bit ( $128 \times 36$ -bit with parity) configuration of the M4K block is unavailable because the number of output drivers is equivalent to the maximum bit width of the M4K block. Because true dual-port RAM has outputs on two ports, the maximum width of the true dual-port RAM equals half of the total number of output drivers. However, multiple M4K blocks can be concatenated to support wider memory configurations. Table 7–5 lists the possible M4K RAM block configurations.

Table 7-5. M4K Block Mixed-Port Width Configurations (True Dual-Port Mode) Port B Port A 4K × 1  $2K \times 2$  $1K \times 4$ 512 × 8 256 × 16  $512 \times 9$  $256 \times 18$  $4K \times 1$  $2K \times 2$  $1K \times 4$ 512 × 8  $256 \times 16$ ✓ 512 × 9 256 × 18

In true dual-port mode, the RAM outputs can only be configured for read-during-write mode. This means that during write operation, data being written to the A or B port of the RAM flows through to the A or B outputs, respectively. When the output registers are bypassed, the new data is available on the rising edge of the same clock cycle it was written on.

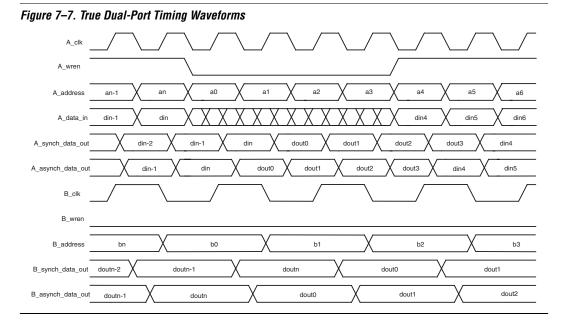
For sample waveforms and other information on mixed-port readduring-write mode, see "Read-during-Write Operation at the Same Address" on page 7–20.

Potential write conflicts must be resolved external to the RAM because simultaneously writing to the same address location at both ports results in unknown data storage at that location. For a valid write operation to the same address of the RAM block, the rising edge of the write clock for port A must occur following the minimum write cycle time interval after the rising edge of the write clock for port B. Since data is written into the M4K blocks at the falling edge of the write clock, the rising edge of the write clock for port A should occur following half of the minimum write cycle time interval after the falling edge of the write clock for port B. If this timing is not met, the data stored in that particular address will be invalid.



For more information about the minimum synchronous write cycle time, refer to the *Cyclone FPGA Family Data Sheet* section of the *Cyclone Device Handbook*.

Figure 7–7 shows true dual-port timing waveforms for a write operation at port A and a read operation at port B.



### Implementing Shift-Register Mode

Embedded memory configurations can implement shift-register blocks for digital signal processing (DSP) applications, such as finite impulse response (FIR) filters, pseudo-random number generators, multi-channel filtering, and auto-correlation and cross-correlation functions. These and other DSP applications require local data storage, traditionally implemented with standard flip-flops that can quickly consume many logic cells for large shift registers. A more efficient alternative is to use embedded memory as a shift-register block, which saves logic cell and routing resources and provides a more efficient implementation.

The size of a  $(w \times m \times n)$  shift register is determined by the input data width (w), the length of the taps (m), and the number of taps (n). The size of a  $(w \times m \times n)$  shift register must be less than or equal to the 4,608 bits. In addition, the size of  $(w \times n)$  must be less than or equal to 36 bits. If a larger shift register is required, memory blocks can be cascaded together.

Data is written into each address location at the falling edge of the clock and read from the address at the rising edge of the clock. The shift-register mode logic automatically controls the positive and negative edge clocking to shift the data in one clock cycle. Figure 7–8 shows the M4K memory block in shift-register mode.

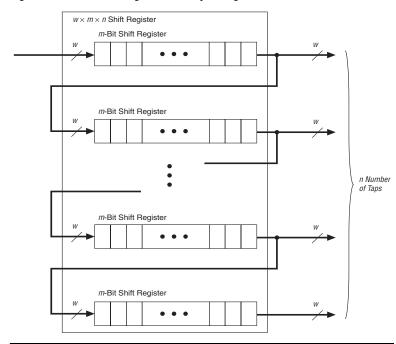


Figure 7–8. M4K Shift-Register Memory Configuration

# **Implementing ROM Mode**

M4K blocks can also be configured as ROM. ROM can be initialized in an M4K block by using a memory initialization file (.mif). Because all M4K memory configurations must have synchronous inputs, the address lines of the ROM are registered. ROM outputs can be registered or combinatorial. The read operation of the ROM is identical to the read operation of the single-port RAM configuration.

# **Implementing FIFO Buffers**

FIFO buffer outputs are always combinatorial. Simultaneous read and write operations from an empty FIFO buffer are not supported.

# **Clock Modes**

Depending on the M4K memory mode, independent, input/output, read/write, and/or single-port clock modes are available. Table 7–6 shows the clock modes supported by the M4K memory modes.

Table 7–6. M4K Memory Clock Modes			
Clocking Mode	True-Dual Port Mode	Simple Dual- Port Mode	Single-Port Mode
Independent	✓	_	_
Input/output	✓	<b>✓</b>	_
Read/write	_	<b>✓</b>	_
Single-port	_	_	✓

## **Independent Clock Mode**

M4K memory blocks can implement independent clock mode for true dual-port memory. In this mode, a separate clock is available for each port (A and B). Clock A controls all registers on the port A side, while clock B controls all registers on the port B side. Each port also supports independent clock-enable signals and asynchronous clear signals for port A and B registers. Figure 7–9 shows an M4K memory block in independent clock mode.

byteena<sub>B</sub>[] address<sub>B</sub>[] data<sub>B</sub>[] EN D ENA Ω ENA Write Pulse Generator □ ¥ Write/Read Enable Byte Enable B Address B Data Out В Memory Block Byte Enable A Write/Read Enable Address A ⋖ Data Out Data In ΕNΑ ۵ Write Pulse Generator o ¥ o ₩ o ¥ o ¥ 8 LAB Row Clocks data<sub>A</sub>[] \_ address<sub>A</sub>[] clken<sub>A</sub> byteena<sub>A</sub>[] wren  $clock_A$ 

Figure 7–9. Independent Clock Mode Note (1)

Note to Figure 7–9:

(1) Violating the setup or hold time on the address registers could corrupt the memory contents. This applies to both read and write operations.

# **Input/Output Clock Mode**

M4K memory blocks can implement input/output clock mode for true and simple dual-port memory. On each of the two ports, A and B, one clock controls all registers for inputs (data input, wren, and address) into the memory block. The other clock controls the block's data output registers. Each memory block port also supports independent clock enables and asynchronous clear signals for input and output registers. Figures 7–10 and 7–11 show the memory block in input/output clock mode for true and simple dual-port modes, respectively.

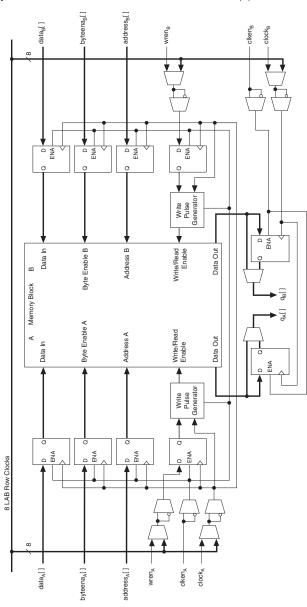


Figure 7–10. Input/Output Clock Mode in True Dual-Port Mode Note (1)

*Note to Figure 7–10:* 

(1) Violating the setup or hold time on the address registers could corrupt the memory contents. This applies to both read and write operations.

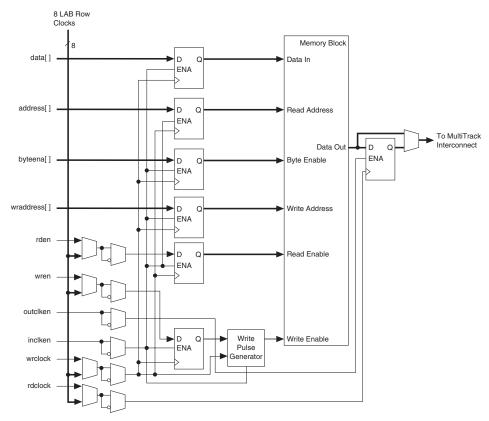


Figure 7–11. Input/Output Clock Mode in Simple Dual-Port Mode Notes (1), (2)

### Notes to Figure 7–11:

- For more information on the MultiTrack<sup>TM</sup> interconnect, refer to the Cyclone FPGA Family Data Sheet section of the Cyclone Device Handbook.
- (2) Violating the setup or hold time on the address registers could corrupt the memory contents. This applies to both read and write operations.

### Read/Write Clock Mode

M4K memory blocks can implement read/write clock mode for simple dual-port memory. This mode can use up to two clocks. The write clock controls the block's data inputs, wraddress, and wren. The read clock controls the data output, rdaddress, and rden. The memory blocks support independent clock enables for each clock and asynchronous clear signals for the read- and write-side registers. Figure 7–12 shows a memory block in read/write clock mode.

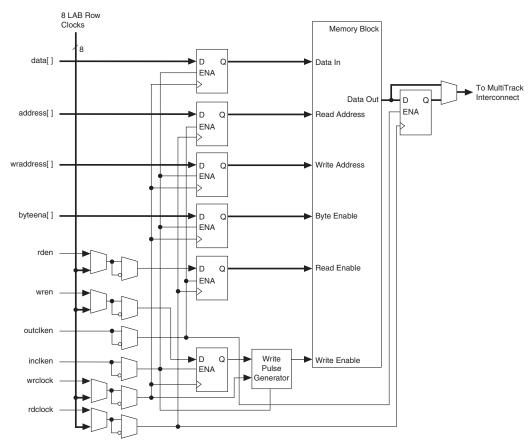


Figure 7–12. Read/Write Clock Mode in Simple Dual-Port Mode Notes (1), (2)

*Notes to Figure 7–12:* 

- (1) For more information on the MultiTrack interconnect, refer to the Cyclone FPGA Family Data Sheet section of the Cyclone Device Handbook.
- (2) Violating the setup or hold time on the address registers could corrupt the memory contents. This applies to both read and write operations.

# **Single-Port Mode**

The M4K memory blocks can implement single-port clock mode when simultaneous read and write operations are not required (see Figure 7–13). A single block in a memory block can support up to two single-port mode RAM blocks in M4K blocks.

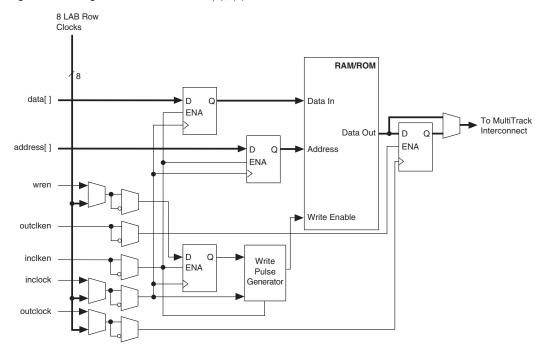


Figure 7–13. Single-Port Mode Notes (1), (2)

#### Notes to Figure 7–13:

- For more information about the MultiTrack interconnect, refer to the Cyclone FPGA Family Data Sheet section of the Cyclone Device Handbook.
- (2) Violating the setup or hold time on the address registers could corrupt the memory contents. This applies to both read and write operations.

# Synchronous and Pseudo-Asynchronous Modes

The M4K memory architecture implements synchronous, pipelined RAM by registering both the input and output signals to the RAM block. All M4K memory inputs are registered, providing synchronous write cycles. In synchronous operation, an M4K block generates its own self-timed strobe write enable (wren) signal derived from the global or regional clock. In contrast, a circuit using asynchronous RAM must generate the RAM wren signal while ensuring its data and address signals meet setup and hold time specifications relative to the wren signal. The output registers can be bypassed.

In an asynchronous memory, neither the input nor the output is registered. While Cyclone devices do not support asynchronous memory, they do support a pseudo-asynchronous read operation where the output data is available during the same clock cycle as when the read address is driven into it. Pseudo-asynchronous reading is possible in the simple and

true dual-port modes of the M4K blocks by clocking the read enable and read address registers on the negative clock edge and bypassing the output registers.

The clear signal for both asynchronous and synchronous mode for the memory are treated similarly in Cyclone devices. All inputs to the memory must be synchronous, therefore, the time it takes a clear signal to reset the input or output registers is synchronous to the clock.



For more information, refer to AN 210: Converting Memory from Asynchronous to Synchronous for Stratix and Stratix GX Designs.

# Read-during-Write Operation at the Same Address

The following two sections describe the functionality of the various M4K memory configurations when reading from an address during a write operation at that same address. There are two types of read-during-write operations: same-port and mixed-port. Figure 7–14 illustrates the difference in data flow between same-port and mixed-port read-during-write.

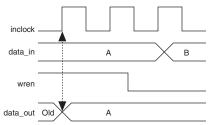
Figure 7-14. Read-during-Write Data Flow

# Same-Port Read-during-Write Mode

For read-during-write operation of a single-port RAM or the same port of a true dual-port RAM, the new data is available on the rising edge of the same clock cycle it was written on. See Figure 7–15 for a sample functional waveform.

When using byte-enable signals in true dual-port RAM mode, the outputs for the masked bytes on the same port are unknown. (See Figure 7–1.) The non-masked bytes are read out as shown in Figure 7–15.

Figure 7–15. Same-Port Read-during-Write Functionality Note (1)



Note to Figure 7-15:

(1) Outputs are not registered.

### Mixed-Port Read-during-Write Mode

This mode is used when a RAM in simple or true dual-port mode has one port reading and the other port writing to the same address location with the same clock. You can configure the M4K memory block to operate in this mode and modify the parameter shown below using the MegaWizard® Plug-In Manager included with the Quartus II software.

The READ\_DURING\_WRITE\_MODE\_MIXED\_PORTS parameter for M4K memory blocks determines whether or not to output the old data at the address. Setting this parameter to OLD\_DATA outputs the old data at that address. Setting this parameter to DONT\_CARE outputs an unknown value. During the instantiation of an ALTSYNCRAM or LPM\_RAM\_DP+ storage megafunction using the Quartus II software, the MegaWizard plug-in manager asks "How should the q output behave when reading a memory location that is being written from the other port?" Clicking "I don't care" assigns the DONT\_CARE value to the parameter, and clicking "Old memory contents appear" assigns the OLD\_DATA value to the parameter.



Altera recommends using the MegaWizard Plug-In Manager to create these memory megafunctions rather than directly creating instances. Once a storage megafunction is created using the MegaWizard Plug-In Manager, use the MegaWizard Plug-In Manager to make any necessary changes.

See Figures 7–16 and 7–17 for sample functional waveforms showing mixed-port read-during-write mode operation. These figures assume that the outputs are not registered.

inclock
address<sub>A</sub> and
address<sub>B</sub>

Port A
data\_in

Port B
wren

Port B
wren

Port B
data\_out

Old

Address Q

Address Q

Address Q

B

Address Q

Address Q

B

Address Q

Address Q

Address Q

B

Address Q

Address Q

Address Q

Address Q

Address Q

Address Q

B

Address Q

Address Q

Address Q

Address Q

B

Address Q

Address Q

Address Q

B

Address Q

Address Q

Address Q

B

Address Q

Address Q

B

Address Q

Address Q

Address Q

Address Q

B

Address Q

Address Q

B

Address Q

Address Q

Address Q

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Address Q

Address Q

Address Q

Address Q

B

Address Q

Address Q

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Address Q

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Address Q

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Address Q

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Address Q

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Address Q

Address Q

B

Address Q

Address Q

B

Address Q

B

Address Q

Address Q

B

Address Q

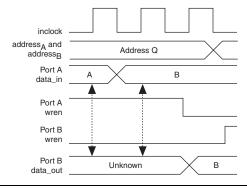
Address Q

B

A

Figure 7-16. Mixed-Port Read-during-Write: OLD\_DATA

Figure 7-17. Mixed-Port Read-during-Write: DONT\_CARE



Mixed-port read-during-write is not supported when two different clocks are used in a dual-port RAM. The output value is unknown during a mixed-port read-during-write operation.



For the minimum synchronous-write-cycle time, refer to the *Cyclone FPGA Family Data Sheet* section of the *Cyclone Device Handbook*.

# **Conclusion**

M4K memory blocks are a flexible memory solution available in Cyclone devices that provide advanced features such as byte-enable capability, parity bit storage capability, and shift-register mode, as well as mixed-port width support and true dual-port mode. This flexibility makes these embedded memory blocks well suited for a wide range of applications including ATM cell packet processing, header/cell storage, channelized functions, and program memory for processors.

# Referenced Documents

This chapter references the following documents:

- AN 210: Converting Memory from Asynchronous to Synchronous for Stratix and Stratix GX Designs
- Cyclone FPGA Family Data Sheet section of the Cyclone Device Handbook

# Document Revision History

Table 7–7 shows the revision history for this chapter.

Table 7-7. Doc	Table 7–7. Document Revision History		
Date and Document Version	Changes Made	Summary of Changes	
May 2008 v1.4	Minor textual and style changes. Added "Referenced Documents" section.	_	
January 2007 v1.3	Added document revision history.	_	
August 2005 v1.2	Minor updates.	_	
February 2005 v1.1	Updated notes for Figures 7-9 through 7-13.	_	
May 2003 v1.0	Added document to Cyclone Device Handbook.	_	



# Section IV. I/O Standards

This section provides information on the Cyclone FPGA I/O capabilities. It also includes information on selecting I/O standards for Cyclone devices in the Quartus II software.

This section contains the following chapters:

- Chapter 8. Using Selectable I/O Standards in Cyclone Devices
- Chapter 9. High-Speed Differential Signaling in Cyclone Devices

# **Revision History**

Refer to each chapter for its own specific revision history. For information on when each chapter was updated, refer to the Chapter Revision Dates section, which appears in the complete handbook.

Altera Corporation Section IV-1

Section IV-2 Altera Corporation



# 8. Using Selectable I/O Standards in Cyclone Devices

C51008-1.6

## Introduction

The proliferation of I/O standards and the need for improved I/O performance have made it critical that low-cost devices have flexible I/O capabilities. Selectable I/O capabilities such as SSTL-2, SSTL-3, and LVDS compatibility allow Cyclone® devices to connect to other devices on the same printed circuit board (PCB) that may require different operating and I/O voltages. With these aspects of implementation easily manipulated using the Altera Quartus® II software, the Cyclone device family enables system designers to use low-cost FPGAs while keeping pace with increasing design complexity.

This chapter is a guide to understanding the input/output capabilities of the Cyclone devices, including:

- Supported I/O Standards
- Cyclone I/O Banks
- Programmable Current Drive Strength
- Hot Socketing
- I/O Termination
- Pad Placement and DC Guidelines
- Quartus II Software Support

"Quartus II Software Support" on page 8–18 describes how to use the Quartus II software to specify device and pin options and assign pins to implement the above features of Cyclone devices.

# Supported I/O Standards

Cyclone devices support the I/O standards shown in Table 8–1.



For more details about the I/O standards discussed in this section, refer to the *Cyclone FPGA Family Data Sheet* section of the *Cyclone Device Handbook*.

Table 8–1. I/O Sta	Table 8–1. I/O Standards Supported by Cyclone Devices       Notes (1), (2)					
I/O Standard	Туре	Input Voltage Level (V)	Output Voltage Level (V)	Input V <sub>REF</sub> (V)	Output V <sub>CCIO</sub> (V)	Termination V <sub>TT</sub> (V)
3.3-V LVTTL/LVCMOS	Single-ended	3.3/2.5	3.3	N/A	3.3	N/A
2.5-V LVTTL/LVCMOS	Single-ended	3.3/2.5	2.5	N/A	2.5	N/A
1.8-V LVTTL/LVCMOS	Single-ended	3.3/2.5/1.8	1.8	N/A	1.8	N/A
1.5-V LVCMOS	Single-ended	3.3/2.5/1.8/1.5	1.5	N/A	1.5	N/A
PCI (3)	Single-ended	3.3	3.3	N/A	3.3	N/A
SSTL-3 Class I and II	Voltage-referenced	-0.3 to 3.9	3.3	1.5	3.3	1.5
SSTL-2 Class I and II	Voltage-referenced	-0.3 to 3.0	2.5	1.25	2.5	1.25
LVDS Compatibility	Differential	0 to 2.4	VOD = 0.25 to 0.55	N/A	2.5	N/A
RSDS Compatibility	Differential	0.1 to 1.4	VOD = 0.1 to 0.6	N/A	2.5	N/A
Differential SSTL - 2	Differential	N/A (4)	2.5	1.25	2.5	1.25

#### Notes to Table 8-1:

- (1) The EP1C3 device in the 100-pin thin quad flat pack (TQFP) package does not have support for a PLL LVDS input or an external clock output.
- (2) Cyclone devices have dual-purpose differential inputs. Outputs are balanced SSTL outputs requiring an external resistor divider.
- (3) EP1C3 devices support PCI by using the LVTTL 16-mA I/O standard and drive strength assignments in the Quartus II software. The device requires an external diode for PCI compliance.
- (4) This I/O standard is only available on output clock pins (PLL\_OUT pins).

### 3.3-V LVTTL (EIA/JEDEC Standard JESD8-B)

The 3.3-V LVTTL I/O standard is a general-purpose, single-ended standard used for 3.3-V applications. The LVTTL standard defines the DC interface parameters for digital circuits operating from a 3.0-V/3.3-V power supply and driving or being driven by LVTTL-compatible devices.

The LVTTL input standard specifies a wider input voltage range of  $-0.3~V \le V_I \le 3.9~V$ . Altera recommends an input voltage range of  $-0.5~V \le V_I \le 4.1~V$ . The LVTTL standard does not require input reference voltages or board terminations. Cyclone devices support both input and output levels for 3.3-V LVTTL.

## 3.3-V LVCMOS (EIA/JEDEC Standard JESD8-B)

The 3.3-V LVCMOS I/O standard is a general-purpose, single-ended standard used for 3.3-V applications. The LVCMOS standard defines the DC interface parameters for digital circuits operating from a 3.0-V or 3.3-V power supply and driving or being driven by LVCMOS-compatible devices.

The LVCMOS standard specifies the same input voltage requirements as LVTTL (–  $0.3~V \le V_I \le 3.9~V$ ). The output buffer drives to the rail to meet the minimum high-level output voltage requirements. The 3.3-V I/O Standard does not require input reference voltages or board terminations. Cyclone devices support both input and output levels specified by the 3.3-V LVCMOS I/O standard.

# 2.5-V LVTTL Normal and Wide Voltage Ranges (EIA/JEDEC Standard EIA/JESD8-5)

The 2.5-V I/O standard is used for 2.5-V LVTTL applications. This standard defines the DC interface parameters for high-speed, low-voltage, non-terminated digital circuits driving or being driven by other 2.5-V devices. The input and output voltage requirements are:

- The 2.5-V normal and wide range input standards specify an input voltage range of  $-0.3 \text{ V} \leq \text{VI} \leq 3.0\text{-V}$ .
- The normal range minimum high-level output voltage requirement (V<sub>OH</sub>) is 2.1-V.
- The wide range minimum high-level output voltage requirement  $(V_{OH})$  is  $V_{CCIO} = 0.2$ -V.

The 2.5-V standard does not require input reference voltages or board terminations. Cyclone devices support input and output levels for both 2.5-V LVTTL ranges.

# 2.5-V LVCMOS Normal and Wide Voltage Ranges (EIA/JEDEC Standard EIA/JESD8-5)

The 2.5-V I/O standard is used for 2.5-V LVCMOS applications. This standard defines the DC interface parameters for high-speed, low-voltage, non-terminated digital circuits driving or being driven by other 2.5-V parts. The input and output voltage ranges are:

- The 2.5-V normal and wide range input standards specify an input voltage range of -0.3-V  $\leq$  V<sub>I</sub>  $\leq$  3.0-V.
- The normal range minimum V<sub>OH</sub> requirement is 2.1 V.
- The wide range minimum  $V_{OH}$  requirement is  $V_{CCIO}$  0.2 V.

The 2.5-V standard does not require input reference voltages or board terminations. Cyclone devices support input and output levels for both 2.5-V LVCMOS ranges.

# 1.8-V LVTTL Normal and Wide Voltage Ranges (EIA/JEDEC Standard EIA/JESD8-7)

The 1.8-V I/O standard is used for 1.8-V LVTTL applications. This standard defines the DC interface parameters for high-speed, low-voltage, non-terminated digital circuits driving or being driven by other 1.8-V parts. The input and output voltage ranges are:

- The 1.8-V normal and wide range input standards specify an input voltage range of  $0.3 \text{ V} \le V_I \le 2.25 \text{ V}$ .
- The normal range minimum  $V_{OH}$  requirement is  $V_{CCIO}$  0.45 V.
- The wide range minimum  $V_{OH}$  requirement is  $V_{CCIO} 0.2 \text{ V}$ .

The 1.8-V standard does not require input reference voltages or board terminations. Cyclone devices support input and output levels for both normal and wide 1.8-V LVTTL ranges.

# 1.8-V LVCMOS Normal and Wide Voltage Ranges (EIA/JEDEC Standard EIA/JESD8-7)

The 1.8-V I/O standard is used for 1.8-V LVCMOS applications. This standard defines the DC interface parameters for high-speed, low-voltage, non-terminated digital circuits driving or being driven by other 1.8-V devices. The input and output voltage ranges are:

- The 1.8-V normal and wide range input standards specify an input voltage range of  $-0.3 \text{ V} \le V_1 \le 2.25 \text{ V}$ .
- The normal range minimum  $V_{OH}$  requirement is  $V_{CCIO}$  0.45 V.
- The wide range minimum  $V_{OH}$  requirement is  $V_{CCIO}$  0.2 V.

The 1.8-V standard does not require input reference voltages or board terminations. Cyclone devices support input and output levels for both normal and wide 1.8-V LVCMOS ranges.

# 1.5-V LVCMOS Normal and Wide Voltage Ranges (EIA/JEDEC Standard JESD8-11)

The 1.5-V I/O standard is used for 1.5-V applications. This standard defines the DC interface parameters for high-speed, low-voltage, non-terminated digital circuits driving or being driven by other 1.5-V devices. The input and output voltage ranges are:

- The 1.5-V normal and wide range input standards specify an input voltage range of  $-0.3 \text{ V} \le V_1 \le 1.9\text{-V}$ .
- The normal range minimum V<sub>OH</sub> requirement is 1.05 V.
- The wide range minimum  $V_{OH}$  requirement is  $V_{CCIO}$  0.2-V.

The 1.5-V standard does not require input reference voltages or board terminations. Cyclone devices support input and output levels for both normal and wide 1.5-V LVCMOS ranges.

# 3.3-V (PCI Special Interest Group (SIG) PCI Local Bus Specification Revision 2.2)

The PCI local bus specification is used for applications that interface to the PCI local bus, which provides a processor-independent data path between highly integrated peripheral controller components, peripheral add-in boards, and processor/memory systems. The conventional PCI specification revision 2.2 defines the PCI hardware environment including the protocol, electrical, mechanical, and configuration specifications for the PCI devices and expansion boards. This standard requires 3.3-V  $\rm V_{\rm CCIO}$ . The 3.3-V PCI standard does not require input reference voltages or board terminations.

The side I/O pins on all Cyclone devices (except the EP1C3 device) are fully compliant with the 3.3-V PCI Local Bus Specification Revision 2.2 and meet 32-bit/66-MHz operating frequency and timing requirements. The EP1C3 device supports the PCI I/O standard by using the LVTTL 16-mA setting and an external diode. The top and bottom I/O pins on all Cylcone devices support PCI by using the LVTTL 16-mA setting and an external diode.

Cyclone devices support PCI input and output levels on I/O banks 1 and 3 only. See "Cyclone I/O Banks" for more details and the IP MegaStore<sup>TM</sup> website.

Table 8–2 lists the specific Cyclone devices that support 64- and 32-bit PCI at  $66\ \mathrm{MHz}.$ 

Table 8–2. Cyclone 66-MHz PCI Support			
	Dooleans	-6 and -7 Speed Grades	
Device	Package -	64 Bit	32 Bit
EP1C4	324-pin FineLine BGA	<b>✓</b>	<b>✓</b>
	400-pin FineLine BGA	✓	✓
EP1C6	240-pin PQFP	_	✓
	256-pin FineLine BGA	_	✓
EP1C12	324-pin FineLine BGA	✓	<b>✓</b>
EP1C20	324-pin FineLine BGA	✓	✓
	400-pin FineLine BGA	✓	✓

Table 8-3 lists the specific Cyclone devices that support 64- and 32-bit PCI at 33 MHz.

Davisa	Dealtone	-6, -7 and -8 Speed Grad	
Device	Package	64 Bit	32 Bit
EP1C4	324-pin FineLine BGA	✓	<b>✓</b>
	400-pin FineLine BGA	✓	✓
EP1C6	240-pin PQFP	_	✓
	256-pin FineLine BGA	_	✓
EP1C12	240-pin PQFP	_	✓
	256-pin FineLine BGA	_	✓
	324-pin FineLine BGA	✓	✓
EP1C20	324-pin FineLine BGA	✓	<b>✓</b>
	400-pin FineLine BGA	✓	<b>✓</b>

### SSTL-3 Class I and II (EIA/JEDEC Standard JESD8-8)

The SSTL-3 I/O standard is a 3.3-V memory bus standard used for applications such as high-speed SDRAM interfaces. This standard defines the input and output specifications for devices that operate in the SSTL-3 logic switching range of 0.0 to 3.3 V. The SSTL-3 standard specifies an input voltage range of – 0.3 V  $\leq$  V $_{\rm I}$   $\leq$  V $_{\rm CCIO}$  + 0.3-V. SSTL-3 requires a 1.5-V V $_{\rm REF}$  and a 1.5-V V $_{\rm TT}$  to which the series and termination resistors are connected (see Figures 8–1 and 8–2). In typical applications, both the termination voltage and reference voltage track the output supply voltage.

Figure 8-1. SSTL-3 Class I Termination

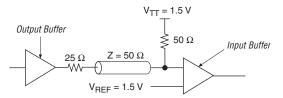
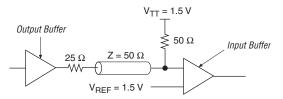


Figure 8-2. SSTL-3 Class II Termination



Cyclone devices support both input and output SSTL-3 Class I and II levels.

# SSTL-2 Class I and II (EIA/JEDEC Standard JESD8-9A)

The SSTL-2 I/O standard is a 2.5-V memory bus standard used for applications such as high-speed double data rate (DDR) SDRAM interfaces. This standard defines the input and output specifications for devices that operate in the SSTL-2 logic switching range of 0.0-V to 2.5-V. This standard improves operation in conditions where a bus must be isolated from large stubs. The SSTL-2 standard specifies an input voltage range of  $-0.3~V \le V_I \le V_{CCIO} + 0.3~V$ . SSTL-2 requires a  $V_{REF}$  value of 1.25 V and a  $V_{TT}$  value of 1.25 V connected to the series and termination resistors (see Figures 8–3 and 8–4).

Figure 8-3. SSTL-2 Class I Termination

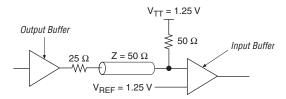
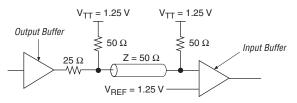


Figure 8-4. SSTL-2 Class II Termination



Cyclone devices support both input and output SSTL-2 Class I and II levels.

## LVDS (ANSI/TIA/EIA Standard ANSI/TIA/EIA-644)

The LVDS I/O standard is a differential high-speed, low-voltage swing, low-power, general-purpose I/O interface standard. This standard is used in applications requiring high-bandwidth data transfer, backplane drivers, and clock distribution. The ANSI/TIA/EIA-644 standard specifies LVDS transmitters and receivers capable of operating at recommended maximum data signaling rates of 655 Mbps. Devices can operate at slower speeds if needed however, and there is a theoretical maximum of 1.923 Gbps. Due to the low-voltage swing of the LVDS I/O standard, the electromagnetic interference (EMI) effects are much smaller than CMOS, TTL, and PECL. This low EMI makes LVDS ideal for applications with low EMI requirements or noise immunity requirements. The LVDS standard specifies a differential output voltage range of 250 mV  $\leq$  VOD  $\leq$  550 mV.

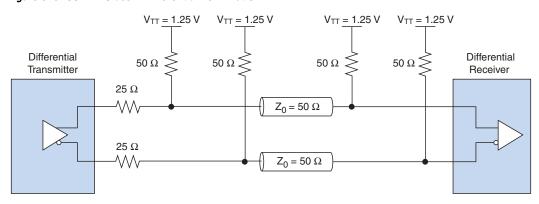
The Cyclone device family meets the ANSI/TIA/EIA-644 standard and is LVDS-compatible but, unlike previous products with LVDS support, Cyclone does not have dedicated SERDES or LVDS drivers. While external resistors are required for LVDS output support, Cyclone does have direct LVDS-compatible input support throughout the device. This

flexible approach to LVDS support allows LVDS compatibility on every bank of the Cyclone device at speeds up to 640 Mbps. (Contact Altera Applications for the latest LVDS specification).

### Differential SSTL-2 - EIA/JEDEC Standard JESD8-9A

The differential SSTL-2 I/O standard is a 2.5-V standard used for applications such as high-speed DDR SDRAM clock interfaces. This standard supports differential signals in systems using the SSTL-2 standard and supplements the SSTL-2 standard for differential clocks. The differential SSTL-2 standard specifies an input voltage range of  $-0.3~\rm V \le V_I \le V_{\rm CCIO} + 0.3-\rm V$ . The differential SSTL-2 standard does not require an input reference voltage differential. See Figure 8–5 for details on differential SSTL-2 termination. Cyclone devices support output clock levels for differential SSTL-2 class II operation.

Figure 8-5. SSTL-2 Class II Differential Termination





For more details about the I/O standards discussed in this section, refer to the *Cyclone FPGA Family Data Sheet* section of the *Cyclone Device Handbook*.

# Cyclone I/O Banks

The I/O pins on Cyclone devices are grouped together into I/O banks and each bank has a separate power bus. This permits designers to select the preferred I/O standard for a given bank enabling tremendous flexibility in the Cyclone device's I/O support.

Each Cyclone device supports four I/O banks regardless of density. Similarly, each device I/O pin is associated with one of these specific, numbered I/O banks. To accommodate voltage-referenced I/O

standards, each Cyclone I/O bank supports three  $V_{REF}$  pins (see Figure 8–6). In the event these pins are not used as  $V_{REF}$  pins, they may be used as regular I/O pins.

Figure 8–6. Cyclone Power Bank and  $V_{REF}$  Arrangement

Additionally, each Cyclone I/O bank has its own VCCIO pins. Any single I/O bank must have only one  $V_{\rm CCIO}$  setting from among 1.5-V, 1.8-V, 2.5-V or 3.3-V. Although there can only be one  $V_{\rm CCIO}$  voltage, Cyclone devices permit additional input signaling capabilities as shown in Table 8–4.

Table 8–4. Accepta	Table 8–4. Acceptable Input Levels for LVTTL/LVCMOS Note (1) (Part 1 of 2)			
Pank V		Acceptable Input Levels		
Bank V <sub>CCIO</sub>	3.3-V	2.5-V	1.8-V	1.5-V
3.3-V	✓	<b>✓</b>	_	_
2.5-V	✓	✓	_	_
1.8-V	<b>√</b> (2)	<b>√</b> (2)	✓	✓

Table 8–4. Acceptable Input Levels for LVTTL/LVCMOS Note (1) (Part 2 of 2)				
Pank V	Acceptable Input Levels			
Bank V <sub>CCIO</sub>	3.3-V	2.5-V	1.8-V	1.5-V
1.5-V	<b>√</b> (2)	<b>√</b> (2)	✓	✓

Notes to Table 8-4:

- (1) For SSTL and LVDS I/O Standard, input buffers are powered by  $V_{CCINT}$  and not  $V_{CCIO}$ . Hence, input buffers can accept input levels of 3.3 V or 2.5 V regardless of  $V_{CCIO}$  level for both SSTL and LVDS I/O Standard.
- (2) These input values overdrive the input buffer, so the pin leakage current is slightly higher than the default value. Check Allow voltage overdrive for LVTTL/LVCMOS input pins in Settings > Device > Device and Pin Options > Pin Placement tab to allow input pins with LVTTL or LVCMOS I/O standards to be placed by the Quartus II software inside an I/O bank with a lower V<sub>CCIO</sub> voltage than the voltage specified by the pins.



For more information about acceptable input levels, refer to *Using Cyclone Devices in Multiple-Voltage Systems* chapter in the *Cyclone Device Handbook*.

Any number of supported single-ended or differential standards can be simultaneously supported in a single I/O bank as long as they use compatible  $\rm V_{CCIO}$  levels for input and output pins. For example, an I/O bank with a 2.5-V  $\rm V_{CCIO}$  setting can support 2.5-V LVTTL inputs and outputs, 2.5-V LVDS-compatible inputs and outputs, and 3.3-V LVCMOS inputs only.

Voltage-referenced standards can be supported in an I/O bank using any number of single-ended or differential standards as long as they use the same  $V_{REF}$  and a compatible  $V_{CCIO}$  value. For example, if you choose to implement both SSTL-3 and SSTL-2 in your Cyclone device, I/O pins using these standards—because they require different  $V_{REF}$  values—must be in different banks from each other. However, SSTL-3 and 3.3-V LVCMOS could be supported in the same bank with the  $V_{CCIO}$  set to 3.3-V and the  $V_{REF}$  set to 1.5-V.

See "Pad Placement and DC Guidelines" on page 8–14 for more information.

All four I/O banks support all of the I/O standards with the exception of PCI, which is only supported on banks 1 and 3 (see Figure 8–7).

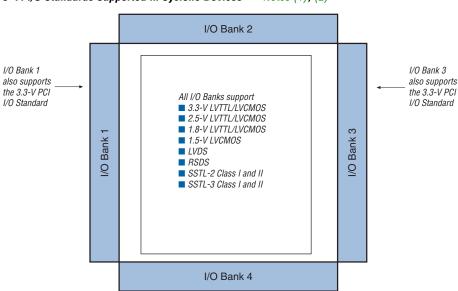


Figure 8–7. I/O Standards Supported in Cyclone Devices Notes (1), (2)

#### Notes to Figure 8-7

- EP1C3 devices support PCI by using the LVTTL 16-mA I/O standard and drive strength assignments in the Quartus II software. The device requires an external diode for PCI compliance.
- (2) The EP1C3 device in the 100-pin thin quad flat pack (TQFP) package does not have support for a PLL LVDS-compatible input or an external clock output.

# Programmable Current Drive Strength

The Cyclone device I/O standards support various output current drive settings as shown in Table 8–5. These programmable drive-strength settings are a valuable tool in helping decrease the effects of simultaneously switching outputs (SSO) in conjunction with reducing system noise. The supported settings ensure that the device driver meets the specifications for  $I_{OH}$  and  $I_{OL}$  of the corresponding I/O standard.

These drive-strength settings are programmable on a per-pin basis (for output and bidirectional pins only) using the Quartus II software. To modify the current strength of a particular pin, refer to "Programmable Drive Strength Settings".

Table 8–5. Programmable Drive Strength		
I/O Standard (1)	I <sub>OH</sub> /I <sub>OL</sub> Current Strength Setting (2)	
3.3-V LVTTL	24, 16, 12, 8, 4 mA	
3.3-V LVCMOS	12, 8, 4, 2 mA	
2.5-V LVTTL/LVCMOS	16, 12, 8, 2 mA	
1.8-V LVTTL/LVCMOS	12, 8, 2 mA	
1.5-V LVCMOS	8, 4, 2 mA	

*Notes to Table 8–5:* 

- The Quartus II software default current setting is the maximum setting for each I/O standard.
- (2) SSTL 2 class I and II, SSTL 3 class I and II, and PCI do not support programmable drive strength.

# **Hot Socketing**

Cyclone devices support any power-up or power-down sequence ( $V_{\text{CCIO}}$  and  $V_{\text{CCINT}}$ ) to facilitate hot socketing. You can drive signals into the device before or during power-up or power-down without damaging the device. Cyclone devices will not drive out until the device is configured and has attained proper operating conditions.

You can power up or power down the VCCIO and VCCINT pins in any sequence. The power supply ramp rates can range from 100 ns to 100 ms. All  $V_{CC}$  supplies must power down within 100 ms of each other to prevent I/O pins from driving out. Additionally, during power-up, the I/O pin capacitance is less than 15 pF and the clock pin capacitance is less than 20pF.

- The hot socketing DC specification is  $|I_{IOPIN}| < 300 \mu A$ .
- The hot socketing AC specification is  $\mid$  I<sub>IOPIN</sub>  $\mid$  < 8 mA for 10 ns or less.

# I/O Termination

The majority of the Cyclone I/O standards are single-ended, non-voltage-referenced I/O standards and, as such, the following I/O standards do not specify a recommended termination scheme:

- 3.3-V LVTTL / LVCMOS
- 2.5-V LVTTL / LVCMOS
- 1.8-V LVTTL / LVCMOS
- 1.5-V LVCMOS
- 3.3-V PCI

The Cyclone device family does not feature on-chip I/O termination resistors.

## Voltage-Referenced I/O Standard Termination

Voltage-referenced I/O standards require both an input reference voltage,  $V_{REF}$ , and a termination voltage,  $V_{TT}$ . An external pull up to  $V_{TT}$  must be provided to the Cyclone device as the device does not have  $V_{TT}$  pins. The reference voltage of the receiving device tracks the termination voltage of the transmitting device.

For more information on termination for voltage-referenced I/O standards, refer to "Supported I/O Standards".

### Differential I/O Standard Termination

Differential I/O standards typically require a termination resistor between the two signals at the receiver. The termination resistor must match the differential load impedance of the bus.

LVDS and RSDS are the only differential I/O standards supported by Cyclone devices. For information on LVDS termination and RSDS termination, refer to the LVDS Receiver and Transmitter Termination and RSDS I/O Standard Support in Cyclone Devices sections, respectively, in the High-Speed Differential Signaling in Cyclone Devices chapter in the Cyclone Device Handbook

# Pad Placement and DC Guidelines

This section provides pad placement guidelines for the programmable I/O standards supported by Cyclone devices and includes essential information for designing systems using the devices' selectable I/O capabilities. This section also discusses the DC limitations and guidelines.

#### Differential Pad Placement Guidelines

In order to maintain an acceptable noise level on the  $V_{CCIO}$  supply, there are restrictions on placement of single-ended I/O pads in relation to differential pads. Use the following guidelines for placing single-ended pads with respect to differential pads in Cyclone devices.

- Single-ended inputs may be only be placed four or more pads away from a differential pad.
- Single-ended outputs and bidirectional pads may only be placed five or more pads away from a differential pad.



The Quartus II software generates an error message for illegally placed pads.

## **V<sub>REF</sub> Pad Placement Guidelines**

In order to maintain an acceptable noise level on the  $V_{CCIO}$  supply and to prevent output switching noise from shifting the  $V_{REF}$  rail, there are restrictions on the placement of single-ended voltage referenced I/Os with respect to  $V_{REF}$  pads and VCCIO/GND pairs. Please use the following guidelines for placing single-ended pads in Cyclone devices.

### Input Pads

Each  $V_{REF}$  pad supports a maximum of 40 input pads with up to 20 on each side of the  $V_{REF}$  pad. This is irrespective of VCCIO/GND pairs.

### Output Pads

When a voltage referenced input or bidirectional pad does not exist in a bank, there is no limit to the number of output pads that can be implemented in that bank. When a voltage referenced input exists, each  ${\tt VCCIO/GND}$  pair supports 9 outputs for Fineline BGA® packages or 4 outputs for quad flat pack (QFP) packages. Any output pads must be placed greater than 1 pad away from your  $V_{REF}$  pad to maintain acceptable noise levels.

#### Bidirectional Pads

Bidirectional pads must satisfy input and output guidelines simultaneously. If the bidirectional pads are all controlled by the same OE and there are no other outputs or voltage referenced inputs in the bank, then there is no case where there is a voltage referenced input active at the same time as an output. Therefore, the output limitation does not apply. However, since the bidirectional pads are linked to the same OE, the bidirectional pads will all act as inputs at the same time. Therefore, the input limitation of 40 input pads (20 on each side of your  $V_{\rm REF}$  pad) will apply.

If the bidirectional pads are all controlled by different output enables (OE) and there are no other outputs or voltage referenced inputs in the bank, then there may be a case where one group of bidirectional pads is acting as inputs while another group is acting as outputs. In such cases, apply the formulas shown in Table 8–6.

Table 8–6. Input-Only Bidirectional Pad Limitation Formulas		
Package Type	Formula	
FineLine BGA	(Total number of bidirectional pads) - (Total number of pads from the smallest group of pads controlled by an OE) ≤9 (per VCCIO/GND pair)	
QFP	(Total number of bidirectional pads) - (Total number of pads from the smallest group of pads controlled by an OE) ≤4 (per VCCIO/GND pair).	

Consider an FineLine BGA package with 4 bidirectional pads controlled by OE1, 4 bidirectional pads controlled by OE2, and 2 bidirectional pads controlled by OE3. If OE1 and OE2 are active and OE3 is inactive, there are 10 bidirectional pads, but it is safely allowable because there would be 8 or fewer outputs per VCCIO/GND pair.

When at least one additional voltage referenced input and no other outputs exist in the same  $V_{\text{REF}}$  bank, the bidirectional pad limitation applies in addition to the input and output limitations. See the following equation.

(Total number of bidirectional pads) + (Total number of input pads)  $\leq$  40 (20 on each side of your  $V_{REF}$  pad)



The bidirectional pad limitation applies to both Fineline BGA packages and QFP packages.

After applying the equation above, apply one of the equations in Table 8–7, depending on package type.

Table 8–7. Bidirectional Pad Limitation Formulas (Where $V_{REF}$ Inputs Exist)	
Package Type Formula	
FineLine BGA	(Total number of bidirectional pads) ≤ 9 (per VCCIO/GND pair)
QFP	(Total number of bidirectional pads) ≤4 (per VCCIO/GND pair)

When at least one additional output exists but no voltage referenced inputs exist, apply the appropriate formula from Table 8–8.

Table 8–8. Bidir Exist)	Table 8–8. Bidirectional Pad Limitation Formulas (Where $V_{REF}$ Outputs Exist)		
Package Type	Formula		
FineLine BGA	(Total number of bidirectional pads) + (Total number of additional output pads) - (Total number of pads from the smallest group of pads controlled by an OE) ≤9 (per VCCIO/GND pair)		
QFP	(Total number of bidirectional pads) + (Total number of additional output pads) - (Total number of pads from the smallest group of pads controlled by an OE) = 4 (per VCCIO/GND pair)		

When additional voltage referenced inputs and other outputs exist in the same  $V_{\text{REF}}$  bank, then the bidirectional pad limitation must again simultaneously adhere to the input and output limitations. As such, the following rules apply:

Total number of bidirectional pads + Total number of input pads  $\leq$ 40 (20 on each side of your V<sub>REF</sub> pad).



The bidirectional pad limitation applies to both Fineline BGA packages and QFP packages.

After applying the equation above apply one of the equations in Table 8–9, depending on package type.

Table 8–9. Bidirectional Pad Limitation Formulas (Multiple V <sub>REF</sub> Inputs and Outputs)		
Package Type	Formula	
FineLine BGA	(Total number of bidirectional pads) + (Total number of output pads) ≤9 (per VCCIO/GND pair)	
QFP	(Total number of bidirectional pads) + (Total number of output pads) ≤4 (per VCCIO/GND pair)	

Each I/O bank can only be set to a single  $V_{CCIO}$  voltage level and a single  $V_{REF}$  voltage level at a given time. Pins of different I/O standards can share the bank if they have compatible  $V_{CCIO}$  values (see Table 8–4 for more details).

In all cases listed above, the Quartus II software generates an error message for illegally placed pads.

### DC Guidelines

There is a current limit of 320 mA per 16 consecutive output pins, as shown by the following equation:

$$\sum_{\text{pin}}^{\text{pin} + 15} I_{\text{pin}} < 320 \text{ mA}$$

Table 8–10 shows the current allowed per pin by select I/O standards as measured under the standard's defined loading conditions. PCI, LVTTL, LVCMOS, and other supported I/O standards not shown in the table do not have standardized loading conditions. As such, the current allowed per pin in a series-loaded condition for these standards is considered negligible.

Table 8–10. I/O Standard DC Specification		
Pin I/O Standard	I Pin (mA)	
	3.3-V V <sub>CCIO</sub>	2.5-V V <sub>CCIO</sub>
SSTL-3 Class I	8	N/A
SSTL-3 Class II	16	N/A
SSTL-2 Class I	N/A	8.1
SSTL-2 Class II	N/A	16.4
LVDS	N/A	

# Quartus II Software Support

Use the Quartus II software to specify which programmable I/O standards to use for Cyclone devices. This section describes Quartus II implementation, placement, and assignment guidelines, including:

- Settings
- Device and pin options
- Assigning pins
- Programmable drive strength settings
- I/O banks in the floorplan view
- Auto placement and verification

## Settings

The Settings dialog box (Assignments menu) includes options allowing you to set a default I/O standard, optimize for I/O placement, assign I/O pins, and numerous other I/O-related options. The most pertinent user features are described in detail below.

### Device and Pin Options

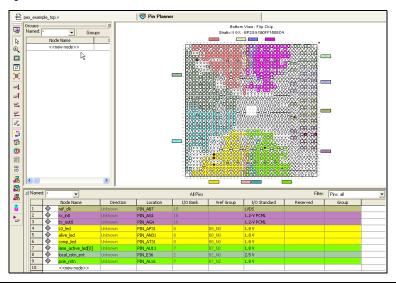
To access Device and Pin Options, choose **Settings** from Assignments menu. From **Settings** dialog box, click **Device and Pin Options**. There are numerous categories in the Device and Pin Options dialog box, including General, Configuration, Programming Files, Unused Pins, Dual-Purpose Pins, and Voltage. Similarly, each of these categories contains settings vital to the device operation such as the default I/O standard applied to the device (Voltage tab), how to reserve all unused pins (Unused Pins tab), specify the capacitive load (in picofarads (pF)) on output pins for each I/O standards (Capacitive Loading tab), and whether or not the device should enable a device-wide reset (General tab).

### Assigning Pins

Assuming a specific device has been chosen in the available devices list in the Device Settings dialog box (Assignments menu), clicking **Pin Planner** provides the device's pin settings and pin assignments (see Figure 8–8). You can view, add, remove and update pin settings in the Pin Planner window. The information for each pin includes:

- Node Name
- Direction
- Location
- I/O Bank
- V<sub>ref</sub> Group
- I/O Standard
- Reserved
- Group

Figure 8-8. Assign Pins





You can use **Filter** in the Pin Planner window to list assigned, unassigned, input, output, bidirectional or all pins.

When you assign an I/O standard that requires a reference voltage to an I/O pin, the Quartus II software automatically assigns  ${\tt VREF}$  pins. Refer to Quartus II Help for instructions on how to use an I/O standard for a pin.

### Programmable Drive Strength Settings

To specify programmable drive strength settings, perform the following steps:

- 1. Choose **Assignment Editor** (Assignments menu).
- Under To field in the Assignment Editor box, right-click on a new row. Select Node Finder. Click List in the Node Finder window. Then select the output or bidirectional pin for which you will specify the current strength.
- 3. Set the **Assignment Name** field to **Current Strength** (accepts wildcards/groups), then enter the desired value in the **Value** field.
- 4. Select **Yes** under **Enabled** field to enable the selected current strength.

The Quartus II software displays the entire range of drive strength choices. While the Quartus II software does not prohibit you from specifying any of these for your I/O pin, not every setting is supported by every I/O standard. See Table 8–5 for supported combinations.

## I/O Banks in the Floorplan View

View the arrangement of the device I/O banks by choosing **Timing Closure Floorplan** (Assignments View menu) with the Floorplan View displayed (see Figure 8–9). Pins that belong to the same I/O bank must use the same  $V_{\text{CCIO}}$  voltage. You can assign multiple I/O standards to the I/O pins in any given I/O bank as long as the  $V_{\text{CCIO}}$  voltage of the desired I/O standards is the same.

A given bank can have up to three  $V_{REF}$  signals, and each signal can support one voltage-referenced I/O standard. Each device I/O pin belongs to a specific, numbered I/O bank. By default, the **Show I/O Banks** option is enabled, allowing the I/O banks to be displayed as color coded (See Figure 8–9).

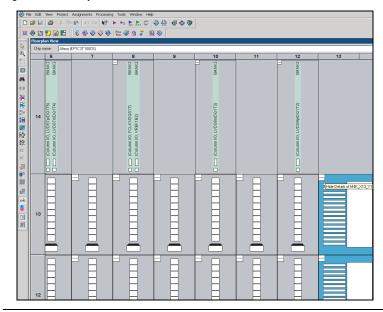


Figure 8-9. Floorplan View Window

#### Auto Placement and Verification of Selectable I/O Standards

The Quartus II software automatically verifies the placement for all I/O and VREF pins and performs the following actions:

- Automatically places I/O pins of different V<sub>REF</sub> standards without pin assignments in separate I/O banks and enables the VREF pins of these I/O banks.
- Verifies that voltage-referenced I/O pins requiring different V<sub>REF</sub> levels are not placed in the same bank.
- Reports an error message if the current limit is exceeded for a Cyclone power bank (See "DC Guidelines").
- Automatically assigns VREF pins and I/O pins such that the current requirements are met and I/O standards are placed properly.

#### Conclusion

Cyclone device I/O capabilities enable system designers to keep pace with increasing design complexity utilizing a low-cost FPGA device family. Support for I/O standards including SSTL and LVDS compatibility allow Cyclone devices to fit into a wide variety of applications. The Quartus II software makes it easy to use these I/O standards in Cyclone device designs. After design compilation, the software also provides clear, visual representations of pads and pins and the selected I/O standards. Taking advantage of the support of these I/O standards in Cyclone devices will allow you to lower your design costs without compromising design flexibility or complexity.

### More Information

For more information about Cyclone devices refer to the following resources:

- Cyclone FPGA Family Data Sheet section of the Cyclone Device Handbook
- Using Cyclone Devices in Multiple-Voltage Systems chapter in the Cyclone Device Handbook
- AN 75: High-Speed Board Designs

### References

For more information on the I/O standards referred to in this document, see the following sources:

- Stub Series Terminated Logic for 2.5-V (SSTL-2), JESD8-9A, Electronic Industries Association, December 2000.
- 1.5-V +/- 0.1-V (Normal Range) and 0.9-V 1.6-V (Wide Range) Power Supply Voltage and Interface Standard for Non-terminated Digital Integrated Circuits, JESD8-11, Electronic Industries Association, October 2000.

- 1.8-V +/- 0.15-V (Normal Range) and 1.2-V 1.95-V (Wide Range) Power Supply Voltage and Interface Standard for Non-terminated Digital Integrated Circuits, JESD8-7, Electronic Industries Association, February 1997.
- 2.5-V +/- 0.2-V (Normal Range) and 1.8-V to 2.7-V (Wide Range) Power Supply Voltage and Interface Standard for Non-terminated Digital Integrated Circuits, JESD8-5, Electronic Industries Association, October 1995.
- Interface Standard for Nominal 3-V/3.3-V Supply Digital Integrated Circuits, JESD8-B, Electronic Industries Association, September 1999.
- PCI Local Bus Specification, Revision 2.2, PCI Special Interest Group, December 1998.
- Electrical Characteristics of Low Voltage Differential Signaling (LVDS) Interface Circuits, ANSI/TIA/EIA-644, American National Standards Institute/Telecommunications Industry/Electronic Industries Association, October 1995.

## Referenced Documents

This chapter references the following documents:

- AN 75: High-Speed Board Designs
- Cyclone FPGA Family Data Sheet section of the Cyclone Device Handbook
- High-Speed Differential Signaling in Cyclone Devices chapter in the Cyclone Device Handbook
- Using Cyclone Devices in Multiple-Voltage Systems chapter in the Cyclone Device Handbook

## Document Revision History

Table 8–11 shows the revision history for this chapter.

Date and Document Version	Changes Made	Summary of Changes
May 2008 v1.6	Minor textual and style changes. Added "Referenced Documents" section.	_
January 2007 v1.5	<ul> <li>Added document revision history.</li> <li>Removed references to "compiler" settings and updated information in "Quartus II Software Support" section.</li> <li>Updated Figure 8–8 and the following handpara note.</li> <li>Updated procedure in "Programmable Drive Strength Settings" section.</li> <li>Minor update in "I/O Banks in the Floorplan View".</li> </ul>	_

August 2005 v1.4	Minor updates.	_
February 2005 v1.3	<ul> <li>Updated information concerning hot socketing AC specifications.</li> <li>Updated the notes to Figures 8-13 through 8-20.</li> <li>Updated text in the Output Pads section. Changed 2 pads away to 1.</li> </ul>	_
October 2003 v1.2	Updated the 3.3-V (PCI Special Interest Group (SIG) PCI Local Bus Specification Revision 2.2) section.	_
September 2003 v1.1	Updated LVDS data rates to 640 Mbps from 311 Mbps.	_
May 2003 v1.0	Added document to Cyclone Device Handbook.	_



## 9. High-Speed Differential Signaling in Cyclone Devices

C51009-1.6

#### Introduction

From high-speed backplane applications to high-end switch boxes, low-voltage differential signaling (LVDS) is the technology of choice. LVDS is a low-voltage differential signaling standard, allowing higher noise immunity than single-ended I/O technologies. Its low-voltage swing allows for high-speed data transfers, low power consumption, and less electromagnetic interference (EMI). LVDS I/O signaling is a data interface standard defined in the TIA/EIA-644 and IEEE Std. 1596.3 specifications.

The reduced swing differential signaling (RSDS) standard is a derivative of the LVDS standard. The RSDS I/O standard is similar in electrical characteristics to LVDS, but has a smaller voltage swing and therefore provides further power benefits and reduced EMI. National Semiconductor Corporation introduced the RSDS specification and now many vendors use it for flat panel display (FPD) links between the controller and the drivers that drive the display column drivers. Cyclone® devices support the RSDS I/O standard at speeds up to 311 megabits per second (Mbps).

Altera® Cyclone devices allow you to transmit and receive data through LVDS signals at a data rate up to 640 Mbps. For the LVDS transmitter and receiver, the Cyclone device's input and output pins support serialization and deserialization through internal logic.

This chapter describes how to use Cyclone I/O pins for LVDS and RSDS signaling and contains the following topics:

- Cyclone I/O Banks
- Cyclone High-Speed I/O Interface
- LVDS Receiver and Transmitter
- RSDS I/O Standard Support in Cyclone Devices
- Cyclone Receiver and Transmitter Termination
- Implementing Cyclone LVDS and RSDS I/O Pins in the Quartus<sup>®</sup> II Software
- Design Guidelines

## Cyclone High-Speed I/O Banks

Cyclone devices offer four I/O banks, as shown in Figure 9–1. A subset of pins in each of the four I/O banks (on both rows and columns) support the high-speed I/O interface. Cyclone pin tables list the pins that support the high-speed I/O interface. The EP1C3 device in the 100-pin thin quad flat pack (TQFP) package does not support the high-speed I/O interface.

Figure 9-1. Cyclone I/O Banks

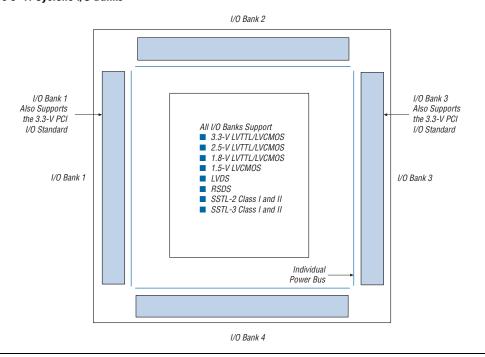


Table 9–1 shows the total number of supported high-speed I/O channels in each Cyclone device. You can use each channel as a receiver or transmitter.

Cyclone devices support different modes ( $\times$  1,  $\times$  2,  $\times$  4,  $\times$  7,  $\times$  8, and  $\times$  10) of operation with a maximum internal clock frequency of 405 MHz (-6 speed grade), 320 MHz (-7 speed grade), or 275 MHz (-8 speed grade), and a maximum data rate of 640 Mbps (-6 speed grade).

Table 9–1. Number of High-Speed I/O Channels Per Cyclone Device								
Device	Pin Count	Total Number of High- Speed I/O Channels						
EP1C3	144	34						
EP1C4	324	103						
	400	129						
EP1C6	144	29						
	240	72						
	256	72						
EP1C12	240	66						
	256	72						
	324	103						
EP1C20	324	95						
	400	129						



For more information about I/O standards supported by Cyclone devices, refer to the *Using Selectable I/O Standards in Cyclone Devices* chapter in the *Cyclone Device Handbook*.

## Cyclone High-Speed I/O Interface

You can use the I/O pins and internal logic to implement an high-speed I/O receiver and transmitter in Cyclone devices. Cyclone devices do not contain dedicated serialization or deserialization circuitry; therefore, shift registers, internal global phase-locked loops (PLLs), and I/O cells are used to perform serial-to-parallel conversions on incoming data and parallel-to-serial conversion on outgoing data.

#### **Clock Domains**

Cyclone devices provide a global clock network and two PLLs (the EP1C3 device only contains one PLL). The global clock network consists of eight global clock lines that drive through the entire device (see Figure 9–2). There are four dedicated clock pins that feed the PLL inputs (two dedicated clocks for each PLL). PLL pins can also act as LVDS input pins. Cyclone PLLs provide general-purpose clocking with clock multiplication and phase shifting as well as external outputs for high-speed differential I/O support. Altera recommends that designers use a data channel for the high-speed clock output for better balanced skew on the transmitter data pins with respect to the output clock.

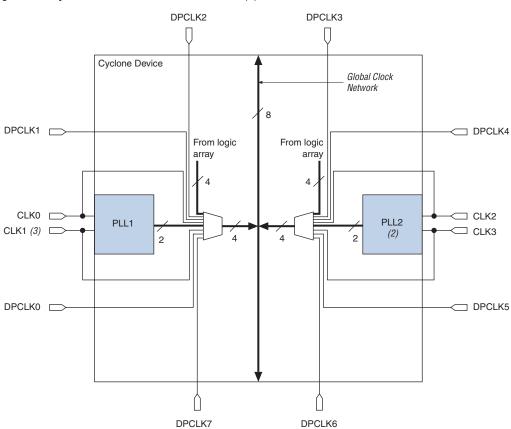


Figure 9–2. Cyclone Global Clock Network Note (1)

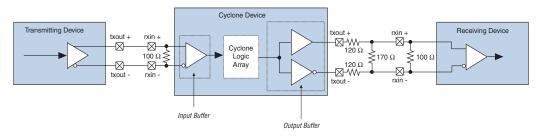
#### *Notes to Figure 9–2:*

- The EP1C3 device in the 100-pin TQFP package has five DPCLK pins (DPCLK2, DPCLK3, DPCLK4, DPCLK6, and DPCLK7).
- (2) EP1C3 devices only contain one PLL (PLL1).
- (3) EP1C3 devices in the 100-pin TQFP package do not support differential clock inputs or outputs.

## LVDS Receiver and Transmitter

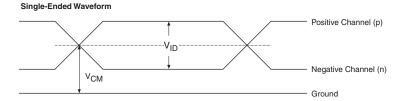
Figure 9–3 shows a simple point-to-point LVDS application where the source of the data is a LVDS transmitter. These LVDS signals are typically transmitted over a pair of printed circuit board (PCB) traces, but a combination of a PCB trace, connectors, and cables is a common application setup.

Figure 9-3. Typical LVDS Application



The Cyclone LVDS I/O pins meet the IEEE 1596 LVDS specification. Figures 9–4 and 9–5 show the signaling levels for LVDS receiver inputs and transmitter outputs.

Figure 9-4. Receiver Input Waveform for the Differential I/O Standard



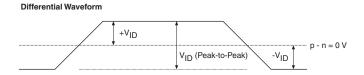
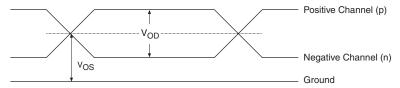


Figure 9–5. Transmitter Output Waveform for Differential I/O Standard

#### Single-Ended Waveform



#### **Differential Waveform**

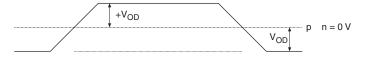


Table 9–2 lists the LVDS I/O specifications.

Table 9–2. LVDS I/O Specifications (Part 1 of 2)											
Symbol	Parameter	Conditions	Min	Тур	Max	Unit					
V <sub>CCINT</sub>	Supply Voltage	_	1.425	1.5	1.575	V					
V <sub>CCIO</sub>	I/O Supply Voltage	_	2.375	2.5	2.625	V					
V <sub>OD</sub>	Differential Output Voltage	R <sub>L</sub> = 100 Ω	250	350	550	mV					
Δ V <sub>OD</sub>	Change in V <sub>OD</sub> between H and L	R <sub>L</sub> = 100 Ω	_	_	50	mV					
V <sub>OS</sub>	Output Offset Voltage	R <sub>L</sub> = 100 Ω	1.125	1.25	1.375	V					
Δ V <sub>OS</sub>	Change in V <sub>OS</sub> between H and L	R <sub>L</sub> = 100 Ω	_	_	50	mV					
V <sub>ID</sub>	Input differential voltage swing (single-ended)	0.1 V ≤V <sub>CM</sub> ≤ 2.0 V	100	_	650	mV					
V <sub>IN</sub>	Receiver input voltage range	_	0	_	2.4	V					

Table 9–2. LVDS I/O Specifications (Part 2 of 2)											
Symbol	Parameter	Conditions	Min	Тур	Max	Unit					
V <sub>CM</sub>	Receiver input common mode voltage	100 mV ≤V <sub>ID</sub> ≤ 650 mV	100	_	2,000	mV					
R <sub>L</sub>	Receiver Differential Input Resistor	_	90	100	110	W					

## RSDS I/O Standard Support in Cyclone Devices

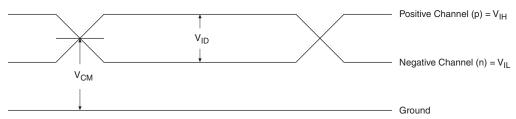
The RSDS specification defines its use in chip-to-chip applications between the timing controller and the column drivers on display panels. The Cyclone characterization and simulations were performed to meet the National Semiconductor Corp. RSDS Interface Specification. Table 9–3 shows the RSDS electrical characteristics for Cyclone devices.

Table 9–3. I	Table 9–3. RSDS Electrical Characteristics for Cyclone Devices										
Symbol	Parameter	Min	Тур	Max	Unit						
V <sub>CCIO</sub>	I/O supply voltage	2.375	2.5	2.625	V						
V <sub>OD</sub>	Differential output voltage	100	200	600	mV						
V <sub>OS</sub>	Output offset voltage	0.5	1.2	1.5	V						
V <sub>TH</sub>	Differential threshold	_	_	±100	mV						
V <sub>CM</sub>	Input common mode voltage	0.3	_	1.5	V						

Figures 9–6 and 9–7 show the RSDS receiver and transmitter signal waveforms.

Figure 9-6. Receiver Input Signal Level Waveforms for RSDS

#### Single-Ended Waveform



#### **Differential Waveform**

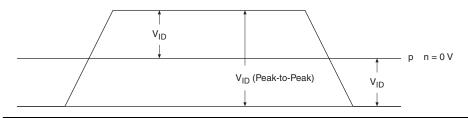
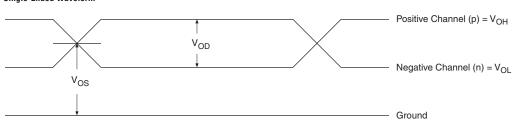
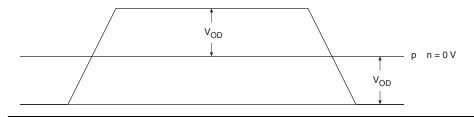


Figure 9-7. Transmitter Output Signal Level Waveforms for RSDS

#### Single-Ended Waveform



#### **Differential Waveform**



Cyclone FPGA devices support all three bus configuration types as defined by the RSDS specification:

- Multi-drop bus with double termination
- Multi-drop bus with single end termination
- Double multi-drop bus with single termination

### **Designing with RSDS**

Cyclone devices support the RSDS standard using the LVDS I/O buffer types. For receivers, the LVDS input buffer can be used without any changes. For transmitters, the LVDS output buffer can be used with the external resistor network shown in Figure 9–8.

Figure 9-8. RSDS Resistor Network

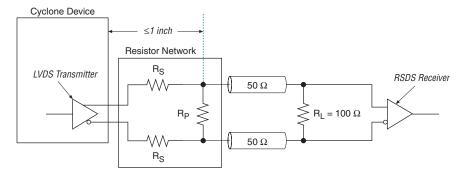


Table 9–4 shows the resistor values recommended for each RSDS bus configuration type.

Table 9–4. Recommended Resistor Values								
Bus Configuration Type $R_{S}(\Omega)$ $R_{P}(\Omega)$								
Multi-drop bus with double termination	160	145						
Multi-drop bus with single end termination	226	124						
Double multi-drop bus with single termination	226	124						



For more information about RSDS bus configuration types, refer to the RSDS specification from the National Semiconductor website (www.national.com).

A resistor network is required to attenuate the LVDS output voltage swing to meet the RSDS specifications. The resistor network values can be modified to reduce power or improve the noise margin. The resistor values chosen should satisfy the following equation:

$$\frac{R_S \times \frac{R_P}{2}}{R_S + \frac{R_P}{2}} = 50 \Omega$$

For example, in the multi-drop bus with single end termination or double multi-drop bus with single termination bus configuration, the resistor values can be modified to  $R_S$  = 200  $\Omega$  and  $R_P$  = 130  $\Omega$  to increase the  $V_{OD}$  or voltage swing of the signal.

Additional simulations using the IBIS models should be performed to validate that custom resistor values meet the RSDS requirements.

#### **RSDS Software Support**

When designing for the RSDS I/O standard, assign the LVDS I/O standard to the I/O pins intended for RSDS in the Quartus II software. Contact Altera Applications for reference designs.

## High-Speed I/O Timing in Cyclone Devices

Since LVDS and RSDS data communication is source synchronous, timing analysis is different than other I/O standards. You must understand how to analyze timing for the high-speed I/O signal, which is based on skew between the data and the clock signal.

You should also consider board skew, cable skew, and clock jitter in your calculation. This section provides details on high-speed I/O standards timing parameters in Cyclone devices.

Table 9–5 defines the parameters of the timing diagram shown in Figure 9–9.

Table 9–5. High-Speed I/O TIming Definitions Note (1)									
Parameter	Symbol	Description							
High-speed clock frequency	f <sub>HSCLK</sub>	High-speed receiver/transmitter input clock frequency.							
High-speed I/O data rate	HSIODR	High-speed receiver/transmitter input and output data rate.							
High-speed external output clock	f <sub>HSCLKOUT</sub>	High-speed transmitter external output clock frequency using an LVDS data channel.							
Channel-to-channel skew	TCCS	The timing difference between the fastest and slowest output edges, including $t_{\rm CO}$ variation and clock skew. The clock is included in the TCCS measurement.							
Sampling window	sw	The period of time during which the data must be valid in order for you to capture it correctly. The setup and hold times determine the ideal strobe position within the sampling window. $SW = t_{SW} \text{ (max)} - t_{SW} \text{ (min)}$ .							
Receiver input skew margin	RSKM	RSKM is defined by the total margin left after accounting for the sampling window and TCCS. The RSKM equation is: RSKM = (TUI – SW – TCCS) / 2							
Input jitter tolerance (peak-to-peak)		Allowed input jitter on the input clock to the PLL that is tolerable while maintaining PLL lock.							
Output jitter (peak-to-peak)		Peak-to-peak output jitter from the PLL.							
Rise time	t <sub>RISE</sub>	Low-to-high transmission time.							
Fall time	t <sub>FALL</sub>	High-to-low transmission time.							
Duty cycle	t <sub>DUTY</sub>	Duty cycle on LVDS transmitter output clock.							
PLL lock time	t <sub>LOCK</sub>	Lock time for the PLL							

Note to Table 9-5:

The TCCS specification applies to the whole bank of LVDS as long as the SERDES logic is placed within the LAB
adjacent to the output pins.

Figure 9-9. High-Speed I/O Timing Diagram

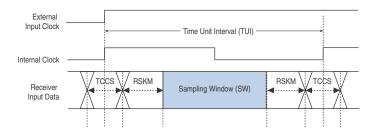
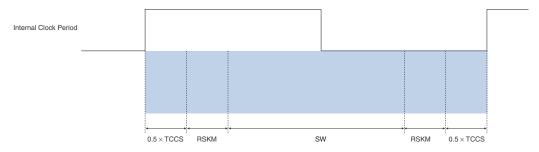


Figure 9–10 shows the high-speed I/O timing budget.

Figure 9–10. Cyclone High-Speed I/O Timing Budget Note (1)



Note to Figure 9-10:

(1) The equation for the high-speed I/O timing budget is:  $Period = 0.5 \times TCCS + RSKM + SW + RSKM + 0.5 \times TCCS$ .

Table 9–6 shows the RSDS timing budget for Cyclone devices at 311 Mbps.

Table 9–6.	Table 9–6. RSDS Timing Specification for Cyclone Devices (Part 1 of 2)										
Symbol	-6 Speed Grad		rade	ade -7 Speed Grade			-8 Speed Grade			Unit	
Syllibul	Conditions	Min	Тур	Max	Min	Тур	Max	Min	Тур	Max	UIIIL
f <sub>HSCLK</sub>	×10	15.625	NA	31.1	15.625	NA	31.1	15.625	NA	31.1	MHz
	×8	15.625	NA	38.875	15.625	NA	38.875	15.625	NA	38.875	MHz
	×7	17.857	NA	44.429	17.857	NA	44.429	17.857	NA	44.429	MHz
	×4	15.625	NA	77.75	15.625	NA	77.75	15.625	NA	77.75	MHz
	×2	15.625	NA	155.5	15.625	NA	155.5	15.625	NA	155.5	MHz
	×1 (1)	15.625	NA	275	15.625	NA	275	15.625	NA	275	MHz

Table 9–6.	Table 9–6. RSDS Timing Specification for Cyclone Devices (Part 2 of 2)										
Oh a l	Conditions	-6 S	peed G	rade	-7 Speed Grade			-8 Speed Grade			II.a.iA
Symbol	Conditions	Min	Тур	Max	Min	Тур	Max	Min	Тур	Max	Unit
HSIODR	×10	156.25	NA	311	156.25	NA	311	156.25	NA	311	Mbps
	×8	125	NA	311	125	NA	311	125	NA	311	Mbps
	×7	125	NA	311	125	NA	311	125	NA	311	Mbps
	×4	62.5	NA	311	62.5	NA	311	62.5	NA	311	Mbps
	×2	31.25	NA	311	31.25	NA	311	31.25	NA	311	Mbps
	×1 (1)	15.625	NA	275	15.625	NA	275	15.625	NA	275	Mbps
f <sub>HSCLKOUT</sub>	_	15.625	NA	275	15.625	NA	275	15.625	NA	275	MHz
TCCS	_	NA	NA	±150	NA	NA	±150	NA	NA	±150	ps
SW	_	NA	NA	500	NA	NA	550	NA	NA	550	ps
Input jitter tolerance (peak-to- peak)	_	NA	NA	400	NA	NA	400	NA	NA	400	ps
Output jitter (peak- to-peak)	_	NA	NA	400	NA	NA	400	NA	NA	400	ps
t <sub>RISE</sub>	_	150	200	250	150	200	250	150	200	250	ps
t <sub>FALL</sub>	_	150	200	250	150	200	250	150	200	250	ps
t <sub>DUTY</sub>	_	45	50	55	45	50	55	45	50	55	%
t <sub>LOCK</sub>	_	NA	NA	100	NA	NA	100	NA	NA	100	μs

#### Note to Table 9-6:

<sup>(1)</sup> The PLL must divide down the input clock frequency to have the internal clock frequency meet the specification shown in the *DC and Switching Characteristics* chapter in the *Cyclone Device Handbook*.

Table 9–7 shows the LVDS timing budget for Cyclone devices at  $640~\mathrm{Mbps}$ .

Table 9–7.	Table 9–7. LVDS Timing Specification for Cyclone Devices										
		-6 Speed Grade			-7 Speed Grade			-8 Speed Grade			11!4
Symbol	Conditions	Min	Тур	Max	Min	Тур	Max	Min	Тур	Max	Unit
f <sub>HSCLK</sub>	×10	15.625	NA	64	15.625	NA	64	15.625	NA	55	MHz
	×8	15.625	NA	80	15.625	NA	80	15.625	NA	68.75	MHz
	×7	17.857	NA	91.429	17.857	NA	91.429	17.857	NA	78.571	MHz
	×4	15.625	NA	160	15.625	NA	160	15.625	NA	137.5	MHz
	×2	15.625	NA	320	15.625	NA	320	15.625	NA	275	MHz
	×1 (1)	15.625	NA	567	15.625	NA	549	15.625	NA	531	MHz
HSIODR	×10	156.25	NA	640	156.25	NA	640	156.25	NA	550	Mbps
	×8	125	NA	640	125	NA	640	125	NA	550	Mbps
	×7	125	NA	640	125	NA	640	125	NA	550	Mbps
	×4	62.5	NA	640	62.5	NA	640	62.5	NA	550	Mbps
	×2	31.25	NA	640	31.25	NA	640	31.25	NA	550	Mbps
	×1 (1)	15.625	NA	320	15.625	NA	320	15.625	NA	275	Mbps
f <sub>HSCLKOUT</sub>		15.625	NA	320	15.625	NA	320	15.625	NA	275	MHz
TCCS		NA	NA	±150	NA	NA	±150	NA	NA	±150	ps
SW		NA	NA	500	NA	NA	500	NA	NA	550	ps
Input jitter tolerance (peak-to- peak)		NA	NA	400	NA	NA	400	NA	NA	400	ps
Output jitter (peak- to-peak)		NA	NA	400	NA	NA	400	NA	NA	400	ps
t <sub>RISE</sub>		150	200	250	150	200	250	150	200	250	ps
t <sub>FALL</sub>		150	200	250	150	200	250	150	200	250	ps
t <sub>DUTY</sub>		45	50	55	45	50	55	45	50	55	%
t <sub>LOCK</sub>		NA	NA	100	NA	NA	100	NA	NA	100	μs

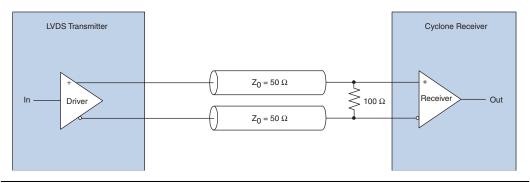
#### *Note to Table 9–7:*

<sup>(1)</sup> The PLL must divide down the input clock frequency to have the internal clock frequency meet the specification shown in the DC and Switching Characteristics chapter in the Cyclone Device Handbook.

# LVDS Receiver and Transmitter Termination

Receiving LVDS signals on Cyclone I/O pins is straightforward, and can be done by assigning LVDS to desired pins in the Quartus II software. A 100- $\Omega$  parallel terminator is required at the receiver input pin, as shown in Figure 9–11.

Figure 9-11. Termination Scheme on Cyclone LVDS Receiver

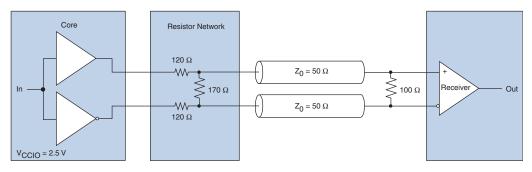




For PCB layout guidelines, refer to AN 224: High-Speed Board Layout Guidelines.

Cyclone LVDS transmitter signals are generated using a resistor network, as shown in Figure 9–12 (with  $R_S$  = 120  $\Omega$  and  $R_{DIV}$  = 170  $\Omega$ ). The resistor network attenuates the driver outputs to levels similar to the LVDS signaling, which is recognized by LVDS receivers with minimal effect on 50- $\Omega$  trace impedance.

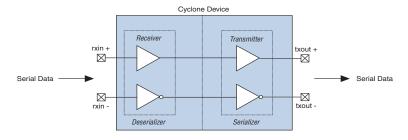
Figure 9-12. Termination Scheme on Cyclone LVDS Transmitter



## Implementing Cyclone LVDS and RSDS I/O Pins in the Quartus II Software

For differential signaling, the receiver must deserialize the incoming data and send it to the internal logic as a parallel signal. Accordingly, the transmitter must serialize the parallel data coming from the internal logic to send it off-chip (see Figure 9–13).

Figure 9-13. Deserialization and Serialization at Receiver and Transmitter



Although Cyclone devices do not incorporate a dedicated serializer/deserializer (SERDES), you can incorporate these functions in your design using the Quartus II software. The device implements the SERDES in logic elements (LEs) and requires a PLL.

LVDS in Cyclone devices is implememented using megafunctions in Quartus II software. The altlvds\_rx megafunction implements a deserialization receiver. The altlvds\_tx megafunction implements a serialization transmitter.

The placement of the LE registers is handled by the LVDS MegaWizard® in the Quartus II software. The Cyclone device DDIO logic placer in the Quartus II software only places the DDIO output registers according to Altera's recommendation and does not check if it meets the TCCS specification. There is no timing analysis done in the Quartus II software to report the TCCS. Verify timing analysis by running the Timing Analyzer in the Quartus II software.

Refer to the Quartus II software documenation and the Quartus II Help for more information on these megafunctions. Follow the recommendations in Tables 9–8 and 9–9 for PLL phase shift settings. The operation of these settings are guaranteed by operation.

The required receiver PLL phase settings for top and bottom I/O banks (I/O banks 2 and 4) based on high-speed I/O data rate and operating mode are shown in Table 9–8.

Table 9–8. Receiver PLL Phase Settings for Top and Bottom I/O Banks										
Dovino	Phase Shift (Degree)									
Device	0	0 22.5 45								
EP1C3	_	_	300 to 640	Mbps						
EP1C4	_	601 to 640	300 to 600	Mbps						
EP1C6	_	601 to 640	300 to 600	Mbps						
EP1C12	_	451 to 640	300 to 450	Mbps						
EP1C20	551 to 640	300 to 550	_	Mbps						

The required receiver PLL phase settings for right and left I/O banks (I/O Bank 1 and 3) based on high-speed I/O data rate and operating mode are shown in Table 9–9.

Table 9–9. Receiver PLL Phase Settingsfor Right and Left I/O Banks								
Device	Phase Shift (Degree)				Unit			
	-22.5	0	22.5	45	UIIIL			
EP1C3	_	_	451 to 640	300 to 450	Mbps			
EP1C4	_	551 to 640	300 to 550	_	Mbps			
EP1C6	_	_	451 to 640	300 to 450	Mbps			
EP1C12	601 to 640	451 to 600	300 to 450	_	Mbps			
EP1C20	501 to 640	300 to 500	_	_	Mbps			

### Design Guidelines

To implement LVDS in Cyclone devices, adhere to the following design guidelines in the Quartus II software.

- Route LVDS CLKOUT to pins through regular user LVDS pins. This routing provides better TCCS margin.
- To meet the t<sub>SU</sub> and t<sub>CO</sub> timing requirement between serial and parallel registers, use the I/O registers of the input and output pins.
- $f_{MAX}$  is limited by the delay between the IOE and the next logic element (LE) register. To achieve an  $f_{MAX}$  of 320 MHz, the delay between the IOE and the next LE register at the receiver and transmitter side must not be more than 3.125 ns.
- The best location to implement the shift registers is within the LAB adjacent to the input or output pin.
- LVDS data and clock should be aligned at the output pin. If these signals are not aligned, use a phase shift to align them.

#### **Differential Pad Placement Guidelines**

To maintain an acceptable noise level on the  $V_{\text{CCIO}}$  supply, there are restrictions on placement of single-ended I/O pins in relation to differential pads.



For placing single-ended pads with respect to differential pads in Cyclone devices, refer to the guidelines in the *Using Selectable I/O Standards in Cyclone Devices* chapter in the *Cyclone Device Handbook*.

### **Board Design Considerations**

This section explains how to get the optimal performance from the Cyclone I/O block and ensure first-time success in implementing a functional design with optimal signal quality. The critical issues of controlled impedance of traces and connectors, differential routing, and termination techniques must all be considered to get the best performance from the integrated circuit (IC). Use this chapter together with the *Cyclone FPGA Family Data Sheet* section of the *Cyclone Device Handbook*.

The Cyclone device generates signals that travel over the media at frequencies as high as 640 Mbps. Use the following general guidelines:

- Base board designs on controlled differential impedance. Calculate and compare all parameters such as trace width, trace thickness, and the distance between two differential traces.
- Maintain equal distance between traces in LVDS pairs, as much as possible. Routing the pair of traces close to each other will maximize the common-mode rejection ratio (CMRR)

- Longer traces have more inductance and capacitance. These traces should be as short as possible to limit signal integrity issues.
- Place termination resistors as close to receiver input pins as possible.
- Use surface mount components.
- Avoid 90° or 45° corners.
- Use high-performance connectors.
- Design backplane and card traces so that trace impedance matches the connector's and/or the termination's impedance.
- Keep equal number of vias for both signal traces.
- Create equal trace lengths to avoid skew between signals. Unequal trace lengths result in misplaced crossing points and decrease system margins as the TCCS value increases.
- Limit vias because they cause discontinuities.
- Use the common bypass capacitor values such as 0.001 μF, 0.01 μF, and 0.1 μF to decouple the high-speed PLL power and ground planes.
- Keep switching TTL signals away from differential signals to avoid possible noise coupling.
- Do not route TTL clock signals to areas under or above the differential signals.
- Analyze system-level signals.

#### Conclusion

Cyclone LVDS I/O capabilities enable you to keep pace with increasing design complexity while offering the lowest-cost FPGA on the market. Support for I/O standards including LVDS allows Cyclone devices to fit into a wide variety of applications. Taking advantage of these I/O standards and Cyclone pricing allows you to lower your design costs while remaining on the cutting edge of technology.

## Referenced Documents

This chapter references the following documents:

- AN 224: High-Speed Board Layout Guidelines
- Cyclone FPGA Family Data Sheet section of the Cyclone Device Handbook
- DC and Switching Characteristics chapter in the Cyclone Device Handbook
- Using Selectable I/O Standards in Cyclone Devices chapter in the Cyclone Device Handbook

## Document Revision History

Table 9–10 shows the revision history for this chapter.

Table 9–10. Document Revision History					
Date and Document Version	Channes Made				
May 2008 v1.6	Minor textual and style changes. Added "Referenced Documents" section.	_			
January 2007 v1.5	Added document revision history.	_			
August 2005 v1.4	Updated minimum LVDS LOD value listed in Table 9-2.	_			
February 2005 v1.3	Minor updates.	_			
October 2003 v1.2	<ul> <li>Added RSDS information.</li> <li>Removed V<sub>SS</sub> from Figure 9–5.</li> <li>Added RSDS and LVDS timing information in Tables 9–6 and 9–7, respectively.</li> <li>Updated Implementing Cyclone LVDS and RSDS I/O Pins in the Quartus II Software section, including addition of the PLL Circuit section.</li> </ul>	_			
September 2003 v1.1	Updated LVDS data rates to 640 Mbps from 311 Mbps.	_			
May 2003 v1.0	Added document to Cyclone Device Handbook.	_			



## Section V. Design Considerations

This section provides documentation on design considerations when utilizing Cyclone devices. In addition to these design considerations, refer to the Intellectual Property section of the Altera web site for a complete offering of IP cores for Cyclone devices.

This section contains the following chapters:

- Chapter 10, Implementing Double Data Rate I/O Signaling in Cyclone Devices
- Chapter 11. Using Cyclone Devices in Multiple-Voltage Systems
- Chapter 12. Designing with 1.5-V Devices

### **Revision History**

Refer to each chapter for its own specific revision history. For information on when each chapter was updated, refer to the Chapter Revision Dates section, which appears in the complete handbook.

Altera Corporation Section V-1

Section V-2 Altera Corporation



## 10. Implementing Double Data Rate I/O Signaling in Cyclone Devices

C51010-1.2

### Introduction

Double data rate (DDR) transmission is used in many applications where fast data transmission is needed, such as memory access and first-in first-out (FIFO) memory structures. DDR uses both edges of a clock to transmit data, which facilitates data transmission at twice the rate of a single data rate (SDR) architecture using the same clock speed. This method also reduces the number of I/O pins required to transmit data.

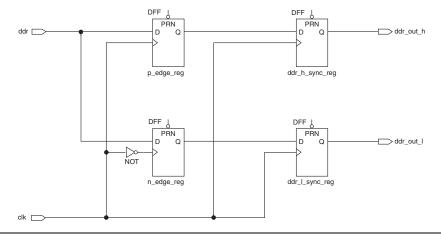
This chapter shows implementations of a double data rate I/O interface using Cyclone<sup>®</sup> devices. Cyclone devices support DDR input, DDR output, and bidirectional DDR signaling.

For more information on using Cyclone devices in applications with DDR SDRAM and FCRAM memory devices, refer to "DDR Memory Support" on page 10–4.

## Double Data Rate Input

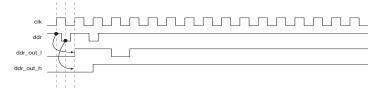
The DDR input implementation shown in Figure 10–1 uses four internal logic element (LE) registers located in the logic array block (LAB) adjacent to the DDR input pin. The DDR data is fed to the first two of four registers. One register captures the DDR data present during the rising edge of the clock. The second register captures the DDR data present during the falling edge of the clock.

Figure 10–1. Double Data Rate Input Implementation



The third and fourth registers synchronize the two data streams to the rising edge of the clock. Figure 10–2 shows examples of functional waveforms from a double data rate input implementation.

Figure 10-2. Double Data Rate Input Functional Waveforms



## Double Data Rate Output

Figure 10–3 shows a schematic representation of double data rate output implemented in a Cyclone device. The DDR output logic is implemented using LEs in the LAB adjacent to the output pin. Two registers are used to synchronize two serial data streams. The registered outputs are then multiplexed by the common clock to drive the DDR output pin at two times the data rate.

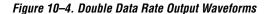
data\_in\_l DFF \ PRN \ D Q \ data1 \ reg\_h \ data0 \ PRN \ D Q \ reg\_l \ reg\_l \ reg\_l \ PRN \ D Q \ reg\_l \ reg\_l \ PRN \ D Q \ reg\_l \ reg\_l \ reg\_l \ PRN \ D Q \ reg\_l \ reg\_l \ reg\_l \ PRN \ D Q \ reg\_l \ reg\_l

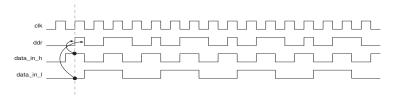
Figure 10-3. Double Data Rate Output Implementation

clk \_\_\_

While the clock signal is logic-high, the output from reg\_h is driven onto the DDR output pin. While the clock signal is logic-low, the output from reg\_1 is driven onto the DDR output pin. The DDR output pin can be any available user I/O pin.

Figure 10–4 shows examples of functional waveforms from a double data rate output implementation.





## Bidirectional Double Data Rate

Figure 10–5 shows a bidirectional DDR interface, constructed using the DDR input and DDR output examples described in the previous two sections. As with the DDR input and DDR output examples, the bidirectional DDR pin can be any available user I/O pin, and the registers used to implement DDR bidirectional logic are LEs in the LAB adjacent to that pin. The tri-state buffer (TRI) controls when the device drives data onto the bidirectional DDR pin.

Figure 10-5. Bidirectional Double Data Rate Implementation

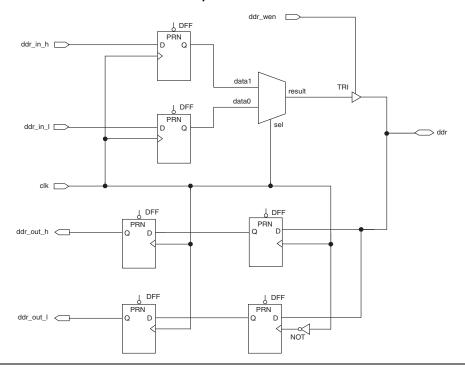
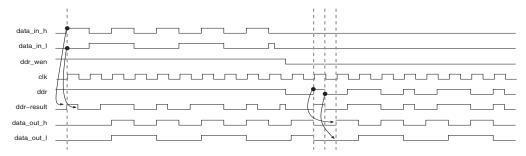


Figure 10–6 shows example waveforms from a bidirectional double data rate implementation.

Figure 10-6. Double Data Rate Bidirectional Waveforms



## DDR Memory Support

The Cyclone device family supports both DDR SDRAM and FCRAM memory interfaces up to 133 MHz.



For more information about extended DDR memory support in Cyclone devices, refer to the *Cyclone FPGA Family Data Sheet* section of the *Cyclone Device Handbook*.

### **Conclusion**

Utilizing both the rising and falling edges of a clock signal, double data rate transmission is a popular strategy for increasing the speed of data transmission while reducing the required number of I/O pins. Cyclone devices can be used to implement this strategy for use in applications such as FIFO structures, SDRAM/FCRAM interfaces, as well as other time-sensitive memory access and data-transmission situations.

## Referenced Documents

This chapter references the following document:

 Cyclone FPGA Family Data Sheet section of the Cyclone Device Handbook

## Document Revision History

Table 10–1 shows the revision history for this chapter.

Table 10–1. Document Revision History				
Date and Document Version	Changes Made	Summary of Changes		
May 2008 v1.2	Minor textual and style changes. Added "Referenced Documents" section.	_		
January 2007 v1.1	Added document revision history.	_		
May 2003 v1.0	Added document to Cyclone Device Handbook.	_		



## 11. Using Cyclone Devices in Multiple-Voltage Systems

C51011-1.2

### Introduction

To meet the demand for higher system speed in data communications, semiconductor vendors use increasingly advanced processing technologies requiring lower operating voltages. As a result, printed circuit boards (PCBs) often incorporate devices conforming to one of several voltage level I/O standards, such as 3.3-V, 2.5-V, 1.8-V and 1.5-V. A mixture of components with various voltage level I/O standards on a single PCB is inevitable.

In order to accommodate this mixture of devices on a single PCB, a device that can act as a bridge or interface between these devices is needed. The Cyclone<sup>®</sup> device family's MultiVolt<sup>TM</sup> I/O operation capability meets the increasing demand for compatibility with devices of different voltages. MultiVolt I/O operation separates the power supply voltage from the output voltage, enabling Cyclone devices to interoperate with other devices using different voltage levels on the same PCB.

In addition to MultiVolt I/O operation, this chapter discusses several other features that allow you to use Cyclone devices in multiple-voltage systems without damaging the device or the system, including:

- Hot-Socketing—add and remove Cyclone devices to and from a powered-up system without affecting the device or system operation
- Power-Up Sequence flexibility—Cyclone devices can accommodate any possible power-up sequence
- Power-On Reset—Cyclone devices maintain a reset state until voltage is within operating range

### I/O Standards

The I/O buffer of a Cyclone device is programmable and supports a wide range of I/O voltage standards. Each I/O bank in a Cyclone device can be programmed to comply with a different I/O standard. All I/O banks can be configured with the following I/O standards:

- 3.3-V LVTTL/LVCMOS
- 2.5-V LVTTL/LVCMOS
- 1.8-V LVTTL/LVCMOS
- 1.5-V LVCMOS
- LVDS
- SSTL-2 Class I and II
- SSTL-3 Class I and II

I/O banks 1 and 3 also include 3.3-V PCI I/O standard interface capability. See Figure 11–1.

I/O Bank 2 I/O Bank 1 also supports the 3.3-V PCI I/O Bank 3 also supports I/O Standard the 3.3-V PCI I/O Standard All I/O Banks support ■ 3.3-V LVTTL/LVCMOS ■ 2.5-V LVTTL/LVCMOS ■ 1.8-V LVTTL/LVCMOS ■ 1.5-V LVCMOS I/O Bank 1 LVDS I/O Bank 3 SSTL-2 Class I and II SSTL-3 Class I and II

Figure 11–1. I/O Standards Supported by Cyclone Devices Notes (1), (2), (3)

I/O Bank 4

#### Notes to Figure 11–1

- (1) Figure 1 is a top view of the silicon die.
- (2) Figure 1 is a graphical representation only. Refer to the pin list and the Quartus <sup>®</sup> II software for exact pin locations.
- (3) The EP1C3 device in the 100-pin thin quad flat pack (TQFP) package does not have support for a PLL LVDS input or an external clock output.

## MultiVolt I/O Operation

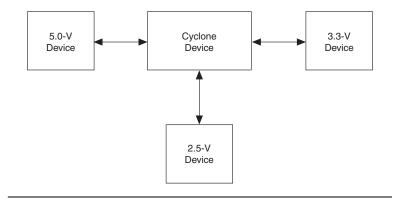
Cyclone devices include MultiVolt I/O operation capability, allowing the core and I/O blocks of the device to be powered-up with separate supply voltages. The VCCINT pins supply power to the device core and the VCCIO pins supply power the device's I/O buffers.

Individual Power Bus



Supply all device VCCIO pins that have MultiVolt I/O capability at the same voltage level (e.g., 3.3-V, 2.5-V, 1.8-V, or 1.5-V). See Figure 11–2.

Figure 11–2. Implementing a Multiple-Voltage System with a Cyclone Device



## 5.0-V Device Compatibility

A Cyclone device may not correctly interoperate with a 5.0-V device if the output of the Cyclone device is connected directly to the input of the 5.0-V device. If  $V_{OUT}$  of the Cyclone device is greater than  $V_{CCIO}$ , the PMOS pull-up transistor still conducts if the pin is driving high, preventing an external pull-up resistor from pulling the signal to 5.0-V.

A Cyclone device can drive a 5.0-V LVTTL device by connecting the VCCIO pins of the Cyclone device to 3.3 V. This is because the output high voltage (V<sub>OH</sub>) of a 3.3-V interface meets the minimum high-level voltage of 2.4-V of a 5.0-V LVTTL device. (A Cyclone device cannot drive a 5.0-V LVCMOS device.)

Because the Cyclone devices are 3.3-V, 64- and 32-bit, 66- and 33-MHz PCI compliant the input circuitry accepts a maximum high-level input voltage ( $V_{IH}$ ) of 4.1-V. To drive a Cyclone device with a 5.0-V device, you must connect a resistor ( $R_2$ ) between the Cyclone device and the 5.0-V device. See Figure 11–3.

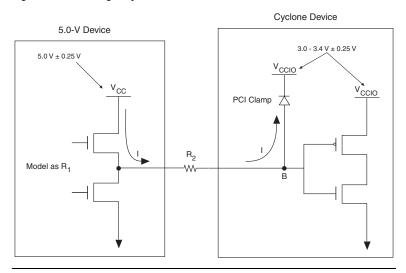


Figure 11–3. Driving a Cyclone Device with a 5.0-Volt Device

If  $V_{\rm CCIO}$  is between 3.0-V and 3.6-V and the PCI clamping diode (not available on EP1C3 devices) is enabled, the voltage at point B in Figure 11–3 is 4.3-V or less. To limit large current draw from the 5.0-V device,  $R_2$  should be small enough for a fast signal rise time and large enough so that it does not violate the high-level output current ( $I_{\rm OH}$ ) specifications of the devices driving the trace. The PCI clamping diode in the Cyclone device can support 25mA of current.

To compute the required value of  $R_{2\prime}$  first calculate the model of the pull-up transistors on the 5.0-V device. This output resistor (R1) can be modeled by dividing the 5.0-V device supply voltage (VCC) by the  $I_{OH}$ :  $R_{1}=V_{CC}/I_{OH}.$ 

Figure 11-4 shows an example of typical output drive characteristics of a 5.0-V device.

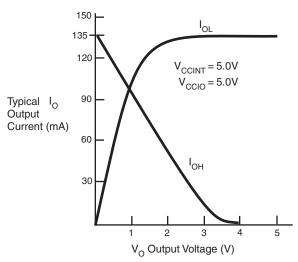


Figure 11–4. Output Drive Characteristics of a 5.0-V Device

As shown above,  $R_1 = 5.0 \text{-V} / 135 \text{ mA}$ .



The values usually shown in data sheets reflect typical operating conditions. Subtract 20% from the data sheet value for guard band. This subtraction applied to the above example gives  $R_{\rm 1}$  a value of 30  $\Omega$ 

 $R_2$  should be selected to not violate the driving device's IOH specification. For example, if the above device has a maximum IOH of 8 mA, given the PCI clamping diode,  $V_{\rm IN} = V_{\rm CCIO} + 0.7\text{-V} = 3.7\text{-V}$ . Given that the maximum supply load of a 5.0-V device ( $V_{\rm CC}$ ) will be 5.25-V, the value of  $R_2$  can be calculated as follows:

$$R_2 = \frac{(5.25V - 3.7 V) - (8 mA \times 30 \Omega)}{8 mA} = 164 \Omega$$

This analysis assumes worst-case conditions. If your system will not see a wide variation in voltage-supply levels, you can adjust these calculations accordingly.



Because 5.0-V device tolerance in Cyclone devices requires use of the PCI clamp (not available on EP1C3 devices), and this clamp is activated during configuration, 5.0-V signals may not be driven into the device until it is configured.

# **Hot-Socketing**

Hot-socketing, also known as hot-swapping, refers to inserting or removing a board or device into or out of a system board while system power is on. For a system to support hot-socketing, plug-in or removal of the subsystem or device must not damage the system or interrupt system operation.

All devices in the Cyclone family are designed to support hot-socketing without special design requirements. The following features have been implemented in Cyclone devices to facilitate hot-socketing:

- Devices can be driven before power-up with no damage to the device.
- I/O pins remain tri-stated during power-up.
- Signal pins do not drive the V<sub>CCIO</sub> or V<sub>CCINT</sub> power supplies.



Because 5.0-V tolerance in Cyclone devices require the use of the PCI clamping diode, and the clamping diode is only available after configuration has finished, be careful not to connect 5.0-V signals to the device.

## **Devices Can Be Driven before Power-Up**

The device I/O pins, dedicated input pins, and dedicated clock pins of Cyclone devices can be driven before or during power-up without damaging the devices.

# I/O Pins Remain Tri-Stated during Power-Up

A device that does not support hot-socketing may interrupt system operation or cause contention by driving out before or during power-up. For Cyclone devices, I/O pins are tri-stated before and during power-up and configuration, and will not drive out.

## Signal Pins Do Not Drive the V<sub>CCIO</sub> or V<sub>CCINT</sub> Power Supplies

A device that does not support hot-socketing will short power supplies together when powered-up through its signal pins. This irregular power-up can damage both the driving and driven devices and can disrupt card power-up.

In Cyclone devices, there is no current path from I/O pins, dedicated input pins, or dedicated clock pins to the VCCIO or VCCINT pins before or during power-up. A Cyclone device may be inserted into (or removed from) a powered-up system board without damaging or interfering with system-board operation. When hot-socketing, Cyclone devices have a minimal effect on the signal integrity of the backplane.



The maximum DC current when hot-socketing Cyclone devices is less than 300  $\mu$ A, whereas the maximum AC current during hot-socketing is less than 8 mA for a period of 10ns or less.

During hot-socketing, the signal pins of a device may be connected and driven by the active system before the power supply can provide current to the device  $V_{CC}$  and ground planes. Known as latch-up, this condition can cause parasitic diodes to turn on within the device, causing the device to consume a large amount of current, and possibly causing electrical damage. This operation can also cause parasitic diodes to turn on inside of the driven device. Cyclone devices are immune to latch-up when hot-socketing.

# Power-Up Sequence

Because Cyclone devices can be used in a multi-voltage environment, they are designed to tolerate any possible power-up sequence. Either  $V_{\rm CCINT}$  or  $V_{\rm CCIO}$  can initially supply power to the device, and 3.3-V, 2.5-V, 1.8-V, or 1.5-V input signals can drive the devices without special precautions before  $V_{\rm CCINT}$  or  $V_{\rm CCIO}$  is applied. Cyclone devices can operate with a  $V_{\rm CCIO}$  voltage level that is higher than the  $V_{\rm CCINT}$  level. You can also change the  $V_{\rm CCIO}$  supply voltage while the board is powered-up. However, you must ensure that the  $V_{\rm CCINT}$  and  $V_{\rm CCIO}$  power supplies stay within the correct device operating conditions.

When  $V_{CCIO}$  and  $V_{CCINT}$  are supplied from different power sources to a Cyclone device, a delay between  $V_{CCIO}$  and  $V_{CCINT}$  may occur. Normal operation does not occur until both power supplies are in their recommended operating range. When  $V_{CCINT}$  is powered-up, the IEEE Std. 1149.1 Joint Test Action Group (JTAG) circuitry is active. If TMS and TCK are connected to  $V_{CCIO}$  and  $V_{CCIO}$  is not powered-up, the JTAG signals are left floating. Thus, any transition on TCK can cause the state machine to transition to an unknown JTAG state, leading to incorrect operation when  $V_{CCIO}$  is finally powered-up. To disable the JTAG state during the power-up sequence, TCK should be pulled low to ensure that an inadvertent rising edge does not occur on TCK.

# Power-On Reset

When designing a circuit, it is important to consider system state at power-up. Cyclone devices maintain a reset state during power-up. When power is applied to a Cyclone device, a power-on-reset event occurs if  $V_{CC}$  reaches the recommended operating range within a certain period of time (specified as a maximum  $V_{CC}$  rise time). A POR event does not occur if these conditions are not met because slower rise times can cause incorrect device initialization and functional failure. The  $V_{CCIO}$  level of the I/O banks that contains configuration pins must also reach an acceptable level to trigger POR event.



If  $V_{CCINT}$  does not remain in the specified operating range, operation is not assured until  $V_{CCINT}$  re-enters the range.

## Conclusion

PCBs often contain a mix of 5.0-V, 3.3-V, 2.5-V, 1.8-V, and 1.5-V devices. The Cyclone device family's MultiVolt I/O operation capability allows you to incorporate newer-generation devices with devices of varying voltage levels. This capability also enables the device core to run at its core voltage,  $V_{\rm CCINT}$ , while maintaining I/O pin compatibility with other logic levels. Altera has taken further steps to make system design easier by designing devices that allow  $V_{\rm CCINT}$  and  $V_{\rm CCIO}$  to power-up in any sequence and by incorporating support for hot-socketing.

# Document Revision History

Table 11–1 shows the revision history for this chapter.

Table 11–1. Document Revision History				
Date and Document Version	Changes Made	Summary of Changes		
May 2008 v1.3	Minor textual and style changes.	_		
January 2007 v1.2	Updated "Power-On Reset" section.	_		
October 2003 v1.1	Added 64-bit PCI support information.	_		
May 2003 v1.0	Added document to Cyclone Device Handbook.	_		



# 12. Designing with 1.5-V Devices

C51012-1.4

### Introduction

The Cyclone® FPGA family provides the best solution for high-volume, cost-sensitive applications. A Cyclone device is fabricated on a leading-edge 1.5-V, 0.13-µm, all-layer copper SRAM process.

Using a 1.5-V operating voltage provides the following advantages:

- Lower power consumption compared to 2.5-V or 3.3-V devices.
- Lower operating temperature.
- Less need for fans and other temperature-control elements.

Since many existing designs are based on 5.0-V, 3.3-V and 2.5-V power supplies, a voltage regulator may be required to lower the voltage supply level to 1.5-V. This document provides guidelines for designing with Cyclone devices in mixed-voltage and single-voltage systems and provides examples using voltage regulators. This document also includes information about:

- "Power Sequencing and Hot Socketing" on page 12–1
- "Using MultiVolt I/O Pins" on page 12–2
- "Voltage Regulators" on page 12–3
- "1.5-V Regulator Application Examples" on page 12–19
- "Board Layout" on page 12–21
- "Power Sequencing and Hot Socketing" on page 12–1

# Power Sequencing and Hot Socketing

Because 1.5-V Cyclone FPGAs can be used in a mixed-voltage environment, they have been designed specifically to tolerate any possible power-up sequence. Therefore, the  $V_{\text{CCIO}}$  and  $V_{\text{CCINT}}$  power supplies may be powered in any order.

You can drive signals into Cyclone FPGAs before and during power up without damaging the device. In addition, Cyclone FPGAs do not drive out during power up since they are tri-stated during power up. Once the device reaches operating conditions and is configured, Cyclone FPGAs operate as specified by the user.



For more information, refer to the *Cyclone FPGA Family Data Sheet* section of the *Cyclone Device Handbook*.

# Using MultiVolt I/O Pins

Cyclone FPGAs require a 1.5-V  $V_{CCINT}$  and a 3.3-V, 2.5-V, 1.8-V, or 1.5-V I/O supply voltage level ( $V_{CCIO}$ ). All pins, including dedicated inputs, clock, I/O, and JTAG pins, are 3.3-V tolerant before and after  $V_{CCINT}$  and  $V_{CCIO}$  are powered.

When  $V_{\rm CCIO}$  is connected to 1.5-V, the output is compatible with 1.5-V logic levels. The output pins can be made 1.8-V, 2.5-V, or 3.3-V compatible by using open-drain outputs pulled up with external resistors. You can use external resistors to pull open-drain outputs up with a 1.8-V, 2.5-V, or 3.3-V  $V_{\rm CCIO}$ . Table 12–1 summarizes Cyclone MultiVolt I/O support.

Table 12–1. Cyclo	Table 12–1. Cyclone MultiVolt I/O Support Note (1)									
y (v)			nput Sign	al		Output Signal				
V <sub>CCIO</sub> (V)	1.5-V	1.8-V	2.5-V	3.3-V	5.0-V	1.5-V	1.8-V	2.5-V	3.3-V	5.0-V
1.5-V	<b>✓</b>	<b>✓</b>	<b>√</b> (2)	<b>√</b> (2)	_	<b>✓</b>	_	_	_	_
1.8-V	<b>✓</b>	<b>✓</b>	<b>✓</b>	<b>✓</b>	_	<b>√</b> (3)	<b>✓</b>	_	_	_
2.5-V	_	_	<b>✓</b>	<b>✓</b>	_	<b>√</b> (5)	<b>√</b> (5)	<b>✓</b>	_	_
3.3-V	_	_	<b>√</b> (4)	<b>✓</b>	<b>√</b> (6)	<b>√</b> (7)	<b>√</b> (7)	<b>√</b> (7)	<b>✓</b>	<b>√</b> (8)

#### *Notes to Table 12–1:*

- (1) The PCI clamping diode must be disabled to drive an input with voltages higher than V<sub>CCIO</sub>.
- (2) When V<sub>CCIO</sub> = 1.5-V and a 2.5-V or 3.3-V input signal feeds an input pin, higher pin leakage current is expected.
- When  $V_{CCIO} = 1.8$ -V, a Cyclone device can drive a 1.5-V device with 1.8-V tolerant inputs.
- (4) When  $V_{CCIO} = 3.3$ -V and a 2.5-V input signal feeds an input pin, or when  $V_{CCIO} = 1.8$ -V and a 1.5-V input signal feeds an input pin, the  $V_{CCIO}$  supply current is slightly larger than expected. The reason for this increase is that the input signal level does not drive to the  $V_{CCIO}$  rail, which causes the input buffer to not completely shut off.
- (5) When  $V_{CCIO} = 2.5$ -V, a Cyclone device can drive a 1.5-V or 1.8-V device with 2.5-V tolerant inputs.
- (6) Cyclone devices can be 5.0-V tolerant with the use of an external resistor and the internal PCI clamp diode.
- (7) When  $V_{CCIO} = 3.3$ -V, a Cyclone device can drive a 1.5-V, 1.8-V, or 2.5-V device with 3.3-V tolerant inputs.
- (8) When V<sub>CCIO</sub> = 3.3-V, a Cyclone device can drive a device with 5.0-V LVTTL inputs but not 5.0-V LVCMOS inputs.

Figure 12–1 shows how Cyclone FPGAs interface with 3.3--V and 2.5-V devices while operating with a 1.5-V  $V_{\rm CCINT}$  to increase performance and save power.

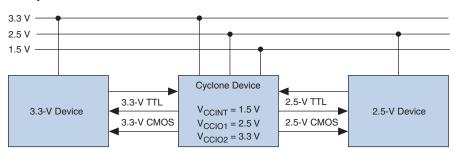


Figure 12-1. Cyclone FPGAs Interface with 3.3-V and 2.5-V Devices

# Voltage Regulators

This section explains how to generate a 1.5-V supply from another system supply. Supplying power to the 1.5-V logic array and/or I/O pins requires a 5.0-V- or 3.3-V-to-1.5-V voltage regulator. A linear regulator is ideal for low-power applications because it minimizes device count and has acceptable efficiency for most applications. A switching voltage regulator provides optimal efficiency. Switching regulators are ideal for high-power applications because of their high efficiency.

This section will help you decide which regulator to use in your system, and how to implement the regulator in your design. There are several companies that provide voltage regulators for low-voltage devices, such as Linear Technology Corporation, Maxim Integrated Products, Intersil Corporation (Elantec), and National Semiconductor Corporation.

Table 12–2 shows the terminology and specifications commonly encountered with voltage regulators. Symbols are shown in parentheses. If the symbols are different for linear and switching regulators, the linear regulator symbol is listed first.

Table 12–2. Voltage Regulator Specifications and Terminology (Part 1 of 2)				
Specification/Terminology	Description			
Input voltage range (V <sub>IN</sub> ,V <sub>CC</sub> )	Minimum and maximum input voltages define the input voltage range, which is determined by the regulator process voltage capabilities.			
Line regulation (line regulation, V <sub>OUT</sub> )	Line regulation is the variation of the output voltage ( $V_{OUT}$ ) with changes in the input voltage ( $V_{IN}$ ). Error amplifier gain, pass transistor gain, and output impedance all influence line regulation. Higher gain results in better regulation. Board layout and regulator pin-outs are also important because stray resistance can introduce errors.			

Specification/Terminology	Description
Load regulation (load regulation, $V_{\text{OUT}}$ )	Load regulation is a variation in the output voltage caused by changes in the input supply current. Linear Technology regulators are designed to minimize load regulation, which is affected by error amplifier gain, pass transistor gain, and output impedance.
Output voltage selection	Output voltage selection is adjustable by resistor voltage divider networks, connected to the error amplifier input, that control the output voltage. There are multiple output regulators that create 5.0-, 3.3-, 2.5-, 1.8- and 1.5-V supplies.
Quiescent current	Quiescent current is the supply current during no-load or quiescent state. This current is sometimes used as a general term for a supply current used by the regulator.
Dropout voltage	Dropout voltage is the difference between the input and output voltages when the input is low enough to cause the output to drop out of regulation. The dropout voltage should be as low as possible for better efficiency.
Current limiting	Voltage regulators are designed to limit the amount of output current in the event of a failing load. A short in the load causes the output current and voltage to decrease. This event cuts power dissipation in the regulator during a short circuit.
Thermal overload protection	This feature limits power dissipation if the regulator overheats. When a specified temperature is reached, the regulator turns off the output drive transistors, allowing the regulator to cool. Normal operation resumes once the regulator reaches a normal operating temperature.
Reverse current protection	If the input power supply fails, large output capacitors can cause a substantial reverse current to flow backward through the regulator, potentially causing damage. To prevent damage, protection diodes in the regulator create a path for the current to flow from $V_{\text{OUT}}$ to $V_{\text{IN}}$ .
Stability	The dominant pole placed by the output capacitor influences stability. Voltage regulator vendors can assist you in output capacitor selection for regulator designs that differ from what is offered.
Minimum load requirements	A minimum load from the voltage divider network is required for good regulation, which also serves as the ground for the regulator's current path.
Efficiency	Efficiency is the division of the output power by the input power. Each regulator model has a specific efficiency value. The higher the efficiency value, the better the regulator.

# **Linear Voltage Regulators**

Linear voltage regulators generate a regulated output from a larger input voltage using current pass elements in a linear mode. There are two types of linear regulators available: one using a series pass element and another using a shunt element (e.g., a zener diode). Altera recommends using series linear regulators because shunt regulators are less efficient.

Series linear regulators use a series pass element (i.e., a bipolar transistor or MOSFET) controlled by a feedback error amplifier (see Figure 12–2) to regulate the output voltage by comparing the output to a reference voltage. The error amplifier drives the transistor further on or off continuously to control the flow of current needed to sustain a steady voltage level across the load.

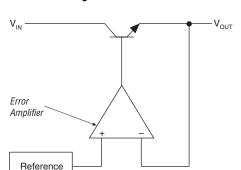


Figure 12-2. Series Linear Regulator

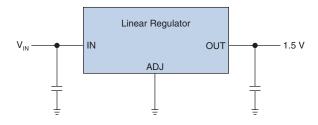
Table 12–3 shows the advantages and disadvantages of linear regulators compared to switching regulators.

Table 12–3. Linear Regulator Advantages and Disadvantages					
Advantages	Disadvantages				
Requires few supporting components Low cost Requires less board space Quick transient response Better noise and drift characteristics No electromagnetic interference (EMI) radiation from the switching components Tighter regulation	Less efficient (typically 60%) Higher power dissipation Larger heat sink requirements				

You can minimize the difference between the input and output voltages to improve the efficiency of linear regulators. The dropout voltage is the minimum allowable difference between the regulator's input and output voltage.

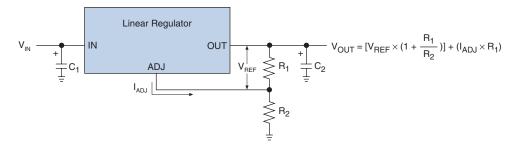
Linear regulators are available with fixed, variable, single, or multiple outputs. Multiple-output regulators can generate multiple outputs (e.g., 1.5- and 3.3-V outputs). If the board only has a 5.0-V power voltage supply, you should use multiple-output regulators. The logic array requires a 1.5-V power supply, and a 3.3-V power supply is required to interface with 3.3- and 5.0-V devices. However, fixed-output regulators have fewer supporting components, reducing board space and cost. Figure 12–3 shows an example of a three-terminal, fixed-output linear regulator.

Figure 12-3. Three-Terminal, Fixed-Output Linear Regulator



Adjustable-output regulators contain a voltage divider network that controls the regulator's output. Figure 12–4 shows how you can also use a three-terminal linear regulator in an adjustable-output configuration.

Figure 12-4. Adjustable-Output Linear Regulator



## **Switching Voltage Regulators**

Step-down switching regulators can provide 3.3-V-to-1.5-V conversion with up to 95% efficiencies. This high efficiency comes from minimizing quiescent current, using a low-resistance power MOSFET switch, and, in higher-current applications, using a synchronous switch to reduce diode losses.

Switching regulators supply power by pulsing the output voltage and current to the load. Table 12–4 shows the advantages and disadvantages of switching regulators compared to linear regulators.



For more information about switching regulators, refer to Linear Technology's application note, *AN35: Step Down Switching Regulators*, at www.linear.com/designtools/app\_notes.jsp.

Table 12–4. Switching Regulator Advantages and Disadvantages				
Advantages Disadvantages				
Highly efficient (typically >80%) Reduced power dissipation Smaller heat sink requirements Wider input voltage range High power density	Generates EMI Complex to design Requires 15 or more supporting components Higher cost Requires more board space			

There are two types of switching regulators, asynchronous and synchronous. Asynchronous switching regulators have one field effect transistor (FET) and a diode to provide the current path while the FET is off (see Figure 12–5).

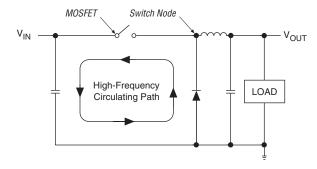


Figure 12-5. Asynchronous Switching Regulator

Synchronous switching regulators have a voltage- or current-controlled oscillator that controls the on and off time of the two MOSFET devices that supply the current to the circuit (see Figure 12–6).

Voltage-Controlled Oscillator (VCO)

Figure 12–6. Voltage-Controlled Synchronous Switching Regulator

### **Maximum Output Current**

Select an external MOSFET switching transistor (optional) based on the maximum output current that it can supply. Use a MOSFET with a low on-resistance and a voltage rating high enough to avoid avalanche breakdown. For gate-drive voltages less than 9-V, use a logic-level MOSFET. A logic-level MOSFET is only required for topologies with a controller IC and an external MOSFET.

## **Selecting Voltage Regulators**

Your design requirements determine which voltage regulator you need. The key to selecting a voltage regulator is understanding the regulator parameters and how they relate to the design.

The following checklist can help you select the proper regulator for your design:

- Do you require a 3.3-V, 2.5-V, and 1.5-V output (V<sub>OUT</sub>)?
- What precision is required on the regulated 1.5-V supplies (line and load regulation)?
- What supply voltages  $(V_{IN} \text{ or } V_{CC})$  are available on the board?
- What voltage variance (input voltage range) is expected on  $V_{IN}$  or  $V_{CC}$ ?
- What is the maximum  $I_{CC}$  ( $I_{OUT}$ ) required by your Altera<sup>®</sup> device?
- What is the maximum current surge  $(I_{OUT(MAX)})$  that the regulator will need to supply instantaneously?

#### Choose a Regulator Type

If required, select either a linear, asynchronous switching, or synchronous switching regulator based on your output current, regulator efficiency, cost, and board-space requirements. DC-to-DC converters have output current capabilities from 1 to 8 A. You can use a controller with an external MOSFET rated for higher current for higher-output-current applications.

#### Calculate the Maximum Input Current

Use the following equation to estimate the maximum input current based on the output power requirements at the maximum input voltage:

$$I_{IN,DC(MAX)} = \frac{V_{OUT} \times I_{OUT(MAX)}}{\eta \times V_{IN(MAX)}}$$

Where  $\eta$  is nominal efficiency: typically 90% for switching regulators, 60% for linear 2.5-V-to-1.5-V conversion, 45% for linear 3.3-V-to-1.5-V conversion, and 30% for linear 5.0-V-to-1.5-V conversion.

Once you identify the design requirements, select the voltage regulator that is best for your design. Tables 12–5 and 12–6 list a few Linear Technology and Elantec regulators available at the time this document was published. There may be more regulators to choose from depending on your design specification. Contact a regulator manufacturer for availability.

Table 12–5. Linear Technology 1.5-V Output Voltage Regulators						
Voltage Regulator	Regulator Type	Total Number of Components	V <sub>IN</sub> (V)	I <sub>OUT</sub> (A)	Special Features	
LT1573	Linear	10	2.5 or 3.3 (1)	6	_	
LT1083	Linear	5	5.0	7.5	_	
LT1084	Linear	5	5.0	5	_	
LT1085	Linear	5	5.0	3	Inexpensive solution	
LTC1649	Switching	22	3.3	15	Selectable output	
LTC1775	Switching	17	5.0	5	_	

Note to Table 12-5:

(1) A 3.3-V V<sub>IN</sub> requires a 3.3-V supply to the regulator's input and 2.5-V supply to bias the transistors.

Table 12–6. Elantec 1.5-V Output Voltage Regulators						
Voltage Regulator	Regulator Type	Total Number of Components	V <sub>IN</sub> (V)	I <sub>OUT</sub> (A)	Special Features	
EL7551C	Switching	11	5.0	1	_	
EL7564CM	Switching	13	5.0	4	_	
EL7556BC	Switching	21	5.0	6	_	
EL7562CM	Switching	17	3.3 or 5.5	2	_	
EL7563CM	Switching	19	3.3	4	_	

## **Voltage Divider Network**

Design a voltage divider network if you are using an adjustable output regulator. Follow the controller or converter IC's instructions to adjust the output voltage.

### 1.5-V Regulator Circuits

This section contains the circuit diagrams for the voltage regulators discussed in this chapter. You can use the voltage regulators in this section to generate a 1.5-V power supply. Refer to the voltage regulator data sheet to find detailed specifications. If you require further information that is not shown in the data sheet, contact the regulator's vendor.

Figures 12–7 through 12–12 show the circuit diagrams of Linear Technology voltage regulators listed in Table 12–5.

The LT1573 linear voltage regulator converts 2.5-V to 1.5-V with an output current of 6A (see Figure 12–7).

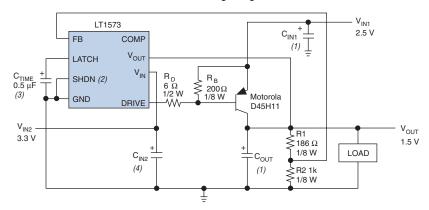


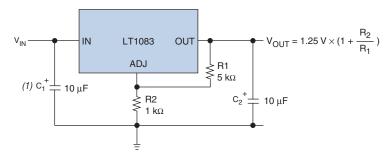
Figure 12-7. LT1573: 2.5-V-to-1.5-V/6.0-A Linear Voltage Regulator

#### Notes to Figure 12–7:

- (1)  $C_{IN1}$  and  $C_{OUT}$  are AVX 100- $\mu$ F/10-V surface-mount tantalum capacitors.
- (2) Use SHDN (active high) to shut down the regulator.
- (3) C<sub>TIME</sub> is a 0.5-μF capacitor for 100-ms time out at room temperature.
- (4)  $C_{IN2}$  is an AVX 15- $\mu$ F/10-V surface-mount tantalum capacitor.

Use adjustable 5.0- to 1.5-V regulators (shown in Figures 12-8 through 12-10) for 3.0- to 7.5-A low-cost, low-device-count, board-space-efficient solutions.

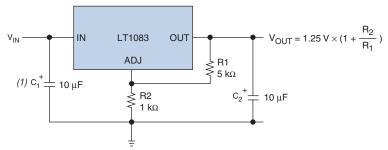
Figure 12-8. LT1083: 5.0-V-to-1.5-V/7.5-A Linear Voltage Regulator



*Note to Figure 12–8:* 

This capacitor is necessary to maintain the voltage level at the input regulator.
 There could be a voltage drop at the input if the voltage supply is too far away.

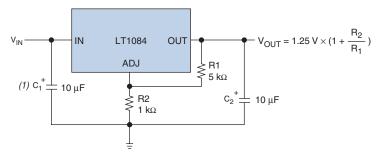
Figure 12–9. LT1084: 5.0-V-to-1.5-V/5.0-A Linear Voltage Regulator



#### Note to Figure 12-9:

(1) This capacitor is necessary to maintain the voltage level at the input regulator. There could be a voltage drop at the input if the voltage supply is too far away.

Figure 12-10. LT1085: 5.0-V-to-1.5-V/3-A Linear Voltage Regulator



#### *Note to Figure 12–10:*

(1) This capacitor is necessary to maintain the voltage level at the input regulator. There could be a voltage drop at the input if the voltage supply is too far away. Figure 12–11 shows a high-efficiency switching regulator circuit diagram. A selectable resistor network controls the output voltage. The resistor values in Figure 12–11 are selected for 1.5-V output operation.

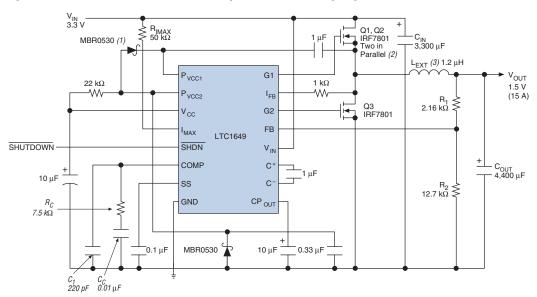


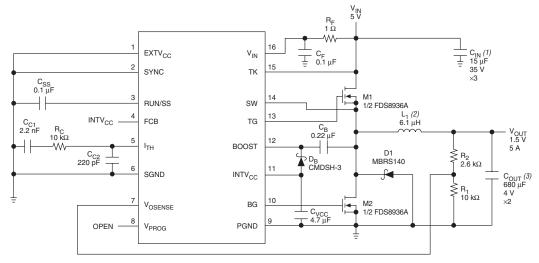
Figure 12-11. LT1649: 3.3-V-to-1.5-V/15-A Asynchronous Switching Regulator

#### Notes to Figure 12-11:

- (1) MBR0530 is a Motorola device.
- (2) IRF7801 is a International Rectifier device.
- (3) Refer to the Panasonic 12TS-1R2HL device.

Figure 12–12 shows synchronous switching regulator with adjustable outputs.

Figure 12-12. LTC1775: 5.0-V-to-1.5-V/5-A Synchronous Switching Regulator



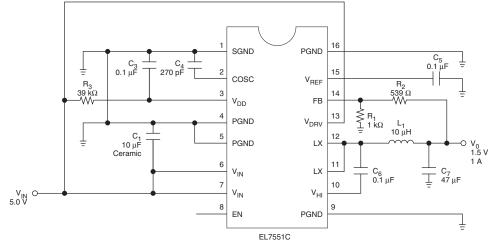
### Notes to Figure 12–12:

- (1) This is a KEMETT495X156M035AS capacitor.
- (2) This is a Sumida CDRH127-6R1 inductor.
- (3) This is a KEMETT510X687K004AS capacitor.

Figures 12–13 through 12–17 show the circuit diagrams of Elantec voltage regulators listed in Table 12–6.

Figures 12–13 through 12–15 show the switching regulator that converts 5.0-V to 1.5-V with different output current.

Figure 12–13. EL7551C: 5.0-V-to-1.5-V/1-A Synchronous Switching Regulator



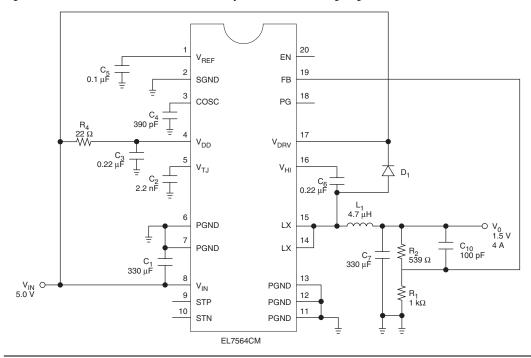


Figure 12-14. EL7564CM: 5.0-V-to-1.5-V/4-A Synchronous Switching Regulator

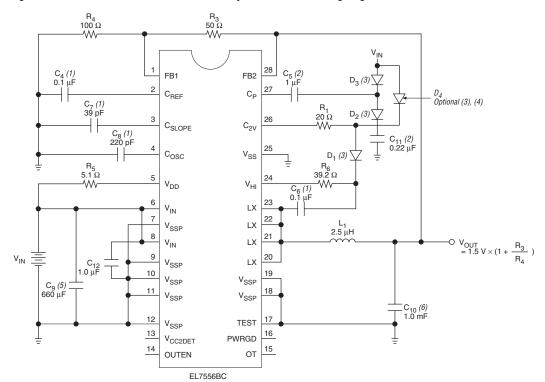


Figure 12-15. EL7556BC: 5.0-V-to-1.5-V/6-A Synchronous Switching Regulator

#### *Notes to Figures 12–13 –12–15:*

- (1) These capacitors are ceramic capacitors.
- (2) These capacitors are ceramic or tantalum capacitor.
- (3) These are BAT54S fast diodes.
- (4) D4 is only required for EL7556ACM.
- (5) This is a Sprague 293D337X96R3 2X330μF capacitor.
- (6) This is a Sprague 293D337X96R3 3X330μF capacitor.

Figures 12–16 and 12–17 show the switching regulator that converts 3.3 V to 1.5 V with different output currents.

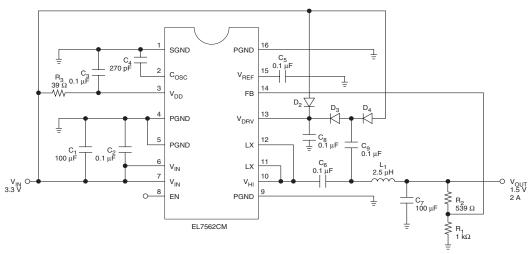
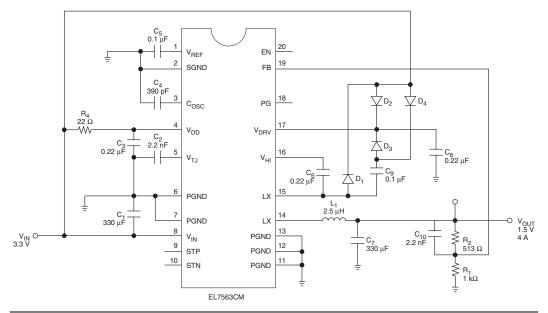


Figure 12–16. EL7562CM: 3.3-V to 1.5-V/2-A Synchronous Switching Regulator

Figure 12-17. EL7563CM: 3.3-V to 1.5-V/4-A Synchronous Switching Regulator



# 1.5-V Regulator Application Examples

The following sections show the process used to select a voltage regulator for three sample designs. The regulator selection is based on the amount of power that the Cyclone device consumes. There are 14 variables to consider when selecting a voltage regulator. The following variables apply to Cyclone device power consumption:

- $f_{MAX}$
- Output and bidirectional pins
- Average toggle rate for I/O pins (tog<sub>IO</sub>)
- Average toggle rate for logic elements (LEs) (tog<sub>LC</sub>)
- User-mode I<sub>CC</sub> consumption
- Maximum power-up I<sub>CCINT</sub> requirement
- Utilization
- V<sub>CCIO</sub> supply level
- V<sub>CCINT</sub> supply level

The following variables apply to the voltage regulator:

- Output voltage precision requirement
- Supply voltage on the board
- Voltage supply output current
- Variance of board supply
- Efficiency

Different designs have different power consumptions based on the variables listed. Once you calculate the Cyclone device's power consumption, you must consider how much current the Cyclone device needs. You can use the Cyclone power calculator (available at www.altera.com) or the PowerGauge<sup>TM</sup> tool in the Quartus II software to determine the current needs. Also check the maximum power-up current requirement listed in the Power Consumption section of the Cyclone FPGA Family Data Sheet because the power-up current requirement may exceed the user-mode current consumption for a specific design.

Once you determine the minimum current the Cyclone device requires, you must select a voltage regulator that can generate the desired output current with the voltage and current supply that is available on the board using the variables listed in this section. An example is shown to illustrate the voltage regulator selection process.

## **Synchronous Switching Regulator Example**

This example shows a worst-case scenario for power consumption where the design uses all the LEs and RAM. Table 12–7 shows the design requirements for 1.5-V design using a Cyclone EP1C12 FPGA.

Table 12–7. Design Requirements for the Example EP1C12F324C				
Design Requirement	Value			
Output voltage precision requirement	±5%			
Supply voltages available on the board	3.3 V			
Voltage supply output current available for this section $(I_{IN,\ DC(MAX)})$	2 A			
Variance of board supply (V <sub>IN</sub> )	±5%			
f <sub>MAX</sub>	150 MHz			
Average tog <sub>IO</sub>	12.5%			
Average tog <sub>LC</sub>	12.5%			
Utilization	100%			
Output and bidirectional pins	125			
V <sub>CCIO</sub> supply level	3.3 V			
V <sub>CCINT</sub> supply level	1.5 V			
Efficiency	≥90%			

Table 12–8 uses the checklist on page 12–8 to help select the appropriate voltage regulator.

Table 12–8. Voltage Regulator Selection Process for EP1C12F324C Design (Part 1 of 2)				
Output voltage requirements	V <sub>OUT</sub> = 1.5 V			
Supply voltages	V <sub>IN</sub> OR V <sub>CC</sub> = 3.3 V			
Supply variance from Linear Technology data sheet	Supply variance = ±5%			
Estimated I <sub>CCINT</sub> Use Cyclone Power Calculator	I <sub>CCINT</sub> = 620 mA			
Estimated $I_{CCIO}$ if regulator powers $V_{CCIO}$ Use Cyclone Power Calculator (not applicable in this example because $V_{CCIO} = 3.3 \text{ V}$ )	I <sub>CCIO</sub> = N/A			
Total user-mode current consumption $I_{CC} = I_{CCINT} + I_{CCIO}$	I <sub>CC</sub> = 620 mA			

Table 12–8. Voltage Regulator Selection Process for EP1C12F324C Design (Part 2 of 2)					
EP1C12 maximum power-up current requirement See Power Consumption section of the Cyclone FPGA Family Data Sheet for other densities	I <sub>PUC(MAX)</sub> =	900 mA			
Maximum output current required Compare I <sub>CC</sub> with I <sub>PUC(MAX)</sub>	I <sub>OUT(MAX)</sub> =	900 mA			
Voltage regulator selection See Linear Technology LTC 1649 data sheet See Intersil (Elantec) EL7562C data sheet	LTC1649 I <sub>OUT(MAX)</sub> = EL7562C I <sub>OUT(MAX)</sub> =				
LTC1649					
Nominal efficiency (η)	Nominal efficiency (η) =	> 90%			
Line and load regulation Line regulation + load regulation = (0.17 mV + 7 mV)/ 1.5 V × 100%	Line and Load Regulation =	0.478% < 5%			
Minimum input voltage $(V_{IN(MIN)})$ $(V_{IN(MIN)}) = V_{IN}(1 - \Delta V_{IN}) = 3.3V(1 - 0.05)$	(V <sub>IN(MIN)</sub> ) =	3.135 V			
Maximum input current $I_{\text{IN, DC(MAX)}} = (V_{\text{OUT}} \times I_{\text{OUT(MAX)}})/(\eta \times V_{\text{IN(MIN)}})$	I <sub>IN, DC(MAX)</sub> =	478 mA < 2 A			
EL7562C					
Nominal efficiency (η)	Nominal efficiency (η) =	> 95%			
Line and load regulation Line regulation + load regulation = (0.17 mV + 7 mV)/ 1.5 V × 100%	Line and Load Regulation =	0.5% < 5%			
Minimum input voltage $(V_{IN(MIN)})$ $(V_{IN(MIN)}) = V_{IN}(1 - \Delta V_{IN}) = 3.3V(1 - 0.05)$	(V <sub>IN(MIN)</sub> ) =	3.135 V			
Maximum input current $I_{\text{IN, DC(MAX)}} = (V_{\text{OUT}} \times I_{\text{OUT(MAX)}}) / (\eta \times V_{\text{IN(MIN)}})$	I <sub>IN, DC(MAX)</sub> =	453 mA < 2 A			

# **Board Layout**

Laying out a printed circuit board (PCB) properly is extremely important in high-frequency ( $\geq\!100~\text{kHz})$  switching regulator designs. A poor PCB layout results in increased EMI and ground bounce, which affects the reliability of the voltage regulator by obscuring important voltage and current feedback signals. Altera recommends using Gerber files —predesigned layout files—supplied by the regulator vendor for your board layout.

If you cannot use the supplied layout files, contact the voltage regulator vendor for help on re-designing the board to fit your design requirements while maintaining the proper functionality.

Altera recommends that you use separate layers for signals, the ground plane, and voltage supply planes. You can support separate layers by using multi-layer PCBs, assuming you are using two signal layers.

Figure 12–18 shows how to use regulators to generate 1.5-V and 2.5-V power supplies if the system needs two power supply systems. One regulator is used for each power supply.

PCB

1.5 V

Regulator

1.5 V

Altera
Cyclone
FPGA

Regulator

2.5 V

Device

Figure 12-18. Two Regulator Solution for Systems that Require 5.0-V, 2.5-V and 1.5-V Supply Levels

Figure 12–19 shows how to use a single regulator to generate two different power supplies (1.5-V and 2.5-V). The use of a single regulator to generate 1.5-V and 2.5-V supplies from the 5.0-V power supply can minimize the board size and thus save cost.

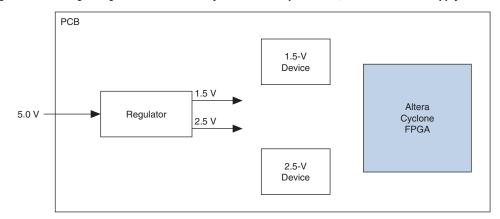


Figure 12-19. Single Regulator Solution for Systems that Require 5.0-V, 2.5-V and 1.5-V Supply Levels

# **Split-Plane Method**

The split-plane design method reduces the number of planes required by placing two power supply planes in one plane (see Figure 12–20). For example, the layout for this method can be structured as follows:

- One 2.5-V plane, covering the entire board
- One plane split between 5.0-V and 1.5-V

This technique assumes that the majority of devices are 2.5-V. To support MultiVolt I/O, Altera devices must have access to 1.5-V and 2.5-V planes.

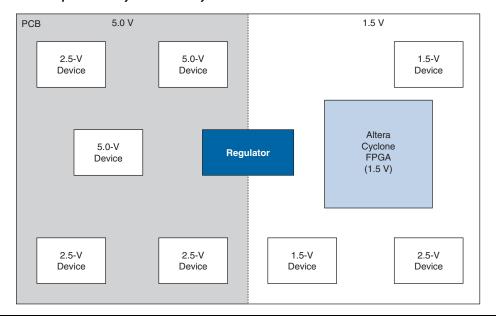


Figure 12-20. Split Board Layout for 2.5-V Systems With 5.0-V and 1.5-V Devices

## Conclusion

With the proliferation of multiple voltage levels in systems, it is important to design a voltage system that can support a low-power device like Cyclone devices. Designers must consider key elements of the PCB, such as power supplies, regulators, power consumption, and board layout when successfully designing a system that incorporates the low-voltage Cyclone family of devices.

## References

Linear Technology Corporation. *Application Note 35 (Step-Down Switching Regulators)*. Milpitas: Linear Technology Corporation, 1989.

Linear Technology Corporation. LT1573 Data Sheet (Low Dropout Regulator Driver). Milpitas: Linear Technology Corporation, 1997.

Linear Technology Corporation. *LT1083/LT1084/LT1085 Data Sheet (7.5 A, 5 A, 3 A Low Dropout Positive Adjustable Regulators)*. Milpitas: Linear Technology Corporation, 1994.

Linear Technology Corporation. *LTC1649 Data Sheet (3.3V Input High Power Step-Down Switching Regulator Controller)*. Milpitas: Linear Technology Corporation, 1998.

Linear Technology Corporation. *LTC1775 Data Sheet (High Power No Rsense Current Mode Synchronous Step-Down Switching Regulator)*. Milpitas: Linear Technology Corporation, 1999.

Intersil Corporation. *EL7551C Data Sheet (Monolithic 1 Amp DC:DC Step-Down Regulator)*. Milpitas: Intersil Corporation, 2002.

Intersil Corporation. EL7564C Data Sheet (Monolithic 4 Amp DC:DC Step-Down Regulator). Milpitas: Intersil Corporation, 2002.

Intersil Corporation. *EL7556BC Data Sheet (Integrated Adjustable 6 Amp Synchronous Switcher)*. Milpitas: Intersil Corporation, 2001.

Intersil Corporation. EL7562C Data Sheet (Monolithic 2 Amp DC:DC Step-Down Regulator). Milpitas: Intersil Corporation, 2002.

Intersil Corporation. EL7563C Data Sheet (Monolithic 4 Amp DC:DC Step-Down Regulator). Milpitas: Intersil Corporation, 2002.

# Referenced Documents

This chapter references the following document:

 Cyclone FPGA Family Data Sheet section of the Cyclone Device Handbook

# Document Revision History

Table 12–9 shows the revision history for this chapter.

Table 12–9. Document Revision History					
Date and Document Version	Changes Made	Summary of Changes			
May 2008 v1.4	Minor textual and style changes. Added "Referenced Documents" section.	_			
January 2007 v1.3	<ul> <li>Added document revision history.</li> <li>Removed references to Stratix in "Introduction" and "Power Sequencing and Hot Socketing" sections.</li> </ul>	_			
August 2005 v1.1	Minor updates.	_			
May 2003 v1.0	Added document to Cyclone Device Handbook.	_			



# Section VI. Configuration

This section provides information for all of the supported configuration schemes for Cyclone devices. The last chapter provides information on EPCS1 and EPCS4 serial configuration devices.

This section contains the following chapters:

- Chapter 13. Configuring Cyclone FPGAs
- Chapter 14. Serial Configuration Devices (EPCS1, EPCS4, EPCS16, EPCS64, and EPCS128) Data Sheet

# **Revision History**

Refer to each chapter for its own specific revision history. For information on when each chapter was updated, refer to the Chapter Revision Dates section, which appears in the complete handbook.

Altera Corporation Section VI–1

Section VI-2 Altera Corporation



# 13. Configuring Cyclone FPGAs

C51013-1.8

## Introduction

You can configure Cyclone® FPGAs using one of several configuration schemes, including the active serial (AS) configuration scheme. This scheme is used with the low cost serial configuration devices. Passive serial (PS) and Joint Test Action Group (JTAG)-based configuration schemes are also supported by Cyclone FPGAs. Additionally, Cyclone FPGAs can receive a compressed configuration bit stream and decompress this data in real-time, reducing storage requirements and configuration time.

This chapter describes how to configure Cyclone devices using each of the three supported configuration schemes.



For more information about setting device configuration options or generating configuration files, refer to the *Software Settings* section in volume 2 of the *Configuration Handbook*.

# Device Configuration Overview

Cyclone FPGAs use SRAM cells to store configuration data. Since SRAM memory is volatile, configuration data must be downloaded to Cyclone FPGAs each time the device powers up. You can download configuration data to Cyclone FPGAs using the AS, PS, or JTAG interfaces (see Table 13–1).

Table 13–1. Cyclone FPGA Configuration Schemes			
Configuration Scheme	Description		
Active serial (AS) configuration	Configuration using: Serial configuration devices (EPCS1, EPCS4, and EPCS16)		
Passive serial (PS) configuration	Configuration using:  Enhanced configuration devices (EPC4, EPC8, and EPC16)  EPC2, EPC1 configuration devices  Intelligent host (microprocessor)  Download cable		
JTAG-based configuration	Configuration via JTAG pins using:  Download cable Intelligent host (microprocessor) Jam <sup>TM</sup> Standard Test and Programming Language (STAPL) Ability to use SignalTap® II Embedded Logic Analyzer.		

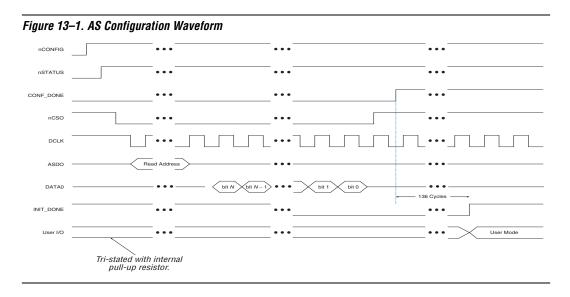
You can select a Cyclone FPGA configuration scheme by driving its  $\tt MSEL1$  and  $\tt MSEL0$  pins either high (1) or low (0), as shown in Table 13–2. If your application only requires a single configuration mode, the <code>MSEL</code> pins can be connected to  $V_{CC}$  (the I/O bank's  $V_{CCIO}$  voltage where the <code>MSEL</code> pin resides) or to ground. If your application requires more than one configuration mode, the <code>MSEL</code> pins can be switched after the FPGA has been configured successfully. Toggling these pins during user mode does not affect the device operation. However, the <code>MSEL</code> pins must be valid before initiating reconfiguration.

Table 13–2. Selecting Cyclone Configuration Schemes			
MSEL1	MSELO	Configuration Scheme	
0	0	AS	
0	1	PS	
0	1	JTAG-based (1)	

*Note to Table 13–2:* 

 JTAG-based configuration takes precedence over other schemes, which means that MSEL pin settings are ignored.

After configuration, Cyclone FPGAs will initialize registers and I/O pins, then enter user mode and function as per the user design. Figure 13–1 shows an AS configuration waveform.



You can configure Cyclone FPGAs using the 3.3-, 2.5-, 1.8-, or 1.5-V LVTTL I/O standard on configuration and JTAG input pins. These devices do not feature a VCCSEL pin; therefore, you should connect the VCCIO pins of the I/O banks containing configuration or JTAG pins according to the I/O standard specifications.

Table 13–3 summarizes the approximate uncompressed configuration file size for each Cyclone FPGA. To calculate the amount of storage space required for multi-device configurations, add the file size of each device together.

Table 13–3. Cyclone Raw Binary File (.rbf) Sizes			
Device	Data Size (Bits)	Data Size (Bytes)	
EP1C3	627,376	78,422	
EP1C4	924,512	115,564	
EP1C6	1,167,216	145,902	
EP1C12	2,323,240	290,405	
EP1C20	3,559,608	435,000	

You should only use the numbers in Table 13–3 to estimate the configuration file size before design compilation. Different file formats, such as .hex or .ttf files, have different file sizes. For any specific version of the Quartus® II software, any design targeted for the same device has the same uncompressed configuration file size. If compression is used, the file size can vary after each compilation.

# Data Compression

Cyclone FPGAs are the first FPGAs to support decompression of configuration data. This feature allows you to store compressed configuration data in configuration devices or other memory, and transmit this compressed bit stream to Cyclone FPGAs. During configuration, the Cyclone FPGA decompresses the bit stream in real time and programs its SRAM cells.

Cyclone FPGAs support compression in the AS and PS configuration schemes. Compression is not supported for JTAG-based configuration.



Preliminary data indicates that compression reduces configuration bit stream size by 35 to 60%.

When you enable compression, the Quartus II software generates configuration files with compressed configuration data. This compression reduces the storage requirements in the configuration device or flash, and decreases the time needed to transmit the bit stream to the Cyclone FPGA.

There are two methods to enable compression for Cyclone bitstreams: before design compilation (in the Compiler Settings menu) and after design compilation (in the **Convert Programming Files** window).

To enable compression in the project's compiler settings, select **Device** under the Assignments menu to bring up the settings window. After selecting your Cyclone device open the **Device and Pin Options** window, and in the **General** settings tab enable the check box for **Generate compressed bitstreams** (as shown in Figure 13–2).

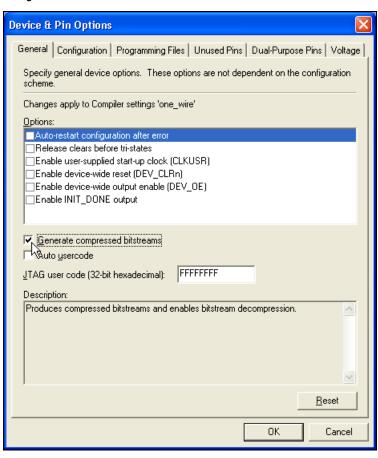
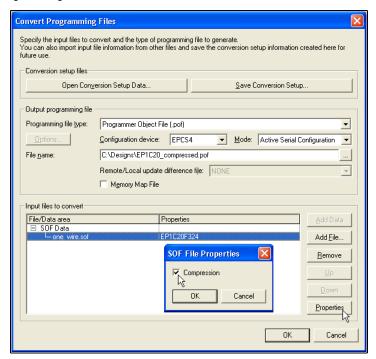


Figure 13–2. Enabling Compression for Cyclone Bitstreams in Compiler Settings

Compression can also be enabled when creating programming files from the **Convert Programming Files** window. See Figure 13–3.

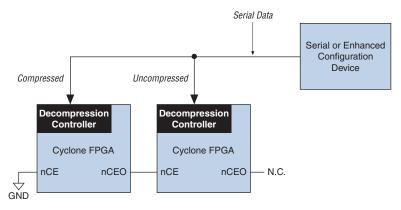
- 1. Click **Convert Programming Files** (File menu).
- 2. Select the programming file type (POF, SRAM HEXOUT, RBF, or TTF).
- 3. For POF output files, select a configuration device.
- 4. Select **Add File** and add a Cyclone SOF file(s).
- Select the name of the file you added to the SOF Data area and click Properties.
- 6. Turn on **Compression**.

Figure 13–3. Enabling Compression for Cyclone Bitstreams in Convert Programming Files



When multiple Cyclone devices are cascaded, the compression feature can be selectively enabled for each device in the chain. Figure 13–4 depicts a chain of two Cyclone FPGAs. The first Cyclone FPGA has the compression feature enabled and therefore receives a compressed bit stream from the configuration device. The second Cyclone FPGA has the compression feature disabled and receives uncompressed data.

Figure 13–4. Compressed and Uncompressed Configuration Data in the Same Programming File Note (1)



#### Note to Figure 13-4:

 The first device in the chain should be set up in AS configuration mode (MSEL[1..0]="00"). The remaining devices in the chain must be set up in PS configuration mode (MSEL[1..0]="01").

You can generate programming files for this setup from the **Convert Programming Files** window (File menu) in the Quartus II software.

The decompression feature supported by Cyclone FPGAs is separate from the decompression feature in enhanced configuration devices (EPC16, EPC8, and EPC4 devices). The data compression feature in the enhanced configuration devices allows them to store compressed data and decompress the bit stream before transmitting to the target devices. When using Cyclone FPGAs with enhanced configuration devices, Altera recommends using compression on one of the devices, not both (preferably the Cyclone FPGA since transmitting compressed data reduces configuration time).

# Configuration Schemes

This section describes the various configuration schemes you can use to configure Cyclone FPGAs. Descriptions include an overview of the protocol, pin connections, and timing information. The schemes discussed are:

- AS configuration (serial configuration devices)
- PS configuration
- JTAG-based configuration

## **Active Serial Configuration (Serial Configuration Devices)**

In the AS configuration scheme, Cyclone FPGAs are configured using the new serial configuration devices. These configuration devices are low cost devices with non-volatile memory that feature a simple four-pin interface and a small form factor. These features make serial configuration devices an ideal solution for configuring the low-cost Cyclone FPGAs.



For more information on programming serial configuration devices, refer to the Cyclone Literature web page at www.altera.com and the Serial Configuration Devices (EPCS1, EPCS4, EPCS16, EPCS64, and EPCS128) Data Sheet.

Serial configuration devices provide a serial interface to access configuration data. During device configuration, Cyclone FPGAs read configuration data via the serial interface, decompress data if necessary, and configure their SRAM cells. This scheme is referred to as an AS configuration scheme because the FPGA controls the configuration interface. This scheme is in contrast to the PS configuration scheme where the configuration device controls the interface.

Serial configuration devices have a four-pin interface: serial clock input (DCLK), serial data output (DATA), AS data input (ASDI), and an active-low chip select (nCS). This four-pin interface connects to Cyclone FPGA pins as shown in Figure 13–5.

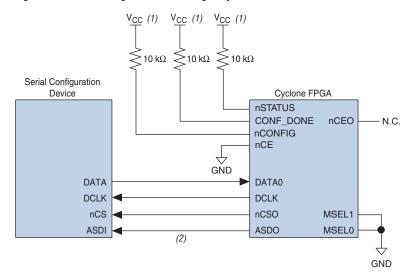


Figure 13–5. AS Configuration of a Single Cyclone FPGA

Notes to Figure 13-5:

- (1) Connect the pull-up resistors to a 3.3-V supply.
- (2) Cyclone FPGAs use the ASDO to ASDI path to control the configuration device.

Connecting the MSEL [1..0] pins to 00 selects the AS configuration scheme. The Cyclone chip enable signal, nCE, must also be connected to ground or driven low for successful configuration.

During system power up, both the Cyclone FPGA and serial configuration device enter a power-on reset (POR) period. As soon as the Cyclone FPGA enters POR, it drives <code>nstatus</code> low to indicate it is busy and drives <code>conf\_downeque</code> low to indicate that it has not been configured. After POR, which typically lasts 100 ms, the Cyclone FPGA releases <code>nstatus</code> and enters configuration mode when this signal is pulled high by the external 10-k $\Omega$  resistor. Once the FPGA successfully exits POR, all user I/O pins are tri-stated. Cyclone devices have weak pull-up resistors on the user I/O pins which are on before and during configuration.



The value of the weak pull-up resistors on the I/O pins that are on before and during configuration can be found in the *DC and Switching Characteristics* chapter in the *Cyclone Device Handbook*.

The serial clock (DCLK) generated by the Cyclone FPGA controls the entire configuration cycle (see Figure 13–1 on page 13–2) and this clock signal provides the timing for the serial interface. Cyclone FPGAs use an

internal oscillator to generate DCLK. After configuration, this internal oscillator is turned off. Table 13-4 shows the active serial DCLK output frequencies.

Table 13–4. Active Serial DCLK Output Frequency			
Minimum	Typical	Maximum	Units
14	17	20	MHz

The serial configuration device latches input/control signals on the rising edge of DCLK and drives out configuration data on the falling edge. Cyclone FPGAs drive out control signals on the falling edge of DCLK and latch configuration data on the falling edge of DCLK.

In configuration mode, the Cyclone FPGA enables the serial configuration device by driving its nCSO output pin low that is connected to the chip select (nCS) pin of the configuration device. The Cyclone FPGA's serial clock (DCLK) and serial data output (ASDO) pins send operation commands and read-address signals to the serial configuration device. The configuration device provides data on its serial data output (DATA) pin that is connected to the DATAO input on Cyclone FPGAs.

After the Cyclone FPGA receives all configuration bits, it releases the open-drain CONF\_DONE pin allowing the external 10-k $\Omega$  resistor to pull this signal to a high level. Initialization begins only after the CONF\_DONE line reaches a high level. The CONF\_DONE pin must have an external 10-k $\Omega$  pull-up resistor in order for the device to initialize.

You can select the clock used for initialization by using the **User Supplied Start-Up Clock** option in the Quartus II software. The Quartus II software uses the 10-MHz (typical) internal oscillator (separate from the AS internal oscillator) by default to initialize the Cyclone FPGA. After initialization, the internal oscillator is turned off. When you enable the **User Supplied Start-Up Clock** option, the software uses the CLKUSR pin as the initialization clock. Supplying a clock on the CLKUSR pin does not affect the configuration process. After all configuration data is accepted and the CONF\_DONE signal goes high, Cyclone devices require 136 clock cycles to initialize properly.

An optional <code>INIT\_DONE</code> pin is available. This pin signals the end of initialization and the start of user mode with a low-to-high transition. The <code>Enable INIT\_DONE</code> output option is available in the Quartus II software. If the <code>INIT\_DONE</code> pin is used, it is high due to an external  $10\text{-}k\Omega$  pull-up resistor when <code>nCONFIG</code> is low and during the beginning of configuration. Once the option bit to enable <code>INIT\_DONE</code> is programmed into the device (during the first frame of configuration data), the

INIT\_DONE pin goes low. When initialization is complete, the INIT\_DONE pin is released and pulled high. This low-to-high transition signals that the FPGA has entered user mode. In user mode, the user I/O pins do not have weak pull-ups and functions as assigned in your design.

If an error occurs during configuration, the Cyclone FPGA asserts the <code>nstatus</code> signal low indicating a data frame error, and the <code>conf\_done</code> signal stays low. With the **Auto-Restart Configuration on Frame Error** option enabled in the Quartus II software, the Cyclone FPGA resets the configuration device by pulsing <code>ncso</code>, releases <code>nstatus</code> after a reset time-out period (about 30  $\mu s$ ), and retries configuration. If this option is turned off, the system must monitor <code>nstatus</code> for errors and then pulse <code>nconfiguration</code>, the <code>conf\_done</code> signal is tri-stated by the target device and then pulled high by the pull-up resistor.

All AS configuration pins, DATAO, DCLK, nCSO, and ASDO, have weak internal pull-up resistors. These pull-up resistors are always active.

When the Cyclone FPGA is in user mode, you can initiate reconfiguration by pulling the <code>nCONFIG</code> pin low. The <code>nCONFIG</code> pin should be low for at least 40  $\mu$ s. When <code>nCONFIG</code> is pulled low, the FPGA also pulls <code>nSTATUS</code> and <code>CONF\_DONE</code> low and all I/O pins are tri-stated. Once <code>nCONFIG</code> returns to a logic high level and <code>nSTATUS</code> is released by the Cyclone FPGA, reconfiguration begins.

## Configuring Multiple Devices (Cascading)

You can configure multiple Cyclone FPGAs using a single serial configuration device. You can cascade multiple Cyclone FPGAs using the chip-enable (nCE) and chip-enable-out (nCEO) pins. The first device in the chain must have its nCE pin connected to ground. You must connect its nCEO pin to the nCE pin of the next device in the chain. When the first device captures all of its configuration data from the bit stream, it drives the nCEO pin low enabling the next device in the chain. You must leave the nCEO pin of the last device unconnected. The nCONFIG, nSTATUS, CONF\_DONE, DCLK, and DATAO pins of each device in the chain are connected (see Figure 13–6).

This first Cyclone FPGA in the chain is the configuration master and controls configuration of the entire chain. You must connect its MSEL pins to select the AS configuration scheme. The remaining Cyclone FPGAs are configuration slaves and you must connect their MSEL pins to select the PS configuration scheme. Figure 13–6 shows the pin connections for this setup.

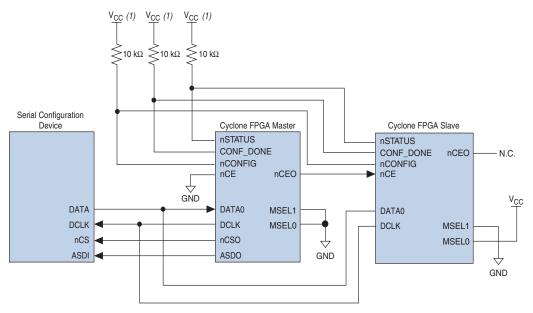


Figure 13–6. Configuring Multiple Devices Using a Serial Configuration Device (AS)

Note to Figure 13-6:

(1) Connect the pull-up resistors to a 3.3-V supply.

As shown in Figure 13–6, the nSTATUS and CONF DONE pins on all target FPGAs are connected together with external pull-up resistors. These pins are open-drain bidirectional pins on the FPGAs. When the first device asserts nCEO (after receiving all of its configuration data), it releases its CONF DONE pin. But the subsequent devices in the chain keep this shared CONF DONE line low until they have received their configuration data. When all target FPGAs in the chain have received their configuration data and have released CONF DONE, the pull-up resistor drives a high level on this line and all devices simultaneously enter initialization mode. If an error occurs at any point during configuration, the nSTATUS line is driven low by the failing FPGA. If you enable the **Auto Restart Configuration on Frame Error** option, reconfiguration of the entire chain begins after a reset time-out period (a maximum of 40 µs). If the option is turned off, the external system must monitor nSTATUS for errors and then pulse nCONFIG low to restart configuration. The external system can pulse nCONFIG if it is under system control rather than tied to V<sub>CC</sub>.



While you can cascade Cyclone FPGAs, serial configuration devices cannot be cascaded or chained together.

If the configuration bit stream size exceeds the capacity of a serial configuration device, you must select a larger configuration device and/or enable the compression feature. While configuring multiple devices, the size of the bit stream is the sum of the individual devices' configuration bit streams.

## Configuring Multiple Devices with the Same Data

Certain applications require the configuration of multiple Cyclone devices with the same design through a configuration bit stream or SOF file. This can actually be done by two methods and they are shown below. For both methods, the serial configuration devices cannot be cascaded or chained together.

#### Method 1

For method 1, the serial configuration device stores two copies of the SOF file. The first copy configures the master Cyclone device, and the second copy configures all the remaining slave devices concurrently. The setup is similar to Figure 13–7 where the master is setup in AS mode (MSEL=00) and the slave devices are setup in PS mode (MSEL01).

To configure four identical Cyclone devices with the same SOF file, you could setup the chain similar to the example shown in Figure 13–6, except connect the three slave devices for concurrent configuration. The nCEO pin from the master device drives the nCE input pins on all three slave devices, and the DATA and DCLK pins connect in parallel to all four devices. During the first configuration cycle, the master device reads its configuration data from the serial configuration device while holding nCEO high. After completing its configuration cycle, the master drives nCE low and transmits the second copy of the configuration data to all three slave devices, configuring them simultaneously. The advantage of using the setup in Figure 13–7 is you can have a different SOF file for the Cyclone master device. However, all the Cyclone slave devices must be configured with the same SOF file.

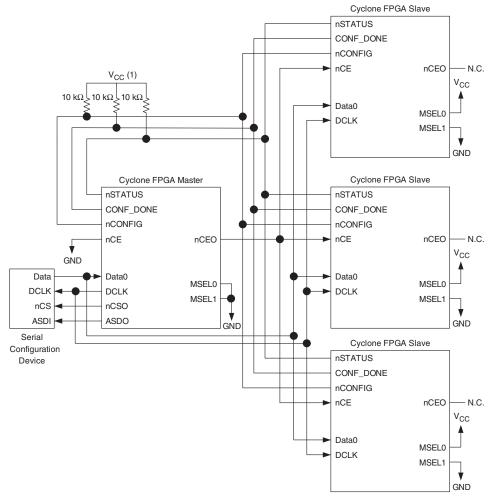


Figure 13-7. Configuring Multiple Devices with the Same Design Using a Serial Configuration Device

*Note to Figure 13–7:* 

(1) The pull-up resistor should be connected to the same supply voltage as the configuration device.

#### Method 2

Method 2 configures multiple Cyclone devices with the same SOFs by storing only one copy of the SOF in the serial configuration device. This saves memory space in the serial configuration device for general-purpose use and may reduce costs. This method is shown in Figure 13–8 where the master device is set up in AS mode (MSLE=00), and

the slave devices are set up in PS mode (MSEL=01). You could set up one or more slave devices in the chain and all the slave devices are set up in the same way as the design shown in Figure 13–8.

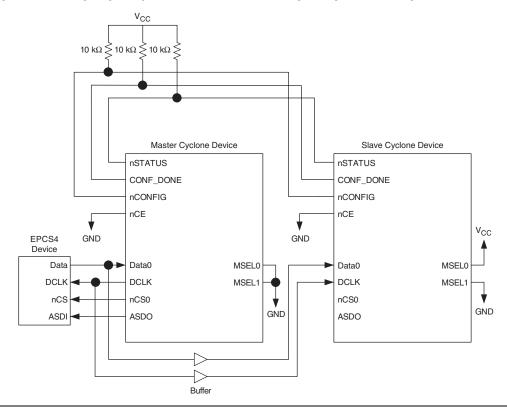


Figure 13-8. Configuring Multiple Devices with the Same Design Using a Serial Configuration Device

In this setup, all the Cyclone devices in the chain are connected for concurrent configuration. This reduces the active serial configuration time because all the Cyclone devices are configured in only one configuration cycle. To achieve this, the nCE input pins on all the Cyclone devices are connected to ground and the nCEO output pins on all the Cyclone devices are left unconnected. The DATA and DCLK pins connect in parallel to all the Cyclone devices.

It is recommended to add a buffer before the DATA and DCLK output from the master Cyclone to avoid signal strength and signal integrity issues. The buffer should not significantly change the DATA-to-DCLK relationships or delay them with respect to other ASMI signals, which are

ASDI and nCS signals. Also, the buffer should only drive the slave Cyclone devices, so that the timing between the master Cyclone device and serial configuration device is unaffected.

This setup can support both compressed and uncompressed SOFs. Therefore, if the configuration bit stream size exceeds the capacity of a serial configuration device, you can enable the compression feature on the SOF used or you can select a larger serial configuration device.

## Estimating Active Serial Configuration Time

Active serial configuration time is dominated by the time it takes to transfer data from the serial configuration device to the Cyclone FPGA. This serial interface is clocked by the Cyclone DCLK output (generated from an internal oscillator). As listed in Table 13–4, the DCLK minimum frequency is 14 MHz (71 ns). Therefore, the maximum configuration time estimate for an EP1C3 device (0.628 MBits of uncompressed data) is:

 $(0.628 \text{ MBits} \times 71 \text{ ns}) = 47 \text{ ms}.$ 

The typical configuration time is 33 ms.

Enabling compression reduces the amount of configuration data that is transmitted to the Cyclone device, reducing configuration time. On average, compression reduces configuration time by 50%.

## Programming Serial Configuration Devices

Serial configuration devices are non-volatile, flash-memory-based devices. You can program these devices in-system using the ByteBlaster™ II download cable. Alternatively, you can program them using the Altera Programming Unit (APU) or supported third-party programmers.

You can perform in-system programming of serial configuration devices via the AS programming interface. During in-system programming, the download cable disables FPGA access to the AS interface by driving the nCE pin high. Cyclone FPGAs are also held in reset by a low level on nCONFIG. After programming is complete, the download cable releases nCE and nCONFIG, allowing the pull-down and pull-up resistor to drive GND and VCC, respectively. Figure 13–9 shows the download cable connections to the serial configuration device.



For more information about the ByteBlaster II cable, refer to the *ByteBlaster II Download Cable User Guide*.

The serial configuration devices can be programmed in-system by an external microprocessor using SRunner. SRunner is a software driver developed for embedded serial configuration device programming that can be customized to fit in different embedded systems. The SRunner can read a Raw Programming Data file (.rpd) and write to the serial configuration devices. The programming time is comparable to the Quartus II software programming time.



For more information about SRunner, refer to the *AN 418: SRunner: An Embedded Solution for Serial Configuration Device Programming* and the source code on the Altera website (www.altera.com).

 $V_{CC}$  (1)  $V_{CC}$  (1)  $V_{CC}$  (1)  $10 \text{ k}\Omega \stackrel{>}{\leq} 10 \text{ k}\Omega \stackrel{>}{\leq}$ **≥**10 kΩ Cyclone FPGA CONF\_DONE nSTATUS nCEO N.C. (2) Serial nCONFIG Configuration Device nCE **≶**10 kΩ DATA DATA0 DCLK DCLK nCS nCSO MSEL1 MSEL0 **ASDO ASDI** GND V<sub>CC</sub>(3) Pin 1 

ByteBlaser II 10-Pin Male Header

Figure 13-9. In-System Programming of Serial Configuration Devices

#### Notes to Figure 13-9:

- (1) Connect these pull-up resistors to 3.3-V supply.
- (2) The nCEO pin is left unconnected.
- (3) Power up the ByteBlaster II cable's V<sub>CC</sub> with a 3.3-V supply.

You can program serial configuration devices by using the Quartus II software with the APU and the appropriate configuration device programming adapter. All serial configuration devices are offered in an eight-pin small outline integrated circuit (SOIC) package and can be programmed using the PLMSEPC-8 adapter.

In production environments, serial configuration devices can be programmed using multiple methods. Altera programming hardware (APU) or other third-party programming hardware can be used to program blank serial configuration devices before they are mounted onto PCBs. Alternatively, you can use an on-board microprocessor to program the serial configuration device in-system using C-based software drivers provided by Altera.



For more information on programming serial configuration devices, refer to the Cyclone Literature web page at www.altera.com and the Serial Configuration Devices (EPCS1, EPCS4, EPCS16, EPCS64, and EPCS128) Data Sheet.



Device configuration options and how to create configuration files are discussed further in the *Software Settings* section in volume 2 of the *Configuration Handbook*.

## **Passive Serial Configuration**

Cyclone FPGAs also feature the PS configuration scheme supported by all Altera FPGAs. In the PS scheme, an external host (configuration device, embedded processor, or host PC) controls configuration. Configuration data is clocked into the target Cyclone FPGAs via the DATA0 pin at each rising edge of DCLK. The configuration waveforms for this scheme are shown in Figure 13–10.

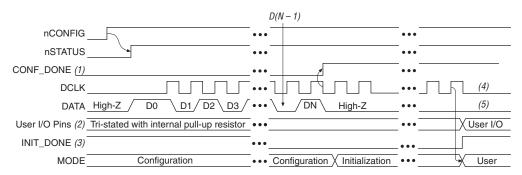


Figure 13–10. PS Configuration Cycle Waveform

#### Notes to Figure 13-10:

- (1) During initial power up and configuration, CONF\_DONE is low. After configuration, CONF\_DONE goes high to indicate successful configuration. If the device is reconfigured, CONF\_DONE goes low after nCONFIG is driven low.
- (2) User I/O pins are tri-stated during configuration. Cyclone FPGAs also have a weak pull-up resistor on I/O pins during configuration. After initialization, the user I/O pins perform the function assigned in the user's design.
- (3) When used, the optional INIT\_DONE signal is high when nCONFIG is low before configuration and during the first 136 clock cycles of configuration.
- (4) In user mode, DCLK should be driven high or low when using the PS configuration scheme. When using the AS configuration scheme, DCLK is a Cyclone output pin and should not be driven externally.
- (5) In user mode, DATAO should be driven high or low.

## PS Configuration Using Configuration Device

In the PS configuration device scheme, nconfig is usually tied to  $V_{CC}$  (when using EPC16, EPC8, EPC4, or EPC2 devices, you can connect nconfig to ninit\_conf). Upon device power-up, the target Cyclone FPGA senses the low-to-high transition on nconfig and initiates configuration. The target device then drives the open-drain conf\_down bin low, which in-turn drives the configuration device's ncs pin low. When exiting POR, both the target and configuration device release the open-drain nstatus pin (typically Cyclone POR lasts 100 ms).

Before configuration begins, the configuration device goes through a POR delay of up to 100 ms (maximum) to allow the power supply to stabilize. You must power the Cyclone FPGA before or during the POR time of the enhanced configuration device. During POR, the configuration device drives its OE pin low. This low signal delays configuration because the OE pin is connected to the target device's nSTATUS pin. When the target and configuration devices complete POR, they both release the nSTATUS to OE line, which is then pulled high by a pull-up resistor.

When configuring multiple devices, configuration does not begin until all devices release their OE or nSTATUS pins. When all devices are ready, the configuration device clocks out DATA and DCLK to the target devices using an internal oscillator.

After successful configuration, the Cyclone FPGA starts initialization using the 10-MHz internal oscillator as the reference clock. After initialization, this internal oscillator is turned off. The CONF\_DONE pin is released by the target device and then pulled high by a pull-up resistor. When initialization is complete, the target Cyclone FPGA enters user mode. The CONF\_DONE pin must have an external 10-k $\Omega$ pull-up resistor in order for the device to initialize.

If an error occurs during configuration, the target device drives its nSTATUS pin low, resetting itself internally and resetting the configuration device. If you turn on the **Auto-Restart Configuration on Frame Error** option, the device reconfigures automatically if an error occurs. To set this option, select **Compiler Settings** (Processing menu), and click on the **Chips & Devices** tab. Select **Device and Pin Options**, and click on the **Configuration** tab.

If the Auto-Restart Configuration on Frame Error option is turned off, the external system (configuration device or microprocessor) must monitor nSTATUS for errors and then pulse nCONFIG low to restart configuration. The external system can pulse nCONFIG if it is under system control rather than tied to  $V_{CC}.$  When configuration is complete, the target device releases CONF\_DONE, which disables the configuration device by driving nCS high. The configuration device drives DCLK low before and after configuration.

In addition, if the configuration device sends all of its data and then detects that <code>CONF\_DONE</code> has not gone high, it recognizes that the target device has not configured successfully. (For <code>CONF\_DONE</code> to reach a high state, enhanced configuration devices wait for 64 <code>DCLK</code> cycles after the last configuration bit. EPC2 devices wait for 16 <code>DCLK</code> cycles.) In this case, the configuration device pulses its <code>OE</code> pin low for a few microseconds, driving the target device's <code>nSTATUS</code> pin low. If the <code>Auto-Restart</code> <code>Configuration</code> on <code>Frame Error</code> option is set in the Quartus II software, the target device resets and then releases its <code>nSTATUS</code> pin after a reset timeout period. When <code>nSTATUS</code> returns high, the configuration device reconfigures the target device.

You should not pull CONF\_DONE low to delay initialization. Instead, use the Quartus II software's **User-Supplied Start-Up Clock** option to synchronize the initialization of multiple devices that are not in the same configuration chain. Devices in the same configuration chain initialize together since their CONF\_DONE pins are tied together.

CONF\_DONE goes high during the first few clock cycles of initialization. Hence, when using the CLKUSR feature you would not see the CONF\_DONE signal high until you start clocking CLKUSR. However, the device does retain configuration data and waits for these initialization clocks to release CONF\_DONE and go into user mode. Figure 13–11 shows how to configure one Cyclone FPGA with one configuration device.

V<sub>CC</sub> (1) V<sub>CC</sub> (1) Vcc (1) Configuration ≤10 kΩ  $\leq$  10 k $\Omega$ Cyclone FPGA Device **DCLK** DATA DATA0 OE **nSTATUS** CONF DONE nCS nCONFIG nINIT\_CONF (2) Vcc (4) - N.C. (3) nCEO MSEL0 MSEL1 nCE GND GND

Figure 13-11. Single Device Configuration Circuit

#### *Notes to Figure 13–11:*

- (1) The pull-up resistor should be connected to the same supply voltage as the configuration device. This pull-up resistor is 10 kΩ The EPC16, EPC8, EPC4, and EPC2 devices' OE and nCS pins have internal, user-configurable pull-up resistors. If you use internal pull-up resistors, do not use external pull-up resistors on these pins.
- (2) The ninit\_conf pin is available on EPC16, EPC8, EPC4, and EPC2 devices and has an internal pull-up resistor that is always active. If ninit\_conf is not used, nconfig can be pulled to V<sub>CC</sub> directly or through a resistor.
- (3) The nCEO pin is left unconnected for the last device in the chain.
- (4) Connect MSEL0 to the  $V_{CC}$  supply voltage of the I/O bank it resides in.

### Configuring Multiple Cyclone FPGAs

You can use a single configuration device to configure multiple Cyclone FPGAs. In this setup, the nCEO pin of the first device is connected to the nCE pin of the second device in the chain. If there are additional devices, connect the nCE pin of the next device to the nCEO pin of the previous device. You should leave the nCEO pin on the last device in the chain unconnected. To configure properly, all of the target device CONF\_DONE and nSTATUS pins must be tied together. Figure 13–12 shows an example of configuring multiple Cyclone FPGAs using a single configuration device.

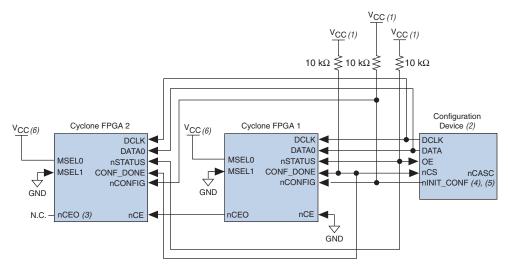


Figure 13–12. Configuring Multiple Cyclone FPGAs with a Single Configuration Device

#### *Notes to Figure 13–12:*

- (1) The pull-up resistor should be connected to the same supply voltage as the configuration device. The EPC16, EPC8, EPC4, and EPC2 devices' OE and nCS pins have internal, user-configurable pull-up resistors. If you use internal pull-up resistors, do not use external pull-up resistors on these pins.
- (2) EPC16, EPC8, and EPC4 configuration devices cannot be cascaded.
- (3) The nCEO pin is left unconnected for the last device in the chain.
- (4) The ninit\_conf pin is available on EPC16, EPC8, EPC4, and EPC2 devices. If ninit\_conf is not used, nconfig must be pulled to V<sub>CC</sub> directly or through a resistor.
- (5) The ninit\_conf pin has an internal pull-up resistor that is always active in EPC16, EPC8, EPC4, and EPC2 devices. These devices do not need an external pull-up resistor on the ninit conf pin.
- (6) Connect MSELO to the V<sub>CC</sub> supply voltage of the I/O bank it resides in.

When performing multi-device PS configuration, you must generate the configuration device programming file (.sof) from each project. Then you must combine multiple .sof files using the Quartus II software through the Convert Programming Files dialog box.

After the first Cyclone FPGA completes configuration during multidevice configuration, its nCEO pin activates the second device's nCE pin, prompting the second device to begin configuration. Because all device CONF\_DONE pins are tied together, all devices initialize and enter user mode at the same time.

In addition, all nSTATUS pins are tied together; therefore, if any device (including the configuration device) detects an error, configuration stops for the entire chain. Also, if the configuration device does not detect CONF\_DONE going high at the end of configuration, it resets the chain by

pulsing its OE pin low for a few microseconds. For CONF\_DONE to reach a high state, enhanced configuration devices wait for 64 DCLK cycles after the last configuration bit. EPC2 devices wait for 16 DCLK cycles.

If the **Auto-Restart Configuration on Frame Error** option is turned on in the Quartus II software, the Cyclone FPGA releases its nSTATUS pins after a reset time-out period (about 30 µs). When the nSTATUS pins are released and pulled high, the configuration device reconfigures the chain. If the **Auto-Restart Configuration on Frame Error** option is not turned on, the devices drive nSTATUS low until they are reset with a low pulse on nCONFIG.

You can also cascade several EPC2 or EPC1 configuration devices to configure multiple Cyclone FPGAs. When all data from the first configuration device is sent, it drives nCASC low, which in turn drives nCS on the subsequent EPC2 or EPC1 device. Because a configuration device requires less than one clock cycle to activate a subsequent configuration device, the data stream is uninterrupted. You cannot cascade EPC16, EPC8, and EPC4 configuration devices.

Figure 13–13 shows how to configure multiple devices using cascaded EPC2 or EPC1 devices.

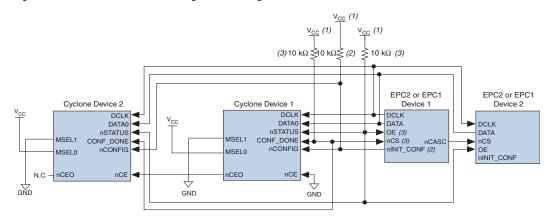


Figure 13–13. Multi-Device PS Configuration Using Cascaded EPC2 or EPC1 Devices

#### *Notes to Figure 13–13:*

- (1) The pull-up resistor should be connected to the same supply voltage as the configuration device.
- (2) The ninit\_conf pin (available on enhanced configuration devices and EPC2 devices only) has an internal pull-up resistor that is always active, meaning an external pull-up resistor should not be used on the ninit\_conf-nconf-nconfig line. The ninit\_conf pin does not need to be connected if its function is not used. If ninit\_conf is not used or not available (such as on EPC1 devices), nconfig must be pulled to V<sub>CC</sub> either directly or through a resistor.
- (3) The enhanced configuration devices' and EPC2 devices' OE and nCS pins have internal programmable pull-up resistors. External 10-kΩ pull-up resistors should be used. To turn off the internal pull-up resistors, check the Disable nCS and OE pull-ups on configuration device option when generating programming files.

## PS Configuration Using a Download Cable

Using a download cable in PS configuration, an intelligent host (for example, your PC) transfers data from a storage device (for example, your hard drive) to the Cyclone FPGA through a USB Blaster, ByteBlaster II, MasterBlaster, or ByteBlasterMV cable. To initiate configuration in this scheme, the download cable generates a low-to-high transition on the nCONFIG pin. The programming hardware then sends the configuration data one bit at a time on the device's DATAO pin. The data is clocked into the target device using DCLK until the CONF\_DONE goes high.

When using programming hardware for the Cyclone FPGA, turning on the **Auto-Restart Configuration on Frame Error** option does not affect the configuration cycle because the Quartus II software must restart configuration when an error occurs. Figure 13–14 shows the PS configuration setup for the Cyclone FPGA using a USB Blaster, ByteBlaster II, MasterBlaster, or ByteBlasterMV cable.

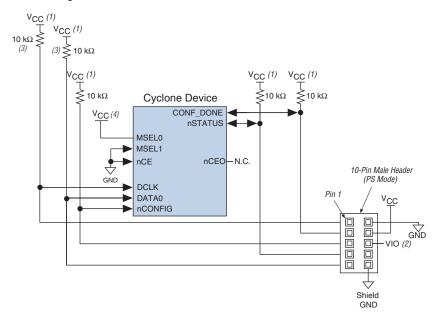


Figure 13–14. PS Configuration Circuit with a Download Cable

#### Notes to Figure 13–14:

- You should connect the pull-up resistor to the same supply voltage as the MasterBlaster (VIO pin) or ByteBlasterMV cable.
- (2) Pin 6 of the header is a V<sub>IO</sub> reference voltage for the MasterBlaster output driver. V<sub>IO</sub> should match the device's V<sub>CCIO</sub>. This pin is a no-connect pin for the ByteBlasterMV header.
- (3) The pull-up resistors on DATAO and DCLK are only needed if the download cable is the only configuration scheme used on your board. This is to ensure that DATAO and DCLK are not left floating after configuration. For example, if you are also using a configuration device, the pull-up resistors on DATAO and DCLK are not needed.
- (4) Connect MSEL0 to the  $V_{CC}$  supply voltage of the I/O bank it resides in.

You can use the download cable to configure multiple Cyclone FPGAs by connecting each device's nCEO pin to the subsequent device's nCE pin. All other configuration pins are connected to each device in the chain.

Because all CONF\_DONE pins are tied together, all devices in the chain initialize and enter user mode at the same time. In addition, because the nSTATUS pins are tied together, the entire chain halts configuration if any device detects an error. In this situation, the Quartus II software must restart configuration; the **Auto-Restart Configuration on Frame Error** option does not affect the configuration cycle. Figure 13–15 shows how to configure multiple Cyclone FPGAs with a ByteBlaster II, MasterBlaster, or ByteBlasterMV cable.

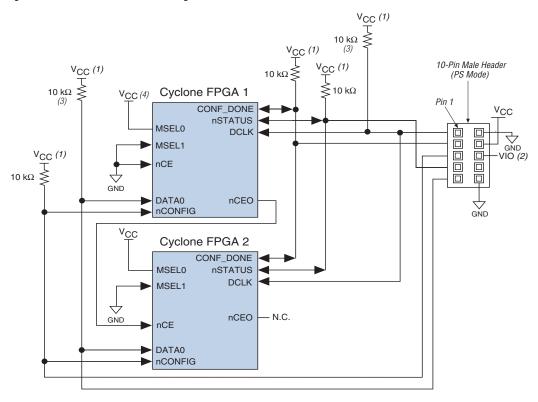


Figure 13–15. Multi-Device PS Configuration with a Download Cable

#### *Notes to Figure 13–15:*

- You should connect the pull-up resistor to the same supply voltage as the MasterBlaster (VIO pin) or ByteBlasterMV cable.
- (2) V<sub>IO</sub> is a reference voltage for the MasterBlaster output driver. V<sub>IO</sub> should match the device's V<sub>CCIO</sub>. Refer to the MasterBlaster Serial/USB Communications Cable User Guide for this value.
- (3) The pull-up resistors on DATAO and DCLK are only needed if the download cable is the only configuration scheme used on your board. This is to ensure that DATAO and DCLK are not left floating after configuration. For example, if you are also using a configuration device, the pull-up resistors on DATAO and DCLK are not needed.
- (4) Connect MSEL0 to the  $V_{CC}$  supply voltage of the I/O bank it resides in.

If you are using a ByteBlaster II, MasterBlaster, or ByteBlasterMV cable to configure device(s) on a board that also is populated with configuration devices, you should electrically isolate the configuration devices from the target device(s) and cable. One way to isolate the configuration devices is to add logic, such as a multiplexer, that can select between the configuration devices and the cable. The multiplexer allows bidirectional transfers on the <code>nstatus</code> and <code>conf\_done</code> signals. Another option is to add switches to the five common signals (<code>CONF\_DONE</code>, <code>nstatus</code>, <code>DCLK</code>,

nCONFIG, and DATAO) between the cable and the configuration devices. The last option is to remove the configuration devices from the board when configuring with the cable. Figure 13–16 shows a combination of a configuration device and a ByteBlaster II, MasterBlaster, or ByteBlasterMV cable to configure a Cyclone FPGA.

V<sub>CC</sub> (1) T 10 kΩ≶ Download Cable 10-Pin Male Header (PS Mode) Cyclone FPGA ∿⊻ ⊤ 10 kΩ≶ 10 kΩ ≶ CONF DONE (5)MSEL0 nSTATUS MSEL1 DCLK Ò **GND** VIO nCEO-N.C. nCE (2)GND (3) (3) (3)DATA0 **nCONFIG** GND Configuration Device (3) DCI K DATA OE (3) nCS nINIT CONF (4)

Figure 13–16. Configuring with a Combined PS and Configuration Device Scheme

#### Notes to Figure 13–16:

- (1) You should connect the pull-up resistor to the same supply voltage as the configuration device.
- (2) Pin 6 of the header is a V<sub>IO</sub> reference voltage for the MasterBlaster output driver. V<sub>IO</sub> should match the target device's V<sub>CCIO</sub>. This is a no-connect pin for the ByteBlasterMV header.
- (3) You should not attempt configuration with a ByteBlaster II, MasterBlaster, or ByteBlasterMV cable while a configuration device is connected to a Cyclone FPGA. Instead, you should either remove the configuration device from its socket when using the download cable or place a switch on the five common signals between the download cable and the configuration device. Remove the ByteBlaster II, MasterBlaster, or ByteBlasterMV cable when configuring with a configuration device.
- (4) If nINIT CONF is not used, nCONFIG must be pulled to  $V_{CC}$  either directly or through a resistor.
- (5) The pull-up resistors on DATAO and DCLK are only needed if the download cable is the only configuration scheme used on your board. This is to ensure that DATAO and DCLK are not left floating after configuration. For example, if you are also using a configuration device, the pull-up resistors on DATAO and DCLK are not needed.
- (6) Connect MSELO to the V<sub>CC</sub> supply voltage of the I/O bank it resides in.



For more information on how to use the ByteBlaster II, MasterBlaster, or ByteBlasterMV cables, see the following documents:

- ByteBlaster II Download Cable User Guide
- ByteBlasterMV Download Cable User Guide
- MasterBlaster Serial/USB Communications Cable User Guide

## PS Configuration from a Microprocessor

In PS configuration with a microprocessor, a microprocessor transfers data from a storage device to the target Cyclone FPGA. To initiate configuration in this scheme, the microprocessor must generate a low-to-high transition on the nCONFIG pin and the target device must release nSTATUS. The microprocessor then places the configuration data one bit at a time on the DATAO pin of the Cyclone FPGA. The least significant bit (LSB) of each data byte must be presented first. Data is clocked continuously into the target device using DCLK until the CONF\_DONE signal goes high.

The Cyclone FPGA starts initialization using the internal oscillator after all configuration data is transferred. After initialization, this internal oscillator is turned off. The device's CONF\_DONE pin goes high to show successful configuration and the start of initialization. During configuration and initialization and before the device enters user ode the microprocessor must not drive CONF\_DONE low. Driving DCLK to the device after configuration does not affect device operation.

Since the PS configuration scheme is a synchronous scheme, the configuration clock speed must be below the specified maximum frequency to ensure successful configuration. Maximum DCLK frequency supported by Cyclone FPGAs is 100 MHz (see Table 13–5 on page 13–30). No maximum DCLK period (i.e., minimum DCLK frequency) exists. You can pause configuration by halting DCLK for an indefinite amount of time.

If the target device detects an error during configuration, it drives its nSTATUS pin low to alert the microprocessor. The microprocessor can then pulse nCONFIG low to restart the configuration process. Alternatively, if the **Auto-Restart Configuration on Frame Error** option is turned on in the Quartus II software, the target device releases nSTATUS after a reset time-out period. After nSTATUS is released, the microprocessor can reconfigure the target device without needing to pulse nCONFIG low.

The microprocessor can also monitor the CONF\_DONE and INIT\_DONE pins to ensure successful configuration and initialization. If the microprocessor sends all data, but CONF\_DONE and INIT\_DONE has not gone high, it must reconfigure the target device. Figure 13–17 shows the circuit for PS configuration with a microprocessor.

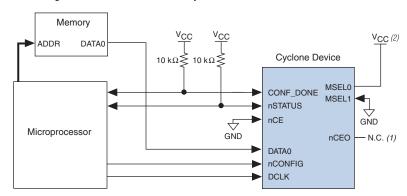


Figure 13–17. PS Configuration Circuit with a Microprocessor

Notes to Figure 13–17:

- (1) The nCEO pin is left unconnected.
- (2) Connect MSELO to the  $V_{CC}$  supply voltage of the I/O bank it resides in.

## Configuring Cyclone FPGAs with the MicroBlaster Software

The MicroBlaster™ software driver allows you to configure Altera FPGAs, including Cyclone FPGAs, through the ByteBlaster II or ByteBlasterMV cable in PS mode. The MicroBlaster software driver supports a Raw Binary File (.rbf) programming input file and is targeted for embedded PS configuration. The source code is developed for the Windows NT operating system, although you can customize it to run on other operating systems.



For more information about the MicroBlaster software driver, refer to the *AN 423: Configuring the MicroBlaster Passive Serial Software Driver* and source files on the Altera website at www.altera.com.

## Passive Serial Timing

For successful configuration using the PS scheme, several timing parameters such as setup, hold, and maximum clock frequency must be satisfied. The enhanced configuration and EPC2 devices are designed to meet these interface timing specifications. If you use a microprocessor or another intelligent host to control the PS interface, ensure that you meet these timing requirements.

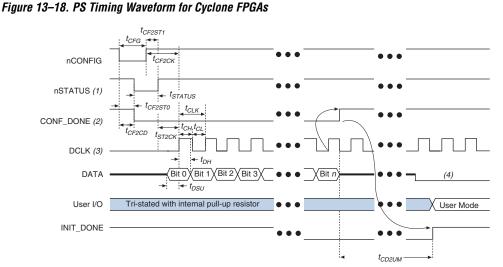


Figure 13–18 shows the PS timing waveform for Cyclone FPGAs.

# Notes to Figure 13–18:

- Upon power-up, the Cyclone FPGA holds nSTATUS low for about 100 ms.
- Upon power-up and before configuration, CONF DONE is low.
- In user mode, DCLK should be driven high or low when using the PS configuration scheme. When using the AS configuration scheme, DCLK is a Cyclone output pin and should not be driven externally.
- DATA should not be left floating after configuration. It should be driven high or low, whichever is more convenient. (4)

**Table 13–5. PS Timing Parameters for Cyclone Devices** Note (1) (Part 1 of 2) Symbol Parameter Min Max Units nCONFIG low to CONF DONE low 800 ns t<sub>CF2CD</sub> nCONFIG low to nSTATUS low 800 ns t<sub>CF2ST0</sub> t<sub>CF2ST1</sub> nCONFIG high to nSTATUS high 40 (4) μs nCONFIG low pulse width (2) 40 μs t<sub>CFG</sub> 10 t<sub>STATUS</sub> nSTATUS low pulse width 40 (4) μs 40 t<sub>CF2CK</sub> nCONFIG high to first rising edge on DCLK μs nSTATUS high to first rising edge on DCLK 1  $t_{ST2CK}$ μs 7 Data setup time before rising edge on DCLK ns  $t_{DSU}$ 0 Data hold time after rising edge on DCLK  $t_{DH}$ ns DCLK high time 7

Table 13–5 contains the PS timing information for Cyclone FPGAs.

 $t_{CH}$ 

ns

Table 13–5. PS Timing Parameters for Cyclone Devices Note (1) (Part 2 of 2)					
Symbol	Parameter	Min	Max	Units	
$t_{CL}$	DCLK low time	7		ns	
t <sub>CLK</sub>	DCLK period	15		ns	
f <sub>MAX</sub>	DCLK maximum frequency		66	MHz	
t <sub>CD2UM</sub>	CONF_DONE high to user mode (3)	6	20	μs	

#### Notes to Table 13-5:

- (1) This information is preliminary.
- (2) This value applies only if the internal oscillator is selected as the clock source for device initialization. If the clock source is CLKUSR, multiply the clock period by 270 to obtain this value. CLKUSR must be running during this period to reset the device.
- (3) The minimum and maximum numbers apply only if the internal oscillator is chosen as the clock source for device initialization. If the clock source is CLKUSR, multiply the clock period by 140 to obtain this value.
- (4) You can obtain this value if you do not delay configuration by extending the nSTATUS low-pulse width.



Device configuration options and how to create configuration files are discussed further in the *Software Settings* section in volume 2 of the *Configuration Handbook*.

# **JTAG-Based Configuration**

JTAG has developed a specification for boundary-scan testing. This boundary-scan test (BST) architecture offers the capability to efficiently test components on printed circuit boards (PCBs) with tight lead spacing. The BST architecture can test pin connections without using physical test probes and capture functional data while a device is operating normally. You can also use the JTAG circuitry to shift configuration data into Cyclone FPGAs. The Quartus II software automatically generates <code>.sof</code> files that can be used for JTAG configuration.



For more information about JTAG boundary-scan testing, refer to AN 39: IEEE 1149.1 (JTAG) Boundary-Scan Testing in Altera Devices.

To use the SignalTap II Embedded Logic Analyzer, you need to connect the JTAG pins of your Cyclone device to a download cableheader on your PCB.



For more information about SignalTap II, refer to the *Design Debugging Using the SignalTap II Embedded Logic Analyzer* chapter in volume 3 of the *Quartus II Handbook*.

Cyclone devices are designed such that JTAG instructions have precedence over any device operating modes. So JTAG configuration can take place without waiting for other configuration to complete (e.g.,

configuration with serial or enhanced configuration devices). If you attempt JTAG configuration in Cyclone FPGAs during non-JTAG configuration, non-JTAG configuration is terminated and JTAG configuration is initiated.



The Cyclone configuration data decompression feature is not supported in JTAG-based configuration.

A device operating in JTAG mode uses four required pins: TDI, TDO, TMS, and TCK. Cyclone FPGAs do not support the optional TRST pin. The three JTAG input pins, TCK, TDI, and TMS, have weak internal pull-up resistors, whose values are approximately 20 to 40 k $\Omega$  All user I/O pins are tri-stated during JTAG configuration.

Table 13-6 shows each JTAG pin's function.

Table 13–6. JTAG Pin Descriptions				
Pin	Description	Function		
TDI	Test data input	Serial input pin for instructions as well as test and programming data. Data is shifted in on the rising edge of ${\tt TCK}.$ If the JTAG interface is not required on the board, the JTAG circuitry can be disabled by connecting this pin to ${\tt V}_{\tt CC}.$		
TDO	Test data output	Serial data output pin for instructions as well as test and programming data. Data is shifted out on the falling edge of TCK. The pin is tri-stated if data is not being shifted out of the device. If the JTAG interface is not required on the board, the JTAG circuitry can be disabled by leaving this pin unconnected.		
TMS	Test mode select	Input pin that provides the control signal to determine the transitions of the Test Access Port (TAP) controller state machine. Transitions within the state machine occur on the rising edge of ${\tt TCK}$ . Therefore, ${\tt TMS}$ must be set up before the rising edge of ${\tt TCK}$ . TMS is evaluated on the rising edge of ${\tt TCK}$ . If the JTAG interface is not required on the board, the JTAG circuitry can be disabled by connecting this pin to $V_{\tt CC}$ .		
TCK	Test clock input	The clock input to the BST circuitry. Some operations occur at the rising edge, while others occur at the falling edge. If the JTAG interface is not required on the board, the JTAG circuitry can be disabled, by connecting this pin to GND.		

## JTAG Configuration Using a Download Cable

During JTAG configuration, data is downloaded to the device on the board through a USB Blaster, ByteBlaster II, ByteBlasterMV, or MasterBlaster download cable. Configuring devices through a cable is similar to programming devices in-system. See Figure 13–19 for pin connection information.

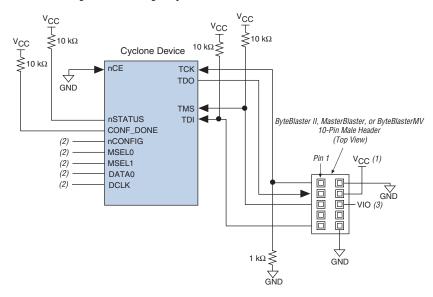


Figure 13-19. JTAG Configuration of Single Cyclone FPGA

*Notes to Figure 13–19:* 

- (1) You should connect the pull-up resistor to the same supply voltage as the download cable.
- (2) You should connect the nCONFIG, MSEL0, and MSEL1 pins to support a non-JTAG configuration scheme. If you only use JTAG configuration, connect nCONFIG and MSEL0 to V<sub>CC</sub>, and MSEL1 to ground. Pull DATAO and DCLK to high or low.
- (3) V<sub>IO</sub> is a reference voltage for the MasterBlaster output driver. V<sub>IO</sub> should match the device's V<sub>CCIO</sub>. Refer to the MasterBlaster Serial/USB Communications Cable User Guide for this value. In the ByteBlaster MV, this pin is a no connect. In the USB Blaster and ByteBlaster II, this pin is connected to nCE when it is used for Active Serial programming; otherwise it is a no connect.
- (4) nce must be connected to GND or driven low for successful configuration.

To configure a single device in a JTAG chain, the programming software places all other devices in bypass mode. In bypass mode, devices pass programming data from the TDI pin to the TDO pin through a single bypass register without being affected internally. This scheme enables the programming software to program or verify the target device. Configuration data driven into the device appears on the TDO pin one clock cycle later.

The Quartus II software verifies successful JTAG configuration upon completion. The software checks the state of CONF\_DONE through the JTAG port. If CONF\_DONE is not high, the Quartus II software indicates that configuration has failed. If CONF\_DONE is high, the software indicates that configuration was successful. After the configuration bit stream is transmitted serially via the JTAG TDI port, the TCK port is clocked an additional 134 cycles to perform device initialization.



If  $V_{CCIO}$  is tied to 3.3-V, both the I/O pins and the JTAG TDO port drive at 3.3-V levels.

Cyclone FPGAs have dedicated JTAG pins. Not only can you perform JTAG testing on Cyclone FPGAs before and after, but also during configuration. While other device families do not support JTAG testing during configuration, Cyclone FPGAs support the BYPASS, IDCODE, and SAMPLE instructions during configuration without interrupting configuration. All other JTAG instructions may only be issued by first interrupting configuration and reprogramming I/O pins using the CONFIG IO instruction.

The CONFIG\_IO instruction allows I/O buffers to be configured via the JTAG port, and when issued, interrupts configuration. This instruction allows you to perform board-level testing prior to configuring the Cyclone FPGA or waiting for a configuration device to complete configuration. Once configuration has been interrupted and JTAG testing is complete, the part must be reconfigured via JTAG (PULSE\_CONFIG instruction) or by pulsing nCONFIG low.

The chip-wide reset and output enable pins on Cyclone FPGAs do not affect JTAG boundary-scan or programming operations. Toggling these pins does not affect JTAG operations (other than the usual boundary-scan operation).

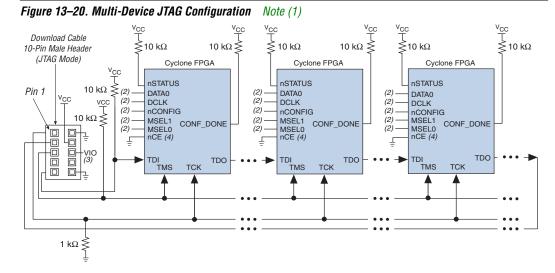
When designing a board for JTAG configuration of Cyclone FPGAs, you should consider the dedicated configuration pins. Table 13–7 shows how you should connect these pins during JTAG configuration.

Table 13–7. Dedicated Configuration Pin Connections During JTAG Configuration				
Signal	Description			
nCE	Drive all Cyclone devices in the chain low by connecting $nCE$ to ground, pulling it down via a resistor, or driving it low by some control circuitry. For devices in a multi-device PS and AS configuration chains, connect the $nCE$ pins to ground during JTAG configuration or configure them via JTAG in the same order as the configuration chain.			
nCEO	For all Cyclone devices in a chain, the nCEO pin can be left floating or connected to the nCE pin of the next device. See nCE description above.			
nSTATUS	Pulled to $V_{CC}$ through a 10-k $\Omega$ resistor. When configuring multiple devices in the same JTAG chain, pull up each <code>nSTATUS</code> pin to $V_{CC}$ individually.			
CONF_DONE	Pulled to $V_{CC}$ through a 10-k $\Omega$ resistor. When configuring multiple devices in the same JTAG chain, pull up each CONF_DONE pin to $V_{CC}$ individually. The CONF_DONE pin must have an external 10-k $\Omega$ pull-up resistor in order for the device to initialize.			
nCONFIG	Driven high by connecting to V <sub>CC</sub> , pulling up through a resistor, or driving it high by some control circuitry.			
MSELO, MSEL1	Do not leave these pins floating. These pins support whichever non-JTAG configuration is used in production. If only JTAG configuration is used, you should tie these pins to ground.			
DCLK	Do not leave these pins floating. Drive low or high, whichever is more convenient.			
DATA0	Do not leave these pins floating. Drive low or high, whichever is more convenient.			

## JTAG Configuration of Multiple Devices

When programming a JTAG device chain, one JTAG-compatible header, such as the ByteBlaster II header, is connected to several devices. The number of devices in the JTAG chain is limited only by the drive capacity of the download cable. However, when four or more devices are connected in a JTAG chain, Altera recommends buffering the TCK, TDI, and TMS pins with an on-board buffer.

JTAG-chain device configuration is ideal when the system contains multiple devices, or when testing your system using JTAG BST circuitry. Figure 13–20 shows multi-device JTAG configuration.



#### Notes to Figure 13–20:

- (1) Cyclone, Stratix, Stratix GX, APEX™ II, APEX 20K, Mercury™, ACEX® 1K, and FLEX® 10K devices can be placed within the same JTAG chain for device programming and configuration.
- (2) Connect the nCONFIG, MSEL0, and MSEL1 pins to support a non-JTAG configuration scheme. If only JTAG configuration is used, connect nCONFIG to V<sub>CC</sub>, and MSEL0 and MSEL1 to ground. Pull DATAO and DCLK to either high or low.
- (3) V<sub>IO</sub> is a reference voltage for the MasterBlaster output driver. V<sub>IO</sub> should match the device's V<sub>CCIO</sub>. Refer to the MasterBlaster Serial/USB Communications Cable User Guide for this value. In the ByteBlaster MV, this pin is a no connect. In the USB Blaster and ByteBlaster, this pin is connected to nCE when it is used for Active Serial programming; otherwise it is a no connect.
- (4) nCE must be connected to GND or driven low for successful configuration.

Connect the nCE pin to ground or drive it low during JTAG configuration. In multi-device PS and AS configuration chains, connect the first device's nCE pin to ground and connect the nCEO pin to the nCE pin of the next device in the chain. The last device's nCE input comes from the previous device, while its nCEO pin is left floating. After the first device completes configuration in a multi-device configuration chain, it's nCEO pin drives low to activate the second device's nCE pin, which prompts the second device to begin configuration. Therefore, if these devices are also in a JTAG chain, you should make sure the nCE pins are connected to ground during JTAG configuration or that the devices are configured via JTAG in the same order as the configuration chain. As long as the devices are configured in the same order as the multi-device configuration chain, the nCEO pin of the previous device drives the nCE pin of the next device low when it has successfully been configured.

Figure 13–21 shows the JTAG configuration of a Cyclone FPGA with a microprocessor.

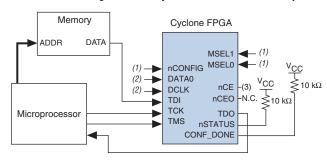


Figure 13–21. JTAG Configuration of Cyclone FPGAs with a Microprocessor

## Notes to Figure 13-21:

- (1) Connect the nCONFIG, MSEL1, and MSEL0 pins to support a non-JTAG configuration scheme. If your design only uses JTAG configuration, connect the nCONFIG pin to V<sub>CC</sub> and the MSEL1 and MSEL0 pins to ground.
- (2) Pull DATAO and DCLK to either high or low.
- (3) nce must be connected to GND or driver low for successful JTAG configuration.



For more information about JTAG programming in an embedded environment, refer to AN 122: Using JamSTAPL for ISP &ICR via an Embedded Processor.

# Configuring Cyclone FPGAs with JRunner

JRunner is a software driver that allows you to configure Altera FPGAs, including Cyclone FPGAs, through the ByteBlaster II or ByteBlasterMV cables in JTAG mode. The programming input file supported is in .rbf format. JRunner also requires a Chain Description File (.cdf) generated by the Quartus II software. JRunner is targeted for embedded JTAG configuration. The source code has been developed for the Windows NT operating system (OS). You can customize the code to make it run on other platforms. For more information on the JRunner software driver, see JRunner Software Driver: An Embedded Solution to the JTAG Configuration and the source files on the Altera website.

#### Jam STAPI

Jam STAPL, JEDEC standard JESD-71, is a standard file format for insystem programmability (ISP) purposes. Jam STAPL supports programming or configuration of programmable devices and testing of electronic systems, using the IEEE 1149.1 JTAG interface. Jam STAPL is a freely licensed open standard.



Both JTAG connection methods should include space for the MasterBlaster or ByteBlasterMV header connection. The header is useful during prototyping because it allows you to verify or modify the Cyclone FPGA's contents. During production, you can remove the header to save cost.

## **Program Flow**

The Jam Player provides an interface for manipulating the IEEE Std. 1149.1 JTAG TAP state machine. The TAP controller is a 16-state, state machine that is clocked on the rising edge of TCK, and uses the TMS pin to control JTAG operation in a device. Figure 13–22 shows the flow of an IEEE Std. 1149.1 TAP controller state machine.

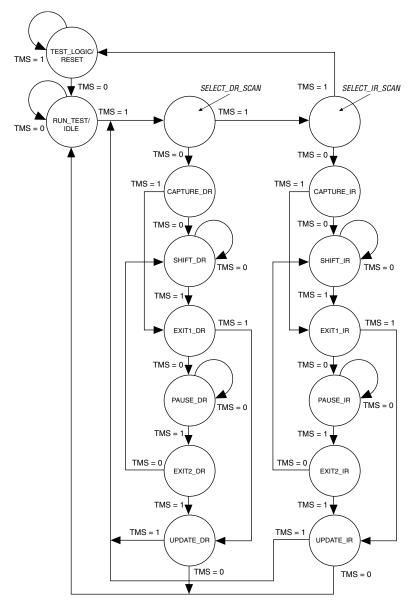


Figure 13-22. JTAG TAP Controller State Machine

While the Jam Player provides a driver that manipulates the TAP controller, the Jam Byte-Code File (.jbc) provides the high-level intelligence needed to program a given device. All Jam instructions that

send JTAG data to the device involve moving the TAP controller through either the data register leg or the instruction register leg of the state machine. For example, loading a JTAG instruction involves moving the TAP controller to the SHIFT\_IR state and shifting the instruction into the instruction register through the TDI pin. Next, the TAP controller is moved to the RUN\_TEST/IDLE state where a delay is implemented to allow the instruction time to be latched. This process is identical for data register scans, except that the data register leg of the state machine is traversed.

The high-level Jam instructions are the DRSCAN instruction for scanning the JTAG data register, the IRSCAN instruction for scanning the instruction register, and the WAIT command that causes the state machine to sit idle for a specified period of time. Each leg of the TAP controller is scanned repeatedly, according to instructions in the .jbc file, until all of the target devices are programmed.

Figure 13–23 shows the functional behavior of the Jam Player when it parses the .jbc file. When the Jam Player encounters a DRSCAN, IRSCAN, or WAIT instruction, it generates the proper data on TCK, TMS, and TDI to complete the instruction. The flow diagram shows branches for the DRSCAN, IRSCAN, and WAIT instructions. Although the Jam Player supports other instructions, they are omitted from the flow diagram for simplicity.

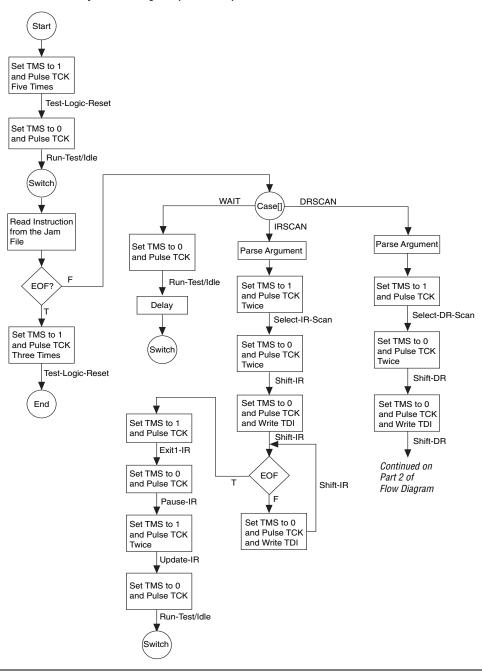


Figure 13-23. Jam Player Flow Diagram (Part 1 of 2)

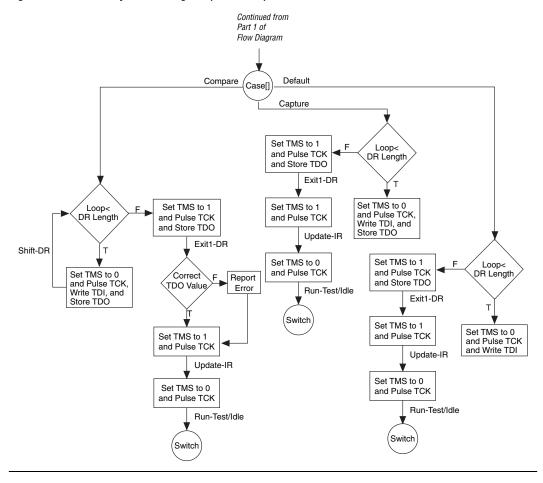


Figure 13–24. Jam Player Flow Diagram (Part 2 of 2)

Execution of a Jam program starts at the beginning of the program. The program flow is controlled using GOTO, CALL/RETURN, and FOR/NEXT structures. The GOTO and CALL statements refer to labels that are symbolic names for program statements located elsewhere in the Jam program. The language itself enforces almost no constraints on the organizational structure or control flow of a program.



The Jam language does not support linking multiple Jam programs together or including the contents of another file into a Jam program.

#### **Jam Instructions**

Each Jam statement begins with one of the instruction names listed in Table 13–8. The instruction names, including the names of the optional instructions, are reserved keywords that you cannot use as variable or label identifiers in a Jam program.

Table 13–8. Instruction Names						
BOOLEAN	INTEGER	PREIR				
CALL	IRSCAN	PRINT				
CRC	IRSTOP	PUSH				
DRSCAN	LET	RETURN				
DRSTOP	NEXT	STATE				
EXIT	NOTE	WAIT				
EXPORT	POP	VECTOR (1)				
FOR	POSTDR	VMAP (1)				
GOTO	POSTIR	_				
IF	PREDR	_				

#### Note to Table 13-8:

Table 13–9 shows the state names that are reserved keywords in the Jam language. These keywords correspond to the state names specified in the IEEE Std. 1149.1 JTAG specification.

Table 13–9. Reserved Keywords (Part 1 of 2)						
IEEE Std. 1149.1 JTAG State Names	Jam Reserved State Names					
Test-Logic-Reset	RESET					
Run-Test-Idle	IDLE					
Select-DR-Scan	DRSELECT					
Capture-DR	DRCAPTURE					
Shift-DR	DRSHIFT					
Exit1-DR	DREXIT1					
Pause-DR	DRPAUSE					
Exit2-DR	DREXIT2					
Update-DR	DRUPDATE					
Select-IR-Scan	IRSELECT					
Capture-IR	IRCAPTURE					

<sup>(1)</sup> This instruction name is an optional language extension.

Table 13–9. Reserved Keywords (Part 2 of 2)						
IEEE Std. 1149.1 JTAG State Names	Jam Reserved State Names					
Shift-IR	IRSHIFT					
Exit1-IR	IREXIT1					
Pause-IR	IRPAUSE					
Exit2-IR	IREXIT2					
Update-IR	IRUPDATE					

#### Example Jam File that Reads the IDCODE

The following illustrates the flexibility and utility of the Jam STAPL. The example code reads the IDCODE out of a single device in a JTAG chain.



The array variable,  $I\_IDCODE$ , is initialized with the IDCODE instruction bits ordered the LSB first (on the left) to most significant bit (MSB) (on the right). This order is important because the array field in the IRSCAN instruction is always interpreted and sent, MSB to LSB.

#### **Example Jam File Reading IDCODE**

```
BOOLEAN read data[32];
BOOLEAN I IDCODE[10] = BIN 1001101000; 'assumed
BOOLEAN ONES DATA[32] = HEX FFFFFFF;
INTEGER i;
'Set up stop state for IRSCAN
IRSTOP IRPAUSE;
'Initialize device
STATE RESET;
IRSCAN 10, I IDCODE[0..9]; 'LOAD IDCODE INSTRUCTION
STATE IDLE;
WAIT 5 USEC, 3 CYCLES;
DRSCAN 32, ONES DATA[0..31], CAPTURE read data[0..31];
'CAPTURE IDCODE
PRINT "IDCODE:";
FOR i=0 to 31;
PRINT read data[i];
NEXT i;
EXIT 0;
```

# Combining Configuration Schemes

This section shows you how to configure Cyclone FPGAs using multiple configuration schemes on the same board.

#### **Active Serial and JTAG**

You can combine the AS configuration scheme with JTAG-based configuration. Set the  ${\tt MSEL[1..0]}$  pins to 00 in this setup, as shown in Figure 13–25. This setup uses two 10-pin download cable headers on the board. The first header programs the serial configuration device in-system via the AS programming interface, and the second header configures the Cyclone FPGA directly via the JTAG interface.

If you try configuring the device using both schemes simultaneously, JTAG configuration takes precedence and AS configuration is terminated.

V<sub>CC</sub> (1) V<sub>CC</sub> (1)  $\lesssim$ 10 k $\Omega \lesssim$ 10 k $\Omega$ Serial Configuration Cyclone FPGA Device **nSTATUS** CONF\_DONE nCEO nCONFIG 10 k $\Omega$ nCE 10 kΩ \left\{ MSEL1 MSEL0 10  $k\Omega$ GŇD GŇD DATA DATA **TCK DCLK DCLK** TDO nCS nCSO TMS Download Cable **ASDI ASDO** TDI (JTAG Mode) 10-Pin Male Header (top View) Pin 1 V<sub>CC</sub> (1) 回  $V_{IO}$ **₹** 1 kΩ Download Cable (AS Mode)

10-Pin Male Header

Figure 13-25. Combining AS and JTAG Configuration

Note to Figure 13–25:

Connect these pull-up resistors to 3.3 V.

# Device Configuration Pins

Tables 13-10 through 13-12 describe the connections and functionality of all the configuration related pins on the Cyclone device. Table 13-10 describes the dedicated configuration pins. These pins are required to be connected properly on your board for successful configuration. Some of these pins may not be required for your configuration schemes.

Table 13–10.	Table 13–10. Dedicated Cyclone Device Configuration Pins (Part 1 of 3)						
Pin Name	User Mode	Configuration Scheme	Pin Type	Description			
MSEL1 MSEL0	_	All	Input	Two-bit configuration input that set the Cyclone device configuration scheme (see Table 13–2). Use these pins to select the Cyclone configuration schemes for the appropriate connections. These pins must remain at a valid state during power-up before nconfiguration and during configuration. This pin uses Schmitt trigger input buffers.			
nCONFIG	-	All	Input	Configuration control input. Pulling this pin low during user-mode causes the FPGA to lose its configuration data, enter a reset state, and tri-state all I/O pins. Returning this pin to a logic high initiates a reconfiguration. If the configuration scheme uses an enhanced configuration device or EPC2 device, the nconfig pin can be tied directly to V <sub>CC</sub> or to the configuration device's ninit_conf pin. This pin uses Schmitt trigger input buffers			

Table 13–10. Dedicated Cyclone Device Configuration Pins (Part 2 of 3)							
Pin Name	User Mode	Configuration Scheme	Pin Type	Description			
nSTATUS	_	All	Bidirectional open-drain	The device drives nSTATUS low immediately after power-up and releases it within 5 µs. (When using a configuration device, the configuration device holds nSTATUS low for up to 200 ms.)			
				Status output. If an error occurs during configuration, nSTATUS is pulled low by the target device.			
				Status input. If an external source drives the nSTATUS pin low during configuration or initialization, the target device enters an error state. Driving nSTATUS low after configuration and initialization does not affect the configured device.			
				If the design uses a configuration device, driving nSTATUS low causes the configuration device to attempt to configure the FPGA, but since the FPGA ignores transitions on nSTATUS in user-mode, the FPGA does not reconfigure. To initiate a reconfiguration, nCONFIG must be pulled low. The OE and nCS pins in the enhanced configuration devices and EPC2 devices have optional internal programmable pull-up resistors. If the design uses internal pull-up resistors, do not use external $10\text{-}k\Omega$ pull-up resistors on these pins. This pin uses Schmitt trigger input buffers			
CONF_DONE	_	All	Bidirectional open-drain	Status output. The target device drives the CONF_DONE pin low before and during configuration. Once all configuration data is received without error and the initialization clock cycle starts, the target device releases CONF_DONE.			
				Status input. After all data is received and CONF_DONE goes high, the target device initializes and enters user mode.			
				Driving CONF_DONE low after configuration and initialization does not affect the configured device. The OE and nCS pins in the enhanced configuration devices and EPC2 devices have optional internal programmable pull-up resistors. If the design uses internal pull-up resistors, do not use external 10-k $\Omega$ pull-up resistors on these pins. This pin uses Schmitt trigger input buffers			

Table 13–10. Dedicated Cyclone Device Configuration Pins (Part 3 of 3)							
Pin Name	User Mode	Configuration Scheme	Pin Type	Description			
DCLK	_	PS AS	Input (PS) Output (AS)	In PS configuration, the clock input clocks data from an external source into the target device. Data is latched into the FPGA on the rising edge of DCLK. In AS configuration, DCLK is an output from the Cyclone FPGA that provides timing for the configuration interface. After configuration, the logic levels on this pin do not affect the Cyclone FPGA. This pin uses Schmitt trigger input buffers			
ASDO	I/O in PS mode, N/A in AS mode	AS	Output	Control signal from the Cyclone FPGA to the serial configuration device in AS mode used to read out configuration data.			
nCSO	I/O in PS mode, N/A in AS mode	AS	Output	Output control signal from the Cyclone FPGA to the serial configuration device in AS mode that enables the configuration device.			
nCE	_	All	Input	Active-low chip enable. The nCE pin activates the device with a low signal to allow configuration. The nCE pin must be held low during configuration, initialization, and user mode. In single device configuration, tie the nCE pin low. In multi-device configuration, the first device's nCE pin is tied low while its nCEO pin is connected to nCE of the next device in the chain. Hold the nCE pin low for programming the FPGA via JTAG. This pin uses Schmitt trigger input buffers			
nCEO	-	All	Output	Output that drives low when device configuration is complete. In single device configuration, this pin is left floating. In multi-device configuration, this pin feeds the next device's nCE pin. The nCEO of the last device in the chain is left floating.			
DATA0	-	All	Input	Data input. In serial configuration mode, bit-wide configuration data is presented to the target device on the DATAO pin. Toggling DATAO after configuration does not affect the configured device. This pin uses Schmitt trigger input buffers			

Table 13–11 describes the optional configuration pins. If these optional configuration pins are not enabled in the Quartus II software, they are available as general-purpose user I/O pins. Therefore during configuration, these pins function as user I/O pins and are tri-stated with weak pull-ups.

Table 13-11	Table 13–11. Optional Cyclone Device Configuration Pins					
Pin Name	User Mode	Pin Type	Description			
CLKUSR	N/A if option is on, I/O if option is off	Input	Optional user-supplied clock input. Synchronizes the initialization of one or more devices. This pin is enabled by turning on the <b>Enable user-supplied start-up clock (CLKUSR)</b> option in the Quartus II software.			
INIT_DONE	N/A if option is on, I/O if option is off	Output open-drain	Status pin. Can be used to indicate when the device has initialized and is in user mode. The <code>INIT_DONE</code> pin must be pulled to $V_{CC}$ with a 10-k $\Omega$ resistor. The <code>INIT_DONE</code> pin drives low during configuration. Before and after configuration, the <code>INIT_DONE</code> pin is released and is pulled to $V_{CC}$ by an external pull-up resistor. Because <code>INIT_DONE</code> is tri-stated before configuration, it is pulled high by the external pull-up resistor. Thus, the monitoring circuitry must be able to detect a low-to-high transition. This pin is enabled by turning on the <code>Enable INIT_DONE</code> output option in the Quartus II software.			
DEV_OE	N/A if the option is on, I/O if the option is off.	Input	Optional pin that allows the user to override all tri-states on the device. When this pin is driven low, all I/O pins are tri-stated; when this pin is driven high, all I/O pins behave as programmed. This pin is enabled by turning on the <b>Enable device-wide output enable (DEV_OE)</b> option in the Quartus II software.			
DEV_CLRn	N/A if the option is on, I/O if the option is off.	Input	Optional pin that allows you to override all clears on all device registers. When this pin is driven low, all registers are cleared; when this pin is driven high, all registers behave as programmed. This pin is enabled by turning on the <b>Enable device-wide reset</b> ( <b>DEV_CLRn</b> ) option in the Quartus II software.			

Table 13–12 describes the dedicated JTAG pins. JTAG pins must be kept stable before and during configuration to prevent accidental loading of JTAG instructions.

Table 13-	Table 13–12. Dedicated JTAG Pins					
Pin Name	User Mode	Pin Type	Description			
TDI	N/A	Input	Serial input pin for instructions as well as test and programming data. Data is shifted in on the rising edge of ${\tt TCK}.$ If the JTAG interface is not required on the board, the JTAG circuitry can be disabled by connecting this pin to $V_{\tt CC}.$ This pin uses Schmitt trigger input buffers			
TDO	N/A	Output	Serial data output pin for instructions as well as test and programming data. Data is shifted out on the falling edge of TCK. The pin is tri-stated if data is not being shifted out of the device. If the JTAG interface is not required on the board, the JTAG circuitry can be disabled by leaving this pin unconnected.			
TMS	N/A	Input	Input pin that provides the control signal to determine the transitions of the TAP controller state machine. Transitions within the state machine occur on the rising edge of ${\tt TCK}.$ Therefore, ${\tt TMS}$ must be set up before the rising edge of ${\tt TCK}.$ TMS is evaluated on the rising edge of ${\tt TCK}.$ If the JTAG interface is not required on the board, the JTAG circuitry can be disabled by connecting this pin to ${\tt V_{CC}}.$ This pin uses Schmitt trigger input buffers			
TCK	N/A	Input	The clock input to the BST circuitry. Some operations occur at the rising edge, while others occur at the falling edge. If the JTAG interface is not required on the board, the JTAG circuitry can be disabled by connecting this pin to ground. This pin uses Schmitt trigger input buffers			

# Referenced Documents

This chapter references the following documents:

- AN 39: IEEE 1149.1 (JTAG) Boundary-Scan Testing in Altera Devices
- AN 418: SRunner: An Embedded Solution for Serial Configuration Device Programming
- AN 423: Configuring the MicroBlaster Passive Serial Software Driver
- ByteBlaster II Download Cable User Guide
- ByteBlasterMV Download Cable User Guide
- Cyclone FPGA Family Data Sheet section of the Cyclone Device Handbook
- DC and Switching Characteristics chapter in the Cyclone Device Handbook
- Design Debugging Using the SignalTap II Embedded Logic Analyzer chapter in volume 3 of the Quartus II Handbook
- MasterBlaster Serial/USB Communications Cable User Guide
- Serial Configuration Devices (EPCS1, EPCS4, EPCS16, EPCS64, and EPCS128) Data Sheet
- Software Settings section in volume 2 of the Configuration Handbook

# Document Revision History

Table 13–13 shows the revision history for this chapter.

v1.8  Docum  January 2007 v1.7  Ad  Re  Up  Up  Up  Up  Up  Up  Up  Up  Up  U	ded document revision history.  Ided document revision history.  Ided document revision history.  Ided document revision history.  Ided Figure 13–1.  Idea of Table 13–3.  Idea of Table 13–3.  Idea of Table 13–3.  Idea of Table 13–3.  Idea of Table 13–1.  Idea of Table 13–1.  Idea of Table 13–1.  Idea of Table 13–11.  Idea of Table 13–11.  Idea of Table 13–12.  Idea of Table 13–19.  Idea of Table 13–19.  Idea of Table 13–19.  Idea of Table 13–1.  Idea of Table 13–1.  Idea of Table 13–1.	— — —
v1.7	moved a note from Table 13–2. dated Figure 13–1. dated Table 13–3. dated feetpara note in "Active Serial Configuration (Serial infiguration Devices)" section. dated feetpara note on page 13–18. dated Note (2) in Figure 13–11. dated Note (4) in Figure 13–12. dated Note (2) in Figure 13–19. dated Note (3) in Figure 13–19. dated Figure 13–19. dated Figure 13–19.	
v1.6  August 2005 v1.5  Mir  March 2005 v1.4  February 2005 v1.3  August 2004 v1.2  De  Re  De	dated tables. for text updates. dated Figure 13–1.	_ _ _
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July 2003 v1.1 Update	ed .rbf sizes. Minor updates throughout the document.	_



# 14. Serial Configuration Devices (EPCS1, EPCS4, EPCS16, EPCS64, and EPCS128) Data Sheet

C51014-3.1

### Introduction

The serial configuration devices provide the following features:

- 1-, 4-, 16-, 64-, and 128-Mbit flash memory devices that serially configure Stratix<sup>®</sup> III, Stratix II GX, and Stratix II FPGAs, Arria<sup>TM</sup> GX FPGAs, and the Cyclone<sup>®</sup> series FPGAs using the active serial (AS) configuration scheme
- Easy-to-use four-pin interface
- Low cost, low-pin count, and non-volatile memory
- Low current during configuration and near-zero standby mode current
- 3.3-V operation
- Available in 8-pin and 16-pin small outline integrated circuit (SOIC) package
- Enables the Nios® processor to access unused flash memory through AS memory interface
- Re-programmable memory with more than 100,000 erase/program cycles
- Write protection support for memory sectors using status register bits
- In-system programming support with SRunner software driver
- In-system programming support with USB Blaster<sup>™</sup>, EthernetBlaster<sup>™</sup>, or ByteBlaster<sup>™</sup> II download cables
- Additional programming support with the Altera® Programming Unit (APU) and programming hardware from BP Microsystems, System General, and other vendors
- Software design support with the Altera Quartus<sup>®</sup> II development system for Windows-based PCs as well as Sun SPARC station and HP 9000 Series 700/800
- Delivered with the memory array erased (all the bits set to 1)



The term "serial configuration devices" used in this document refers to Altera EPCS1, EPCS4, EPCS16, EPCS64, and EPCS128.

# Functional Description

With SRAM-based devices that support active serial configuration, configuration data must be reloaded each time the device powers up, the system reconfigures, or when new configuration data is required. Serial configuration devices are flash memory devices with a serial interface that can store configuration data for FPGA devices that support active serial configuration and reload the data to the device upon power-up or reconfiguration. Table 14–1 lists the serial configuration devices.

Table 14–1. Serial Configuration Devices (3.3-V Operation)					
Device Memory Size (Bits)					
EPCS1	1,048,576				
EPCS4	4,194,304				
EPCS16	16,777,216				
EPCS64	67,108,864				
EPCS128	134,217,728				

For an 8-pin SOIC package, you can migrate vertically from the EPCS1 to the EPCS4 or EPCS16 since the EPCS devices are offered in the same device package. Similarly, for a 16-pin SOIC package, you can migrate vertically from the EPCS16 to the EPCS64 or EPCS128.



EPCS16 is available in 8-pin and 16-pin SOIC packages.

Table 14–2 lists the serial configuration device used with each Stratix III FPGA and the configuration file size. Stratix III devices can be used with EPCS16, EPCS64, or EPCS128.

Table 14–2. Serial Configuration Device Support for Stratix III Devices (Part 1 of 2)							
Stratix III Device	Raw Binary File Size	Serial Configuration Device					
	(Bits) (1)	EPCS1	EPCS4	EPCS16	EPCS64	EPCS128	
EP3SL50	22,178,792	_	_	<b>√</b> (2)	<b>✓</b>	<b>✓</b>	
EP3SL70	22,178,792	_	_	<b>√</b> (2)	✓	✓	
EP3SL110	47,413,312	_	_	_	<b>✓</b>	<b>✓</b>	
EP3SL150	47,413,312	_	_	_	✓	✓	
EP3SL200	93,324,656	_	_	_	<b>√</b> (2)	<b>✓</b>	
EP3SL340	117,384,664	_	_	_	_	✓	
EP3SE50	25,891,968	_	_	_	✓	✓	
EP3SE80	48,225,392	_	_	_	✓	✓	

Table 14–2. Serial Configuration Device Support for Stratix III Devices (Part 2 of 2)							
Strativ III Davice	Raw Binary File Size	Serial Configuration Device					
Stratix III Device	(Bits) (1)	EPCS1	EPCS4	EPCS16	EPCS64	EPCS128	
EP3SE110	48,225,392	_	_	_	<b>✓</b>	<b>✓</b>	
EP3SE260	93,324,656	_		_	<b>√</b> (2)	<b>✓</b>	

#### Notes to Table 14-2:

- (1) These are uncompressed file sizes.
- (2) This is with the Stratix III compression feature enabled.

Table 14–3 lists the serial configuration device used with each Stratix II GX FPGA and the configuration file size. Stratix II GX devices can be used with EPCS16, EPCS64, or EPCS128.

Table 14–3. Serial Co	nfiguration Device Supp	ort for Strati	x II GX Devi	ces		
Stratix II GX Device	Raw Binary File Size		Serial (	Configuration	Device	
Stratix ii GX Device	(Bits) (1)	EPCS1	EPCS4	EPCS16	EPCS64	EPCS128
EP2SGX30C EP2SGX30D	9,640,672	_	_	<b>✓</b>	<b>✓</b>	<b>✓</b>
EP2SGX60C EP2SGX60D EP2SGX60E	16,951,824	_	_	<b>√</b> (2)	<b>✓</b>	<b>✓</b>
EP2SGX90E EP2SGX90F	25,699,104	_	_	_	<b>✓</b>	~
EP2SGX130G	37,325,760	_	_	_	<b>✓</b>	<b>✓</b>

#### Notes to Table 14-3:

- (1) These are uncompressed file sizes.
- (2) This is with the Stratix II GX compression feature enabled.

Table 14–4 lists the serial configuration device used with each Stratix II FPGA and the configuration file size. Stratix II devices can be used with EPCS4, EPCS16, EPCS64, or EPCS128.

Table 14–4. Serial Configur	ation Device Support for Str	atix II Device	s		
Chrotiv II Dovice	Raw Binary File Size		Serial Configu	ıration Devid	е
Stratix II Device	(Bits) (1)	EPCS4	EPCS16	EPCS64	EPCS128
EP2S15	4,721,544	<b>√</b> (2)	<b>✓</b>	<b>✓</b>	<b>✓</b>
EP2S30	9,640,672	_	✓	✓	<b>✓</b>
EP2S60	16,951,824	_	<b>√</b> (2)	<b>✓</b>	✓
EP2S90	25,699,104	_	<b>√</b> (2)	<b>✓</b>	<b>✓</b>
EP2S130	37,325,760	_	_	✓	<b>✓</b>
EP2S180	49,814,760	_	_	✓	✓

#### Notes to Table 14-4:

- (1) These are uncompressed file sizes.
- (2) This is with the Stratix II compression feature enabled.

Table 14–5 lists the serial configuration device used with each Arria GX FPGA and the configuration file size. Arria GX devices can be used with EPCS16, EPCS64, or EPCS128.

Table 14–5. Serial Co	onfiguration Device Supp	ort for Arria	GX Devices			
Arria GX Device	Raw Binary File Size		Serial (	Configuration	Device	
Arria GX Device	(Bits) (1)	EPCS1	EPCS4	EPCS16	EPCS64	EPCS128
EP1AGX20C	9,640,672	_	_	<b>✓</b>	<b>✓</b>	<b>✓</b>
EP1AGX35C EP1AGX35D	9,640,672	_	_	<b>✓</b>	<b>✓</b>	~
EP1AGX50C EP1AGX50D	16,951,824	_	_	<b>√</b> (2)	<b>✓</b>	~
EP1AGX60C EP1AGX60D EP1AGX60E	16,951,824	_	_	<b>√</b> (2)	<b>✓</b>	<b>✓</b>
EP1AGX90E	25,699,104	_	_	_	✓	✓

#### Notes to Table 14-5:

- (1) These are uncompressed file sizes.
- (2) This is with the Arria GX compression feature enabled.

Table 14–6 lists the serial configuration device used with each Cyclone III FPGA and the configuration file size. Cyclone III devices can be used with EPCS4, EPCS16, EPCS64, or EPCS128.

Cualona III Davisa	Raw Binary File Size		Serial (	Configuration	n Device	
Cyclone III Device	(Bits) (1)	EPCS1	EPCS4	EPCS16	EPCS64	EPCS128
EP3C5	2,944,088	_	<b>✓</b>	<b>✓</b>	<b>✓</b>	<b>✓</b>
EP3C10	2,944,088	_	<b>✓</b>	<b>✓</b>	<b>✓</b>	<b>✓</b>
EP3C16	4,086,848	_	✓	<b>✓</b>	<b>✓</b>	<b>✓</b>
EP3C25	5,748,552	_	_	<b>✓</b>	<b>✓</b>	<b>✓</b>
EP3C40	9,534,304	_	_	<b>✓</b>	<b>✓</b>	<b>✓</b>
EP3C55	14,889,560	_	_	<b>✓</b>	<b>✓</b>	<b>✓</b>
EP3C80	19,965,752	_	_	<b>√</b> (2)	<b>✓</b>	<b>✓</b>
EP3C120	28,571,696	_	_	_	<b>✓</b>	<b>✓</b>

#### Notes to Table 14-6:

- (1) These are uncompressed file sizes.
- (2) This is with the Cyclone III compression feature enabled.

Table 14–7 lists the serial configuration device used with each Cyclone II FPGA and the configuration file size. Cyclone II devices can be used with EPCS1, EPCS4, EPCS16, EPCS64, or EPCS128.

Table 14–7. Serial Co	onfiguration Device for C	yclone II De	vices			
Cyclone II Dovice	Raw Binary File Size		Serial (	Configuration	n Device	
Cyclone II Device	(Bits) (1)	EPCS1	EPCS4	EPCS16	EPCS64	EPCS128
EP2C5	1,265,792	<b>√</b> (2)	<b>✓</b>	<b>✓</b>	<b>✓</b>	<b>✓</b>
EP2C8	1,983,536	_	<b>✓</b>	<b>✓</b>	<b>✓</b>	✓
EP2C20	3,892,496	_	<b>✓</b>	<b>✓</b>	<b>✓</b>	<b>✓</b>
EP2C35	6,848,608	_	_	<b>✓</b>	<b>✓</b>	<b>✓</b>
EP2C50	9,951,104	_	_	<b>✓</b>	<b>✓</b>	<b>✓</b>
EP2C70	14,319,216	_	_	<b>✓</b>	<b>✓</b>	✓

#### *Notes to Table 14–7:*

- (1) These are uncompressed file sizes.
- (2) This is with the Cyclone II compression feature enabled.

Table 14–8 lists the serial configuration device used with each Cyclone FPGA and the configuration file size. Cyclone devices can be used with EPCS1, EPCS4, EPCS16, EPCS64, or EPCS128.

Table 14–8. Serial Co	onfiguration Device Supp	ort for Cyclo	ne Devices			
Cualana Davisa	Raw Binary File		Serial (	Configuration	n Device	
Cyclone Device	Size (Bits) (1)	EPCS1	EPCS4	EPCS16	EPCS64	EPCS128
EP1C3	627,376	<b>✓</b>	<b>✓</b>	<b>✓</b>	<b>✓</b>	<b>✓</b>
EP1C4	924,512	<b>✓</b>	<b>✓</b>	<b>✓</b>	<b>✓</b>	<b>✓</b>
EP1C6	1,167,216	<b>√</b> (2)	<b>✓</b>	<b>✓</b>	<b>✓</b>	<b>✓</b>
EP1C12	2,323,240	_	✓	<b>✓</b>	<b>✓</b>	<b>✓</b>
EP1C20	3,559,608	_	✓	<b>✓</b>	<b>✓</b>	<b>✓</b>

#### Notes to Table 14-8:

- (1) These are uncompressed file sizes.
- (2) This is with the Cyclone compression feature enabled.

With the new data-decompression feature in the Stratix III, Stratix II GX, and Stratix II FPGAs, Arria GX FPGAs, and Cyclone FPGA families, you can use smaller serial configuration devices to configure larger FPGAs.



Serial configuration devices cannot be cascaded.



For more information about the FPGA decompression feature, refer to the configuration chapter in the appropriate device handbook.

The serial configuration devices are designed to configure Stratix III, Stratix II GX, and Stratix II FPGAs and the Cyclone series FPGAs and cannot configure other existing Altera FPGA device families.

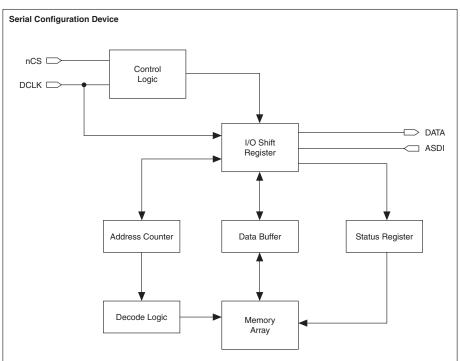


Figure 14–1 shows the serial configuration device block diagram.

# Figure 14–1. Serial Configuration Device Block Diagram

## **Accessing Memory in Serial Configuration Devices**

You can access the unused memory locations of the serial configuration device to store or retrieve data through the Nios processor and SOPC Builder. SOPC Builder is an Altera tool for creating bus-based (especially microprocessor-based) systems in Altera devices. SOPC Builder assembles library components such as processors and memories into custom microprocessor systems.

SOPC Builder includes the EPCS device controller core, which is an interface core specifically designed to work with the serial configuration device. With this core, you can create a system with a Nios embedded processor that allows software access to any memory location within the serial configuration device.



For more information about accessing memory within the serial configuration device, refer to the *Active Serial Memory Interface Data Sheet*.

# Active Serial FPGA Configuration

The following Altera FPGAs support Active Serial (AS) configuration scheme with serial configuration devices:

- Stratix III
- Stratix II GX
- Stratix II
- Arria GX
- Cyclone series FPGAs



This section is only relevant for FPGAs that support the AS configuration scheme.

There are four signals on the serial configuration device that interface directly with the FPGA's control signals. The serial configuration device signals DATA, DCLK, ASDI, and nCS interface with DATAO, DCLK, ASDO, and nCSO control signals on the FPGA, respectively. Figure 14–2 shows a serial configuration device programmed via a download cable, which configures an FPGA in AS mode. Figure 14–3 shows a serial configuration device programmed using the APU or a third-party programmer configuring an FPGA in AS configuration mode.

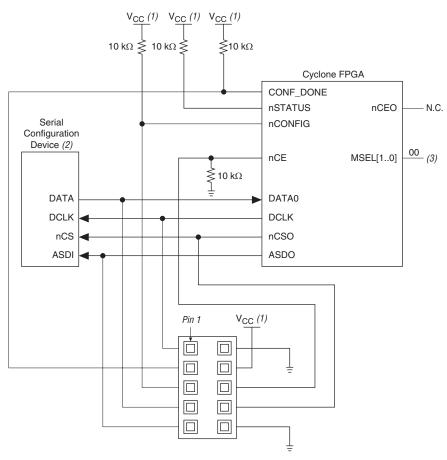


Figure 14–2. Cyclone FPGA Configuration in AS Mode (Serial Configuration Device Programmed Using Download Cable) Note (4)

Notes to Figure 14-2:

- (1)  $V_{CC} = 3.3 \text{ V}.$
- (2) Serial configuration devices cannot be cascaded.
- (3) Connect the FPGA MSEL[] input pins to select the AS configuration mode. For details, refer to the appropriate FPGA family chapter in the *Configuration Handbook*.
- (4) For more information about configuration pin I/O requirements in an AS scheme for a Cyclone III FPGA, refer to the *Configuring Cyclone III Devices* chapter in volume 1 of the *Cyclone III Device Handbook*.

 $V_{CC}$  (1)  $V_{CC}$  (1)  $V_{CC}$  (1)  $10 \text{ k}\Omega \gtrsim 10 \text{ k}\Omega \gtrsim$ **≤**10 kΩ Cyclone FPGA CONF\_DONE nSTATUS nCEO N.C. Serial nCONFIG Configuration Device (2) nCE MSEL[1..0] DATA DATA0 **DCLK DCLK** nCSO nCS **ASDI** ASDO

Figure 14–3. Cyclone FPGA Configuration in AS Mode (Serial Configuration Device Programmed by APU or Third-Party Programmer) Note (4)

#### Notes to Figure 14-3:

- (1)  $V_{CC} = 3.3 \text{ V}.$
- (2) Serial configuration devices cannot be cascaded.
- (3) Connect the FPGA MSEL[] input pins to select the AS configuration mode. For details, refer to the appropriate FPGA family chapter in the *Configuration Handbook*.
- (4) For more information about configuration pin I/O requirements in an AS scheme for a Cyclone III FPGA, refer to the Configuring Cyclone III Devices chapter in volume 1 of the Cyclone III Device Handbook.

The FPGA acts as the configuration master in the configuration flow and provides the clock to the serial configuration device. The FPGA enables the serial configuration device by pulling the nCS signal low via the nCSO signal (refer to Figures 14–2 and 14–3). Subsequently, the FPGA sends the instructions and addresses to the serial configuration device via the ASDO signal. The serial configuration device responds to the instructions by sending the configuration data to the FPGA's DATAO pin on the falling edge of DCLK. The data is latched into the FPGA on the DCLK signal's falling edge.

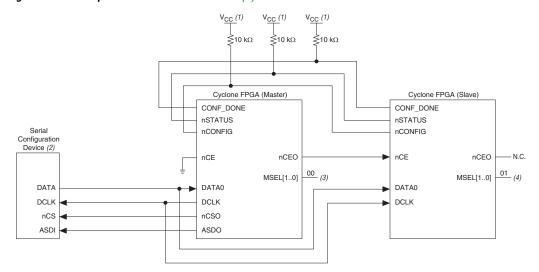
The FPGA controls the <code>nstatus</code> and <code>conf\_done</code> pins during configuration in AS mode. If the <code>conf\_done</code> signal does not go high at the end of configuration or if the signal goes high too early, the FPGA will pulse its <code>nstatus</code> pin low to start reconfiguration. Upon successful configuration, the FPGA releases the <code>conf\_done</code> pin, allowing the external <code>10-k\Omegaresistor</code> to pull this signal high. Initialization begins after the <code>conf\_done</code> goes high. After initialization, the FPGA enters user mode.



Refer to the configuration chapter in the appropriate device handbook for more information about configuring the FPGAs in AS mode or other configuration modes.

Multiple devices can be configured by a single EPCS device. However, serial configuration devices cannot be cascaded. Refer to Table 14–1 to ensure the programming file size of the cascaded FPGAs does not exceed the capacity of a serial configuration device. Figure 14–4 shows the AS configuration scheme with multiple FPGAs in the chain. The first FPGA is the configuration master and has its MSEL[] pins set to AS mode. The following FPGAs are configuration slave devices and have their MSEL[] pins set to PS mode.

Figure 14–4. Multiple Devices in AS Mode Note (5)



#### Notes to Figure 14-4:

- (1)  $V_{CC} = 3.3 \text{ V}.$
- (2) Serial configuration devices cannot be cascaded.
- (3) Connect the FPGA MSEL[] input pins to select the AS configuration mode. For details, refer to the appropriate FPGA family chapter in the Configuration Handbook.
- (4) Connect the FPGA MSEL[] input pins to select the PS configuration mode. For details, refer to the appropriate FPGA family chapter in the *Configuration Handbook*.
- (5) For more information about configuration pin I/O requirements in an AS scheme for a Cyclone III FPGA, refer to the *Configuring Cyclone III Devices* chapter in volume 1 of the *Cyclone III Device Handbook*.

# Serial Configuration Device Memory Access

This section describes the serial configuration device's memory array organization and operation codes. Timing specifications for the memory are provided in the "Timing Information" section.

#### **Memory Array Organization**

Table 14–9 provides details about the memory array organization in EPCS128, EPCS64, EPCS16, EPCS1, and EPCS1.

Table 14–9. Mer	nory Array Organiz	ation in Serial Co	nfiguration Device	s	
Details	EPCS128	EPCS64	EPCS16	EPCS4	EPCS1
Bytes (bits)	16,777,216 bytes (128 Mbits)	8,388,608 bytes (64 Mbits)	2,097,152 bytes (16 Mbits)	524,288 bytes (4 Mbits)	131,072 bytes (1 Mbit)
Number of sectors	64	128	32	8	4
Bytes (bits) per sector	262,144 (2 Mbits)	65,536 bytes (512 Kbits)	65,536 bytes (512 Kbits)	65,536 bytes (512 Kbits)	32,768 bytes (256 Kbits)
Pages per sector	1,024	256	256	256	128
Total number of pages	65,536	32,768	8,192	2,048	512
Bytes per page	256 bytes	256 bytes	256 bytes	256 bytes	256 bytes

Tables 14–10 through 14–14 show the address range for each sector in EPCS128, EPCS64, EPCS16, EPCS4, and EPCS1.

Conton	S Range for Sectors in EPCS128 (Part 1 of 3)  Address Range (Byte Addresses in HEX)			
Sector	Start	End		
63	H'FC0000	H'FFFFFF		
62	H'F80000	H'FBFFFF		
61	H'F40000	H'F7FFFF		
60	H'F00000	H'F3FFFF		
59	H'EC0000	H'EFFFFF		
58	H'E80000	H'EBFFFF		
57	H'E40000	H'E7FFFF		
56	H'E00000	H'E3FFFF		
55	H'DC0000	H'DFFFFF		
54	н'д80000	H'DBFFFF		

0	Address Range (Byt	e Addresses in HEX	
Sector	Start	End	
53	H'D40000	H'D7FFFF	
52	H'D00000	H'D3FFFF	
51	H'CC0000	H'CFFFFF	
50	H'C80000	H'CBFFFF	
49	H'C40000	H'C7FFFF	
48	H'C00000	H'C3FFFF	
47	н'вс0000	H'BFFFFF	
46	н'в80000	H'BBFFFF	
45	н'в40000	H'B7FFF	
44	н'в00000	H'B3FFFF	
43	H'AC0000	H'AFFFF	
42	н'А80000	H'ABFFFF	
41	H'A40000	H'A7FFF	
40	н'А00000	H'A3FFFF	
39	н'9С0000	H'9FFFF	
38	н'980000	H'9BFFFF	
37	н'940000	H'97FFFF	
36	н'900000	H'93FFFF	
35	н'8С0000	H'8FFFF	
34	н'880000	H'8BFFFF	
33	H'840000	H'87FFF	
32	н'800000	H'83FFFF	
31	н'7с0000	H'7FFFF	
30	н'780000	H'7BFFFF	
29	н'740000	н'77ғғғ	
28	н'700000	H'73FFFF	
27	н'6С0000	H'6FFFFF	
26	н'680000	H'6BFFFF	
25	н'640000	H'67FFFF	
24	н'600000	H'63FFFF	
23	н'5С0000	H'5FFFF	
22	н'580000	H'5BFFFF	

0	Address Range (Byte Addresses in HEX)			
Sector	Start	End		
21	н'540000	H'57FFFF		
20	н'500000	H'53FFFF		
19	н'4С0000	H'4FFFFF		
18	н'480000	H'4BFFFF		
17	Н'440000	H'47FFFF		
16	н'400000	H'43FFFF		
15	н'3С0000	H'3FFFFF		
14	н'380000	H'3BFFFF		
13	н'340000	H'37FFFF		
12	н'300000	H'33FFFF		
11	H'2C0000	H'2FFFFF		
10	н'280000	H'2BFFFF		
9	H'240000	H'27FFFF		
8	н'200000	H'23FFFF		
7	н'1С0000	H'1FFFFF		
6	н'180000	H'1BFFFF		
5	H'140000	H'17FFFF		
4	н'100000	H'13FFFF		
3	н'0С0000	H'OFFFFF		
2	н'080000	H'OBFFFF		
1	H'040000	H'07FFFF		
0	н'000000	H'03FFFF		

Table 14–11. Address	ble 14–11. Address Range for Sectors in EPCS64 (Part 1 of 5)				
Conton	Address Range (Byte Addresses in HEX)				
Sector	Start	End			
127	H'7F0000	H'7FFFFF			
126	H'7E0000	H'7EFFFF			
125	н'7D0000	H'7DFFFF			
124	н'7С0000	H'7CFFFF			
123	н'7в0000	H'7BFFFF			

Conton	Address Range (Byt	e Addresses in HEX	
Sector	Start	End	
122	н'7А0000	H'7AFFFF	
121	н'790000	H'79FFFF	
120	н'780000	H'78FFFF	
119	н'770000	H'77FFFF	
118	н'760000	H'76FFF	
117	н'750000	H'75FFFF	
116	н'740000	H'74FFF	
115	н'730000	H'73FFFE	
114	н'720000	H'72FFFF	
113	н'710000	H'71FFFE	
112	н'700000	H'70FFFE	
111	н'6F0000	H'6FFFF	
110	н'6Е0000	H'6EFFFF	
109	н'6D0000	H'6DFFFF	
108	н'6С0000	H'6CFFFF	
107	н'6В0000	H'6BFFFF	
106	н'6А0000	H'6AFFFE	
105	н'690000	H'69FFFF	
104	н'680000	H'68FFFF	
103	н'670000	H'67FFF	
102	н'660000	H'66FFFF	
101	н'650000	H'65FFFF	
100	н'640000	H'64FFF	
99	н'630000	H'63FFFF	
98	н'620000	H'62FFFF	
97	н'610000	H'61FFFF	
96	н'600000	H'60FFFF	
95	H'5F0000	H'5FFFF	
94	H'5E0000	H'5EFFFF	
93	H'5D0000	H'5DFFFF	
92	н'5С0000	H'5CFFFF	
91	н'5в0000	H'5BFFFF	

Castan	Address Range (Byte Addresses in HEX		
Sector	Start	End	
90	н'5А0000	H'5AFFFF	
89	н'590000	H'59FFFF	
88	н'580000	H'58FFFF	
87	н'570000	н'57ғғғ	
86	н'560000	H'56FFFF	
85	н'550000	H'55FFFF	
84	н'540000	H'54FFFF	
83	н'530000	H'53FFFF	
82	н'520000	H'52FFFF	
81	н'510000	H'51FFFF	
80	н'500000	H'50FFFF	
79	H'4F0000	H'4FFFFF	
78	H'4E0000	H'4EFFFF	
77	H'4D0000	H'4DFFFF	
76	H'4C0000	H'4CFFFF	
75	н'4В0000	H'4BFFFF	
74	H'4A0000	H'4AFFFF	
73	н'490000	H'49FFFF	
72	н'480000	H'48FFFF	
71	н'470000	H'47FFFF	
70	н'460000	H'46FFFF	
69	н'450000	H'45FFFF	
68	H'440000	H'44FFFF	
67	н'430000	H'43FFFF	
66	H'420000	H'42FFFF	
65	н'410000	H'41FFFF	
64	н'400000	H'40FFFF	
63	н'3F0000	H'3FFFFF	
62	н'3Е0000	H'3EFFFF	
61	H'3D0000	H'3DFFFF	
60	н'3С0000	H'3CFFFF	

O-atau	Address Range (Byte Addresses in HEX		
Sector	Start	End	
58	н'ЗА0000	H'3AFFFF	
57	н'390000	H'39FFFF	
56	н'380000	H'38FFFF	
55	н'370000	H'37FFFF	
54	н'360000	H'36FFFF	
53	н'350000	H'35FFFF	
52	н'340000	H'34FFFE	
51	н'330000	H'33FFFE	
50	н'320000	H'32FFFF	
49	н'310000	H'31FFFE	
48	н'300000	H'30FFFE	
47	H'2F0000	H'2FFFF	
46	H'2E0000	H'2EFFFF	
45	H'2D0000	H'2DFFFF	
44	H'2C0000	H'2CFFFF	
43	н'2В0000	H'2BFFFF	
42	н'2А0000	H'2AFFFF	
41	н'290000	H'29FFFF	
40	н'280000	H'28FFF	
39	н'270000	H'27FFFF	
38	н'260000	H'26FFFF	
37	н'250000	H'25FFFF	
36	н'240000	H'24FFFF	
35	н'230000	H'23FFFF	
34	н'220000	H'22FFFF	
33	н'210000	H'21FFFF	
32	н'200000	H'20FFFF	
31	H'1F0000	H'1FFFFF	
30	H'1E0000	H'1EFFFF	
29	H'1D0000	H'1DFFFF	
28	н'1С0000	H'1CFFFF	

14-11. Address	s Range for Sectors in EPCS64 (Part 5 of 5)  Address Range (Byte Addresses in HEX)		
Sector	Start	End	
26	H'1A0000	H'1AFFFF	
25	н'190000	H'19FFFF	
24	н'180000	H'18FFFF	
23	н'170000	H'17FFFF	
22	н'160000	H'16FFFF	
21	н'150000	H'15FFFF	
20	н'140000	H'14FFFF	
19	н'130000	H'13FFFF	
18	н'120000	H'12FFFF	
17	н'110000	H'11FFFF	
16	н'100000	H'10FFFF	
15 14	H'0F0000	H'OFFFFF H'OEFFFF H'ODFFFF	
	H'0E0000		
13	H'0D0000		
12	н'0С0000	H'OCFFFF	
11	н'0в0000	H'OBFFFF	
10	H'0A0000	H'OAFFFF	
9	н'090000	H'09FFFF	
8	н'080000	H'08FFFF	
7	н'070000	H'07FFFF	
6	н'060000	H'06FFFF	
5	н'050000	H'05FFFF	
4	H'040000	H'04FFFF	
3	н'030000	H'03FFFF	
2	н'020000	H'02FFFF	
1	н'010000	H'01FFFF	
0	н'000000	H'00FFFF	

Sector         Start           31         H'1F0000           30         H'1E0000           29         H'1D0000           28         H'1C0000           27         H'1B0000	H'1EFFFE H'1DFFFE H'1CFFFE
30 H'1E0000 29 H'1D0000 28 H'1C0000 27 H'1B0000	H'1EFFFE H'1DFFFE H'1CFFFE
29 H'1D0000 28 H'1C0000 27 H'1B0000	H'1DFFFE
28 H'1C0000 27 H'1B0000	H'1CFFFE
27 H'1B0000	
	H'1BFFFE
06	
26 H'1A0000	H'1AFFFE
<b>25</b> H'190000	H'19FFFE
24 H'180000	H'18FFFE
23 H'170000	H'17FFFE
22 H'160000	H'16FFFE
21 H'150000	H'15FFFE
20 н'140000	H'14FFFE
19 н'130000	H'13FFFE
18 H'120000	H'12FFFE
17 H'110000	H'11FFFE
16 н'100000	H'10FFFE
15 H'0F0000	H'OFFFF
14 H'0E0000	H'OEFFFE
13 Н'ОДОООО	H'ODFFFE
12 H'0C0000	H'OCFFFE
11 н'0в0000	H'OBFFFE
10 H'0A0000	H'OAFFFE
9 н'090000	H'09FFFE
8 н'080000	H'08FFFE
7 H'070000	H'07FFFE
6 н'060000	H'06FFFE
5 н'050000	H'05FFFE
4 Н'040000	H'04FFF
3 н'030000	H'03FFFE
2 н'020000	H'02FFFE
1 H'010000	H'01FFFE

Table 14–13. Address Range for Sectors in EPCS4				
Contar	Address Range (Byte Addresses in HEX)			
Sector	Start	End		
7	н'70000	H'7FFFF		
6	н'60000	H'6FFFF		
5	н'50000	H'5FFFF		
4	н'40000	H'4FFFF		
3	н'30000	H'3FFFF		
2	н'20000	H'2FFFF		
1	н'10000	H'1FFFF		
0	н'00000	H'OFFFF		

Table 14–14. Address Range for Sectors in EPCS1				
Contor	Address Range (Byte Addresses in HEX)			
Sector	Start	End		
3	н'18000	H'1FFFF		
2	н'10000	H'17FFF		
1	н'08000	H'OFFFF		
0	н'00000	H'07FFF		

## **Operation Codes**

This section describes the operations that can be used to access the memory in serial configuration devices. The DATA, DCLK, ASDI, and nCS signals access the memory in serial configuration devices. All serial configuration device operation codes, addresses and data are shifted in and out of the device serially, with the most significant bit (MSB) first.

The device samples the active serial data input on the first rising edge of the DCLK after the active low chip select (nCS) input signal is driven low. Shift the operation code (MSB first) serially into the serial configuration device through the active serial data input pin. Each operation code bit is latched into the serial configuration device on the rising edge of the DCLK.

Different operations require a different sequence of inputs. While executing an operation, you must shift in the desired operation code, followed by the address bytes, data bytes, both, or neither. The device

must drive nCS high after the last bit of the operation sequence is shifted in. Table 14–15 shows the operation sequence for every operation supported by the serial configuration devices.

For the read byte, read status, and read silicon ID operations, the shifted-in operation sequence is followed by data shifted out on the DATA pin. You can drive the nCS pin high after any bit of the data-out sequence is shifted out.

For the write byte, erase bulk, erase sector, write enable, write disable, and write status operations, drive the nCS pin high exactly at a byte boundary (drive the nCS pin high a multiple of eight clock pulses after the nCS pin is driven low); otherwise, the operation is rejected and is not executed.

All attempts to access the memory contents while a write or erase cycle is in progress will not be granted, and the write or erase cycle will continue unaffected.

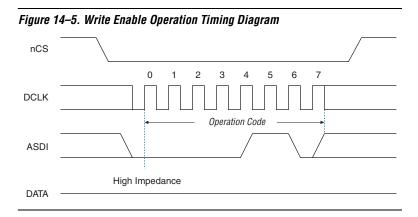
Table 14–15. Operation Codes for Serial Configuration Devices					
Operation	Operation Code (1)	Address Bytes	Dummy Bytes	Data Bytes	DCLK f <sub>MAX</sub> (MHz)
Write enable	0000 0110	0	0	0	25
Write disable	0000 0100	0	0	0	25
Read status	0000 0101	0	0	1 to infinite (2)	25
Read bytes	0000 0011	3	0	1 to infinite (2)	20
Read silicon ID (4)	1010 1011	0	3	1 to infinite (2)	25
Write status	0000 0001	0	0	1	25
Write bytes	0000 0010	3	0	1 to 256 (3)	25
Erase bulk	1100 0111	0	0	0	25
Erase sector	1101 1000	3	0	0	25
Read Device Identification (5)	1001 1111	0	2	1 to infinite (2)	25

#### *Notes to Table 14–15:*

- (1) The MSB is listed first and the least significant bit (LSB) is listed last.
- (2) The status register, data or silicon ID are read out at least once on the DATA pin and will continuously be read out until nCS is driven high.
- (3) Write bytes operation requires at least one data byte on the DATA pin. If more than 256 bytes are sent to the device, only the last 256 bytes are written to the memory.
- (4) Read silicon ID operation is available only for EPCS1, EPCS4, EPCS16, and EPCS64.
- (5) Read Device Identification operation is available only for EPCS128.

#### Write Enable Operation

The write enable operation code is b'00000110, and the MSB is listed first. The write enable operation sets the write enable latch bit, which is bit 1 in the status register. Always set the write enable latch bit before write bytes, write status, erase bulk, and erase sector operations. Figure 14–5 shows the timing diagram for the write enable operation. Figures 14–7 and 14–8 show the status register bit definitions.

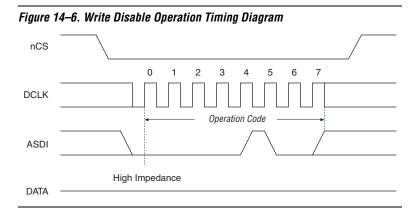


#### Write Disable Operation

The write disable operation code is b'0000 0100, with the MSB listed first. The write disable operation resets the write enable latch bit, which is bit 1 in the status register. To prevent the memory from being written unintentionally, the write enable latch bit is automatically reset when implementing the write disable operation as well as under the following conditions:

- Power up
- Write bytes operation completion
- Write status operation completion
- Erase bulk operation completion
- Erase sector operation completion

Figure 14–6 shows the timing diagram for the write disable operation.



#### Read Status Operation

The read status operation code is b'0000 0101, with the MSB listed first. You can use the read status operation to read the status register. Figures 14–7 and 14–8 show the status bits in the status register of both serial configuration devices.

Figure 14–7. EPCS4, EPCS16, EPCS64, and EPCS128 Status Register Status Bits

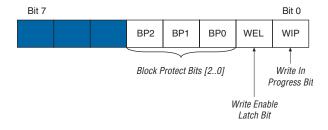
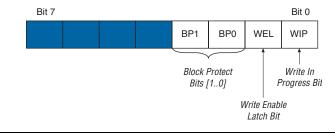


Figure 14-8. EPCS1 Status Register Status Bits



Setting the write in progress bit to 1 indicates that the serial configuration device is busy with a write or erase cycle. Resetting the write in progress bit to 0 means no write or erase cycle is in progress.

Resetting the write enable latch bit to 0 indicates that no write or erase cycle will be accepted. Set the write enable latch bit to 1 before every write bytes, write status, erase bulk, and erase sector operation.

The non-volatile block protect bits determine the area of the memory protected from being written or erased unintentionally. Table 14–16 through Table 14–20 show the protected area in the serial configuration devices with reference to the block protect bits. The erase bulk operation is only available when all the block protect bits are 0. When any of the block protect bits are set to 1, the relevant area is protected from being written by write bytes operations or erased by erase sector operations.

Table 14–16. Block Protection Bits in EPCS1					
Status Regi	ster Content	Memory Content			
BP1 Bit BP0 Bit		Protected Area	Unprotected Area		
0	0	None	All four sectors: 0 to 3		
0	1	Sector 3	Three sectors: 0 to 2		
1	0	Two sectors: 2 and 3	Two sectors: 0 and 1		
1	1	All sectors	None		

Table 14-	Table 14–17. Block Protection Bits in EPCS4					
Status Register Content			Memory Content			
BP2 Bit BP1 Bit BP0 Bit		Protected Area	Unprotected Area			
0	0	0	None	All eight sectors: 0 to 7		
0	0	1	Sector 7	Seven sectors: 0 to 6		
0	1	0	Sectors 6 and 7	Six sectors: 0 to 5		
0	1	1	Four sectors: 4 to 7	Four sectors: 0 to 3		
1	0	0	All sectors	None		
1	0	1	All sectors	None		
1	1	0	All sectors	None		
1	1	1	All sectors	None		

Table	Table 14–18. Block Protection Bits in EPCS16							
Status Register Content			Memory Content					
BP2 Bit	BP1 Bit	BP0 Bit	Protected Area	Unprotected Area				
0	0	0	None	All sectors (32 sectors 0 to 31)				
0	0	1	Upper 32nd (Sector 31)	Lower 31/32nds (31 sectors: 0 to 30)				
0	1	0	Upper sixteenth (two sectors: 30 and 31)	Lower 15/16ths (30 sectors: 0 to 29)				
0	1	1	Upper eighth (four sectors: 28 to 31)	Lower seven-eighths (28 sectors: 0 to 27)				
1	0	0	Upper quarter (eight sectors: 24 to 31)	Lower three-quarters (24 sectors: 0 to 23)				
1	0	1	Upper half (sixteen sectors: 16 to 31)	Lower half (16 sectors: 0 to 15)				
1	1	0	All sectors (32 sectors: 0 to 31)	None				
1	1	1	All sectors (32 sectors: 0 to 31)  None					

Table 14–19. Block Protection Bits in EPCS64						
Status Register Content			Memory Content			
BP2 Bit	BP1 Bit	BP0 Bit	Protected Area Unprotected Area			
0	0	0	None	All sectors (128 sectors: 0 to 127)		
0	0	1	Upper 64th (2 sectors: 126 and 127) Lower 63/64ths (126 sectors: 0 to 125)			
0	1	0	Upper 32nd (4 sectors: 124 to 127) Lower 31/32nds (124 sectors: 0 to 123)			
0	1	1	Upper sixteenth (8 sectors: 120 to 127) Lower 15/16ths (120 sectors: 0 to 119)			
1	0	0	Upper eighth (16 sectors: 112 to 127)  Lower seven-eighths (112 sectors: 0 to 1			
1	0	1	Upper quarter (32 sectors: 96 to 127)  Lower three-quarters (96 sectors: 0 to 95)			
1	1	0	Upper half (64 sectors: 64 to 127)  Lower half (64 sectors: 0 to 63)			
1	1	1	All sectors (128 sectors: 0 to 127) None			

Table	Table 14–20. Block Protection Bits in EPCS128							
Status Register Content Memory			Memor	y Content				
BP2 Bit	BP1 Bit	BP0 Bit	Protected Area Unprotected Area					
0	0	0	None	All sectors (64 sectors: 0 to 63)				
0	0	1	Upper 64th (1 sector: 63)	Lower 63/64ths (63 sectors: 0 to 62)				
0	1	0	Upper 32nd (2 sectors: 62 to 63)	Lower 31/32nds (62 sectors: 0 to 61)				
0	1	1	Upper 16th (4 sectors: 60 to 63)	Lower 15/16ths (60 sectors: 0 to 59)				
1	0	0	Upper 8th (8 sectors: 56 to 63)	Lower seven-eighths (56 sectors: 0 to 55)				
1	0	1	Upper quarter (16 sectors: 48 to 63)	pper quarter (16 sectors: 48 to 63)  Lower three-quarters (48 sectors: 0 to 47)				
1	1	0	Upper half (32 sectors: 32 to 63)	Lower half (32 sectors: 0 to 31)				
1	1	1	All sectors (64 sectors: 0 to 63)	None				

You can read the status register at any time, even while a write or erase cycle is in progress. When one of these cycles is in progress, you can check the write in progress bit (bit 0 of the status register) before sending a new operation to the device. The device can also read the status register continuously, as shown in Figure 14–9.

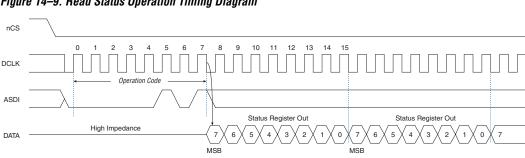


Figure 14–9. Read Status Operation Timing Diagram

#### Write Status Operation

The write status operation code is b'0000 0001, with the MSB listed first. Use the write status operation to set the status register block protection bits. The write status operation has no effect on the other bits. Therefore, you can implement this operation to protect certain memory sectors, as defined in Table 14–16 through Table 14–20. After setting the block protect bits, the protected memory sectors are treated as read-only memory. You must execute the write enable operation before the write status operation so the device sets the status register's write enable latch bit to 1.

The write status operation is implemented by driving nCS low, followed by shifting in the write status operation code and one data byte for the status register on the ASDI pin. Figure 14–10 shows the timing diagram for the write status operation. nCS must be driven high after the eighth bit of the data byte has been latched in, otherwise, the write status operation is not executed.

Immediately after nCS drives high, the device initiates the self-timed write status cycle. The self-timed write status cycle usually takes 5 ms for all serial configuration devices and is guaranteed to be less than 15 ms (refer to  $t_{WS}$  in Table 14–23). You must account for this delay to ensure that the status register is written with desired block protect bits. Alternatively, you can check the write in progress bit in the status register by executing the read status operation while the self-timed write status cycle is in progress. The write in progress bit is 1 during the self-timed write status cycle, and 0 when it is complete.

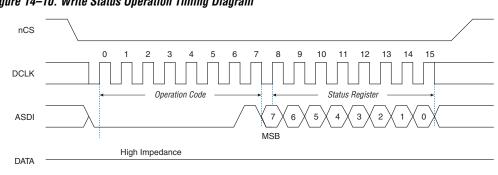


Figure 14-10. Write Status Operation Timing Diagram

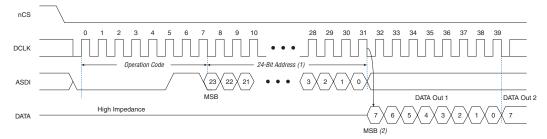
#### Read Bytes Operation

The read bytes operation code is b'0000 0011, with the MSB listed first. To read the memory contents of the serial configuration device, the device is first selected by driving nCS low. Then, the read bytes operation code is shifted in followed by a 3-byte address (A [23..0]). Each address bit must be latched in on the rising edge of the DCLK. After the address is latched in, the memory contents of the specified address are shifted out serially on the DATA pin, beginning with the MSB. For reading Raw Programming Data files (.rpd), the content is shifted out on the falling edge of

<code>DCLK</code>. The maximum <code>DCLK</code> frequency during the read bytes operation is 20 MHz. Figure 14–11 shows the timing diagram for the read bytes operation.

The first byte address can be at any location. The device automatically increments the address to the next higher address after shifting out each byte of data. Therefore, the device can read the whole memory with a single read bytes operation. When the device reaches the highest address, the address counter restarts at  $0 \times 000000$ , allowing the memory contents to be read out indefinitely until the read bytes operation is terminated by driving nCS high. The device can drive nCS high any time after data is shifted out. If the read bytes operation is shifted in while a write or erase cycle is in progress, the operation is not executed and has no effect on the write or erase cycle in progress.





#### *Notes to Figure 14–11:*

- (1) Address bit A[23] is a don't-care bit in EPCS64. Address bits A[23..21] are don't-care bits in EPCS16. Address bits A[23..19] are don't-care bits in EPCS1.
- For RPD files, the read sequence shifts out the LSB of the data byte first.

#### Read Silicon ID Operation

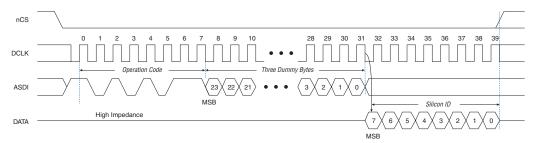
The read silicon ID operation code is b'1010 1011, with the MSB listed first. Only EPCS1, EPCS4, EPCS16, and EPCS64 support this operation. It reads the serial configuration device's 8-bit silicon ID from the DATA output pin. If this operation is shifted in during an erase or write cycle, it is ignored and has no effect on the cycle that is in progress.

Table 14–21 shows the serial configuration device silicon IDs.

Table 14–21. Serial Configuration Device Silicon ID				
Serial Configuration Device	Silicon ID (Binary Value)			
EPCS1	b'0001 0000			
EPCS4	b'0001 0010			
EPCS16	b'0001 0100			
EPCS64	b'0001 0110			

The device implements the read silicon ID operation by driving nCS low then shifting in the read silicon ID operation code followed by three dummy bytes on ASDI. The serial configuration device's 8-bit silicon ID is then shifted out on the DATA pin on the falling edge of DCLK, as shown in Figure 14–12. The device can terminate the read silicon ID operation by driving nCS high after the silicon ID has been read at least once. Sending additional clock cycles on DCLK while nCS is driven low can cause the silicon ID to be shifted out repeatedly.

Figure 14–12. Read Silicon ID Operation Timing Diagram Note (1)



#### Note to Figure 14–12:

(1) Only EPCS1, EPCS4, EPCS16, and EPCS64 support Read Silicon ID operation.

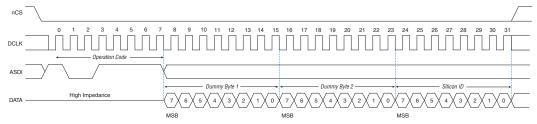
#### Read Device Identification Operation

The read device identification operation code is b' 1001 1111, with the MSB listed first. Only EPCS128 supports this operation. It reads the serial configuration device's 8-bit device identification from the DATA output pin. If this operation is shifted in during an erase or write cycle, it is ignored and has no effect on the cycle that is in progress. Table 14–22 shows the serial configuration device identification.

Table 14–22. Serial Configuration Device Identification					
Serial Configuration Device	Serial Configuration Device Silicon ID (Binary Value)				
EPCS128	b'0001 1000				

The device implements the read device identification operation by driving nCS low then shifting in the read device identification operation code followed by one dummy byte on ASDI. The serial configuration device's 16-bit device identification is then shifted out on the DATA pin on the falling edge of DCLK, as shown in Figure 14–13. The device can terminate the read device identification operation by driving nCS high after reading the device identification at least once.





#### Note to Figure 14–13:

(1) Only EPCS128 supports read device identification operation.

#### Write Bytes Operation

The write bytes operation code is b'0000 0010, with the MSB listed first. The write bytes operation allows bytes to be written to the memory. The write enable operation must be executed prior to the write bytes operation to set the write enable latch bit in the status register to 1.

The write bytes operation is implemented by driving nCS low, followed by the write bytes operation code, three address bytes and a minimum one data byte on ASDI. If the eight least significant address bits (A[7..0]) are not all 0, all sent data that goes beyond the end of the current page is not written into the next page. Instead, this data is written at the start address of the same page (from the address whose eight LSBs are all 0). Drive nCS low during the entire write bytes operation sequence, as shown in Figure 14–14.

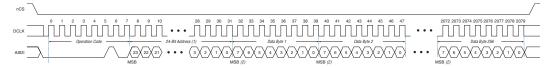
If more than 256 data bytes are shifted into the serial configuration device with a write bytes operation, the previously latched data is discarded and the last 256 bytes are written to the page. However, if less than 256 data bytes are shifted into the serial configuration device, they are guaranteed to be written at the specified addresses and the other bytes of the same page are unaffected.

If the design must write more than 256 data bytes to the memory, it needs more than one page of memory. Send the write enable and write bytes operation codes followed by three new targeted address bytes and 256 data bytes before a new page is written.

nCS must be driven high after the eighth bit of the last data byte has been latched in. Otherwise, the device will not execute the write bytes operation. The write enable latch bit in the status register is reset to 0 before the completion of each write bytes operation. Therefore, the write enable operation must be carried out before the next write bytes operation.

The device initiates the self-timed write cycle immediately after nCS is driven high. Refer to  $t_{WB}$  in Table 14–23 for the self-timed write cycle time for the respective EPCS devices. Therefore, you must account for this amount of delay before another page of memory is written. Alternatively, you can check the status register's write in progress bit by executing the read status operation while the self-timed write cycle is in progress. The write in progress bit is set to 1 during the self-timed write cycle, and 0 when it is complete.

Figure 14–14. Write Bytes Operation Timing Diagram



#### Notes to Figure 14–14:

- (1) Address bit A[23] is a don't-care bit in EPCS64. Address bits A[23..21] are don't-care bits in EPCS16. Address bits A[23..19] are don't-care bits in EPCS1.
- For RPD files, write the LSB of the data byte first.

#### Erase Bulk Operation

The erase bulk operation code is b'1100 0111, with the MSB listed first. The erase bulk operation sets all memory bits to 1 or 0xFF. Similar to the write bytes operation, the write enable operation must be executed prior to the erase bulk operation so that the write enable latch bit in the status register is set to 1.

You can implement the erase bulk operation by driving nCS low and then shifting in the erase bulk operation code on the ASDI pin. nCS must be driven high after the eighth bit of the erase bulk operation code has been latched in. Figure 14–15 shows the timing diagram.

The device initiates the self-timed erase bulk cycle immediately after nCS is driven high. Refer to  $t_{EB}$  in Table 14–23 for the self-timed erase bulk cycle time for the respective EPCS devices.

You must account for this delay before accessing the memory contents. Alternatively, you can check the write in progress bit in the status register by executing the read status operation while the self-timed erase cycle is in progress. The write in progress bit is 1 during the self-timed erase cycle and 0 when it is complete. The write enable latch bit in the status register is reset to 0 before the erase cycle is complete.

Figure 14-15. Erase Bulk Operation Timing Diagram

#### Erase Sector Operation

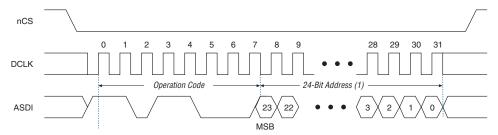
The erase sector operation code is b'1101 1000, with the MSB listed first. The erase sector operation allows the user to erase a certain sector in the serial configuration device by setting all bits inside the sector to 1 or  $0 \times FF$ . This operation is useful for users who access the unused sectors as general purpose memory in their applications.

The write enable operation must be executed prior to the erase sector operation so that the write enable latch bit in the status register is set to 1.

The erase sector operation is implemented by first driving nCS low, then shifting in the erase sector operation code and the three address bytes of the chosen sector on the ASDI pin. The three address bytes for the erase sector operation can be any address inside the specified sector. (Refer to Tables 14–10 through 14–14 for sector address range information.) Drive nCS high after the eighth bit of the erase sector operation code has been latched in. Figure 14–16 shows the timing diagram.

Immediately after the device drives nCS high, the self-timed erase sector cycle is initiated. Refer to  $t_{\rm ES}$  in Table 14–23 for the self-timed erase sector cycle time for the respective EPCS devices. You must account for this amount of delay before the memory contents can be accessed. Alternatively, you can check the write in progress bit in the status register by executing the read status operation while the erase cycle is in progress. The write in progress bit is 1 during the self-timed erase cycle and 0 when it is complete. The write enable latch bit in the status register resets to 0 before the erase cycle is complete.

Figure 14–16. Erase Sector Operation Timing Diagram



Note to Figure 14–16:

(1) Address bit A[23] is a don't-care bit in EPCS64. Address bits A[23..21] are don't-care bits in EPCS16. Address bits A[23..19] are don't-care bits in EPCS1.

# Power and Operation

This section describes the power modes, power-on reset (POR) delay, error detection, and initial programming state of serial configuration devices.

#### Power Mode

Serial configuration devices support active power and standby power modes. When nCS is low, the device is enabled and is in active power mode. The FPGA is configured while in active power mode. When nCS is high, the device is disabled but could remain in active power mode until all internal cycles have completed (such as write or erase operations). The serial configuration device then goes into stand-by power mode. The  $\rm I_{CC1}$  parameter specifies the  $\rm V_{CC}$  supply current when the device is in active power mode and the  $\rm I_{CC0}$  parameter specifies the current when the device is in stand-by power mode (refer to Table 14–29).

#### **Power-On Reset**

During initial power-up, a POR delay occurs to ensure the system voltage levels have stabilized. During AS configuration, the FPGA controls the configuration and has a longer POR delay than the serial configuration device.



For the POR delay time, refer to the configuration chapter in the appropriate device handbook.

#### **Error Detection**

During AS configuration with the serial configuration device, the FPGA monitors the configuration status through the nSTATUS and CONF\_DONE pins. If an error condition occurs (nSTATUS drives low) or if the CONF\_DONE pin does not go high, the FPGA will initiate reconfiguration by pulsing the nSTATUS and nCSO signals, which controls the chip select pin on the serial configuration device (nCS).

After an error, configuration automatically restarts if the **Auto-Restart Upon Frame Error** option is turned on in the Quartus II software. If the option is turned off, the system must monitor the nSTATUS signal for errors and then pulse the nCONFIG signal low to restart configuration.

# Timing Information

Figure 14–17 shows the timing waveform for write operation to the serial configuration device.

Figure 14-17. Write Operation Timing

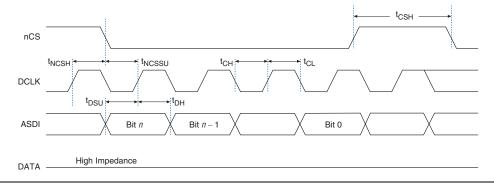


Table 14–23 defines the serial configuration device timing parameters for write operation.

Table 14–23. Write Operation Parameters (Part 1 of 2)							
Symbol	Parameter	Min	Тур	Max	Unit		
f <sub>WCLK</sub>	Write clock frequency (from FPGA, download cable, or embedded processor) for write enable, write disable, read status, read silicon ID, write bytes, erase bulk, and erase sector operations	_	_	25	MHz		
t <sub>CH</sub>	DCLK high time	20	_	_	ns		
t <sub>CL</sub>	DCLK low time	20	_	_	ns		
t <sub>NCSSU</sub>	Chip select (nCS) setup time	10	_	_	ns		
t <sub>NCSH</sub>	Chip select (nCS) hold time	10	_	_	ns		
t <sub>DSU</sub>	Data (ASDI) in setup time before rising edge on DCLK	5	_	_	ns		
t <sub>DH</sub>	Data (ASDI) hold time after rising edge on DCLK	5	_	_	ns		
t <sub>CSH</sub>	Chip select high time	100	_	_	ns		
t <sub>WB</sub> (1)	Write bytes cycle time for EPCS1, EPCS4, EPCS16, and EPCS64	_	1.5	5	ms		
	Write bytes cycle time for EPCS128	_	2.5	7	ms		
t <sub>WS</sub> (1)	Write status cycle time	_	5	15	ms		

Table 14–23. Write Operation Parameters (Part 2 of 2)						
Symbol	Parameter	Min	Тур	Max	Unit	
t <sub>EB</sub> (1)	Erase bulk cycle time for EPCS1	_	3	6	s	
	Erase bulk cycle time for EPCS4	_	5	10	S	
	Erase bulk cycle time for EPCS16	_	17	40	S	
	Erase bulk cycle time for EPCS64	_	68	160	S	
	Erase bulk cycle time for EPCS128	_	105	250	S	
t <sub>ES</sub> (1)	Erase sector cycle time for EPCS1, EPCS4, EPCS16, and EPCS64	_	2	3	S	
	Erase sector cycle time for EPCS128	_	2	6	S	

#### *Note to Table 14–23:*

Figure 14–18 shows the timing waveform for the serial configuration device's read operation.

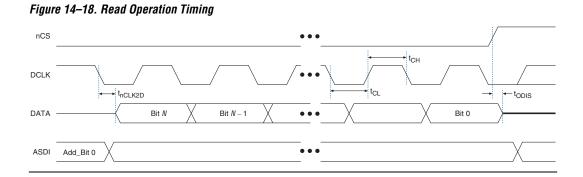


Table 14–24 defines the serial configuration device timing parameters for read operation.

Table 14–24. Read Operation Parameters (Part 1 of 2)						
Symbol Parameter Min Max Ur						
f <sub>RCLK</sub>	Read clock frequency (from FPGA or embedded processor) for read bytes operation	_	20	MHz		
t <sub>CH</sub>	DCLK high time	25	_	ns		
t <sub>CL</sub>	DCLK low time	25	_	ns		

<sup>(1)</sup> These parameters are not shown in Figure 14–17.

Table 14–24. Read Operation Parameters (Part 2 of 2)						
Symbol Parameter Min Max Uni						
t <sub>odis</sub>	Output disable time after read	_	15	ns		
t <sub>nCLK2D</sub>	Clock falling edge to data	_	15	ns		

Figure 14–19 shows the timing waveform for FPGA AS configuration scheme using a serial configuration device.

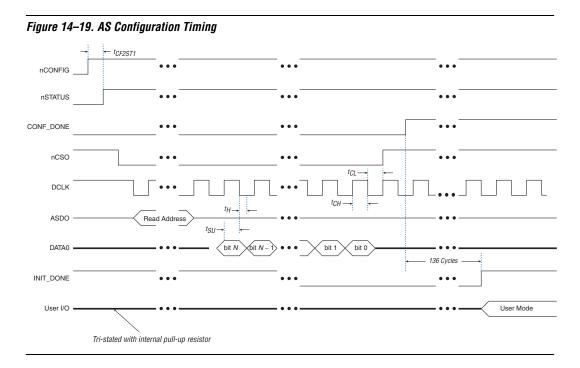


Table 14–25 shows the timin	parameters for A	S configuration i	mode.
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Table 14	Table 14–25. Timing Parameters for AS Configuration						
Symbol	Parameter	Min	Тур	Max	Unit		
f <sub>CLK</sub>	DCLK frequency from Cyclone FPGA	14	17	20	MHz		
	DCLK frequency from Stratix II or Cyclone II FPGA (40 MHz) (1)	20	26	40	MHz		
	DCLK frequency from Stratix II or Cyclone II FPGA (20 MHz)	10	13	20	MHz		
	DCLK frequency from Cyclone III FPGA (1)	20	30	40	MHz		
	DCLK frequency from Stratix III FPGA (1)	15	25	40	MHz		
t <sub>H</sub>	Data hold time after rising edge on DCLK	0	_	_	ns		
t <sub>SU</sub>	Data set up time before rising edge on DCLK	5		_	ns		

#### Note to Table 14-25:

(1) Existing batches of EPCS1 and EPCS4 manufactured on 0.15 µm process geometry supports AS configuration up to 40 MHz. However, batches of EPCS1 and EPCS4 manufactured on 0.18 µm process geometry support only up to 20 MHz. EPCS16, EPCS64, and EPCS128 are not affected. For information about product traceability and transition date to differentiate between 0.15 µm process geometry and 0.18 µm process geometry EPCS1 and EPCS4, refer to PCN 0514 Manufacturing Changes on EPCS Family process change notification on the Altera website at www.altera.com.

# Programming and Configuration File Support

The Quartus II design software provides programming support for serial configuration devices. After selecting the serial configuration device, the Quartus II software automatically generates the Programmer Object File (.pof) to program the device. The software allows users to select the appropriate serial configuration device density that most efficiently stores the configuration data for a selected FPGA.

The serial configuration device can be programmed in-system by an external microprocessor using SRunner. SRunner is a software driver developed for embedded serial configuration device programming that designers can customize to fit in different embedded systems. The SRunner can read RPD file and write to the serial configuration devices. The programming time is comparable to the Quartus II software programming time. Note that writing and reading the RPD file to the EPCS is different from other data and address bytes. The LSB of RPD bytes must be shifted out first during the read bytes instruction and the LSB of RPD bytes must be shifted in first during the write bytes instruction. This is because the FPGA reads the LSB of the RPD data first during the configuration process.



For more information about SRunner, refer to the *AN 418: SRunner: An Embedded Solution for Serial Configuration Device Programming User Guide* and the source code on the Altera website (www.altera.com).

Serial configuration devices can be programmed using the APU with the appropriate programming adapter (PLMSEPC-8) via the Quartus II software, USB Blaster, EthernetBlaster, or the ByteBlaster II download cable via the Quartus II software. In addition, many third-party programmers, such as BP Microsystems and System General, offer programming hardware that supports serial configuration devices.

During in-system programming of a serial configuration device via the USB Blaster, EthernetBlaster, or ByteBlaster II download cable, the cable pulls <code>nCONFIG</code> low to reset the FPGA and overrides the  $10\text{-}k\Omega$  pull-down resistor on the FPGA's <code>nCE</code> pin (refer to Figure 14–2). The download cable then uses the four interface pins (<code>DATA, nCS, ASDI,</code> and <code>DCLK</code>) to program the serial configuration device. Once the programming is complete, the download cable releases the serial configuration device's four interface pins and the FPGA's <code>nCE</code> pin, and pulses <code>nCONFIG</code> to start configuration.

The FPGA can program the serial configuration device in-system using the JTAG interface with the Serial FlashLoader. This solution allows you to indirectly program the serial configuration device using the same JTAG interface that is used to configure the FPGA.



For more information about the Serial FlashLoader, refer to *AN 370: Using the Serial FlashLoader with the Quartus II Software.* 



For more information on programming and configuration support, refer to the following documents:

- Altera Programming Hardware Data Sheet
- Programming Hardware Manufacturers
- USB-Blaster Download Cable User Guide
- ByteBlaster II Download Cable User Guide
- EthernetBlaster Communications Cable User Guide

## Operating Conditions

Tables 14–26 through 14–30 provide information on absolute maximum ratings, recommended operating conditions, DC operating conditions, and capacitance for serial configuration devices.

Table 14	1–26. Absolute Maximum Ratings	Note (1) (Part 1 of 2)			
Symbol	Parameter	Condition	Min	Max	Unit
V <sub>CC</sub>	Supply voltage for EPCS1, EPCS4, and EPCS16	With respect to ground	-0.6	4.0	V
	Supply voltage for EPCS64 and EPCS128	With respect to ground	-0.2	4.0	V

Table 14	1–26. Absolute Maximum Ratings	Note (1) (Part 2 of 2)			
Symbol	Parameter	Condition	Min	Max	Unit
VI	DC input voltage for EPCS1, EPCS4, and EPCS16	With respect to ground	-0.6	4.0	V
	DC input voltage for EPCS64 and EPCS128	With respect to ground	-0.5	4.0	V
I <sub>MAX</sub>	DC V <sub>CC</sub> or GND current	_	_	15	mA
I <sub>OUT</sub>	DC output current per pin	_	-25	25	mA
$P_D$	Power dissipation	_	_	54	mW
T <sub>STG</sub>	Storage temperature	No bias	-65	150	°C
T <sub>AMB</sub>	Ambient temperature	Under bias	-65	135	°C
T <sub>J</sub>	Junction temperature	Under bias	_	135	°C

Table 14	Table 14–27. Recommended Operating Conditions								
Symbol	Parameter	Conditions	Min	Max	Unit				
V <sub>CC</sub>	Supply voltage	(2)	2.7	3.6	V				
Vı	Input voltage	Respect to GND	-0.3	0.3 + V <sub>CC</sub>	V				
Vo	Output voltage	_	0	V <sub>CC</sub>	V				
T <sub>A</sub>	Operating temperature	For commercial use	0	70	°C				
		For industrial use	-40	85	°C				
t <sub>R</sub>	Input rise time	_	_	5	ns				
t <sub>F</sub>	Input fall time	_	_	5	ns				

Table 14	Table 14–28. DC Operating Conditions							
Symbol	Parameter	Conditions	Min	Max	Unit			
V <sub>IH</sub>	High-level input voltage for EPCS1, EPCS4, and EPCS16	_	$0.6 \times V_{CC}$	V <sub>CC</sub> + 0.4	V			
	High-level input voltage for EPCS64 and EPCS128	_	$0.6 \times V_{CC}$	V <sub>CC</sub> + 0.2	V			
V <sub>IL</sub>	Low-level input voltage	_	-0.5	$0.3 \times V_{CC}$	V			
V <sub>OH</sub>	High-level output voltage	$I_{OH} = -100 \ \mu A \ (3)$	V <sub>CC</sub> - 0.2	_	V			
V <sub>OL</sub>	Low-level output voltage	I <sub>OL</sub> = 1.6 mA (3)	_	0.4	V			
I <sub>I</sub>	Input leakage current	V <sub>I</sub> = V <sub>CC</sub> or GND	-10	10	μΑ			
I <sub>OZ</sub>	Tri-state output off-state current	V <sub>O</sub> = V <sub>CC</sub> or GND	-10	10	μА			

Table 14–29. I <sub>CC</sub> Supply Current							
Symbol	Parameter	Conditions	Min	Max	Unit		
I <sub>CC0</sub>	V <sub>CC</sub> supply current (standby) for EPCS1, EPCS4, and EPCS16	_	_	50	μА		
	V <sub>CC</sub> supply current (standby) for EPCS64 and EPCS128	_	_	100	μА		
I <sub>CC1</sub>	V <sub>CC</sub> supply current (during active power mode) for EPCS1, EPCS4, and EPCS16	_	5	15	mA		
	V <sub>CC</sub> supply current (during active power mode) for EPCS64 and EPCS128	_	5	20	mA		

Table 14	Table 14–30. CapacitanceNote (4)						
Symbol	Parameter	Conditions	Min	Max	Unit		
C <sub>IN</sub>	Input pin capacitance	$V_{IN} = 0 V$	_	6	pF		
C <sub>OUT</sub>	Output pin capacitance	V <sub>OUT</sub> = 0 V	_	8	pF		

#### Notes to Table 14–26 through 14–30:

- (1) Refer to the Operating Requirements for Altera Devices Data Sheet.
- (2) Maximum V<sub>CC</sub> rise time is 100 ms.
- (3) The I<sub>OH</sub> parameter refers to high-level TTL or CMOS output current; the I<sub>OL</sub> parameter refers to low-level TTL or CMOS output current.
- (4) Capacitance is sample-tested only at  $T_A = 25$  °C and at a 20-MHz frequency.

#### **Pin Information**

As shown in Figures 14–20 and 14–21, the serial configuration device is an 8-pin or 16-pin device. The control pins on the serial configuration device are: serial data output (DATA), active serial data input (ASDI), serial clock (DCLK), and chip select (nCS). Table 14–31 shows the serial configuration device's pin descriptions.

Figure 14–20 shows the Altera serial configuration device 8-pin SOIC package and its pin-out diagram.

Figure 14–20. Altera Serial Configuration Device 8-Pin SOIC Package Pin-Out Diagram

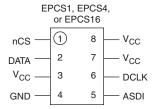
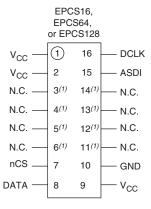


Figure 14–21 shows the Altera serial configuration device 16-pin SOIC package and its pin-out diagram.

Figure 14–21. Altera Serial Configuration Device 16-Pin SOIC Package Pin-Out Diagram



Note to Figure 14–21:

 These pins can be left floating or connected to V<sub>CC</sub> or GND, whichever is more convenient on the board.

Table 1	Table 14–31. Serial Configuration Device Pin Description					
Pin Name	Pin Number in 8-Pin SOIC Package	Pin Number in 16-Pin SOIC Package	Pin Type	Description		
DATA	2	8	Output	The DATA output signal transfers data serially out of the serial configuration device to the FPGA during read/configuration operation. During a read/configuration operations, the serial configuration device is enabled by pulling nCS low. The DATA signal transitions on the falling edge of DCLK.		
ASDI	5	15	Input	The AS data input signal is used to transfer data serially into the serial configuration device. It receives the data that should be programmed into the serial configuration device. Data is latched on the rising edge of DCLK.		
nCS	1	7	Input	The active low chip select input signal toggles at the beginning and end of a valid instruction. When this signal is high, the device is deselected and the DATA pin is tri-stated. When this signal is low, it enables the device and puts the device in an active mode. After power up, the serial configuration device requires a falling edge on the nCS signal before beginning any operation.		
DCLK	6	16	Input	DCLK is provided by the FPGA. This signal provides the timing of the serial interface. The data presented on ASDI is latched to the serial configuration device on the falling edge of DCLK. Data on the DATA pin changes after the falling edge of DCLK and is latched into the FPGA on the falling edge.		
V <sub>CC</sub>	3, 7, 8	1, 2, 9	Power	Power pins connect to 3.3 V.		
GND	4	10	Ground	Ground pin.		

### **Package**

All serial configuration devices are available in 8-pin or 16-pin plastic SOIC package.



For more information on Altera device packaging including mechanical drawing and specifications for this package, refer to the *Altera Device Package Information Data Sheet*.

### **Ordering Code**

Table 14–32 shows the ordering codes for serial configuration devices.

Table 14–32. Serial Configuration Device Ordering Codes					
Device	Ordering Code (1)				
EPCS1	EPCS1SI8 EPCS1SI8N				
EPCS4	EPCS4SI8 EPCS4SI8N				
EPCS16	EPCS16SI16N EPCS16SI8N				
EPCS64	EPCS64SI16N				
EPCS128	EPCS128SI16N				

Note to Table 14-32:

(1) N: Lead free.

# Referenced Documents

This chapter references the following documents:

- Active Serial Memory Interface Data Sheet
- Altera Device Package Information Data Sheet
- Altera Programming Hardware Data Sheet
- AN 370: Using the Serial FlashLoader with the Quartus II Software
- AN 418: SRunner: An Embedded Solution for Serial Configuration Device Programming User Guide
- ByteBlaster II Download Cable User Guide
- Configuring Cyclone III Devices chapter in volume 1 of the Cyclone III Device Handbook
- EthernetBlaster Communications Cable User Guide
- Operating Requirements for Altera Devices Data Sheet
- Programming Hardware Manufacturers
- USB-Blaster Download Cable User Guide

# Document Revision History

Table 14–33 shows the revision history for this chapter.

Table 14–33. Document Revision History (Part 1 of 2)					
Date and Document Version	Changes Made	Summary of Changes			
May 2008 v3.1	<ul> <li>Updated Tables 14–2, 14–5, 14–6, 14–27, and 14–28.</li> <li>Deleted Note 5 to Table 14–30.</li> <li>Added "Referenced Documents" section.</li> </ul>	_			
August 2007 v3.0	<ul> <li>Updated "Introduction" section.</li> <li>Updated "Functional Description" section.</li> <li>Updated Tables 14–1 through 14–3 and Tables 14–6 through 14–8 to with EPCS128 information.</li> <li>Added Table 14–5 on Arria GX.</li> <li>Added Note (4) to Figure 14–3.</li> <li>Added Note (5) to Figure 14–4.</li> <li>Updated Table 14–9 with EPCS128 information.</li> <li>Added new Table 14–10 on address range for sectors in EPCS128.</li> <li>Updated Table 14–15 with information on "Read Device Identification" and added Note (5).</li> <li>Added new Table 14–20 on block protection bits in EPCS128.</li> <li>Added Note (1) to Figure 14–12.</li> <li>Added new section "Read Device Identification Operation" with Table 14–22 and Figure 14–13.</li> <li>Updated "Write Bytes Operation", "Erase Bulk Operation" and "Erase Sector Operation" sections.</li> <li>Updated Table 14–23 to include EPCS128 information.</li> <li>Updated Note (1) to Table 14–25.</li> <li>Updated V<sub>CC</sub> and V<sub>I</sub> information to include EPCS128 in Table 14–26.</li> <li>Updated I<sub>CC0</sub> and I<sub>CC1</sub> information to include EPCS128 in Table 14–29.</li> <li>Updated Figure 14–21 and Table 14–32 with EPCS128 information.</li> </ul>	Updated document to include EPCS128.     Updated document to include Arria GX.			
April 2007 v2.0	<ul> <li>Updated "Introduction" section.</li> <li>Updated "Functional Description" section and added handpara note.</li> <li>Added Tables 14–3, 14–5, and 14–6.</li> <li>Updated "Active Serial FPGA Configuration" section and its handpara note.</li> <li>Added Note (4) to Figure 14–2.</li> <li>Updated Table 14–25 and added Note (1).</li> <li>Updated Figure 14–20.</li> <li>Updated Table 14–32.</li> </ul>	<ul> <li>Updated chapter to include Stratix II GX, Stratix III, and Cyclone III support for EPCS devices.</li> <li>Added information about EPCS16SI8N.</li> </ul>			
January 2007 v1.7	<ul> <li>Removed reference to PLMSEPC-16 in "Programming and Configuration File Support".</li> <li>Updated DCLK pin information in Table 14–31.</li> </ul>	_			

Table 14–33. Document Revision History (Part 2 of 2)					
Date and Document Version	Changes Made	Summary of Changes			
October 2006 v1.6	<ul><li>Updated Figure 14–19.</li><li>Updated Table 14–29 and Table 14–31.</li></ul>	_			
August 2005 v1.5	Updated table 4-4 to include EPCS64 support for Cyclone devices.	_			
August 2005 v1.4	<ul><li>Updated tables.</li><li>Minor text updates.</li></ul>	_			
February 2005 v1.3	Updated hot socketing AC specifications.	_			
October 2003 v1.2	<ul> <li>Added Serial Configuration Device Memory Access section.</li> <li>Updated timing information in Tables 4–10 and 4–11.section.</li> <li>Updated timing information in Tables 4-16 and 4-17.</li> </ul>	_			
July 2003 v1.1	Minor updates.	_			
May 2003 v1.0	Added document to the Cyclone Device Handbook.	_			



# Section VII. Cyclone Device Package Information

This section provides information for board layout designers to successfully layout their boards for Cyclone devices. It contains the required PCB layout guidelines, device pin tables, and package specifications.

This section includes the following chapter:

■ Chapter 15. Package Information for Cyclone Devices

#### **Revision History**

Refer to each chapter for its own specific revision history. For information on when each chapter was updated, refer to the Chapter Revision Dates section, which appears in the complete handbook.

Altera Corporation Section VII–1

Section VII-2 Altera Corporation



# 15. Package Information for Cyclone Devices

C52006-1.3

#### Introduction

This data sheet provides package information for Altera® devices. It includes the following sections:

- "Device and Package Cross Reference" on page 15–1
- "Thermal Resistance" on page 15–2
- "Package Outlines" on page 15–2

In this data sheet, packages are listed in the order of ascending pin count.

# Device and Package Cross Reference

Table 15–1 shows which Altera Cyclone® devices are available in FineLine BGA packages.

Table 15–1. Cyclone Devices in FineLine BGA Packages					
Device	Package	Pins			
EP1C4	Non-Thermally Enhanced FineLine BGA	324			
	Non-Thermally Enhanced FineLine BGA	400			
EP1C6	Non-Thermally Enhanced FineLine BGA	256			
EP1C12 Non-Thermally Enhanced FineLine BGA		256			
	Non-Thermally Enhanced FineLine BGA	324			
EP1C20	Non-Thermally Enhanced FineLine BGA	324			
	Non-Thermally Enhanced FineLine BGA	400			

### Thermal Resistance

Table 15–2 provides  $\theta_{JA}$  (junction-to-ambient thermal resistance) and  $\theta_{JC}$  (junction-to-case thermal resistance) values for Altera Cyclone devices.

Table 15-2	Table 15–2. Thermal Resistance of Cyclone Devices   Notes (1), (2)						
Device	Pin Count	Package	θ <sub>JC</sub> (° C/W)	θ <sub>JA</sub> (° C/W) Still Air	θ <sub>JA</sub> (° C/W) 100 ft./min.	θ <sub>JA</sub> (° C/W) 200 ft./min.	θ <sub>JA</sub> (° C/W) 400 ft./min.
EP1C3	100	TQFP	11.0	37.5	35.4	33.4	29.8
	144	TQFP	10.0	31.1	29.4	27.9	25.5
EP1C4	324	FineLine BGA	8.3	28.5	24.4	22.1	20.3
	400	FineLine BGA	7.9	20.7	17.5	15.5	13.9
EP1C6	144	TQFP	9.8	29.4	28.0	26.7	24.7
	240	PQFP	4.3	27.2	24.7	22.1	17.8
	256	FineLine BGA	8.8	28.7	24.5	22.3	20.5
EP1C12	240	PQFP	4.0	26.0	23.4	20.8	17.1
	256	FineLine BGA	6.6	24.3	20.2	18.1	16.4
	324	FineLine BGA	6.1	23.0	19.8	17.7	16.1
EP1C20	324	FineLine BGA	5.0	21.0	17.7	15.6	14.1
	400	FineLine BGA	4.7	20.7	17.5	15.5	13.9

Notes to Table 15-2:

### Package Outlines

The package outlines on the following pages are listed in order of ascending pin count. Altera package outlines meet the requirements of *JEDEC Publication No. 95*.

<sup>(1)</sup> TQFP: thin quad flat pack

<sup>(2)</sup> PQFP: plastic quad flat pack

### Document Revision History

Table 15–3 shows the revision history for this chapter.

Table 15–3. Document Revision History					
Date and Document Version	Changes Made	Summary of Changes			
May 2008 v1.3	Minor changes to format.	_			
January 2007 v1.2	Added document revision history.	_			





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